

In the Matter of

**CERTAIN PLASTIC ENCAPSULATED
INTEGRATED CIRCUITS**

Investigation No. 337-TA-315

**USITC PUBLICATION 2574
NOVEMBER 1992**

**United States International Trade Commission
Washington, DC 20436**



UNITED STATES INTERNATIONAL TRADE COMMISSION

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Secretary to the Commission
United States International Trade Commission
Washington, DC 20436**

UNITED STATES INTERNATIONAL TRADE COMMISSION
Washington, DC 20436

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In the Matter of)

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CERTAIN PLASTIC ENCAPSULATED)
INTEGRATED CIRCUITS)
_____)

Investigation No. 337-TA-315

NOTICE OF ISSUANCE OF LIMITED EXCLUSION ORDER
AND CEASE AND DESIST ORDERS

AGENCY: U.S. International Trade Commission.

ACTION: Notice

SUMMARY: Notice is hereby given that the Commission has issued a limited exclusion order and cease and desist orders in the above-captioned investigation.

FOR FURTHER INFORMATION CONTACT: Andrea C. Casson, Esq., Office of the General Counsel, U.S. International Trade Commission, 500 E Street, S.W., Washington, D.C. 20436, telephone 202-205-3105.

SUPPLEMENTARY INFORMATION: The authority for the Commission's determination is contained in section 337 of the Tariff Act of 1930, as amended (19 U.S.C. § 1337), and in section 210.58 of the Commission's Interim Rules of Practice and Procedure (19 C.F.R. § 210.58).

On July 9, 1990, Texas Instruments Incorporated (TI) filed a complaint under section 337 of the Tariff Act of 1930 (19 U.S.C. § 1337) alleging that respondents Analog Devices, Inc. (Analog), Integrated Device Technology, Inc. (IDT), LSI Logic Corporation (LSI), VLSI Technology, Inc. (VLSI), and Cypress Semiconductor Corporation (Cypress), had imported and sold within the United States certain plastic encapsulated integrated circuits manufactured by a process covered by certain claims of U.S. Letters Patent 4,043,027 (the '027 patent). The Commission instituted an investigation of the complaint and issued a notice of investigation that was published in the Federal Register on August 15, 1990 (55 Fed. Reg. 33388).

On October 15, 1991, the presiding administrative law judge (ALJ) issued a final initial determination (ID) finding a violation of section 337 on the ground that certain of respondents' imported plastic encapsulated integrated circuits were manufactured by a process covered by claims 12 and 14 of the '027 patent. The ALJ found that the processes used for manufacturing these products was not covered by claims 1 and 17 of the '027 patent. In addition, he found that certain other plastic encapsulated integrated circuits imported by respondents (those encapsulated using a process called "same-side" gating) were not covered by claims 1, 12, 14, or 17 of the '027 patent.

On December 12, 1991, the Commission determined to review the issues of (1) claim construction and infringement of claim 17 of the '027 patent and (2) whether the claims in controversy of the '027 patent are invalid as obvious under 35 U.S.C. § 103. The Commission determined not to review the remainder of the ID. The Commission solicited comments from the parties, interested government agencies, and other persons concerning the issues under review and the issues of remedy, the public interest, and bonding.

Complainant, all respondents, and the Commission investigative attorneys filed briefs addressing the issues under review and the issues of remedy, the public interest, and bonding. No comments were filed by interested government agencies or other persons.

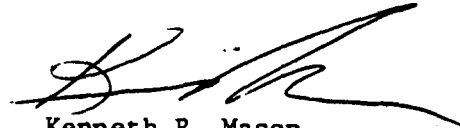
After review, the Commission affirmed the ALJ's determination that all respondents had violated section 337 in the importation of opposite-side gated plastic encapsulated integrated circuits manufactured by a process covered by claims 12 and 14 of the '027 patent. In addition, the Commission determined that respondents Analog and VLSI had violated section 337 in the importation of opposite-side gated plastic encapsulated integrated circuits manufactured by a process covered by claim 17 of the '027 patent.

Having determined that there is a violation of section 337, the Commission considered the questions of the appropriate remedy, whether the statutory public interest factors preclude the issuance of a remedy, and bonding during the Presidential review period. The Commission determined that the appropriate form of relief is a limited exclusion order prohibiting all respondents from importing plastic encapsulated integrated circuits manufactured abroad by a process covered by claims 12 and 14 of the '027 patent, and additionally prohibiting respondents Analog and VLSI from importing plastic encapsulated integrated circuits manufactured abroad by a process covered by claim 17 of the '027 patent. The Commission further determined to issue cease and desist orders directed to each respondent. The Commission also determined that the public interest factors enumerated in 19 U.S.C. § 1337(d) do not preclude the issuance of the aforementioned relief, and that the bond during the Presidential review period covering infringing products imported or sold by respondents Cypress, IDT, LSI, and VLSI shall be in the amount of 2.5 percent of the entered value of the imported articles concerned, not to exceed \$0.50 per plastic encapsulated integrated circuit. The Commission further determined that respondent Analog will not be required during the Presidential review period to post a bond for products imported or sold.

Copies of the Commission's orders and all other nonconfidential documents filed in connection with this investigation are available for inspection during official business hours (8:45 a.m. to 5:15 p.m.) in the Office of the Secretary, U.S. International Trade Commission, 500 E Street, S.W., Washington, D.C. 20436, telephone 202-205-2000. Hearing-impaired

persons are advised that information on this matter can be obtained by contacting the Commission's TDD terminal on 202-205-1810.

By order of the Commission.

A handwritten signature in black ink, appearing to read 'K. R. Mason', with a long horizontal flourish extending to the right.

Kenneth R. Mason
Secretary

Issued: February 18, 1992

UNITED STATES INTERNATIONAL TRADE COMMISSION
Washington, DC 20436

In the Matter of)

CERTAIN PLASTIC ENCAPSULATED)
INTEGRATED CIRCUITS)

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) Investigation No. 337-TA-315
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ORDER

The Commission, having determined that there is a violation of section 337 of the Tariff Act of 1930 (19 U.S.C. § 1337) in the unlawful importation and sale of certain plastic encapsulated integrated circuits manufactured abroad according to a process, which, if practiced in the United States, would be covered by claims 12, 14, and 17 of U.S. Letters Patent 4,043,027, and having considered the issues of remedy, the public interest, and bonding, hereby ORDERS that--

1. Plastic encapsulated integrated circuits manufactured abroad according to a process covered by claims 12 or 14 of U.S. Letters Patent 4,043,027, and manufactured or imported by or on behalf of Analog Devices, Inc. (Analog), Integrated Device Technology, Inc. (IDT), LSI Logic Corporation (LSI), VLSI Technology, Inc. (VLSI), or Cypress Semiconductor Corporation (Cypress) or any of their affiliated companies, parents, subsidiaries, licensees, or other related business entities, or their successors or assigns, are excluded from entry into the United States for the remaining term of the patent, except under license of the patent owner or as provided by law.

2. Plastic encapsulated integrated circuits manufactured abroad according to a process covered by claim 17 of U.S. Letters Patent 4,043,027, and manufactured or imported by or on behalf of Analog or VLSI, or any of their affiliated companies, parents, subsidiaries, licensees, or other related business entities, or their successors or assigns, are excluded from entry into the United States for the remaining term of the patent, except under license of the patent owner or as provided by law.

3. Plastic encapsulated integrated circuits manufactured abroad according to a process covered by claims 12 or 14 of U.S. Letters Patent 4,043,027, assembled onto circuit boards or other similar carriers, and manufactured or imported by or on behalf of Analog, IDT, LSI, VLSI, or

Cypress or any of their affiliated companies, parents, subsidiaries, licensees, or other related business entities, or their successors or assigns are excluded from entry into the United States for the remaining term of the patent, except under license of the patent owner or as provided by law.

4. Plastic encapsulated integrated circuits manufactured abroad according to a process covered by claim 17 of U.S. Letters Patent 4,043,027, assembled onto circuit boards or other similar carriers, and manufactured or imported by or on behalf of Analog or VLSI, or any of their affiliated companies, parents, subsidiaries, licensees, or other related business entities, or their successors or assigns are excluded from entry into the United States for the remaining term of the patent, except under license of the patent owner or as provided by law.

5. The provisions of this order do not apply to downstream products (e.g., computers, computer peripheral devices, telecommunications equipment, other electronic equipment, or finished components thereof.)

6. The provisions of this order do not apply to products licensed by Texas Instruments, Inc.

7. Plastic encapsulated integrated circuits which are not manufactured by a process covered by claims 12, 14, or 17 of U.S. Letters Patent 4,043,027 and which are manufactured or imported by or on behalf of Analog, IDT, LSI, VLSI, or Cypress shall be permitted entry into the United States if the manufacturer or importer provides a certification to accompany the commercial invoice (whether filed electronically or otherwise) stating: [Name of Manufacturer/Importer] certifies that the plastic encapsulated integrated circuits that accompany this invoice either (i) are not made by a process covered by claims 12, 14, or 17 of U.S. Letters Patent 4,043,027, or (ii) are covered by a license.

8. The plastic encapsulated integrated circuits ordered to be excluded and manufactured or imported by or on behalf of IDT, LSI, VLSI, or Cypress are entitled to entry into the United States under bond in the amount of 2.5 percent of the entered value of the article, not to exceed \$0.50 per plastic encapsulated integrated circuit, after this Order is received by the President, pursuant to subsection (j) of section 337 of the Tariff Act of 1930, until such time as the President notifies the Commission that he approves or disapproves this action, but no later than 60 days after the date of receipt of this Order by the President.

9. The plastic encapsulated integrated circuits ordered to be excluded and manufactured or imported by or on behalf of Analog are entitled to entry into the United States without bond, after this Order is received by the President, pursuant to subsection (j) of section 337 of the Tariff Act of 1930, until such time as the President notifies the Commission that he approves or disapproves this action, but no later than 60 days after the date of receipt of this Order by the President.

10. Products identified in paragraphs (3) and (4) of this Order are entitled to entry into the United States from the day after this Order is received by the President, pursuant to subsection (j) of section 337 of the Tariff Act of 1930, until such time as the President notifies the Commission that he approves or disapproves this action, but no later than 60 days after the date of receipt of this Order by the President, subject to any bond requirements set forth in paragraph 8. Persons importing such products shall certify to the best of their knowledge the number of plastic encapsulated integrated circuits subject to this Order contained in such products, pursuant to procedures to be specified by the U.S. Customs Service.

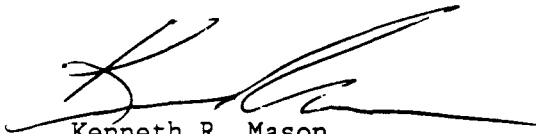
11. In accordance with 19 U.S.C. § 1337(1), the provisions of this Order shall not apply to plastic encapsulated integrated circuits imported by and for the use of the United States, or imported for, and to be used for, the United States with the authorization or consent of the Government.

12. The Commission may amend this Order in accordance with the procedure described in section 211.57 of the Commission's Interim Rules of Practice and Procedure (19 C.F.R. § 211.57).

13. The Secretary shall serve copies of this Order upon each party of record in this investigation and upon the Department of Health and Human Services, the Department of Justice, the Federal Trade Commission, and the U.S. Customs Service.

14. Notice of this Order shall be published in the Federal Register.

By order of the Commission.



Kenneth R. Mason
Secretary

Issued: February 18, 1992

UNITED STATES INTERNATIONAL TRADE COMMISSION
Washington, DC 20436

_____)
In the Matter of)
)
CERTAIN PLASTIC ENCAPSULATED)
INTEGRATED CIRCUITS)
_____)

Investigation No. 337-TA-315

ORDER TO CEASE AND DESIST

IT IS HEREBY ORDERED THAT Analog Devices, Inc., One Technology Way, Norwood, Massachusetts, 02062-4700, cease and desist from any unlicensed importing, selling for importation, assembling, testing, marketing, distributing, offering for sale, selling, or otherwise transferring (except for exportation) in the United States of imported plastic encapsulated integrated circuits made by a process covered by claims 12, 14, or 17 of U.S. Letters Patent 4,043,027, in violation of section 337 of the Tariff Act of 1930, as amended, 19 U.S.C. § 1337.

I.

(Definitions)

As used in this Order:

(A) "Commission" shall mean the United States International Trade Commission.

(B) "Complainant" shall mean Texas Instruments, Inc., P.O. Box 225474, 13500 North Central Expressway, Dallas, Texas 75265.

(C) "Respondent" shall mean Analog Devices, Inc., One Technology Way, Norwood, Massachusetts, 02062-4700.

(D) "Person" shall mean an individual, or any non-governmental

partnership, firm, association, corporation, or other legal or business entity other than the above Respondent or its majority owned and/or controlled subsidiaries, their successors, or assigns.

(E) "United States" shall mean the fifty States, the District of Columbia, and Puerto Rico;

(F) "Covered product" shall mean any "opposite-side gated" plastic encapsulated integrated circuit manufactured abroad according to a process which, if practiced in the United States, would infringe claims 12, 14, or 17 of U.S. Letters Patent 4,043,027.

II

(Applicability)

The provisions of this Cease and Desist **Order** shall apply to Respondent and to its principals, stockholders, officers, directors, employees, agents, licensees, distributors, controlled (whether by stock ownership or otherwise) and/or majority owned business entities, successors and assigns, and to each of them, in accordance with Section VII hereof.

III

(Conduct Prohibited)

The following conduct of Respondent in the United States is prohibited by this **Order**: Respondent shall not, except to the extent that it is licensed to do so, import or sell for importation into the United States, assemble, test, market, distribute, offer for sale, sell, or otherwise transfer (except for exportation) in the United States covered products, for the remaining term of U.S. Letters Patent 4,043,027.

IV

(Conduct Permitted)

Notwithstanding any other provision of this Order, specific conduct otherwise prohibited by the terms of this Order shall be permitted if, in a written instrument, Complainant licenses or authorizes such specific conduct, or such specific conduct is related to the importation or sale of covered products by or for the United States.

V

(Reporting)

Respondent shall submit quarterly reports during the period commencing on February 18, 1992, and extending through the remaining term of U.S. Letter Patent 4,043,027. The first report of Respondent shall be submitted within 60 days of the issuance of this Order. Thereafter, reports shall be submitted within 21 days of the close of each quarter. This reporting requirement shall continue in force until the expiration of U.S. Letters Patent 4,043,027 on August 23, 1994 unless, pursuant to subsection (j) of section 337 of the Tariff Act of 1930, the President notifies the Commission within 60 days after the date he receives this Order, that he disapproves this Order.

Respondent shall report to the Commission its importation and sales in the United States, including licensed sales, measured in units, of covered products, if any, during the reporting period in question.

Any failure to report shall constitute a violation of this Order.

VI

(Recordkeeping and Inspection)

(A) For the purpose of securing compliance with this Order, Respondent shall retain any and all records relating to the sale, offer for sale,

marketing, or distribution in the United States of covered products, made and received in the usual and ordinary course of business, whether in detail or in summary form, for a period of two years from the close of the fiscal year to which they pertain. Respondent shall also retain any and all records regarding licensed importation or sale of covered products.

(B) For the purposes of determining or securing compliance with this **Order** and for no other purpose, and subject to any privilege recognized by the Federal Courts of the United States, duly authorized representatives of the Commission shall, upon reasonable written notice by the Commission or its staff, be permitted access and the right to inspect and copy in Respondent's principal offices during office hours, and in the presence of counsel or other representatives if Respondent so chooses, all books, ledgers, accounts, correspondence, memoranda, financial reports, and other records and documents, both in detail and in summary form, for the purpose of verifying any matter or statement contained in the reports required to be retained under subparagraph VI(A) of this **Order**.

VII

(Service of Cease and Desist Order)

Respondent is ordered and directed to:

(A) Serve, within thirty (30) days after the effective date of this **Order**, a copy of this **Order** upon each of its respective officers, directors, managing agents, agents and employees who have any responsibility for the marketing, distribution, or sale of covered products in the United States;

(B) Serve, within thirty (30) days after the succession of any persons referred to in subparagraph VII(A) of this **Order**, a copy of the **Order** upon each successor; and

(C) Maintain such records as will show the name, title, and address of each person upon whom the Order has been served, as described in subparagraphs VII(A) and VII(B) of this Order, together with the date on which service was made.

The obligations set forth in subparagraphs VII(B) and VII(C) shall remain in effect until the date of expiration of U.S. Letters Patent 4,043,027.

VIII

(Confidentiality)

Information obtained by means provided for in Sections V and VI of this Order will be made available only to the Commission and its authorized representatives, will be entitled to confidential treatment, and will not be divulged by any authorized representative of the Commission to any person other than duly authorized representatives of the Commission, except as may be required in the course of securing compliance with this Order, or as otherwise required by law. Disclosure hereunder will not be made by the Commission without ten (10) days prior notice in writing to Respondent.

(Enforcement)

Violation of this Order may result in any of the actions specified in section 211.56 of the Commission's Interim Rules of Practice and Procedure, 19 C.F.R. § 211.56, including an action for civil penalties in accordance with section 337(f) of the Tariff Act of 1930, 19 U.S.C. § 1337(f), and any other action as the Commission may deem appropriate. In determining whether Respondent is in violation of this Order, the Commission may infer facts adverse to Respondent if Respondent fails to provide adequate or timely information.

X

(Modification)

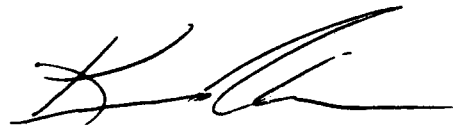
The Commission may amend this **Order** on its own motion or in accordance with the procedure described in section 211.57 of the Commission's Interim Rules of Practice and Procedure, 19 C.F.R. § 211.57.

XI

(Bonding)

The conduct prohibited by Section III of this **Order** may be continued by Respondent during the period in which this **Order** is under review by the President pursuant to section 337(j) of the Tariff Act of 1930 (19 U.S.C. § 1337(j)) without the necessity to post a bond.

By order of the Commission.



Kenneth R. Mason
Secretary

Issued: February 18, 1992

UNITED STATES INTERNATIONAL TRADE COMMISSION
Washington, DC 20436

In the Matter of)

CERTAIN PLASTIC ENCAPSULATED)
INTEGRATED CIRCUITS)
_____)

Investigation No. 337-TA-315

ORDER TO CEASE AND DESIST

IT IS HEREBY ORDERED THAT Integrated Device Technology, Inc., 2975 Stender Way, Santa Clara, California 95054; LSI Logic Corporation, 1551 McCarthy Boulevard, Milpitas, California 95035; VLSI Technology, Inc., 1109 McKay Drive, San Jose, California 95131; and Cypress Semiconductor Corporation, 3901 North First Street, San Jose, California 95134-1599, cease and desist from any unlicensed importing, selling for importation, assembling, testing, marketing, distributing, offering for sale, selling, or otherwise transferring (except for exportation) in the United States of imported plastic encapsulated integrated circuits made by a process covered by claims 12 or 14 of U.S. Letters Patent 4,043,027, in violation of section 337 of the Tariff Act of 1930, as amended, 19 U.S.C. § 1337.

IT IS FURTHER ORDERED THAT VLSI Technology, Inc., 1109 McKay Drive, San Jose, California 95131 cease and desist from any unlicensed importing, selling for importation, assembling, testing, marketing, distributing, offering for sale, selling, or otherwise transferring (except for exportation) in the United States of imported plastic encapsulated integrated circuits made by a process covered by claim 17 of U.S. Letters

Patent 4,043,027, in violation of section 337 of the Tariff Act of 1930, as amended, 19 U.S.C. § 1337.

I.

(Definitions)

As used in this Order:

(A) "Commission" shall mean the United States International Trade Commission.

(B) "Complainant" shall mean Texas Instruments, Inc., P.O. Box 225474, 13500 North Central Expressway, Dallas, Texas 75265.

(C) "Respondents" shall mean Integrated Device Technology, Inc., 2975 Stender Way, Santa Clara, California 95054; LSI Logic Corporation, 1551 McCarthy Boulevard, Milpitas, California 95035; VLSI Technology, Inc., 1109 McKay Drive, San Jose, California 95131; and Cypress Semiconductor Corporation, 3901 North First Street, San Jose, California 95134-1599.

(D) "Person" shall mean an individual, or any non-governmental partnership, firm, association, corporation, or other legal or business entity other than the above Respondents or their majority owned and/or controlled subsidiaries, their successors, or assigns.

(E) "United States" shall mean the fifty States, the District of Columbia, and Puerto Rico;

(F) "Covered product" shall mean any "opposite-side gated" plastic encapsulated integrated circuit manufactured abroad according to a process, which, if practiced in the United States, would infringe claims 12 or 14 of U.S. Letters Patent 4,043,027. With respect to respondent VLSI Technology, Inc., "covered product" shall additionally include any "opposite-side gated"

plastic encapsulated integrated circuit manufactured abroad according to a process, which, if practiced in the United States, would infringe claim 17 of U.S. Letters Patent 4,043,027.

II

(Applicability)

The provisions of this Cease and Desist **Order** shall apply to Respondents and to their principals, stockholders, officers, directors, employees, agents, licensees, distributors, controlled (whether by stock ownership or otherwise) and/or majority owned business entities, successors and assigns, and to each of them, in accordance with Section VII hereof.

III

(Conduct Prohibited)

The following conduct of Respondents in the United States is prohibited by this **Order**: Respondents shall not import or sell for importation into the United States, assemble, test, market, distribute, offer for sale, sell, or otherwise transfer (except for exportation) in the United States covered products, for the remaining term of U.S. Letters Patent 4,043,027.

IV

(Conduct Permitted)

Notwithstanding any other provision of this **Order**, specific conduct otherwise prohibited by the terms of this **Order** shall be permitted if, in a written instrument, Complainant licenses or authorizes such specific conduct, or such specific conduct is related to the importation or sale of covered products by or for the United States.

V

(Reporting)

Respondents shall each submit quarterly reports during the period commencing on February 18, 1992, and extending through the remaining term of U.S. Letters Patent 4,043,027. The first reports of Respondents shall be submitted within 60 days of the issuance of this Order. Thereafter, reports shall be submitted within 21 days of the close of each quarter. This reporting requirement shall continue in force until the expiration of U.S. Letters Patent 4,043,027 on August 23, 1994, unless, pursuant to subsection (j) of section 337 of the Tariff Act of 1930, the President notifies the Commission within 60 days after the date he receives this Order, that he disapproves this Order.

Respondents shall each report to the Commission their importation and sales in the United States, measured in units, of covered products, if any, during the reporting period in question.

Any failure to report shall constitute a violation of this Order.

VI

(Recordkeeping and Inspection)

(A) For the purpose of securing compliance with this Order, Respondents shall retain any and all records relating to the sale, offer for sale, marketing, or distribution in the United States of covered products, made and received in the usual and ordinary course of business, whether in detail or in summary form, for a period of two years from the close of the fiscal year to which they pertain.

(B) For the purposes of determining or securing compliance with this Order and for no other purpose, and subject to any privilege recognized by the Federal Courts of the United States, duly authorized representatives of the Commission shall, upon reasonable written notice by the Commission or its staff, be permitted access and the right to inspect and copy in the principal offices of Respondents during office hours, and in the presence of counsel or other representatives if Respondents so choose, all books, ledgers, accounts, correspondence, memoranda, financial reports, and other records and documents, both in detail and in summary form, for the purpose of verifying any matter or statement contained in the reports required to be retained under subparagraph VI(A) of this Order.

VII

(Service of Cease and Desist Order)

Respondents are ordered and directed to:

(A) Serve, within thirty (30) days after the effective date of this Order, a copy of this Order upon each of their respective officers, directors, managing agents, agents, and employees who have any responsibility for the marketing, distribution, or sale of covered products in the United States;

(B) Serve, within thirty (30) days after the succession of any persons referred to in subparagraph VII(A) of this Order, a copy of the Order upon each successor; and

(C) Maintain such records as will show the name, title, and address of each person upon whom the Order has been served, as described in subparagraphs VII(A) and VII(B) of this Order, together with the date on which service was made.

The obligations set forth in subparagraphs VII(B) and VII(C) shall remain in effect until the date of expiration of U.S. Letters Patent 4,043,027.

VIII

(Confidentiality)

Information obtained by means provided for in Sections V and VI of this **Order** will be made available only to the Commission and its authorized representatives, will be entitled to confidential treatment, and will not be divulged by any authorized representative of the Commission to any person other than duly authorized representatives of the Commission, except as may be required in the course of securing compliance with this **Order**, or as otherwise required by law. Disclosure hereunder will not be made by the Commission without ten (10) days prior notice in writing to the Respondent affected.

IX

(Enforcement)

Violation of this **Order** may result in any of the actions specified in section 211.56 of the Commission's Interim Rules of Practice and Procedure, 19 C.F.R. § 211.56, including an action for civil penalties in accordance with section 337(f) of the Tariff Act of 1930, 19 U.S.C. § 1337(f), and any other action as the Commission may deem appropriate. In determining whether a Respondent is in violation of this **Order**, the Commission may infer facts adverse to a Respondent if the Respondent fails to provide adequate or timely information.

X

(Modification)

The Commission may amend this Order on its own motion or in accordance with the procedure described in section 211.57 of the Commission's Interim Rules of Practice and Procedure, 19 C.F.R. § 211.57.

XI

(Bonding)

The conduct prohibited by Section III of this Order may be continued during the period in which this Order is under review by the President pursuant to section 337(j) of the Tariff Act of 1930 (19 U.S.C. § 1337(j)), subject to the posting of a bond in the amount of 2.5 (two and one half) percent of the entered value of the articles in question, not to exceed \$0.50 per plastic encapsulated integrated circuit. This bond provision does not apply to conduct that is otherwise permitted by Section IV of this Order. Infringing products imported on or after February 18, 1992, are subject to the entry bond as set forth in the limited exclusion order issued by the Commission on February 18, 1992, and are not subject to this bond provision.

The bond is to be posted in accordance with the procedures established by the Commission for the posting of bonds by complainants in connection with the issuance of temporary exclusion orders. See Commission Interim Rule 210.58, 19 C.F.R. § 210.58. The bond and any accompanying documentation is to be provided to and approved by the Commission prior to the commencement of conduct which is otherwise prohibited by Section III of this Order.

The bond is to be forfeited in the event that the President approves, or does not disapprove within the Presidential review period, the Commission's

Orders of February 18, 1992, or any subsequent final order issued after the completion of Investigation 337-TA-315, unless the U.S. Court of Appeals for the Federal Circuit, in a final judgment, reverses any Commission final determination and order on appeal, or unless the products subject to this bond are exported or destroyed, and certification to that effect satisfactory to the Commission is provided.

The bond is to be released in the event the President disapproves this Order and no subsequent order is issued by the Commission and approved, or not disapproved, by the President, upon service on Respondents of an Order issued by the Commission based upon application therefor made to the Commission.

By order of the Commission. .



Kenneth R. Mason
Secretary

Issued: February 18, 1992

CONFIDENTIAL INFORMATION DELETED

PUBLIC VERSION

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- (3) LSI Logic Corporation (LSI), a Delaware corporation with its principal place of business in Milpitas, California;
- (4) VLSI Technology, Inc. (VLSI), a Delaware corporation with its principal place of business in San Jose, California; and
- (5) Cypress Semiconductor Corporation (Cypress), a Delaware corporation with its principal place of business in San Jose, California.³

On January 9, 1991, the presiding Commission administrative law judge (ALJ) issued an initial determination (ID) (Order No. 17) designating the investigation "more complicated," pursuant to section 337(b)(1) of the Tariff Act of 1930. In that ID, he also granted TI's motion to amend the complaint and notice of investigation to include claim 1 of the '027 patent. The Commission determined not to review the ID.⁴

The ALJ conducted an evidentiary hearing from May 13 to May 22, 1991. Respondents defended against TI's complaint on the grounds that the claims of the '027 patent are invalid for obviousness, are not infringed, and there is no domestic industry. In addition, respondent Analog contended that TI was equitably estopped from maintaining this section 337 action against it in light of a license agreement between TI and [

] after this investigation was instituted.

On October 15, 1991, the ALJ issued his final ID in the investigation. He found a violation of section 337 of the Tariff Act of 1930, on the ground that respondents had imported and sold certain plastic encapsulated circuits (those encapsulated using a process called "opposite-side" or "bottom" gating) which infringed claims 12 and 14 of the '027 patent. He found that those

³ For the purposes of this Opinion, IDT, LSI, VLSI, and Cypress are collectively referred to as "the California respondents."

⁴ 56 Fed. Reg. 4851 (Feb. 6, 1991).

PUBLIC VERSION

imported integrated circuits did not, however, infringe claims 1 or 17 of the patent. In addition, he found that certain other accused integrated circuits (those encapsulated using a process called "same-side" or "top" gating) did not infringe claims 1, 12, 14, or 17.

The ALJ concluded that the '027 patent was not invalid for obviousness, and he further found that there exists a domestic industry which practices the '027 patent, including claims 12 and 14.

With respect to Analog's license argument, the ALJ found that Analog had a partial license for part of the period of time during which this investigation has been pending.⁵ He concluded, however, that the existence of this license was not grounds for dismissal of the investigation against Analog, because Analog did not have a license when the investigation was instituted and because the license is limited to a certain dollar amount of sales.⁶

On December 2, 1991, the Commission issued a notice that it had determined to review the issues of (1) construction and infringement of claim 17 of the '027 patent and (2) obviousness under 35 U.S.C. § 103.⁷ The Commission determined not to review the remainder of the ID.⁸ With regard to the portions of the ID to be reviewed, the Commission indicated particular interest in the following issues:

1. Whether the ALJ erred in construing the language of claim 17, "electrical connections between electrical terminals of the device

⁵ ID at 104.

⁶ ID at 105.

⁷ 56 Fed. Reg. 64643 (Dec. 11, 1991).

⁸ The ID's conclusions with respect to those issues that the Commission determined not to review have become the determinations of the Commission. 19 C.F.R. § 210.53(h).

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and a plurality of conductors arranged substantially parallel to one another," as requiring that each of the conductors be substantially parallel to all the other conductors. If the ALJ erred in construing claim 17, what is the correct construction of that claim, and given that construction, (i) is the claim infringed by any of respondents' "opposite-side" gated imported products, and (ii) is the claim practiced by the domestic industry.

2. Whether the ALJ erred, as a factual matter, in finding that none of respondents' imported products infringe claim 17 of the '027 patent, as claim 17 was construed by the ALJ. Specifically, the parties are asked to identify any imported products in evidence in which all conductors are arranged substantially parallel to one another, and further, to address whether such products are encapsulated by a process which uses "opposite-side" gating. The parties are also requested to brief the issue of whether claim 17, as construed by the ALJ, is practiced by the domestic industry.
3. Whether respondents have shown by clear and convincing evidence that the '027 patent is invalid for obviousness under 35 U.S.C. § 103. In particular, the parties are asked to address: (1) the differences between the claimed invention as a whole and the prior art, as that prior art has been identified by the ALJ, and (2) the objective indicia of nonobviousness, with citations to relevant evidence of record. With respect to commercial success, the parties are requested to brief the issue of whether the ALJ's reliance on pre-1975 information is prejudicial to respondents and, if so, whether the Commission's reliance on pre-1975 information would be prejudicial, in light of this opportunity to readdress commercial success.

The Commission's notice requested that the parties file briefs discussing the issues under review, and solicited comments from the parties, interested government agencies, and any other persons concerning the issues of remedy, the public interest, and bonding.

Complainant, all respondents, and the Commission investigative attorneys (IAs) filed briefs and reply briefs addressing both the issues under review

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and remedy, the public interest, and bonding.⁹ No comments were filed by interested government agencies or other persons.

BACKGROUND

TI is the owner by assignment of the '027 patent, which is entitled "Process for Encapsulating Electronic Components in Plastic." The patent was issued on August 23, 1977, and expires on that date in 1994. The history of the patent, however, dates back to December 16, 1963, when inventors Robert O. Birchler and E. W. Williams filed the grandparent patent application. On October 17, 1968, the inventors filed a divisional application (the parent application), which was followed by the filing of a continuation application on July 30, 1973. It is this latter application which matured into the '027 patent on August 23, 1977.

The '027 patent has 17 claims, but TI has alleged infringement of only four of those claims--claims 1, 12, 14, and 17.¹⁰ The patent relates generally to the manufacture of semiconductors. It claims a process for encapsulating delicate electrical circuit devices through the use of transfer molding.

Transfer molding is the rapid injection of liquid plastic under pressure to encapsulate a product secured in a mold. A thermosetting plastic (i.e., a plastic that melts with the application of heat and then hardens upon cooling)

⁹ In connection with the review phase, Analog and the California respondents requested oral argument. TI and the IAs indicated that they did not believe oral argument was necessary. TI's reply brief at 25, n.29; IAs' reply brief at 12, n.16. We believe that the issues involved were thoroughly briefed, and that oral argument was unnecessary. No participating Commissioner voted in favor of granting the requests for oral argument, see 19 C.F.R. § 210.56(a), and the requests therefore have been denied.

¹⁰ The ALJ found no infringement of claim 1, and the Commission determined not to review that finding.

is melted in a cylinder and then "transferred" or forced out of the cylinder through pipelike runners into one or more mold cavities. The transfer of the plastic occurs under controlled pressure and velocity conditions. The device to be encapsulated is held or supported in the cavity and the plastic is made to flow around the device and encapsulate it. After hardening, the encapsulated device is removed from the mold and the process is repeated with another device.

Transfer molding was first introduced in 1926. By the early 1960s, manufacturers of semiconductors (principally diodes and transistors) had begun an industry-wide drive to develop low cost, mass-produced transistors that could be sold inexpensively and used in many applications. As part of this effort, industry leaders sought to improve upon their costly existing method of encapsulation, called the "header and can process," which contributed significantly to the selling price of several dollars per transistor. The expense of this encapsulation process was due largely to the need to protect the delicate "whisker wires" used to connect the terminals of the transistor with conductor leads to the external circuitry.

According to the claimed process, a semiconductor wafer is attached to three conductor wires, and electrical contact is made between an active region of the wafer and one conductor wire. Whisker wire leads provide contact between the other active wafer regions and the other conductor wires. After trimming, the wafer, whisker wires, and conductor wires are enclosed in a mold cavity. One end of the conductor wires is clamped to the exterior of the mold to prevent movement. Liquid plastic is then injected into the mold cavity to encapsulate the device. The specification of the '027 patent states:

An important aspect of the invention is the manner in which the fluid plastic material is gated into the mold so as to prevent damage to the delicate whisker wire leads and transistor wafer. In general, this entails introducing the material into a portion of the mold cavity remote from the transistor device and whisker wire leads, and generally parallel to the whisker wire leads.¹¹

Following encapsulation, the conductor wires may be severed or the lead frame assembly trimmed.¹²

Some encapsulated integrated circuits are sold individually to manufacturers of electronic products. Others are used in the fabrication of circuit boards, which also are sold to manufacturers of electronic equipment. The integrated circuits accused of being encapsulated by a process that infringes the '027 patent include a variety of devices, viz., static random access memories (SRAMs), microprocessors, digital signal processors, logic devices, erasable programmable read only memories (EPROMs), programmable logic devices, application specific integrated circuits (ASICs), and cache devices.

DISCUSSION

ISSUES UNDER REVIEW

A. Construction of Claim 17

Claim 17 states that the encapsulation process, inter alia, comprises:

providing electrical connections between electrical terminals of the device and a plurality of conductors arranged substantially parallel to one another

. . . .¹³

¹¹ Patent at column 2, lines 41-47.

¹² Patent at column 8, lines 13-24, figure 10.

¹³ Col. 14, lines 8-10.

The ALJ construed the "plain meaning" of this language to require that each of the conductors be substantially parallel to the other conductors.¹⁴ He rejected TI's argument that the claim requires only that at least two of the conductors be substantially parallel to each other. In this regard, he noted that TI's construction of the term "plurality" would read out of the claim the "to one another" limitation.¹⁵

Respondents submit that the ALJ correctly construed claim 17 to require that all the conductors used be parallel to one another.

Analog argues that the ALJ's construction is the only one that is consistent with the specification and drawings, in which the three conductors shown are all parallel to one another. Analog argues that the ALJ correctly found that, in the context of claim 17, "plurality" must refer to all the conductors in the lead frame to which an integrated circuit is connected. Analog agrees with the ALJ that any other interpretation would be inconsistent with the "parallel to one another" language. Analog also notes that the '027 patent's specification and drawings disclose a three-conductor support connected to the three terminals of the transistor, with each conductor parallel to each of the others. Analog agrees with the ALJ that the number of conductors has to be equal to the number of terminals used in the integrated circuit to which the conductors are connected,¹⁶ and that this "plurality" of conductors is defined in claim 17 as being arranged "substantially parallel to one another."

¹⁴ ID at 15-16.

¹⁵ Id.

¹⁶ According to Analog, if only two of the three transistor terminals were connected to conductors, the structure would be inoperative.

Analog also argues that the plain meaning of the language of claim 17 requires that the conductors be substantially parallel over their entire lengths, not just over a portion, even a substantial portion, of their lengths.

Both TI and the IAs seek reversal of the ALJ's finding that the "plurality" language in claim 17 requires that "all" conductors be arranged substantially parallel to one another. According to TI and the IAs, claim 17 covers processes which have at least two conductors that are substantially parallel to each other. Both refer to standard patent drafting rules to support their arguments. The IAs point to the use of the transition word "comprising" in the preface to claim 17. They note that "comprising" is a term of art used in claim drafting to designate an open-ended claim, which covers all the elements set forth in the body of the claim while permitting an unlimited number of additional, unrecited elements. Based on this language, the IAs argue that the "plain language" indicates that parallelism among all the conductors used is not required. The IAs further suggest that the "to one another" phrase indicates that the conductors must be parallel to other conductors, as opposed to being parallel to the lead frame, sides of the mold, or some other structure.

According to TI, the term "plurality" is a term of art in patent claims that means at "least two." TI argues that the "substantially parallel" language "simply describes the basic (and necessary) arrangement of conductors in all semiconductor devices," *i.e.*, substantially parallel to one another as opposed to intersecting one another.

In response to the IAs' argument concerning the use of the phrase "comprising," Analog argues that the "comprising" language is open-ended as to

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each of the four process steps set out in claim 17, but for each of these processes, the elements defining the process constitute structural limitations. In support of its argument, Analog cite to a Federal Circuit case in which the Court held that the transitional phrase, "which comprises," did not exclude additional unrecited elements of the process claim in that case, but also did not affect the scope of the particular structural limitation recited within the process claim's step.¹⁷ Under this analysis, a process would infringe the claim as long as it followed at least the four steps of the process, or if it followed the four steps plus additional steps. But the elements of each of the four processes are explicit and not open-ended. As such, according to Analog, the parallelism requirement constitutes a structural limitation essential to the claim.

We affirm the ALJ's construction of this claim to require parallelism among all conductors used. Even using TI's definition of plurality to mean "two or more," the claim is worded to provide for electrical connections between device terminals and "a plurality of conductors" (not a plurality of the conductors) "arranged substantially parallel to one another." The claim language in question thus allows for use of two or more conductors, but does not, as TI and the IAs posit, require parallelism only between any two of the conductors used.

As the ALJ found, it is significant that the claim recites the requirement that the conductors be parallel to "one another," rather than recite that any one conductor be parallel to another conductor. The IAs have argued that the "one another" language simply means that the conductor should

¹⁷ Moleculon Research Corp. v. CBS, Inc., 793 F.2d 1261, 1271 (Fed. Cir. 1986).

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be parallel to another conductor, as opposed to another structure such as the lead frame. That analysis begs the point, because the claim in question does not address the relationship of the conductors to the lead frames or other structures.

The ALJ's construction is further buttressed, as Analog suggests, by the specification and drawings, which show all conductors arranged parallel to one another. In addition, when the patent is read in its entirety, it becomes apparent that the word "plurality" is used to indicate that two or more conductors may be used, not that only two need meet the parallelism requirement. For example, claim 14 claims a process in which electrical connections are provided between the electrical terminals of the device and "a plurality of conductors arranged in a substantially common plane." No one has argued that only two of the conductors used need be arranged in a common place. Rather, all of the two or more conductors used must be arranged in a common plane.

We also agree with Analog that the patent term "comprising," as used in claim 17, is open-ended only as to the four process steps covered by the claim, and that the requirements within each step constitute structural limitations. As such, the parallel requirement for the conductors is not met simply by aligning two (but not all) of the conductors parallel to each other. Rather, however many conductors are used must be parallel to one another.

The testimony of TI's own witness supports the ALJ's construction of the term "plurality." When asked the meaning of "substantially parallel," TI's witness, Dr. Seiling, responded:

Substantially parallel is shown on the claim chart.
Each of the individual conductors as they appear on

the x-ray are parallel to their closest neighbor.
(Emphasis supplied.) Tr. 449

With respect to the meaning of "substantially parallel," no party has pointed to any testimony or exhibits of record that are particularly helpful in construing this language.¹⁸ The ALJ did not expressly address this question, but suggested that the claim requires parallelism among all conductors "over a significant portion of their lengths."¹⁹

Upon review, TI urges that "substantially parallel" be construed to mean "not perpendicular." While one dictionary definition of "parallel" is "not perpendicular," that definition is inconsistent with the specification and drawings of the '027 patent, in which the conductors are at all points equidistant from one another. Moreover, construing "parallel" to mean "not perpendicular" would render the modifier "substantially" meaningless. The use of "substantially" reasonably contemplates a slight departure from a perfectly parallel arrangement, e.g., by a small bend in the conductors or by a small portion of the structure containing nonparallel (but also nonperpendicular) conductors. Given the absence of contrary evidence in the record on this question, the ALJ's construction is the most reasonable. We find, therefore,

¹⁸ As noted above, TI's witness, Dr. Seiling, was asked to define this term, but gave a response which addressed the "plurality" question rather than the meaning of "substantially" parallel. See Tr. 449. When asked to explain the term "substantially parallel," he stated that "each of the individual conductors as they appear on the x-ray are parallel to their closest neighbor." Tr. 449.

¹⁹ See ID at 30, 36, 137 (FF A 132, 133). It was not necessary for the ALJ to explicitly rule on the meaning of "substantially parallel," because he found as a factual matter that although some of respondents' products have a lead arrangement in which many of the leads are parallel over a significant portion of their lengths, none have all of their leads parallel over a significant portion of their lengths. Thus, it was on the basis of this configuration that, the ALJ found that none based of respondents' products infringe claim 17. ID at 30.

that the term requires that the conductors be parallel over a significant portion of their lengths.

B. Infringement of claim 17 by respondents' opposite-side gated products

The ALJ found that respondents' same-side gated products did not infringe any of the claims in issue of the '027 patent. He found that respondents' opposite-side gated products infringed claims 12 and 14, but not claims 1 and 17, as those claims were construed by him. Further, as noted, he found no infringement of claim 17 because "none of the respondents' products" arrange the conductors so they are all substantially parallel.²⁰ In his findings of fact, the ALJ similarly stated that "[r]espondents' products do not incorporate conductors all of which are substantially parallel to one another."²¹ In making this finding, he referenced numerous exhibits submitted by TI illustrating accused products. The ALJ did find, based upon the physical evidence, that "[s]ome products of the California Respondents have a lead arrangement in which many of the leads are parallel over a significant portion of their lengths."²²

With the exception of the parallelism requirement, the requirements of claim 17 are all contained in claim 14, which we, in adopting the ALJ's findings and conclusions regarding construction and infringement of claim 14, have found was infringed by all respondents. Accordingly, the only remaining infringement question with respect to claim 17 is whether the respondents' products are manufactured by a process in which the parallelism requirement, properly construed, is met.

²⁰ ID at 36.

²¹ FF A 133 (ID at 137).

²² ID at 30.

In our notice of review, we requested that the parties brief the question of whether, as a factual matter, the ALJ erred in the conclusion that none of respondents' products infringed claim 17, even as that claim was construed by the ALJ. TI and the IAs state that the opposite-side gated 8-pin PDIPs²³ and SOICs²⁴ imported by at least two of the respondents--Analog and VLSI--infringe claim 17 as construed by the ALJ. Specifically, it is alleged that these products have all their conductors arranged parallel over a significant portion of the conductors' length. Although our notice of review requested that the parties "identify any imported products in evidence in which all conductors are arranged substantially parallel to one another," the only exhibit specifically identified by TI and the IAs is CX-205, which illustrates Analog's 8-pin PDIP. Analog expressly concedes that its 8-pin PDIP illustrated in CX-205 employs a lead frame in which all the leads are parallel,²⁵ and does not disagree that other respondents' low-pin-count integrated circuits (*i.e.*, those with less than 8 leads) are manufactured by a process that infringes claim 17.²⁶

In light of the uncontested evidence that claim 17 reads on at least the Analog 8-pin PDIP device depicted in CX-205, we find that Analog has infringed that claim. In addition, the California respondents have indicated that the

²³ PDIP stands for Plastic Dual Inline Package.

²⁴ SOIC stands for Small Outline Integrated Circuit.

²⁵ Analog's main brief at 4.

²⁶ Analog's reply brief at 6. The California respondents cursorily state that they do not use lead frames in which all conductors are arranged substantially parallel to one another. To show this, they attach drawings (from Exhibits 65-67) of several "representative lead frames." California respondents' main brief at 38. However, they adopt Analog's arguments concerning claim 17, noting that their encapsulation processes, including lead configurations, are "essentially the same" as Analog's. *Id.* and reply brief at 30.

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encapsulation processes used by them, including lead configurations, are essentially the same as Analog's.²⁷ There is uncontested evidence in the record (the testimony of VLSI's witness) that respondent VLSI also imports into the United States an 8-pin PDIP.²⁸ In light of the California respondents' admission that their processes and lead configurations are essentially the same as Analog's, and the clear evidence of parallel leads in Analog's 8-pin PDIP and the evidence that VLSI has also imported an 8-pin PDIP, we find that VLSI has also violated section 337 by importing plastic encapsulated integrated circuits that infringe claim 17 of the '027 patent.

Given the absence of evidence that Cypress, IDT, or LSI import 8-pin or lower integrated circuits, we affirm the ALJ's finding that these respondents have not infringed claim 17 of the '027 patent.

C. Domestic Industry

a. Background

The Omnibus Trade and Competitiveness Act of 1988 (OTCA) amended section 337 of the Tariff Act of 1930 to specify the types of unfair acts covered by that section.²⁹ As amended, section 337 explicitly prohibits the importation and sale of imported articles that --

- (i) infringe a valid and enforceable United States patent . . . ;
or

²⁷ California respondents' main brief at 37-38. The parties agree that the types of plastic encapsulated integrated circuits likely to have all conductors parallel to each other are those with low-pin counts. See TI's main brief at 9; Analog's main brief at 5-6 and reply brief at 6.

²⁸ CPX-3 (Deposition of [

] at 25-27, 32-35 and Ex. 3).

²⁹ Under the amended statute, there is no requirement to show injury to the domestic industry in cases involving alleged infringement of patents (including process patents), copyrights, registered trademarks, or mask works.

- (ii) are made, produced, processed, or mined under, or by means of, a process covered by the claims of a valid and enforceable United States patent.

19 U.S.C. § 1337 (a)(1)(B).

In order to prove a violation of section 337 in a patent-based case, a complainant must show that an industry exists in the United States practicing the patent. Specifically, there can be a violation of section 337 --

only if an industry in the United States, relating to the articles protected by the patent, . . . exists or is in the process of being established.

19 U.S.C. § 1337(a)(2).

In cases involving alleged infringement of statutory intellectual property rights, section 337(a)(3) defines domestic industry as follows:

- (a) (3) . . . an industry in the United States shall be considered to exist if there is in the United States, with respect to the articles protected by the patent, copyright, [registered] trademark, or mask work concerned--
 - (A) significant investment in plant and equipment;
 - (B) significant employment of labor or capital; or
 - (C) substantial investment in its exploitation, including engineering, research and development, or licensing.

19 U.S.C. § 1337 (a)(3).

Thus, this section 337 investigation requires a determination as to whether a domestic industry exists, that is, whether the complainant is exploiting or practicing the patent in controversy. See Certain Doxorubicin and Preparations Containing Same, USITC Inv. No. 337-TA-300, Commission Opinion (Public Version) at 21 (May 2, 1991).

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The ALJ applied the domestic industry criteria set out in section 337(a)(3) to find that TI's domestic activities are sufficient to demonstrate the existence of a domestic industry.³⁰ He found that TI practices the '027 patent at its domestic facility,³¹ and that TI is specifically practicing claims 12 and 14 of the '027 patent at its domestic facility.³² He based this finding on the agreement among witnesses that TI and the respondents use the same or similar processes, coupled with his finding that respondents use an encapsulation process covered by claims 12 and 14. Because the ALJ found no infringement of claim 17, he did not make a finding regarding TI's practice of claim 17.

As noted, the parties agree that the types of plastic encapsulated integrated circuits likely to have all conductors parallel to each other are those with low-pin counts. Respondents argue that because TI did not introduce into evidence any lead frames produced in the United States which include parallel leads and "because TI has never manufactured low-pin count integrated circuits (i.e. less than 8 leads) at its domestic facility," TI does not practice claim 17.³³ TI admits that it does not presently manufacture low-pin count package types at its domestic facility.³⁴

³⁰ ID at 82-92.

³¹ ID at 93-94.

³² ID at 94.

³³ Id. Analog incorrectly states that the ALJ found that TI does not practice claim 17. Analog's reply brief at 6. The ALJ did find that TI's domestic facility currently encapsulates package types consisting of 20 or more pins. ID at 248 (FF E 54).

³⁴ TI's main brief at 9.

TI and the IAs argue, however, that the Commission's finding that the domestic industry practices claims 12 and 14 is sufficient for the Commission to find a violation of section 337 based on infringement of claim 17.

In addressing domestic industry, we are mindful that the statute requires only that any one of the three criteria set out in section 337(a)(3) be met in order to satisfy the domestic industry requirement. In this respect, we note that we have adopted, inter alia, the ALJ's factual findings and conclusions regarding the existence of a domestic industry as evidenced by TI's engineering and research and development efforts.³⁵ As the ALJ found, "it is difficult in situations such as that presented in this investigation to draw a bright line dividing those projects which exploit the patent at issue from those which to not."³⁶ Likewise, it is equally, if not more difficult to segregate those projects that exploit claims 12 and 14 of the patent, but not claim 17. Given the close similarity and overlap among these three claims, there is no bright line separating the research and development efforts relating to one of these claims from those relating to the others.

We accordingly find that TI's research and development efforts represent a substantial investment in exploitation of all claims found infringed, including claim 17. By virtue of this finding, it is unnecessary to decide specifically whether the claims that are infringed must be the ones that are practiced by the domestic industry in order for there to be a violation of section 337.³⁷

³⁵ See ID at 85-86 and FF E 1- E 257.

³⁶ ID at 86.

³⁷ The IAs argue that the language of section 337 and the legislative history of the 1988 amendments support the view that where the domestic

(continued...)

D. Validity; Obviousness under 35 U.S.C. § 103a. Legal Standards

A patent is presumed valid. 35 U.S.C. § 282. The burden of proving invalidity is on the party asserting it and must be met by clear and convincing evidence. Hybritech, Inc. v. Monoclonal Antibodies, Inc., 231 USPQ 81 (Fed. Cir. 1986).

³⁷ (...continued)

industry practices some of the claims of a patent, a respondent's infringement of any of the claims of that patent provides a basis for finding a violation of section 337. The IAs note that the statute emphasizes infringement and practice of the patent, rather than infringement and practice of the individual claims of the patent. Specifically, the IAs quote the language of the statute referring to infringement of a U.S. patent (19 U.S.C. § 1337(a)(1)(B)(i)); the requirement that an industry exist in the United States "relating to the articles protected by the patent," (Id. at § 1337(a)(2)); and the domestic industry requirements "with respect to the articles protected by the patent" (Id. at § 1337(a)(3)).

In making this argument, the IAs question several IDs or orders in which Commission ALJs have held that there must be "claim correspondence," i.e., that a violation of section 337 can be based on a particular claim only if the domestic industry practices that claim. Certain Chemiluminescent Compositions, Inv. No. 337-TA-285, ID (Order No. 25) (March 22, 1989). See also, Certain Heavy-Duty Mobile Scrap Shears, Inv. No. 337-TA-252, ID at 44-45 (Feb. 12, 1990); Certain Concealed Cabinet Hinges and Mounting Plates, Inv. No. 337-TA-289, ID at 108 (Sept. 28, 1989); Certain Scanning Multiple-Beam Equalization Systems for Chest Radiography and Components Thereof, Inv. No. 337-TA-326, Order No. 20 at 3-4 (Aug. 5, 1991), Order No. 23 (Aug. 20, 1991). Only in Chemiluminescent Compositions, however, did the presiding ALJ determine that the lack of claim correspondence failed to provide a sufficient basis for the existence of a domestic industry. See Order No. 25 at 90, n. 16. The claim correspondence requirement was not reviewed by the Commission and was not appealed to the Federal Circuit. The ID did, however, become the Commission's determination by virtue of the Commission's decision not to review it.

In light of our determination that there is a domestic industry meeting each claim at issue we need not determine whether claim correspondence is necessary to establish the existence of a domestic industry. The Commission notes, however, that, in a future investigation, it may be necessary to evaluate the propriety of a claim correspondence approach to the domestic industry analysis and fully consider the rationale set forth by the presiding ALJ in Chemiluminescent Compositions.

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A patent is invalid if the claimed invention does not satisfy the requirement for nonobviousness found in 35 U.S.C. § 103. Section 103 provides in relevant part that:

A patent may not be obtained though the invention is not identically disclosed or described as set forth in § 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains.

The leading decision on obviousness is that of the Supreme Court in Graham v. John Deere Co., 383 U.S. 1 (1966), which sets out four factors which must be considered: (1) the scope and content of the prior art; (2) the differences between the prior art and the claimed invention; (3) the level of ordinary skill in the pertinent art; and (4) objective evidence of nonobviousness (the so-called "secondary considerations"). With these facts determined, the ultimate inquiry was described by the Federal Circuit in Panduit Corporation v. Dennison Manufacturing Co., 1 USPQ2d 1593, 1595-96, (Fed. Cir. 1987) as follows:

With the involved facts determined, the decisionmaker confronts a ghost, i.e., "a person having ordinary skill in the art," not unlike the "reasonable man" and other ghosts in the law. To reach a proper conclusion under section 103, the decisionmaker must step backward in time and into the shoes worn by that "person" when the invention was unknown and just before it was made. In light of all the evidence, the decisionmaker must then determine whether the patent challenger has convincingly established, 35 U.S.C. § 282, that the claimed invention as a whole would have been obvious at that time to that person. 35 U.S.C. § 103. The answer to that question partakes more of the nature of law than of fact, for it is an ultimate conclusion based on a foundation formed of all the probative facts.

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When the party asserting invalidity relies upon a combination of prior art references to establish obviousness, that party bears the burden of showing some teaching or suggestion in those references which supported their use in combination to render the claimed invention obvious. Ashland Oil, Inc. v. Delta Resins and Refractories, 776 F.2d 281, 293, 297; 227 USPQ 657 (Fed. Cir. 1985), cert. denied, 475 U.S. 1017 (1986). The problem confronted by the inventor must be considered in determining whether it would have been obvious to combine references in order to resolve the problem. Diversitech Corp. v. Century Steps, Inc., 850 F.2d 675, 679 (Fed. Cir. 1988). It is impermissible to pick and chose from among prior art references to recreate a suggestion of the claimed invention. SmithKline Diagnostics, Inc. v. Helena Labs Corp., 859 F.2d 878, 886-87 (Fed. Cir. 1988).

All evidence, including relevant evidence concerning "secondary considerations" of nonobviousness, must be considered before reaching a conclusion on obviousness or nonobviousness. Lindemann Maschinenfabrik GMBH v. American Hoist and Derrick Co., 730 F.2d 1452, 1461 (Fed. Cir. 1984); Ashland Oil, 776 F.2d at 306. As stated in Stratoflex, Inc. v. Aeroquip Corp., 713 F.2d 1530, 1539 (Fed. Cir. 1983):

Enroute to a conclusion on obviousness, a court must not stop until all pieces of evidence on that issue have been fully considered and each has been given its appropriate weight. Along the way, some pieces will weigh more heavily than others, but decision should be held in abeyance, and doubt maintained, until all the evidence has had its say. . . . It is error to exclude [evidence on "secondary considerations"] from consideration.

Secondary considerations of nonobviousness include commercial success, long-felt need, the failure of others to solve the problem in question, commercial acquiescence (e.g., licensing), professional approval, and copying. See generally, 2 CHISUM, PATENTS, § 5.05 (1991).

When a patentee asserts that one or more of the secondary considerations support its contention of nonobviousness, the patentee bears the burden of coming forth with evidence sufficient to constitute a prima facie case of nexus between the merits of the claimed invention and the evidence offered. Demaco Corp. v. F. Von Langsdorff Licensing Ltd., 851 F.2d 1387, 1392 (Fed. Cir. 1988); Stratoflex, 713 F.2d at 1539. If the patentee has presented a prima facie case of nexus, the burden of coming forward with rebuttal evidence shifts to the party asserting obviousness. Demaco, 851 F.2d at 1393.

b. Discussion

i. Scope and content of prior art

As an initial matter, we affirm the ALJ's finding that the operative date for determining which references constituted prior art is September 1963.³⁸ We also adopt his findings as to which references constitute prior art. The following references constitute prior art that must be considered in our obviousness analysis:³⁹

(a) The Doyle Process

The Doyle process is claimed in U.S. Letters Patent 3,367,025, which was assigned to Motorola.⁴⁰ The patent is entitled "Method for Fabricating and Plastic Encapsulating a Semiconductor Device." It issued on February 6, 1968,

³⁸ The ALJ found that the constructive date of invention for the '027 patent was December 16, 1963, the date on which the grandfather patent application was filed. However, based upon corroborated evidence that TI had used the invention for production in September 1963, the ALJ found that the patent was actually reduced to practice (i.e., invented) in that month. ID at 52-53.

³⁹ In our notice of review, we requested the parties to address "the differences between the claimed invention as a whole and the prior art, as that prior art has been identified by the ALJ."

⁴⁰ RX 011.

based on an application filed in January 15, 1964. In an interference proceeding,⁴¹ the U.S. Patent Office's Board of Patent Interferences determined that Doyle's invention had been conceived and reduced to practice "well prior" to the filing of the grandparent application of the '027 application. The Board awarded Doyle priority of invention with respect to certain claims (1, 3, 4, and 6) of his patent. Thus, it is Doyle's process, upon which his patent is based, which is the "prior art" to be compared with the process claimed in the '027 patent.

In the process disclosed by the Doyle patent, the plurality of conductor leads are held in a "pin circle" (i.e. non-planar) arrangement in a jig. The semiconductor is electrically and mechanically attached to the flattened head of one of the conductors, which is positioned slightly lower than the other two conductors. The semiconductor is attached to the other two conductors by "tiny wires." The lead heads "protrude from" the jig. The jig is transferred to a plastics transfer mold, and serves as the lower portion of the mold. The assembled mold has a cavity which encompasses the semiconductor device, the tiny wires, and the projecting end section of the conductor leads. During the encapsulation process, liquid plastic is introduced under pressure into a bore in the upper portion of the mold, and transferred from the bore through a gate (entrance) into the cavity into which the lead end section assembly protrudes.

The ALJ found that in the Doyle patent the gate through which the liquid material enters the cavity is at the floor of the cavity and below the lead

⁴¹ An interference proceeding is an administrative proceeding conducted at the U.S. Patent Office to determine which of two or more inventors was the first to invent and therefore is entitled to the patent.

head assembly.⁴² As such, the liquid plastic enters beneath, or opposite from, the semiconductor device and whisker wires, and does not directly impinge upon the whisker wires.⁴³ The ALJ based his findings on the patent claims, patent drawings, the hearing testimony of Doyle and others concerning the distance of the lead heads from the bottom of the mold, samples and x-ray exhibits of transistors molded by Doyle during the relevant period, and an invention disclosure that Doyle prepared for the Motorola Patent Committee.⁴⁴

(b) U.S. Letters Patent 3,235,937 (Lanzl)

The Lanzl patent is entitled "Low Cost Transistor." The application was filed on May 10, 1963, and the patent issued on February 26, 1966. Because the Lanzl application was filed before the invention of the '027 patent, the ALJ properly considered it to be prior art under 35 U.S.C. § 102(e).⁴⁵ The Lanzl patent is not a process patent. It does not disclose transfer molding

⁴² ID at 54, 147 (FF B 56).

⁴³ Id. at 63, 144-147 (FF B 41, 46, 46a, 49, 56, 58, 62.).

⁴⁴ The IAs contend that no conclusion can be drawn from the patent itself as to the relative position of the components and gate location. They object to the ALJ's reliance on the invention disclosure that Doyle prepared for the Motorola Patent Committee, arguing that the information contained in the disclosure was not prior art under 35 U.S.C. § 102(g) because it was "suppressed or concealed."

On the basis of the information in the record, we disagree with the IAs' assertion that Doyle's invention disclosure is not prior art or, if it was prior art, was suppressed and concealed. The Federal Circuit has held that a prior invention that meets the requirements of section 102(g) constitutes prior art for purposes of section 103, even if the applicant (or the public generally) did not have knowledge of the invention. Kimberly-Clark Corp. v. Johnson & Johnson, 745 F.2d 1437, 223 U.S.P.Q. 603 (Fed. Cir. 1984). Doyle's patent disclosure accordingly constitutes prior art under section 102(g). The eight-month period between Doyle's actual reduction of his invention to practice (May 1963) and the filing of the patent application (January 1964) does not evidence abandonment, suppression, or concealment, particularly since during part of this period the invention was under review by the Motorola Patent Committee, which approved the filing of a patent application in October 1963. See Corregge v. Murphy, 705 F.2d 1326, 217 USPQ 753 (Fed. Cir. 1983).

⁴⁵ ID at 55.

or any other specific method of encapsulation. At the evidentiary hearing, respondents' witness testified that Lanzl transistors were encapsulated by potting.

The Lanzl patent does disclose a transistor with planar leads. A silicon transistor is mounted upon one of the leads and is connected by whisker wires one mil⁴⁶ in diameter to the other two leads. The semiconductor device and wires are located on the same side of the plane formed by the three leads. The Lanzl transistor utilizes a header which stays on the finished product.

(c) The Sylvania Transistor/ Carruth and Sussman Article

From mid-1958 through mid-1963, Sylvania Electric Products, Inc. conducted a program to develop a process for encapsulating germanium transistors in plastic. The ALJ found that Sylvania's TF-61 and TF-62 transistors, manufactured about March 1963, were encapsulated by transfer molding and used a header.⁴⁷ These transistors were described in an article by Carruth and Sussman entitled "Epoxy Pellet Encapsulation for Transistors" (RX 24), which was published in April 1963, and which the ALJ found to constitute prior art. The three conductor wires in the Sylvania transistor were parallel to each other and in a common plane. The germanium device was mounted on a circular base tab which was then soldered to the center lead in the header. The base tab and transistor were mounted in a plane generally perpendicular to the plane formed by the conductors. In contrast to the one mil gold whisker wires utilized in transistors for which the '027 patent was

⁴⁶ A mil is one thousandth of an inch.

⁴⁷ ID at 54-55.

intended, Sylvania's transistors utilized nickel bond wires with diameters of 5-10 mils. The Carruth and Sussman article stated that the transfer molded transistors were still in the development stage, but offered the advantages of reduced costs, better heat dissipation, and the ability to pack closely together in low power applications.

(d) The Zecher Article

In July 1962, a trade journal published an article by Robert F. Zecher of the Hull Corporation entitled "High Production Encapsulation of Electronic Device." (RX 478). The article broadly discusses transfer molding techniques, and lists a variety of items, including transistors, that were being packaged by transfer molding.⁴⁸

Relevant to the comparison of prior art references, one paragraph of that article states as follows:

The single drawback to many other new programs is the inherently poor design of a component for encapsulation. Many manufacturers who have been skimming through product development without giving much thought to final packaging are now beginning to wish they had used stiffer leads which could support the device in a mold, that the lead configuration occupied only one plane, so the mold need have only one parting line, that they had not used fiber washers which outgas when heated, and so forth.

RX 478 at 7.

(e) U.S. Letters Patent 2,757,439 (Burns)

The Burns patent is entitled "Transistor Assemblies." It issued on August 7, 1956, based on an application filed February 25, 1955. The patent

⁴⁸ RX 478 at 7; ID at 57.

does not disclose a process; it discloses a transistor utilizing planar leads.⁴⁹

ii. Obviousness analysis in the ID

The ALJ noted that the parties do not dispute the level of ordinary skill in the art in 1963, i.e., that of an ordinary technician,⁵⁰ and we agree with this finding.

In comparing the invention claimed in the '027 patent and the prior art, the ALJ found that the Doyle patent is like the '027 patent in that it teaches the utilization of a remote gate to transfer mold a device which has whisker wires leading from the semiconductors.⁵¹ He noted that the difference between the two patents is that Doyle's leads are not in a common plane. He found, however, that the two prior art references which he had found were not considered by the patent examiner, i.e., the Sylvania transistor and the Zecher article, used or suggested the use of planar leads.⁵² On the basis of Sylvania and Zecher, the ALJ found the requisite suggestion that one could transfer mold a transistor, as did Doyle, when the transistor had the specific arrangement of leads described in the claims at issue.⁵³

Before reaching his ultimate conclusion on the question of obviousness, however, the ALJ discussed secondary considerations of nonobviousness, and found that those considerations, particularly commercial success, strongly supported a conclusion that the invention of the '027 patent was nonobvious.⁵⁴

⁴⁹ ID at 62.

⁵⁰ ID at 67.

⁵¹ ID at 63.

⁵² ID at 63-64, 68.

⁵³ ID at 68.

⁵⁴ ID at 71.

In finding commercial success, he relied on statements made in TI's annual reports for the years 1964-1968,⁵⁵ which tell of increased sales of semiconductor devices, particularly those encapsulated in plastic, despite the competitive nature of the market.⁵⁶ These reports, although submitted into evidence by TI without objection from the other parties,⁵⁷ were not expressly relied on by TI during discovery, the evidentiary hearing, or in its briefs. Rather, TI indicated throughout the proceedings that it was attempting to show commercial success by evidence of commercial sales occurring between 1975 and 1990.⁵⁸

The ALJ noted that the excerpts from the 1964-1968 annual reports reflect an expansion in the use of transistors as low-cost plastic encapsulated products entered the market. He referred to the Carruth/Sussman article, which noted the costs and physical advantages of plastic encapsulated semiconductors, and noted that these advantages allowed the use of plastic encapsulated semiconductors in an increasing number of applications. He found that the headerless construction of TI's low-cost plastic encapsulated transistors would not have been possible without the '027 process. Thus, he found the requisite nexus between the merits of the '027 patent and the commercial success of TI's transistors.⁵⁹

⁵⁵ CX 297.

⁵⁶ ID at 65-66, citing CX 297.

⁵⁷ The exhibit list in this investigation is lengthy. The documentary exhibits alone number over 700.

⁵⁸ E.g., Tr. 1143, SPX-7 (deposition of TI's witness Anthony Adams), TI's posthearing memorandum at 29-30, CXs 436-439.

⁵⁹ ID at 66.

The ALJ rejected TI's suggestion that TI's granting of licenses under the '027 patent to over 60 companies is indicative of commercial success. He found that there was no nexus established between these licenses and the '027 patent because TI's typical licensing agreement did not specify particular patents but is a "blanket" license.⁶⁰

In addressing secondary considerations, the ALJ also found evidence of a long-felt need for the invention, strong economic incentives to develop a low-cost transistor,⁶¹ and industry recognition of the advantage of a process like that claimed in the '027 patent.⁶²

iii. Positions of the parties

All parties take issue with various aspects of the ALJ's obviousness analysis. TI and the IAs contest the ALJ's finding that a comparison, standing alone, of the '027 process with the prior art suggests that the claimed process would have been obvious in 1963 to one of ordinary skill in the art.

The parties disagree concerning whether the Doyle patent discloses opposite-side gating. The IAs and TI note that the ALJ did not find that the Doyle patent itself taught opposite-side gating with respect to a planar configuration of conductors to avoid dislocation of whisker wires. In this regard, they further emphasize that there is no "plane" in the Doyle process,

⁶⁰ ID at 67, n. 33, citing Tr. 852-853 (testimony of TI witness Richard Donaldson). Although the sample cross-licensing agreement referred to (RX 306, see also, CX 422) does ostensibly cover all TI patents, the witness, whose testimony the ALJ relied on, actually indicated that the negotiations leading to the agreement focused on 50 or fewer selected patents for each company.

⁶¹ ID at 65, 69.

⁶² ID at 65.

either as disclosed in the invention disclosure or in the patent, and therefore there can be no opposite side and no opposite-side gating.

Both TI and the IAs also challenge the ALJ's reliance on the Zecher article. They note that Zecher does not discuss or teach gate location and configuration to address the problems of avoiding damage to delicate whisker wires.

Analog and the California respondents contest the ALJ's reliance on secondary considerations to find nonobviousness. They object particularly to the ALJ's findings regarding commercial success and his reliance on TI's 1964-1968 annual reports. They argue that the reports are self-serving and fail to link increased sales to the claims in controversy of the '027 patent, thus failing to establish the required nexus between commercial success and the patent claims in controversy.

Respondents further argue that they were prejudiced by the ALJ's reliance on TI's 1964-1968 annual reports, and would likewise be prejudiced were the Commission to rely on these reports as evidence of nonobviousness, because TI indicated during discovery that it was relying only on post-1975 sales to show commercial success. TI responds that respondents did not object to the admission of the annual reports into evidence.

The IAs state that the annual reports were properly admitted, but are of limited probative value. In the IAs' view, the ALJ erred in relying on these reports to support commercial success because TI did not establish a nexus between the invention claimed in the '027 patent and TI's pre-1975 commercial success. The IAs state, however, that the ALJ's reliance on these reports was harmless error, since there is other evidence of secondary considerations of nonobviousness.

d. Analysis and conclusion regarding obviousness

We affirm the ALJ's conclusion that the '027 patent is not invalid for obviousness. For the purposes of comparing the prior art to the '027 patent, it is significant that the patented process resulted from an effort to develop a low cost (headerless) encapsulation process that would not damage the fragile whisker wires used in many semiconductor devices. As the ALJ found, the problem facing inventors Birchler and Williams was to develop a process for the encapsulation of a low-cost transistor.⁶³ To meet this goal, they sought to devise a process which eliminated the costly header used in then-existing encapsulation processes. Another problem facing the inventors was how to mold their headerless devices in a mass production setting without damaging the delicate whisker wire components.⁶⁴ The invention of the '027 patent addressed these problems in claims 12, 14, and 17 by utilizing a particular arrangement of leads (i.e., planar) and semiconductor device, and a remote gate location to achieve the goal of successfully transfer molding a semiconductor without disturbing the whisker wire connections.

An examination of the Doyle patent appears to show, as the ALJ found, that the gate (number 52) is located on the floor of the cavity (number 51), and therefore below the protruding lead heads and assembly. The Doyle patent claims and specification, which refer to protruding heads and describe the injection process, support a finding that the fluid in the Doyle process enters below the lead assembly. There remains, however, a significant difference between the Doyle process and the '027 process in that there is no

⁶³ ID at 45.

⁶⁴ Id. at 46.

well-defined plane in Doyle to equate with the planar division in the '027 patent which allows for the injection of fluid on the "opposite side" of the lead assembly.

The transfer molding process employed in making the Sylvania transistor used planar leads, but differed from the '027 process in that Sylvania used a header, and had 5-10 mil wire bonds rather than 1-mil wire bond. We accord more weight than did the ALJ to the differences between the Sylvania process and the '027 process, viz., important features of the patented process are not present in the Sylvania process, particularly, the headerless construction and the use of fragile and easily-damaged whisker wires. We believe there is merit to TI's assertion that Sylvania, because it uses a header, actually "teaches away" from the '027 patent.⁶⁵ See Ashland Oil, 776 F.2d at 301.

The Lanzl and Burns references plainly do not teach or suggest the process of the '027 patent. Indeed, these references do not refer to processes at all.

While the Zecher article discusses the use of planar leads in transfer molding, it does not suggest the use of remote gating to protect delicate whisker wires from damage caused by direct high velocity contact with the molten plastic. In this respect, we disagree with the ALJ's finding that the prior art references in combination suggest the process claimed in the '027 patent.

In addition to significant differences between the invention claimed in the '027 patent and the prior art, secondary considerations of nonobviousness

⁶⁵ TI's Response to Petitions for Review at 7.

support a finding of nonobviousness.⁶⁶ Most significantly, the record demonstrates a long-felt need for the invention and a problem that was solved by the inventors.⁶⁷ As found by the ALJ, and supported by the evidence, prior to the invention of the encapsulation process of the '027 patent in 1964, there were strong economic incentives to develop an inexpensive means of mass producing transistors. The evidence demonstrates that in the late 1950s and early 1960s, several transistor manufacturers were actively working on the development of inexpensive transistors. Because the header and can process used at that time accounted for a significant cost component of the transistor, many of these manufacturers were looking for less expensive ways to encapsulate transistors without damaging their fragile electrical connections. The inventors of the '027 patent were able to develop such an inexpensive encapsulation means, thereby meeting the long-felt need for a means of producing inexpensive transistors and solving the problem of doing so without damaging the fragile wires.

For example, the Carruth/Sussman article noted the costs and physical advantages of plastic encapsulated semiconductors and further noted that these advantages allowed the use of plastic encapsulated semiconductors in an increasing number of applications. As the ALJ found, the headerless

⁶⁶ We agree with the IAs statement that TI's 1960s annual reports were properly admitted, but are of limited probative value. While TI presented evidence of commercial success based on sales after 1975, the 1960s reports cannot be relied on to support commercial success because TI did not establish a nexus between the invention claimed in the '027 patent and TI's pre-1975 commercial success. The ALJ's reliance on these reports was harmless error, since, as discussed above, we find that there are appreciable differences between the prior art references and the '027 process and because there is other evidence of secondary considerations of nonobviousness.

⁶⁷ ID at 64-65, 67, 69.

construction of TI's low-cost plastic encapsulated transistors would not have been possible without the '027 process. In this regard, the inventors of the '027 process enabled TI to resolve the longstanding problems in producing long-needed low cost transistors.

Moreover, as the ALJ stated,⁶⁸ the subsequent production of low cost transistors by the entire electronics industry is not direct evidence of copying, but does further demonstrate the industry's recognition of an economic need to produce low cost transistors.

Accordingly, we affirm the ALJ's conclusion that respondents have not met their burden of showing by clear and convincing evidence that the claims in issue of the '027 patent are invalid on grounds of obviousness.

REMEDY

Having found a violation of section 337, the Commission must decide the issues of remedy, the public interest, and bonding. Under the statute, the Commission may issue an exclusion order, a cease and desist order, or both, depending on the circumstances. 19 U.S.C. § 1337(d)-(f).

The Commission has broad discretion in selecting the form, scope, and extent of the remedy in a section 337 proceeding.⁶⁹ In addition, the Commission has the power to make factual determinations in the remedy phase of a section 337 investigation, to the extent necessary, to reach its determination. These factual determinations may be made on the basis of the evidence of record in the violation phase of the investigation, or on the

⁶⁸ ID at 65.

⁶⁹ Viscofan, S.A. v. United States International Trade Commission, 787 F.2d 544, 548 (fed. Cir. 1986).

basis of information submitted by the parties in the remedy phase of the investigation.

A. Remedy with respect to California respondents

Complainant TI requested that the Commission issue a limited exclusion order, as well as cease and desist orders, directed to all five respondents and entities authorized by each respondent. TI proposed that the limited exclusion order exclude all of respondents' infringing bottom-gated plastic encapsulated integrated circuits of the various package types.

TI did not seek exclusion of "downstream" products, such as computers and telecommunications equipment, that contain infringing plastic encapsulated integrated circuits. TI did, however, request exclusion of integrated circuits assembled onto a circuit board or incorporated into a carrier, in order to prevent evasion of the limited exclusion order by importing integrated circuits in carriers or circuit boards rather than as individual chips.

TI further requested cease and desist orders directed to each of the five respondents ordering them to stop all unfair activities regarding infringing integrated circuits, including but not limited to the following activities: warehousing, testing, distributing, selling, and advertising infringing products currently held in inventory in the United States.

The California respondents and the IAs generally agreed with the scope of the limited exclusion order proposed by TI. The IAs also agreed with TI that a cease and desist order directed to the California respondents is appropriate. With respect to the California respondents, the IAs agreed with TI that a limited exclusion order and cease and desist orders are appropriate. In concurring with TI as to the issuance of cease and desist orders, the IAs

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noted that the California respondents have advised them that each respondent currently has U.S. inventories [] plastic encapsulated integrated circuits.⁷⁰

The California respondents oppose the issuance of cease and desist orders on public interest grounds. See discussion of "Public Interest," infra.

We have determined that issuance of a limited exclusion order is an appropriate remedy in this investigation. We have issued a limited exclusion order excluding infringing plastic encapsulated integrated circuits manufactured by or on behalf of the California respondents. The scope of this order generally conforms to the scope agreed upon as appropriate by the parties. To the extent possible, the limited exclusion order is also consistent with the outstanding limited exclusion order covering DRAMs manufactured by a process that infringes certain claims of the '027 patent.⁷¹

In order to prevent circumvention of the limited exclusion order, the order, like the outstanding DRAMs order, excludes carriers and circuit boards that consist merely of groups of plastic encapsulated integrated circuits. The order specifically does not cover finished downstream products such as computers, televisions, or telephones.

The limited exclusion order also contains a certification requirement similar to that contained in the DRAMs exclusion order and consistent with

⁷⁰ Id. at 8.

⁷¹ See Certain Dynamic Random Access Memories, Components Thereof and Products Containing the Same (DRAMs), Inv. No. 337-TA-242, Commission Opinion on Violation, Remedy, Bonding, and Public Interest, USITC Pub. 2034 (Nov. 1987) and Commission Opinion on Remedy, the Public Interest, and Bonding, Following Remand, (March 1990).

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that suggested by the parties. Under this provision, importation of plastic encapsulated integrated circuits is permitted if the items are accompanied by a certification that either (1) they are not manufactured by an process found to infringe the relevant claims of the '027 patent or (2) are covered by a license.

We have also determined that it is appropriate to issue a cease and desist order directing each of the California respondents to cease and desist from any unlicensed importing, selling for importation, assembling, testing, marketing, distributing, offering for sale, selling, or otherwise transferring (except for exportation) in the United States imported plastic encapsulated integrated circuits which have been determined to be infringing. In issuing this order, we note the evidence submitted by respondents in the remedy phase of the investigation indicating that each of the California respondents currently has U.S. inventories of [] plastic encapsulated integrated circuits.

B. Remedy with respect to Analog

At the time the investigation was instituted, respondent Analog did not hold a license under the '027 patent. Several months after institution of the investigation, Analog acquired all of the assets of [

], a corporation which held a cross-license from TI that covered, in addition to other patents, the '027 patent. In an unreviewed portion of the ID, the ALJ found that Analog obtained [] license with its acquisition of []. The license agreement allows Analog to sell "licensed products" (which include plastic encapsulated integrated circuits manufactured by the '027 process) []

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[]⁷² As such, Analog holds a limited license under the '027 patent.

With respect to Analog, TI recommended that Analog's plastic encapsulated integrated circuits be excluded from entry into the United States after Analog's sales of plastic encapsulated circuits, the date on which Analog purchased [] TI arrived at this figure based upon the percentage of [] total sales of products subject to the TI-[] license, at the time of Analog's acquisition of [] attributable to sales of plastic encapsulated integrated circuits.

Analog argued that no remedy is warranted against it. In making this assertion, Analog merely reiterated to some extent its arguments on an issue that the Commission has already determined not to review, viz., whether the investigation should have been dismissed as to Analog because, after institution of the investigation, Analog acquired a limited license from TI which Analog allegedly has not exceeded. Assuming unlicensed importation after institution, Analog argued that it is now licensed and that therefore any prior unlicensed importations of infringing plastic encapsulated circuits cannot be remedied by the Commission.

Analog noted that the ALJ found that its sales of plastic encapsulated integrated circuits in 1990 []

]

⁷² See ID at 94-105.

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[] held by the Commission not to infringe the claims at issue of the '027 patent.

Finally, Analog contended that, because it conducts final testing, packaging, and sales of its imported chips at its Massachusetts plant (the former [] facility), it is a member of the domestic industry and for this reason alone should not have a remedy imposed upon it.

The IAs recommended issuance of a cease and desist order to Analog, regardless of inventory levels, in order to permit monitoring to insure that Analog does not sell plastic encapsulated integrated circuits manufactured by the '027 process in excess of the limit of its license with TI. The IAs further recommended that the Commission impose a quarterly reporting requirement upon Analog to assure that Analog does not exceed its license limit. They also recommended that Analog be named in the limited exclusion order, but that the exclusion order state that it will only be effective as to Analog upon further notification to Customs from the Commission.

The IAs disagreed with TI's contention that the limited exclusion order should become effective after Analog has sold more than [] of licensed products. The IAs argued that TI's position contradicts the terms of the license agreement and the ALJ's finding that Analog is licensed for sales not to exceed the annual sales of licensed products being made by [] (about []) at the time it was acquired by Analog.

The Commission has already rejected Analog's contention that it should not be a party to this investigation. Analog's efforts to resurrect this issue in the remedy phase of the investigation are likewise rejected.

Analog's argument against remedial action ignores the fact that at the time this investigation was instituted, Analog was not licensed under the '027

patent and was in fact infringing the patent. It was only through Analog's acquisition of a firm previously licensed under the patent, several months after the investigation was instituted, that it became licensed. Moreover, Analog possesses only a limited license and is potentially able to exceed the license ceiling and thereby infringe the '027 patent. Analog's citation to Commission interim rule 210.51 is inapposite because that rule merely permits the parties to an investigation to terminate the investigation on the basis of a license agreement. The rule does not require termination of the investigation upon entry into a license agreement.

Nor can Analog escape remedial action based upon its contention that it is a member of the domestic industry. Section 337 does not exempt persons who import infringing products because those persons may conduct some operations domestically. Analog has imported plastic encapsulated integrated circuits that infringe claims 12, 14, or 17 of the '027 patent. As such, Analog is in violation of section 337 and is subject to remedial action, even if it conducts some domestic activities.

We have determined that it is appropriate that Analog be subject to the limited exclusion order issued in this investigation. Because the limited exclusion order expressly does not cover licensed sales, any sales by Analog under the license agreement will not be subject to exclusion under the limited exclusion order. The certification provision of the limited exclusion order allows for the importation of plastic encapsulated integrated circuits that would otherwise be infringing upon certification that the items are covered by a license.

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We also determine that it is appropriate to issue a cease and desist order to the extent that Analog's imports of plastic encapsulated integrated circuits are not covered by a license with TI.

We have declined to impose a reporting requirement to monitor Analog's compliance with the license. It has been the Commission's practice in the past not to interfere with private licenses between parties, and we see no reason to deviate from that practice here. We note that this is not a case in which enforcement is impossible without Commission monitoring. Given our finding that TI and Analog are cross-licensees to a limited license agreement, there are presumably mechanisms in place for Analog and TI to keep track of each others' sales under the licence agreement. As such, TI and Analog are in the best position to agree between themselves as to the appropriate means for complying with the terms of the license agreement, and consequently with the limited exclusion order and cease and desist orders, which only become operative as to Analog when the scope of the limited license is exceeded.

THE PUBLIC INTEREST

Section 337 provides that the Commission shall issue a remedy unless, after considering the effect of such a remedy upon (1) the public health and welfare, (2) competitive conditions in the U.S. economy, (3) the U.S. production of article that are like or directly competitive with those which are the subject of the investigation, and (4) U.S. consumers, it finds that a remedy should not be issued.⁷³

Analog argues that the public interest factors preclude issuance of a limited exclusion order or a cease and desist order against it. In this

⁷³ 19 U.S.C. § 1337(d).

regard, Analog argues that the domestic market cannot be adequately supplied with integrated circuits if imported integrated circuits are excluded. This argument is purely hypothetical, because the limited exclusion order is limited to the named respondents. TI and the numerous companies licensed by TI remain able to manufacture and import plastic encapsulated integrated circuits that are manufactured according to the '027 process.

Analog contends that it manufactures nonsubstitutable proprietary integrated circuits for use by certain customers in laboratories and hospitals. According to Analog, the exclusion of these products would adversely affect the companies and deprive the American public of state of the art medical technology. To support this contention, Analog offers the affidavit of its own chief patent counsel. Analog has not submitted affidavits from any laboratories or hospitals to support this claim. Notwithstanding the Commission's solicitation of comments from members of the public, no comments were received from the customers who will allegedly be harmed by the Commission's remedial action. Further, Analog does not contend that TI or one of the numerous firms licensed by TI could not manufacture the integrated circuits as specified by the customers, albeit perhaps after some delay.

In fact, Analog itself is licensed to produce products under the '027 patent, and has stated that it did not last year, and does not intend in future years, to exceed the license ceiling. Analog is free under the license agreement to concentrate its sales of licensed products on integrated circuits that other companies are less able to produce.

The California respondents do not raise public interest concerns regarding the issuance of a limited exclusion order of the scope proposed.

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They do, however, assert that issuance of cease and desist orders is unwarranted given the public interest concerns. They allege that, cumulatively, they are currently holding in inventory opposite-side gated plastic encapsulated integrated circuits [] based upon production cost.⁷⁴ According to respondents, many of these integrated circuits are specifically designed for particular customers and cannot be exported for resale to other customers.

Respondents further argue that issuance of cease and desist orders would create shortages of integrated circuits essential to the U.S. electronic industry, would threaten respondents' survival and undermine U.S. competitiveness, and would threaten the jobs of their employees as well as the those of their customers. Respondents suggest that the inability of their customers to purchase respondents' inventoried products would have crippling effects upon those customers, particularly on leading U.S. computer manufacturers and defense contractors. However, they have not provided substantiation of these allegations, and none of their customers has filed a public interest submission in this investigation. Further, respondents' sales to or for use by the Defense Department would not be affected, because articles imported by or for the use of the U.S. government are statutorily exempt from the cease and desist orders, as well as the limited exclusion order.⁷⁵

⁷⁴ California respondents' reply brief on remedy at 12.

⁷⁵ 19 U.S.C. § 1337(1).

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As discussed infra, we have set a relatively modest bond during the Presidential review period.⁷⁶ The bond will apply to products in inventory prior to the start of the Presidential review period,⁷⁷ and should make it feasible for respondents to sell their inventoried products during the Presidential review period without suffering anywhere near the [] financial loss that they say they will suffer if they are forced to discard their inventories of opposite-side gated integrated circuits.

BONDING

Under section 337(g)(3), infringing articles are entitled to entry into the United States during the 60-day Presidential review period only under bond.⁷⁸ The Commission is to set the bond at a level sufficient to "offset any competitive advantages resulting from the unfair method of competition or unfair act enjoyed by persons benefitting from the importation."⁷⁹

TI suggested that the Commission set the bond at 100 percent ad valorem, because of the difficulty in calculating appropriate bond amounts for the many different types and sizes of plastic encapsulated integrated circuits. In making this suggestion, TI relied on the fact that the Commission set a bond of 100 percent bond in the EPROMs investigation.⁸⁰ In EPROMs, however, the patents at issue covered the circuitry of the computer chips, whereas the '027

⁷⁶ The bond is 2.5 percent of the entered value of the articles concerned, not to exceed \$0.50 per plastic encapsulated integrated circuit.

⁷⁷ The bond provisions of the limited exclusion order will apply to articles imported into the United States during the Presidential review period.

⁷⁸ 19 U.S.C. § 1337(g)(3).

⁷⁹ S. Rep. No. 1298, 93d Cong., 2d Sess. 198 (1974); Commission interim rule 210.58(a)(3).

⁸⁰ Inv. No. 337-TA-276 (limited exclusion order issued March 16, 1989).

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patent is directed at the packaging for the integrated circuits, not at the circuitry itself. Thus, the value added by the patented plastic encapsulation is much less than the value added by the patented circuitry in the EPROMs case.

The California respondents argued that they should be able to import and sell the infringing integrated circuits during the Presidential review period free of any bond. They agreed with TI that it is difficult to calculate the precise values of the various sizes and types of plastic encapsulated integrated circuits. The California respondents concluded that in light of this difficulty, and given the negligible percentage of overall product cost attributable to the encapsulation process, they should be permitted to import and sell the products free of any bond during the Presidential review period.

In the limited exclusion order issued at the conclusion of the DRAMs investigation, the Commission set a bond based on a "reasonable royalty," based upon the royalty amounts provided for in the license agreements of the settling respondents.⁸¹ In keeping with this approach, the IAs recommended a bond amount here based upon [

] the IAs recommended that the bond be set at 2.5 percent of the entered value of the articles, not to exceed \$0.50 per plastic encapsulated circuit. We believe the IAs recommendation has merit, and have incorporated their proposed bond in the limited exclusion order and cease and desist orders.⁸²

⁸¹ DRAMs, Commission Opinion on Violation, Remedy, Bonding, and Public Interest, USITC Pub. 2034 (Nov. 1987) at 95.

⁸² In reviewing the original cease and desist orders issued in the EPROMs investigation, the Federal Circuit held that the statute requires the

(continued...)

Analog contends that it should not be required to post a bond for articles it imports or sells during the Presidential review period, in light of its limited license and the asserted improbability that it will exceed the license cap during the 60-day Presidential review period. The IAs agree that Analog should not be required to post a bond. We agree with Analog and the IAs, and have provided in the limited exclusion order and the cease and desist order for unbonded sales and importation of Analog's products during the Presidential review period.

⁸² (...continued)

inclusion of provisions in cease and desist orders allowing respondents to sell covered products imported during the Presidential review period. In Re Atmel Corp., No. 89-1382 (Fed. Cir. April 27, 1989) (on petition for writ of mandamus).

PUBLIC VERSION

UNITED STATES INTERNATIONAL TRADE COMMISSION
Washington, D.C.

In the Matter of)
)
CERTAIN PLASTIC ENCAPSULATED)
INTEGRATED CIRCUITS)
)

Investigation No. 337-TA-315

INITIAL DETERMINATION

Administrative Law Judge Sidney Harris

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I. INTRODUCTION

By publication in the Federal Register on August 15, 1990, the Commission gave notice of the institution of an investigation under section 337 of the Tariff Act of 1930 as amended (19 U.S.C. § 1337) pursuant to a complaint filed by Texas Instruments Inc. ("TI"), Dallas, Texas to determine whether there are violations of section 337 in the importation of certain plastic encapsulated integrated circuits into the United States, the sale for importation, or the sale within the United States after importation of certain plastic encapsulated integrated circuits allegedly manufactured produced and assembled by means of a process that infringes claims 12, 14 and 17 of U.S. Letters Patent 4,043,027 and that there exists an industry in the United States as required by subsection (a)(2) Section 337. 55 Fed. Reg. 33388 (August 15, 1990). TI's complaint requested that the Commission institute an investigation and, after a full investigation, issue a permanent limited exclusion order and permanent cease and desist orders.

The Commission named Texas Instruments the Complainant and the following companies as respondents:

Analog Devices, Inc. ("Analog")
Norwood, Massachusetts

Integrated Device Technology ("IDT")
Santa Clara, California

LSI Logic Corporation ("LSI")
Milpitas, California

VLSI Technology Incorporation ("VLSI")
San Jose, California

Cypress Semiconductor Corporation ("Cypress")
San Jose, California

Thomas L. Jarvis, Esq. and Linda C. Odom, Esq., Office of Unfair Import

Investigations, were designated as the Commission Investigative Attorneys. Notice of Designation of Additional Commission Investigative Attorney (August 30, 1990).

Chief Administrative Law Judge Janet D. Saxon designated Administrative Law Judge Sidney Harris to preside over this investigation.

A preliminary conference in this investigation was conducted on September 19, 1990. Appearances were made on behalf of Complainant Texas Instruments, Inc., all Respondents and the Commission Investigative Staff.

On November 8, 1990, Respondents Cypress Semiconductor Corporation, Integrated Device Technology, Inc., LSI Logic Corporation and VLSI Technology, Inc. (collectively "California Respondents") moved to amend Order No. 1: Protective Order to grant certain in-house counsel access to confidential business information. Motion Docket No. 315-11. Staff responded in support on November 15, 1990. No response was received from the Complainants. On November 9, 1990, Complainants moved to modify the Protective Order to deny access to licensing documents to certain outside counsel. Motion Docket No. 315-13. Staff responded in support on November 15, 1990. No responses were received from the Respondents. Both motions were granted in Order No. 13 on November 30, 1990.

On November 19, 1990, Respondent Analog Devices, Inc. ("Analog") moved for a summary determination terminating this investigation with respect to it. Motion Docket No. 315-16. On November 26, 1990, TI moved for an order refusing application of Motion 315-16 or, in the alternative, ordering continuance of the motion. Motion Docket No. 315-18. On November 27, 1990, Analog responded in opposition. TI filed a reply on November 28, 1990. No response was received from the Commission Investigative Attorney. This motion

was granted in Order No. 12 on November 29, 1991.

On January 2, 1991, Complainant Texas Instruments Incorporated ("TI") responded in opposition to Analog's motion for summary determination and Analog filed a reply to TI's opposition on January 9, 1991. On January 18, 1991, the Commission Investigative Attorney ("Staff") responded in opposition to the motion. On January 25, 1991, Analog filed a reply to the Staff's opposition. Motion Docket No. 315-16 was granted in part in Order No. 21 on February 22, 1991.

On December 7, 1990, California Respondents moved for the entry of an Initial Determination designating this investigation "more complicated." Motion Docket No. 315-24. On December 17, 1990, TI responded in opposition and Analog responded in support. On December 19, 1990, the Staff responded in opposition. Reply memoranda were filed by the California Respondents on December 19, 1990, and by Analog on December 27, 1990. Surreply memoranda were filed by TI on January 2, 1991 and by the California Respondents on January 4, 1991. On December 17, 1990, TI moved for the entry of an Initial Determination amending Paragraph 36 of the complaint and introducing a revised Exhibit 49. Motion Docket No. 315-28. On December 27, 1990, the California Respondents responded in opposition to Motion No. 28. On January 4, 1991, the Staff, with leave of the Administrative Law Judge, responded in support of the motion. On December 31, 1990, TI moved for the entry of an Initial Determination amending the complaint and notice of investigation by including Claim 1 of the suit patent, U.S. Letters Patent No. 4,043,027 (the '027 patent), as one of the claims at issue. Motion Docket No. 315-38. On January 4, 1991, the California Respondents responded in opposition to Motion No. 38, and Analog responded in opposition on January 7, 1991. The Staff responded in

support of Motion No. 38 on January 4, 1991. In doing so, the Staff revised its position regarding Motion No. 24 and argued that granting TI's motion to include infringement allegations pertaining to Claim 1 would necessitate designating the investigation "more complicated." On January 9, 1991, the Administrative Law Judge granted TI's Motions Nos. 315-28 and 315-38 and the California Respondents' Motion No. 315-24 (Order No. 17).

On December 28, 1990, TI moved for a summary determination that a domestic industry, for purposes of § 337, exists with respect to the patent at suit (the '027 patent). Motion Docket No. 315-35. On February 8, 1991, Analog and California Respondents responded in opposition. On February 12, 1991, the Staff responded in opposition. On January 23, 1991, Analog filed a cross motion for summary determination on the issue of whether a domestic industry exists with respect to the '027 patent. Motion Docket No. 315-42. TI responded in opposition on February 1, 1991. On February 12, 1991, the Staff responded in opposition. Motions Nos. 315-35 and 315-42 were denied on April 23, 1991 (Order No. 27).

The hearing in the matter of Certain Plastic Encapsulated Integrated Circuits commenced on May 13, 1991 and concluded on May 23, 1991.

This Initial Determination is based on the entire record of this proceeding. Proposed findings not herein adopted, either in form or in substance, are rejected as not being supported by the evidence or as involving immaterial matters. Any motions not specifically ruled upon or withdrawn are hereby denied.

The findings of fact include references to supporting evidentiary items in the record. Such references are intended to serve as guides to the depositions, exhibits, and testimony supporting the findings of fact; they do

not necessarily represent complete summaries of the evidence supporting each finding. Some of the findings of fact are contained only in the opinion.

The following abbreviations are used in this Initial Determination:

CX - Complainant's Exhibit (followed by its number and the reference page(s)).

CPX - Complainant's Physical Exhibit

CRX - Complainant's Rebuttal Exhibit

RX - Respondent's Exhibit (followed by its number and the reference page(s)).

RPX - Respondent's Physical Exhibit

RRX - Respondent's Rebuttal Exhibit

SX - Staff Exhibit

SPX - Staff Physical Exhibit

SRX - Staff Rebuttal Exhibit

ALJX- Administrative Law Judge's Exhibit

FF - Finding of Fact

Dep.- Deposition

Tr.- Transcript

II. INFRINGEMENT

A. Law Of Patent Infringement

A determination of whether the accused processes infringe the at-issue claims of the '027 patent requires a two-step analysis. One must construe the claims, followed by reading them on the accused processes. La Bounty Manufacturing, Inc. v. U.S. International Trade Commission, 867 F.2d 1572, 9 U.S.P.Q.2d 1995 (Fed. Cir. 1989), Autogiro Co. of America v. United States, 384 F.2d 391, 155 U.S.P.Q. 697 (Ct. Cl. 1967). Claims are construed in light of the specification, prosecution history, prior art and other claims in the patent. Specialty Composites v. Cabot Corp., 845 F.2d 981, 6 U.S.P.Q.2d 1601 (Fed. Cir. 1988). They are interpreted as they would be by one skilled in the relevant art and are given their usual and customary meaning in that art, unless it is apparent the inventor meant otherwise. Smithkline Diagnostics, Inc. v. Helena Laboratories Corp., 859 F.2d 878, 8 U.S.P.Q.2d 1468 (Fed. Cir. 1988). Ultimately, through this analysis, the scope and extent of the patent rights intended to be granted by the Patent and Trademark Office is determined. Autogiro Co. of America v. United States, supra; SRI International v. Matsushita Electric Corp. of America, 775 F.2d 1107, 227 U.S.P.Q. 577 (Fed. Cir. 1985).

B. Claims At Issue And Construction Of Disputed Terms

TI alleges that the respondents infringe claims 1, 12, 14 and 17 of the '027 patent. The parties dispute the meaning of several terms in the claims at issue, as follows:

1. "Conductor"

Each of the relevant claims utilizes the term "conductor." In claim 1, the semiconductor device being encapsulated is connected electrically to "an

intermediate point of a conductor." CX 1, Col. 9, lines 4-6. Claims 1 and 12 state that the device's components are attached mechanically "to at least one of the conductors for support" (Id. at Col. 9, lines 6-8, Col. 12, lines 28-31), and that each of the device's terminals are electrically connected to a conductor. (Id. at Col. 9, lines 4-6, Col. 12 line 28). Further, in claim 1, the device and intermediate portions of the conductors are placed in the mold cavity "with the opposite ends of each of the conductors extending from generally opposite sides of the mold cavity." Id. at Col. 9, lines 4-13. Claims 14 and 17 are each directed to an encapsulation process wherein one of the steps is "providing electrical connections between electrical terminals of the device and a plurality of conductors ...". Id. at Col. 13, lines 5-7, Col. 14, lines 8-10.

In the patent's specification, the device is electrically connected to three "conductor wires" which are designated in the drawings by the numbers 10, 12 and 14 (Id. at Col. 3, lines 46-48), or in an alternate embodiment by the numbers 136, 138, and 140 (Id. at Cols. 7 and 8). The device is bonded to the collector wire (wire 12) so as to provide an electrical connection between wire 12 and the device's collector (42)¹. Id. at Col. 4, lines 27-29. "Whisker wire leads" are utilized to provide a low resistivity electrical connection between the device's base region² (44) and wire 14 and its emitter

¹ A collector is the output terminal of a three-terminal semiconducting device, especially of a transistor. American Heritage Dictionary (2d Coll. ed.) 291. It is the semiconductive region through which a primary flow of charge carriers leaves the transistor's base. Dictionary of Scientific and Technical Terms (McGraw Hill, 4th ed. 1989), 383-384.

² The base is that region that lies between the emitter and the collector of a transistor and into which minority carriers are injected. Dictionary of Scientific and Technical Terms (McGraw Hill, 4th ed. 1989) 187

(46)³ and wire 10. Id. at Col. 4, lines 33-40. The center lead also provides support for the device in the mold. (Id. at Col. 3, lines 46-48).

The specification also provides that the flattened portions of the illustrated conductor wires "serve to increase the quality of the mechanical and electrical connections." Id. at Col. 6, lines 52-54. Further, the specification sets forth that the conductors "may originally be sufficiently long to extend in both directions from the encapsulating material [T]he respective conductor wires can subsequently be cut away to a customer's specification so that any arrangement of leads from the emitter, collector and base can be provided for integration into substantially any circuit. Id. at Col. 6, line 67-Col. 7, line 7 (emphasis added).

The three conductor wires designated in the patent are the three necessary leads for a transistor to properly function in an electrical circuit. The terms "conductor(s)" or "conductor wires" or "leads" are used interchangeably and consistently throughout the specification and illustrations to mean only those wires which are used to connect the semiconductor device into an electrical circuit.⁴ Further, in the specification, a clear distinction is made between those elements of the product that will be used for conducting a current (i.e. "conductors") and those that serve a different purpose such as supporting the product during encapsulation or during mounting the device on a conductor and connecting it with whisker wire leads to the other conductors. For example, the

³ The emitter is the region of a transistor from which the charge carriers that are minority carriers in the base are injected into the base. Dictionary of Scientific and Technical Terms (McGraw Hill, 4th ed. 1989) 638.

⁴ Whisker wires to conduct electricity between the device and the conductors are also referred to as "whisker wire leads."

specification illustrates that the "conductor wires 10, 12 and 14" are "welded or otherwise attached to metal tabs 16 and 18." Id. at Col. 3, lines 47-50. These tabs provide a handle to keep the conductor wires in proper position and relationship to each other as the die and whisker wires are attached. Birchler, Tr. 300. Nowhere in the patent's claims or specification is it suggested that these metal tabs are intended to carry a current, or that they are "conductor(s)." Indeed, after the transfer molding process is completed, the metal tabs are removed from the ends of the conductors. Id. at Col. 6, lines 14-16. The specification also illustrates a fabrication process in which four slots are punched into a rectangular piece of metal, forming "a rectangular support which interconnects with the ends of [the] conductor wires." Id. at Col. 7, lines 39-43; Fig. 9. Again, the specification makes a clear distinction between the conductors and other metallic elements used for support or assembly purposes.

In argument and through the testimony of its expert witness, Dr. Seiling, complainant contends that the term "conductor(s)" in the claims means any material that is capable of conducting electricity. This would include the "thin metal" lead-frame like device and the metal tabs discussed above. These metal elements were not intended by the inventors to "conduct" electricity either before or after encapsulation of the semiconductor device. The patent specification makes absolutely clear that the inventors' purpose was to include as "conductor(s)" only the leads from the device to be used in connecting it in a circuit. The inventors designated as conductors only certain wires; namely wires 10, 12 and 14, or alternately, wires 136, 138 and 140.

The device shown in detail in the specification is only a preferred

embodiment, and other semiconductor devices, such as for example, integrated circuits, may have a greater number of conductors, and may also present a different spatial configuration of conductors. However, the inventors' purpose emerges clearly from the specification that whatever semiconductor device is used, only the leads (however many they may be) which can be used to connect it in an outside circuit are included within the term "conductor" as used in the various claims of the '027 patent.

The '027 patent was previously construed in the prior DRAMS litigation⁵. In that litigation, as in this proceeding, TI argued that the term "conductor" includes all materials that are capable of conducting electricity. In the second Initial Determination in Certain Dynamic Random Access Memories Components Thereof And Products Containing The Same USITC Inv. No. 337-TA-242 ("DRAMS"), the Administrative Law Judge adopted that view. CX 262 at 43. (DRAMS Finding of Fact No. 120, citing Webster's New Collegiate Dictionary.⁶) The Commission in reviewing the first Initial Determination construed the term "conductor strip" in the related '764 patent⁷, found that the metallic "die pad" is not a "conductor strip" because it is not electrically connected to outside circuitry.⁸

The Commission decision came prior in time to the second Initial

⁵ CX 262 at 43. (DRAMS Initial Determination, FF 120)

⁶ None of the parties petitioned the Commission for review of the decision and it became the Commission's decision by operation of law.

⁷ U.S. Letters Patent No. 3,716,764 (Birchler et al.)

⁸ Although the claims in the '764 patent are different than in the '027 patent, and the prior art relevant to lead frames which is the subject of that patent, is different than the art which is relevant to the '027 patent, both patents stem from the same application, and the specification of each is identical. For all practical purposes the issue of the construction of the term "conductor" is identical in both patents.

Determination, and the latter decision became the decision of the Commission. However, the second Initial Determination is not considered binding on the current presiding Administrative Law Judge, since no petition for review was filed, and Finding of Fact No. 120 was not reviewed by the Commission. Moreover, since the respondents were not parties in the prior DRAMS proceeding, they are entitled to a decision which is based upon the evidentiary record created in this litigation.⁹ Thus, although the prior decisions are looked to for relevant guidance, they are not controlling here. Therefore, the term "conductor(s)" in the claims of the '027 patent will be construed in accordance with the intention of the inventors, to mean those wires emanating from the finished, molded semiconductor, which enable it to be connected and to function in an electric circuit.

2. "Conductors ... In A ... Common Plane"

Claim 12 of the '027 patent calls for "disposing the conductors generally in a common plane." Claim 14 requires that electrical connections be provided between the semiconductor device and "a plurality of conductors arranged in a substantially common plane."

A term such as "substantially common plane" cannot be defined in the abstract. This claim limitation is one of relative measurement. When interpreting a term of relative measurement, a finder of fact must pay particularly close attention to the relevant art and ascertain the tolerances the art will accept. See, Uniroyal, Inc. v. Rudkin-Wiley Corp., 837 F.2d 1044, 1056, 5 U.S.P.Q. 2d 1434, 1442 (Fed. Cir. 1988), on remand, 13 U.S.P.Q. 2d 1192, 1195 (D. Conn. 1989) (proper scope of the term "substantially"

⁹ Blonder-Tongue Labs, Inc. v. University of Illinois Foundation, 402 U.S. 313 (1971).

requires a review of the specification and prosecution history; cases interpreting the scope of the term "have little applicability apart from the specific factual circumstances to which those opinions relate.") Two items, separated by a fraction of an inch, may be in a "substantially common plane" on a large piece of heavy machinery, yet unacceptably distant from each other on a very small device such as a semiconductor.

The products encapsulated by the process claimed in the '027 patent are extremely small. The specification of the '027 patent describes semiconductors as "very small" in general (CX 2, Col. 1, line 17) and planar transistors as "very small and delicate" (CX 2, Col. 2, line 1). Dr. Seiling, TI's expert witness, testified that the semiconductors with which Messrs. Birchler and Williams were working when designing the '027 process were approximately 10 to 15 mils¹⁰ square. Seiling, Tr. 679. The transistor exemplified in U.S. Letters Patent No. 3,235,937 (Lanzl) is also informative regarding the size of transistors extant in the prior art at the time of the invention of the '027 process.¹¹ Lanzl's specification states that a "transistor constructed in accordance with the present invention includes an electrically active element ... measuring, for example, 10 to 20 mils on a side and having a thickness of, for example, 5 to 8 mils." RX 7, Col. 1, lines 38-44. The whisker wires connecting the semiconductor to the conductors are approximately one mil in diameter - less than the diameter of a human hair. Schroen, Tr. 22-23. Thus, one of ordinary skill in the semiconductor encapsulation art would know when reading the claims and specification of a

¹⁰ One mil is equal to one one-thousandth of an inch.

¹¹ The application for the Lanzl patent was filed May 10, 1963. RX 7. The application that led to the '027 patent was filed December 16, 1963. CX 2.

patent directed towards semiconductors that he was working on an extremely small scale.

During the prosecution of the application that led to the '027 patent, TI added claims copied from the previously issued U.S. Letters Patent No. 3,367,025 (Doyle)¹² for the purpose of provoking an interference proceeding to determine the priority of invention. The Board of Patent Interferences awarded claims 1, 3, 4 and 6 of the Doyle patent priority over the application that led to the '027 patent. Doyle v. Birchler, Patent Interference No. 96,896 (RX 61). These claims were subsequently cited as prior art and served as one of the bases for the examiner's § 103 rejection of claims directed towards the encapsulation process. CX 2, Paper No. 5.

Doyle's claims disclose an encapsulation process in which the ends of the conductors are bent and flattened. RX 11, Col. 2, lines 59-60. During the Doyle encapsulation process, two of the conductor ends (flats 31 and 32) are on a plane "slightly higher" than the flattened end of the third conductor (flat 30). (RX 11, Col. 3, lines 4-5; RX 172).

The Doyle claims do not set forth a specific distance by which flats 31 and 32 are above flat 30. The specification makes clear, however, that the flats are intended to remain in close proximity to each other. For example, the bends are made so that the span of the thin wires connecting the device to the leads is kept as short as possible. RX 11, Col. 2 lines 51-55; Col. 3 lines 21-25. Further, in the embodiment illustrated in the patent drawings the distance is noticeable, but obviously small, about the thickness of the semiconductor chip. Mr. Doyle testified at the hearing that flats 31 and 32

¹² The Doyle patent is entitled "Method For Fabrication and Plastic Encapsulating a Semiconductor Device."

were approximately 10-15 mils above flat 30. (Doyle, Tr. 966). While this figure is not provided in the Doyle patent, it is consistent with the evidence regarding the size of encapsulated semiconductors extant in the art at that time. Mr. Doyle's testimony illustrates that the examiner was aware that the distance between the flats was on the order of 10-15 mils.

In resolving the appeal from the examiner's rejection,¹³ the Patent Office's Board of Appeals distinguished those application claims which issued as claims 12, 14 and 17¹⁴ over Doyle because "the conductors, not part of them, are defined to be in a parallel or common plane. Doyle's flats 31 and 32 are described as being in a plane slightly above flat 30. These appealed claims when given the broadest reasonable interpretation in light of the specification, ... are not rendered obvious by the invention of Doyle." (CX-2, Paper No. 20, Nov. 30, 1976). It is apparent from this portion of the prosecution history that because of the 10-15 mil difference, the Board of Appeals did not consider flats 31 and 32 of Doyle's device to be in a common plane with flat 30. Accordingly, one of ordinary skill in the art of semiconductor fabrication would construe "substantially in a common plane" as demanding a tolerance of less than 10 mils.

3. "Plurality Of Conductors/Substantially Parallel"

Claim 17 contains as a limitation that the process provide "electrical connections between electrical terminals of the device and a plurality of conductors arranged substantially parallel to one another." RX 11, Col. 14 lines 8-10.

¹³ Ex Parte Birchler, Appeal No. 256-14.

¹⁴ Application claims 15, 21 and 24 issued as claims 12, 14 and 17 respectively.

The term "plurality" is used in patent claims to indicate the presence of more than one element, with no absolute upper limit. Kayton 2 Patent Practice 10-20. TI asserts that the limitation in claim 17 requiring a "plurality of conductors ... substantially parallel" only requires that at least two conductors be substantially parallel to each other. TI's construction thus reads the remainder of the limitation - "to one another" - out of the claim. The phrase "to one another" connotes a substantially parallel relationship among all the conductors, not only between two. The inventor did not utilize a term connoting a relationship between a conductor and only one other, e.g. "to an adjacent conductor" or "to one other conductor." The plain meaning of this limitation, read in its entirety, requires that each of the conductors must be substantially parallel to all the other conductors. TI presented no evidence indicating that the inventors intended the language to mean anything than its plain meaning. Mr. Plummer, respondents' expert, testified that he interpreted the claim as requiring that all of the conductors must be substantially parallel to one another. Tr. 1422-1423.

4. "Intermediate Point"

Claim 1 of the '027 patent calls for electrically connecting each of the electrical terminals of the device to an "intermediate point" of a conductor. CX 1, Col. 9, line 5.

Application claim 1 in the '006 grandparent application provided as follows:

1. A process for encapsulating a miniaturized, semiconductor device having a multiplicity of electrical terminals comprising the steps of:
 - connecting each of the electrical terminals of the device to an intermediate point of an appropriate conductor,
 - disposing the device and the adjacent intermediate portions of the conductors in a mold cavity with the opposite ends of each of the conductors extending from generally

opposite sides of the mold cavity, and holding the portions of the conductors extending from opposite sides of the mold cavity while injecting fluid insulating material into the mold cavity which will subsequently harden thereby embedding said device in said insulating material.

CX 4 at 19.

During the prosecution of the '006 application, the examiner rejected application claims 1-13 as obvious over U.S. Letters Patent No. 3,171,167 (Ikeda) considered in light of U.S. Letters Patent Nos. 2,757,439 (Burns) and 3,221,089 (Cotton). CX 4 at 43.

In appealing the rejection of application claim 1, TI distinguished the arrangement of the conductors and wires in Ikeda from that disclosed in claim

1. Specifically, TI asserted:

Ikeda et al. show the attachment of the ends of the conductors to the terminals of the semiconductor device. Similarly, Burns shows the securement of the ends of conductors to a semiconductor device. It is quite clear that neither of these references in any way show or suggest connecting terminals of the semiconductor device to an intermediate point of an appropriate conductor so that the conductors may be arranged to extend from opposite sides of a mold cavity with the portions of the conductors extending from opposite sides of the cavities being restrained.

CX 4 at 83. (original emphasis)

Figure 4A of the Ikeda patent shows the relationship between the connecting wires leading from the semiconducting element to the conductors. RX 5. The three conductors join in a "T" configuration with the semiconducting element attached to the conductor that serves as the vertical bar of the T. RX 5, Figure 4A. Lead wires connect the element's emitter electrode and base electrode to the other two conductors (each of which serve as half of the T's crossbar) and are attached at points near the tips of these two conductors. RX 5, Col. 2, lines 31-34, Figure 4A.

The points of attachment in Ikeda are not at the extreme tips of the conductors. TI argued, and the PTO agreed, that the points of attachment in Ikeda are sufficiently close to the tips of the conductors to be characterized as being at the "end" of the conductors, and not at an "intermediate point." Similarly, in this proceeding, attachments close to the tip of a conductor do not constitute an "intermediate" point.

5. "Injecting ... Into The Mold On The Other/Opposite Side Of The Plane/Conductors"

Claims 12 and 14 each refer to a plane that is formed by the conductors. The semiconductor device and its electrical connections to the conductors are on one side of the plane, and the plastic insulating material is injected into the mold cavity on the "other" (claim 12) or "opposite" (claim 14) side of the plane. CX 1, Col. 12, lines 34-43; Col. 13, lines 7-17. Claim 17 does not make reference to a "plane", claiming only a configuration where the semiconductor's electrical connections are on one side of the conductors and the material is injected into a portion of the cavity on the opposite side. Id. at Col. 14, lines 11-20.

At the time of their work which resulted in the '027 patent, Messrs. Birchler and Williams believed that during encapsulation, fluid plastic would initially flow across the bottom of the mold cavity, filling that portion of the cavity before filling the upper half. Birchler, Tr. 310; Williams, Tr. 1471; CX 15, Hull DRAM Tr. 1043-45. When Williams conducted the initial transfer molding experiments at the Dow Corning facility in Midland, Michigan in May 1963, he performed some of the molding attempts with the semiconductor device, whisker wires and gate all located in the upper half of the mold cavity where the gate was located. RX 41. The remainder of the attempts were performed with the device and whisker wires located in the bottom half of the

mold cavity, and the gate in the upper half. RX 41, Birchler, Tr. 281-285. Williams discovered that all the attempts to mold semiconductors when the device, wires and gate were located on the same side of the cavity were failures. RX 41. Williams' laboratory notebook entry for May 29, 1963 indicates that "better results" were achieved with the latter configuration, i.e. when the device and wires were located on one side of the conductors and the gate was located on the opposite side. FF A 23. The May 29 notebook entry contains two drawings, illustrating "same side" and "opposite side" configurations. FF A 23. Mr. Lockhart of Dow Corning who worked with Mr. Williams at Dow said Mr. Williams was "elated" when the opposite side gate configuration yielded devices in which the electrical continuity remained intact. RPX 109 Lockhart Dep. Tr. 31.

The feature of opposite side gating was something Williams thought of as a result of the work at Dow. Williams, Tr. 1463. Upon returning from Dow, Williams decided to pursue that feature in subsequent molds. Williams, Tr. 1463-1464. A notebook entry dated June 31, 1963 [sic] describes a new two-cavity mold that was built and tested subsequent to Williams' work at Dow. FF B 191. The entry sets forth the "important features" of the mold, one of which is: "C. The gate is in the bottom half of the mold and the device is in the top." FF B 191. These "important features" are repeated in an invention disclosure Messrs. Birchler and Williams submitted to the TI Patent Department.¹⁵ RX 51. In the disclosure, the inventors stated:

"In order to transfer mold successfully it was found that the gate location was critical. The first experiment placed the gate in the top of the unit, which is the conventional location for end gating. ...

¹⁵ The photocopy of the invention disclosure submitted into evidence does not indicate the date on which it was submitted. RX 51.

The results were most unsatisfactory with the emitter and base lead being broken as the cavity filled. It was found during the same experiment that better results were obtained when the unit was in the top half of the mold so it did not see the plastic as it is initially introduced to the cavity."

RX 51.

Figure 1 of the patent disclosure indicates how the inventors believed the liquid plastic flowed upon entering the cavity of their opposite side gated mold. Birchler, Tr. 291-292, 309. In this drawing, arrows indicate that the liquid plastic enters the mold through a gate which is clearly located in that portion of the mold cavity beneath the plane formed by the conductors and on the opposite side from the device and whisker wires. RX 51, Figure 5.

The inventors' belief regarding how the liquid entered the mold cavity and the importance of gate location is evident in the '027 patent itself. Figure 1 of the disclosure appears as Figure 5 of the '027 patent. CX 51, CX 2, Birchler, Tr. 292.¹⁶ In describing the preferred embodiment of the invention illustrated by Figure 5, the specification sets forth:

"It will also be noted that since the transistor wafer ... and the whisker wire leads ... are connected to the tops of the flattened portions [of the conductors], the wafer and whisker wire leads are positioned in the upper mold cavity half... On the other hand, the gate...is located in the lower mold cavity half... and as previously mentioned is off-set from the center of the mold cavity so as to direct material into the mold cavity at a point remote from the transistor device and its

¹⁶ In Texas Instruments, Inc. v. United States International Trade Commission, No. 87-1267 (Fed. Cir., July 12, 1988) the Federal Circuit ruled the Commission committed legal error by incorporating Figure 5 into the claims of the '027 patent, thus erroneously finding the claims invalid for inoperativeness. The Administrative Law Judge is not incorporating Figure 5 into claims 12, 14 and 17, but is utilizing the drawing and evidence relating to it to construe the term "injecting ... into the mold on the other/opposite side of the plane/conductors."

connecting whisker wire leads. Thus, it will be noted that material will be directed through the gate...into the lower mold cavity half..."

CX 2, Col. 5 lines 37-48 (emphasis added)

It is axiomatic that the claims of a patent, not the specification define the invention. Coleco Industries, Inc. v. United States International Trade Commission, 197 U.S.P.Q. 472 (C.C.P.A. 1978). However, of the specification in conjunction with Figure 5, the prosecution history and the testimony of the inventors clearly illustrate that the proper construction of those claims of the '027 patent which provide for the injection of the liquid plastic "into the mold on the other/opposite side of the plane/conductors" means that the injection of plastic is through a gate located on the other or opposite side of the plane/conductors.

TI asserts that when the liquid plastic enters the mold cavity, it immediately commences a flow pattern known as "plug flow" and, as a consequence, the liquid fills the cavity on both sides of the plane simultaneously. Therefore, TI concludes, location of the gate is immaterial to a determination of whether the "opposite side of the plane" limitation is met because regardless of gate location, the liquid is injected "on the opposite side of the plane." TI further argues that construing claims 12, 14 and 17 to require gate location on the opposite side of the plane impermissibly reads a limitation from the specification into the claims.

While it is accepted that today's liquid plastic encapsulating materials fill mold cavities by "plug flow", there is insufficient evidence to support a conclusion that in 1963 the inventors believed that the cavity was filled by "plug flow" rather than as shown in Fig. 5 of the '027 patent. TI's only evidence in support of this point is the testimony of Mr. Hull in DRAMs. In

the DRAM proceeding Mr. Hull testified as an expert witness that in 1963 it was known to him that the flow of insulating material in a mold was by "plug flow,"¹⁷ by which is meant that the insulating material occupies both sides of the plane or conductors very quickly after entry into the mold cavity, and that it advances in a broad front until the cavity is filled. CX 15, Hull DRAMs, Tr. 1044. However, just before his "plug flow" conclusion, Mr. Hull states that Fig. 5 of the patent shows that the inventors believed the lower cavity was filled first.¹⁸ Id. at 1043-44.

The flow diagram which is Fig. 5 of the '027 patent, the inventor's testimony in this proceeding about their beliefs concerning the flow in the mold cavity, and their early experimental efforts at Dow Corning, as well as their descriptions of the important features of their invention in the Patent Disclosure Form (RX 51), leave no doubt that the inventors' believed that the flow of insulating material was not plug flow, but was as is depicted in Fig. 5 of the '027 patent. Indeed, claims 12, 14, and 17 of the patent would make little sense if the term "injecting" insulating material on the "other" or "opposite" side of the "plane" or "conductors" did not refer to gate location.

¹⁷ To minimize duplication in this proceeding with the prior DRAMS proceeding, the complainant was required to designate those portions of the DRAMS testimony upon which it wished to rely in this proceeding. Respondents were then given the right to cross-examine the witnesses designated by complainant. (See Order No. 3, October 2, 1990). Mr. Hull's testimony was designated by the complainant, but the respondents chose not to cross-examine him. The complainant and the respondents listed him as an expert witness as part of the prehearing procedures, but none of the parties chose to call him as a witness at the hearing.

¹⁸ It should be noted that Mr. Hull's testimony that plug flow occurred in 1963 was made irrelevant in the DRAMS proceeding because both parties stipulated that Fig. 5 is erroneous. There is no such stipulation in this proceeding and the respondents contend that the flow depicted in Fig. 5 describes what actually happened in the early days of transfer molding delicate semiconductors.

If the gate location is immaterial as complainant contends then the cited terms in claims 12, 14 and 17 would be entirely surplusage.

TI asserts other claims of the '027 patent, e.g. claim 4, contain a specific gate location as a limitation and that it is improper to construe claims 12, 14 and 17 as claiming a specific gate location. It is proper to construe claims in light of the other claims in the patent. Specialty Composite, Inc. v. Cabot Corp., 845 F.2d 981. There is a presumed difference in meaning and scope when different words or phrases are used in separate claims. Tandon Corp. v. U.S. International Trade Commission, 831 F.2d 1017, 4 U.S.P.Q.2d 1283 (1987). However, because patent practice has long recognized that claims may define the metes and bounds of an invention in a variety of different ways, two claims which read differently can cover the same subject matter. Id. at 1023-24, 4 U.S.P.Q.2d at 1288.

Claim 4 provides in pertinent part:

[T]he fluid insulating material is directed into the mold cavity generally normal to the conductor wires and at a point longitudinally spaced along the conductor wires from the device and on the other side of the plane.

CX 1, Col. 9 line 66 - Col. 10 line 2

TI argues that in claim 4 use of the term "point" specifies a gate location and the absence of this term from claims 12, 14 and 17 requires they be construed as not specifying a gate location. There is no substantive difference between the language of claim 4 and the claims at issue. Each of the claims at issue is directed to the injection of the encapsulating material "into a portion of the cavity" located "on the other side" (claim 12) or "on the opposite side" (claims 14 and 17) of the conductors. A claim for injecting fluid "into a portion" of the cavity connotes a gate location, just as much as the words "at a point" connote a gate location. In this case the

cited language of all the claims (4, 12, 14 and 17) cover the same subject matter.

The inventors of the '027 patent believed the liquid plastic initially filled the bottom half of their mold, and swirled around to fill the entire cavity. Their claims were drafted in accordance with their beliefs, and it is these claims which are at issue in this investigation. It would be erroneous to expand the construction of the claims to cover processes which the inventors had apparently worked to avoid.

6. "Remote"

Claims 1 and 12 of the '027 patent call for the injection of the fluid insulating material into a portion of the mold cavity "remote from the device." The prosecution history of claim 12 provides guidance as to the proper construction of the term "remote."

Claim 12 was issued as the result of the PTO's decision regarding application claims 14 and 15 of application Ser. No. 384,768. Application claim 14 provided:

A process for encapsulating a semiconductor device comprising:

electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support;

disposing the device and portions of the conductors in a mold cavity; and

holding the ends of the conductors extending from the mold cavity while injecting a fluid insulation material into the mold cavity which will subsequently solidify and embed said device, the fluid insulating material being injected into a portion of the cavity remote from the device and the means electrically connecting the terminals of the device to the conductors whereby the fluid will not directly engage the device and electrical connection means at high velocity; and the conductors will be secured against appreciable displacement by the fluid.

CX 2 at 28

Application claim 15 was dependent upon application claim 14 and provided:

The process according to claim 14 wherein:

the conductor wires are disposed generally in a common plane;

the device and a major portion of the means making electrical connection between the terminals and the conductor wires are disposed generally on one side of the plane, and;

the fluid insulating material is injected into the mold cavity on the other side of the plane.

CX 2 at 28

The examiner rejected application claims 14 and 15 as obvious over Doyle, stating "Doyle clearly teaches to have the orifice of his gate 52 remote from his device." CX 2, Paper No. 9, November 14, 1974.

TI appealed the examiner's decision to the PTO's Board of Appeals. Ex parte Birchler, CX 2, Paper No. 20, November 30, 1977. The Board of Appeals found application claim 14 invalid as obvious over the Doyle claims. The Board found that the Doyle claims expressly required the complete encapsulation of the semiconductor, a requirement which would lead one to a configuration where the semiconductor is disposed in the molding cavity interior. The Board then stated, "This being the case, the fluid material being injected would be at a point remote from the device and connecting means so that the fluid material would not directly impinge upon the semiconductor and tiny connecting wires." CX 2, Paper No. 20 at 4-5 (emphasis added). The Board further held that even without the benefit of the drawing in Doyle, "it is merely a matter of common sense to one of ordinary skill in the art to not inject the full force of the fluid directly on a fragile semiconductor wafer and its tiny connecting wires. Thus, one would inject the fluid remote or offset from the vicinity of the semiconductor assembly." CX 2, Paper No. 20 at 5.

The Board further found that application claim 15 would not have been obvious over Doyle and Otis because it recited a specific arrangement of the connectors, connections and semiconductor wafer within the cavity. Id. It was the specific arrangement set forth in application claim 15, i.e. the placement of the wafer, whisker wires and wire bonds on one side of the plane described by the conductors, that made application claim 15 patentable. Application claim 15, written in independent form, was issued as claim 12. CX 2, Amendment After Board Decision, February 14, 1977.

Thus, the Board made a de facto construction of the term "remote" in its decision to deny application claim 14. According to the decision, a gate through which the fluid material is injected is "remote" if the material does not directly impinge upon the semiconductor device or wires. The material must, of course, eventually impinge upon the device and wires at some point during the encapsulation process. "Remoteness" is achieved if the impingement does not occur "directly", i.e. "immediately" or "instantly" (American Heritage Dictionary, 2d ed. at 400).¹⁹

7. "Opposite Ends Of Each Of The Conductors Extending From Generally Opposite Sides Of The Mold Cavity"

Claim 1 calls for placing the device and conductors into a mold cavity with the opposite ends of each of the conductors extending from generally opposite sides of the mold cavity. The process claimed in claim 1 also calls for holding these opposite ends of the conductors while the encapsulating fluid is injected into the mold cavity. CX 1, col. 9 lines 9-16.

¹⁹ The Board's opinion contains the phrase "remote or offset", suggesting that "remote" may be construed as "offset". However, the prosecution history of claim 13 of the '027 patent indicates that the Board intended the two terms to be nonsynonymous. See, Board's discussion regarding application claims 16 and 18, CX 2, Paper No. 20 at 5.

The plain meaning of this claim language is unambiguous, particularly when read in reference to the patent's drawings.²⁰ Each of the conductors extends in two directions, apparently 180 degrees apart, from the area containing the die. CX 1, Fig. 2. In the preferred embodiment illustrated in Figure 4, the opposite ends of the conductors are placed in recesses on opposite sides of the bottom half of the mold, and in recesses on either side of the molding cavity to achieve the effect of having the conductors extend from generally opposite sides of the mold cavity. CX 1, Fig. 4.

No evidence was adduced suggesting that the inventors intended to utilize the language in this claim in a manner other than its ordinary and customary usage. Indeed, the "double-ended" nature of the device was set forth in Mr. Williams' notebook and invention disclosure as one of the "important features" of what was to become the '027 process:

D. The construction of the device was double ended to prevent any movement of leads, thus breaking the connections. See drawings.

RX 41.

The notebook's drawings show the conductors (referred therein as "leads") extending in a straight line in two directions from opposite sides of the mold cavity. RX 41. Thus, the inventors intended to utilize the plain meaning of the words in this claim limitation.

8. The "Whereby" Clause

A "whereby" clause in a claim is given no weight in an infringement determination if it expresses only a necessary result of the structure already

²⁰ While it is impermissible to read a patent's drawings into a claim as limitations, the claims may be interpreted in light of the patent's specification including the drawings. Grain Processing Corp. v. American Maize-Products Corp., 840 F.2d 902, 5 U.S.P.Q.2d 1788 (Fed. Cir. 1988), Crown Cork & Seal Co., Inc. v. Ethyl Corp., 11 U.S.P.Q.2d 1577 (E.D. Va. 1989)

recited in the body of the claim. In re Certain Personal Computers and Components Thereof, 224 U.S.P.Q. 270, 283 (USITC Inv. No. 337-TA-140). On the other hand, when a claim's "whereby" clause defines the relationship of the components, it imparts a structural limitation on the claim as a whole. In re Venezia, 530 F.2d 956, 189 U.S.P.Q. 149 (C.C.P.A. 1976). When an accused product or process is missing an essential feature described by a whereby clause, it does not infringe. Eltech Systems Corp. v. PPG Industries, Inc., 710 F.Supp. 622, 11 U.S.P.Q.2d 1174 (W.D. La. 1988), aff'd, 903 F.2d 805, 14 U.S.P.Q.2d 1965 (Fed. Cir. 1990).

Each of the claims contains a "whereby"²¹ clause following the recitation of the arrangement of the invention's components. The clause in each claim provides:

... whereby the fluid will not directly engage the device and electrical connection means at a high velocity and the conductors will be secured against appreciable displacement by the fluid.

CX 1, Col. 9 lines 22-25, Col. 12 lines 47-51

This clause describes the result of arranging the components in the manner recited in the claims. As stated previously, a gate is "remote" as claimed in claims 1 and 12 if the fluid going through it does not directly impinge upon the semiconductor device and connections. Further, the claims are for a process wherein the conductors are held by notches in the carrier and lower mold die. CX 1, Col. 4, lines 2-4, lines 58-68, Col. 9, lines 14-16, Col. 12, lines 40-42. Clamping the conductors in these notches with the upper half of the mold die secures them against appreciable displacement. Id. Col. 5, lines 54-59.

Thus, the "whereby" or "to preclude" clauses in each claim does not add

²¹ Claims 14 and 17 utilize the term "to preclude" instead of "whereby".

any structural limitation to the claim, and only express necessary results of what is already recited therein. Accordingly, they will be given no weight in this decision's infringement analysis.

C. The Accused Encapsulation Processes

1. Features Common To All Accused Processes

All respondents' processes share certain common characteristics. Each employs a rectangular metal frame known as a "lead frame". The lead frame provides a structure for mounting, assembling, and handling semiconductor devices. FF C 1. The frames are formed by stamping or etching a continuous piece of metal to create a "spidery" arrangement of slots on its surface. FF C 2; Schroen, Tr. 21. Some of the thin metal strips between the slots will serve as electrical leads in the finished product. FF C 2; Schroen, Tr. 21. (Examples for each of the respondents are illustrated in the following exhibits: Cypress: CX 40; CX 49-52; IDT: CX 155, 183-185; LSI: CX 55, CX 76-77; VLSI: CX 107-110, 122-124; Analog: CX 205). After the stamping or etching step, metal remains between the leads and serves to connect them to each other. FF C 2; RX 320-1. This metal is referred to as a "dam bar." FF C 2.

The semiconductor die is attached to the portion of the lead frame known as the die pad with an adhesive designed to conduct heat. FF C 5; Plummer, Tr. 1342. Most, but not all, respondents' products have a downset die pad. FF C 29, 129, 159, 202. The die pad serves to support the die, and in the finished product does not conduct electricity. Seiling, Tr. 573. The terminals on respondents' dice are connected to the leads on the frame with very fine whisker wires by a process known as "wire bonding". FF C 4. Respondents typically use [C] wire that is [C] in diameter when wire bonding. FF C 4. The whisker wires are bonded to a point on the leads very

close to the particular lead end which will be located in the mold cavity. (Cypress: CX 49-52; LSI, CX 90-92; VLSI, CX 102-105, 138; IDT, CX 182-185; Analog, CX 251).

The leads in respondents' products each have one end resting unsupported in the space near the die. (Cypress: CX 40, CX 49-52; IDT: CX 155, 183-185; LSI: CX 55, CX 76-77; VLSI: CX 107-110, 122-124; Analog: CX 205). The leads radiate outwardly from the die in patterns which differ according to package type, but they are generally of a pattern that may be characterized as a "starburst". Id. Some products of the California Respondents have a lead arrangement in which many of the leads are parallel over a significant portion of their lengths (see CX 40 at CYP000242, CX 77, CX 122, CX 151 at IDT000085). With all products, however, those leads situated towards the center of the side of the device are nearly perpendicular to the longest portion of those leads which are situated near the ends of the device. e.g. CX 40 at CYP000242.

The lead frame and attached die pad are placed in a mold cavity with one end of each lead extending out of the cavity. FF C 7. The other end of each lead is cantilevered inside the cavity like a diving board. FF C 218 (Analog), (Cypress: CX 40, CX 49-52; IDT: CX 155, 183-185; LSI: CX 55, CX 76-77; VLSI: CX 107-110, 122-124; Analog: CX 205). During encapsulation, the upper and lower halves of the mold are clamped together and firmly hold one end of each conductor (which extends from the mold cavity between the halves) and the dam bar. FF C 8. A fluid insulating material (referred to as a "molding compound") is injected into the mold cavity. FF C 9. In the majority of integrated circuits encapsulated by respondents, the gate through which the molding compound enters the mold cavity is located on the other side

of the lead frame from the semiconductor die and whisker wires. FF C 10. This is conventionally referred to as an "opposite side gated" or "bottom gated" mold. FF C 10. The molding compound subsequently solidifies and embeds the semiconductor die. FF C 14.

2. Cypress Semiconductor

Cypress Semiconductor has certain of its package types (PDIPs, SOICs and PLCCs) encapsulated by subcontractors in [C] and [C] FF C 17. Almost all of Cypress's products were transfer molded in a mold with the gate located on the opposite side of the lead frame from the die and whisker wires. FF C 23. The only exception were approximately [C] PDIPs imported and sold by Cypress which were encapsulated in a mold with the gate located on the same side of the leads as the die and whisker wires. FF C 23.

3. Integrated Device Technology

IDT imports plastic integrated circuits (PDIPs, PLCCs, PQFPs and SOICs (including SOJs) which are encapsulated in plastic by assemblers and/or subcontractors in [C] and [C] FF C 65. Almost all of IDT's imported products are transfer molded in a mold with the gate located on the opposite side of the lead frame from the die and whisker wires. FF C 63, 70. The only exception were approximately [C] PDIPs imported by IDT which were encapsulated in a mold with the gate located on the same side of the leads as the die and whisker wires. FF C 70. These devices were molded by placing the lead frames "upside down" in the mold, and they were not sold to any of IDT's customers. FF C 92, 93. Upon testing, it was demonstrated that, from a quality and performance standpoint, the devices were the same. FF C 103. IDT has recently purchased a mold with the gate located in the top half of the mold cavity. FF C 97.

4. LSI

LSI imports integrated circuits (PDIPs, PLCCs and PQFPs) which are plastic encapsulated at facilities in [C] and [C] [C] FF C 105-106. All of LSI's PDIPs and PLCCs were encapsulated in molds with the gate on the opposite side of the lead frame from the whisker wires and device. FF C 117, 119. This is also true with respect to all of LSI's PQFPs except for [C] PQFPs which were molded in a top gated mold at LSI's [C] facility during the second half of 1990. FF C 135-137. These devices were not requalified before they were shipped to LSI's customer, and changing from a bottom gated process to a top gated process did not affect product yield. FF C 137, 140. LSI plans to modify its [C] facility's molding operations to top gating. FF C 138.

5. VLSI

VLSI imports integrated circuits (PDIPs, PLCCs, SOICs (including SOJs and SOGs) and PQFPs) which are plastic encapsulated at facilities in [C] [C] FF C 141-143. All of VLSI's devices are encapsulated in a mold with the gate located on the opposite side of the lead frame from the whisker wires and die. FF C 148, 150, 152, 154, 170, 176.

6. Analog

Analog imports integrated circuits (PDIPs, PLCCs, SOICs and PQFPs) which are plastic encapsulated overseas at its facilities in Ireland and The Phillipines. FF C 181, 182, 185, 189-192. Analog also employs foreign subcontractors in South Korea, Japan and Hong Kong to encapsulate its packages. FF C 183, 193-196. In all of Analog's conventional molding processes, the gate was located on the opposite side of the lead frame from the die and whisker wires. FF C 221-222. Analog has recently concluded an

evaluation of 8-pin PDIP and 8-pin SOIC devices encapsulated in a mold with the gate on the same side of the lead frame. FF C 223-224. Test data did not show any significant difference between the top-gated products and similar bottom gated products. FF C 225.

D. Literal Infringement

1. There Is No Literal Infringement Of Claim 1

Several limitations of claim 1 are not present in the respondents' processes. The semiconductor devices in respondents' products are mounted on a die pad which does not constitute a "conductor" as that term is construed in the '027 patent. Thus, respondents' processes do not meet the claim 1 limitation calling for mechanical attachment of the device to one of the conductors for support.

The electrical connections between the semiconductor devices and the leads in respondents' products are made between the devices and the very end of each lead. Indeed, the connecting wires attach to a point on the leads near the extreme tip of the lead - a connection point almost identical to that illustrated in the Ikeda patent and which TI argued to the PTO did not constitute an "intermediate point." See discussion, supra. Respondents' processes do not electrically connect the semiconductor device to an intermediate point of a conductor.

The leads in respondents' products have one end resting unsupported in the space near the semiconductor device and the other extending outside of the molding cavity. Thus, for each lead, only one end extends outside of the cavity. This is completely unlike the configuration claimed in claim 1, where both ends of each lead extend outside of the cavity. Respondents' processes do not place the device and conductors into a molding cavity with the opposite

ends of each conductor extending from opposite sides of the mold cavity. Similarly, the molds utilized in respondents' processes do not hold the opposite ends of the conductors as they extend from the cavity for the simple reason that only one end so extends.

The limitation in claim 1 requiring that the fluid be injected into a portion of the mold cavity "remote" from the device is present in the processes that encapsulate respondents' devices. As construed in the '027 patent, injection is "remote" if the encapsulating fluid does not directly impinge upon the semiconductor device or wires, i.e., impinge upon them immediately or instantly after injection. See discussion, supra.

In light of the fact that respondents' processes fail to meet claim 1's limitations regarding mounting the device upon a conductor, electrically connecting the conductor to intermediate points on the leads, having the opposite ends of each conductor extend from opposite sides of the mold cavity, and holding these opposite ends during encapsulation, there is no literal infringement of claim 1.

2. There Is No Literal Infringement Of Claim 12

Claim 12 contains the limitation found in claim 1 of mounting the semiconductor device upon a conductor for support. For the same reason respondents' processes do not meet this limitation as set forth in claim 1, their processes do not meet it as set forth in claim 12.

Claim 12 calls for arranging the conductors "generally" in a common plane, placing the device and whisker wire connections on one side of the plane, and injecting the encapsulating fluid into a portion of the mold cavity on the opposite side of this plane. All of the products imported by Analog and VLSI were encapsulated by a process in which the gate through which the

fluid enters the cavity is located on the opposite side of such a plane. Additionally, the overwhelming majority of products imported by Cypress, IDT and LSI were encapsulated by a process with a similarly located gate. These opposite-side gated processes meet this limitation of claim 12. Conversely, the same side gated products of Cypress, IDT and LSI do not meet this limitation.

Claim 12 also calls for holding "the ends of the conductors extending from the mold." Unlike claim 1, there is no requirement that the mold hold the two opposite ends of each conductor. Each of the respondents utilizes a process during which the mold clamps down and holds one end of each of the conductors. Accordingly, this limitation of claim 12 is met by each of the accused processes.

Because none of the accused processes contain the limitation of mounting the device to a conductor for support, there is no literal infringement of claim 12 of the '027 patent.

3. Claim 14 Is Literally Infringed

Claim 14 contains a limitation relating to gate location which is almost identical in wording to the gate location limitation in claim 12. Claim 14 requires the arrangement of the conductors in a "substantially" common plane, with the device and whisker wires mounted on one side of the plane and injecting the encapsulating fluid into a portion of the mold cavity on the opposite side of this plane. There is no requirement that the device be mounted upon a conductor.

Reference to the description of the respondents' processes in the portion of this opinion regarding claim 12 demonstrates that these processes meet all the limitations of claim 14. Accordingly, there is literal infringement of

claim 14.

4. There Is No Literal Infringement Of Claim 17

Claim 17 calls for arranging the conductors so they are "substantially parallel to one another", mounting the device and whisker wires on one side of the conductors, and injecting the encapsulating material into a portion of the cavity on the opposite side of the conductors. There is no requirement that the conductors be in a common plane.

The respondents' processes all place the device and whisker wires on one side of the conductors and, except for certain processes utilized by Cypress, IDT and LSI, inject the fluid through a gate located on the opposite side of the conductors.

However, none of the respondents' products arrange the conductors so they are "substantially parallel to one another" as that term has been construed. Indeed, the conductors radiate outwardly from the center of the lead frame, generally in a starburst pattern. See discussion, supra. In light of the fact that the limitation requiring substantially parallel conductors is absent from all respondents' products, there is no literal infringement of claim 17.

E. Infringement Under The Doctrine Of Equivalents

1. Law Of The Doctrine Of Equivalents

The purpose of the doctrine of equivalents is to protect a patentee from losing the benefit of his invention to one who makes minor changes to a claimed invention so as to remove it from the literal terms of the claim. Graver Tank & Manufacturing Co. v. Linde Air Products Co., 339 U.S. 605, 85 U.S.P.Q. 328 (1950). Under the doctrine, infringement may be found if the accused product or process performs substantially the same function in substantially the same way to achieve substantially the same result. Graver

Tank, 339 U.S. at 607, 85 U.S.P.Q. at 330 (1950), Pennwalt Corp. v. Durand-Wayland, Inc., 833 F.2d 931, 4 U.S.P.Q.2d 1737 (Fed. Cir 1987).

The doctrine does not allow the finder of fact to ignore meaningful structural limitations in the claim at issue. Perkin-Elmer Corp. v. Westinghouse Electric Corp., 822 F.2d 1528, 3 U.S.P.Q.2d 1321 (Fed. Cir. 1987). While an infringement analysis under the doctrine must consider the claimed invention as a whole, Hughes Aircraft Co. v. United States, 717 F.2d 1351, 219 U.S.P.Q. 473 (Fed. Cir. 1983), each limitation or its equivalent must be found in the accused product or process for there to be infringement. Pennwalt Corp. v. Durand-Wayland, Inc., 833 F.2d 931, 4 U.S.P.Q.2d 1737 (Fed. Cir 1987). Infringement under the doctrine does not require that a limitation in a component of the claimed product or process have its equivalent in a corresponding component of the accused product or process. Corning Glass Works v. Sumitomo Electric U.S.A., 868 F.2d 1251, 9 U.S.P.Q.2d 1962 (Fed. Cir. 1989).

A patentee's reliance on the doctrine of equivalents is limited by prosecution history estoppel. Prosecution history estoppel prevents the patentee from asserting a claim interpretation so broad as to either vitiate amendments added to overcome an examiner's prior art rejection, or contrary to arguments submitted to obtain the patent. Jonsson v. The Stanley Works, 903 F.2d 812 14 U.S.P.Q.2d 1863 (Fed. Cir. 1990), Townsend Engineering Company v. HiTec Co., Ltd., 829 F.2d 1086, 4 U.S.P.Q.2d 1136 (Fed. Cir. 1987). The prosecution history of a patent includes amendments to the claims and arguments made to convince the examiner that the invention meets the statutory requirements for patentability. Standard Oil Co. v. American Cyanamid Co., 774 F.2d 448, 227 U.S.P.Q. 293 (Fed. Cir. 1985). Claims may not be enlarged

by equivalents to encompass the teachings of the prior art. Tandon Corp. v. U.S. International Trade Commission, 831 F.2d 1017, 4 U.S.P.Q.2d 1283 (Fed. Cir. 1987).

2. Respondents' Opposite Side Gated Products Infringe Claim 12 Under The Doctrine Of Equivalents

a. Opposite-side Gated Products

The only limitation of claim 12 not literally found in the processes for encapsulating respondents' opposite-side gated products is the attachment of the semiconductor device to a conductor for support. Claim 12's structural limitation requiring the semiconductor device to be mechanically attached to a conductor lends itself to a fairly straightforward function/way/result analysis. Put simply, one of the conductors is to serve the function of supporting the device by being attached thereto so as to hold it in place.

The die pad in respondents' products is the functional equivalent of the supporting conductor described in claim 12. Indeed, it goes beyond the "substantially the same" function/way result test set forth in Graver Tank in that it performs exactly the same function (support the semiconductor) in exactly the same way (mechanical attachment) to achieve exactly the same result (hold the semiconductor in place).

Respondents assert that that the die pad is not the functional equivalent of the supporting conductor because it does not perform the other function performed by the supporting conductor, i.e. electrically connecting the semiconductor to and from an external circuit. Respondents' description of the two functions served by the supporting conductor is accurate. See, CX 1, Col. 12, lines 26-31. However, the doctrine of equivalents is concerned with limitations, not structures. In Sun Studs, Inc. v. ATA Equipment Leasing, Inc., 872 F.2d 978, 10 U.S.P.Q.2d 1338 (Fed. Cir. 1989), the district court

had held that the claim at issue, which outlined the steps performed by the claimed product, required that separate steps must be performed by separate elements in the accused product to make out a finding of infringement under the doctrine of equivalents. 10 U.S.P.Q.2d at 1347. The Federal Circuit reversed the district court's determination of no infringement under the doctrine, holding that a claim describing a combination of components does not require that the function of each component be performed by a separate structure in the apparatus because both the claimed and accused devices must be evaluated as a whole. Id., citing Hughes Aircraft Co. v. United States, supra.

The present situation is analogous to that in Sun Studs. Here, the accused processes divide the two functions of the supporting conductor - support of the die, and electrical connection thereof to an external circuit - between separate components of their processes. To require that the functions of the supporting conductor must be performed by a single component for there to be infringement under the doctrine of equivalents would ignore the invention as a whole, contrary to the Federal Circuit's holdings in Hughes Aircraft, Perkin-Elmer, and Sun Studs. Accordingly, respondents' argument must be rejected. There is infringement of claim 12 by respondents' opposite-side gated products under the doctrine of equivalents.

b. Same-side Gated Products

TI asserts that respondents' same-side gated processes also infringe claim 12 under the doctrine of equivalents because same-side gating is the equivalent of opposite-side gating.

At the time of their invention, Birchler and Williams believed that the encapsulating fluid, when injected into an opposite-side gated mold, filled

the lower half of the mold first. CX 1, Col. 5, lines 46-50 ("Thus, it will be noted that material will be directed through the gate...into the lower mold cavity half..along a path generally parallel to the whisker wire leads...as indicated by the arrows in Fig. 5."). Williams stated in his laboratory notebook that one of the "important features" of his new mold was the location of the gate in the bottom half of the mold, and the device in the top, i.e. opposite-side gating. RX 41.

During the prosecution of the '027 patent's parent application (Ser. No. 331,006), TI filed application claim 22 which, when read with application claim 21, provides coverage identical to that claimed in claim 12 of the '027 patent:

21. A process for encapsulating a semiconductor device comprising:
 - (a) electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support;
 - (b) disposing the device and portions of the conductors in a mold cavity;
 - (c) holding the ends of the conductors extending from the mold cavity while injecting a fluid insulating material into the mold cavity which will subsequently solidify and embed said device the fluid insulating material being injected into a portion of the cavity remote from the device and the means electrically connecting the terminals of the device to the conductors, whereby the fluid will not directly engage the device and electrical connection means, and the conductors will be secured against appreciable displacement by the fluid.

22. The process according to claim 21 wherein:
 - (a) the conductor wires are disposed generally in a common plane;
 - (b) the device and a major portion of the means making electrical connection between the terminals and the conductor wires are disposed generally on one side of the plane, and;
 - (c) the fluid insulating material is injected into the mold cavity on the other side of the plane.

The examiner rejected application claims 21 and 22 as obvious over the Ikeda and Burns patents²² and the "G.E. literature".²³ CX 4 at 73 (Paper No. 22).

TI subsequently argued to the examiner that the arrangement of conductors, device, whisker wires and gate set forth in application claim 22 was not suggested by the cited references:

Claim 22 is dependent upon claim 21 and further specifies that the conductor wires are disposed generally in a common plane, with the device and a major portion of the means making electrical connection between the terminals and the conductor wires being disposed generally on one side of this plane, while the fluid insulating material is injected into the mold cavity on the opposite side of this plane. Consequently, the device and its electrical connections are arranged such that they are not directly engaged by the fluid insulating material injected into the mold cavity. Such an arrangement of course is in no way shown or suggested by any of the cited references. ... [N]one of these references alone or in combination in any way show or suggest the step of injecting the fluid insulating material into a mold cavity on an opposite side of the common plane defined by the conductor wires from the side on which the device and a major portion of the means making electrical connection between the device and the conductor wires are disposed. It is accordingly respectfully submitted that claims 21 and 22 are clearly patentable over the cited references alone or in combination.

CX 4 at 93

TI's argument in support of the issuance of what was to become claim 12 is part of that claim's prosecution history. TI explicitly stated in its argument to the examiner that the feature of injecting encapsulating fluid on the other side of the plane made the claim patentable over the cited references which did not describe or suggest such a limitation. TI now seeks through the doctrine of equivalents to interpret claim 12 so broadly as to

²² U.S. Letters Patent Nos. 3,171,187 and 2,757,439 respectively.

²³ The file wrapper of the '006 application does not contain a copy of the "G.E. literature" and none of the parties was able to obtain a copy.

render this distinction a nullity. Such a reworking of a claim is exactly what prosecution history estoppel is intended to prevent. Having successfully argued to the examiner that the claim is patentable because it calls for opposite-side gating, TI is estopped from asserting here that a process utilizing same-side gating is the equivalent of claim 12. Accordingly, there is no infringement of claim 12 under the doctrine of equivalents.

III. THE '027 PATENT IS NOT INVALID

The '027 patent is presumed valid pursuant to 35 U.S.C. § 282. The party seeking to establish invalidity thus bears the burden of proof as well as the burden of going forward with the evidence. Avia Group International, Inc. v. L.A. Gear California, Inc., 853 F.2d 1557, 1562, 7 U.S.P.Q.2d 1548, 1552 (Fed. Cir. 1988); Stratoflex, Inc. v. Aeroquip Corporation, 713 F.2d 1530, 1534, 218 U.S.P.Q. 871 (Fed. Cir. 1983). The burden of persuasion is one of clear and convincing evidence. Uniroyal Inc. v. Rudkin-Wiley Corp., 837 F.2d 1044, 5 U.S.P.Q.2d 1434 (Fed. Cir. 1988), Medtronic, Inc. v. Intermedics, Inc., 799 F.2d 734, 741, 230 U.S.P.Q. 641, 645 (Fed. Cir. 1986), cert. denied, 479 U.S. 1033 (1987).

Respondents have put forward four invalidity contentions: (1) that claims 12, 14 and 17 of the '027 patent would have been obvious to one of ordinary skill in the art at the time the invention was made; (2) that claims 12, 14 and 17 were anticipated by Motorola's Helda-Lincoln proposal; (3) that claims 1, 12, 14 and 17 are invalid for obviousness-type double patenting; and (4) that the inventors failed to disclose the best mode known to them for performing the patented process.

A. The '027 Patent Is Not Invalid For Obviousness

1. Law Of Obviousness

In Graham v. John Deere Co., 383 U.S. 1, 148 U.S.P.Q. 459 (1966), the Supreme Court set forth the approach by which a court is to determine whether a patent is invalid for obviousness:

"Under § 103, the scope and content of the prior art are to be determined; differences between the prior art and the claims at issue are to be ascertained; and the level of ordinary skill in the pertinent art resolved. ... Such secondary considerations as commercial success, long felt but unsolved needs, failure of others, etc., might be utilized to give light to the circumstances surrounding the origin of the subject matter sought to be patented. As indicia of obviousness or nonobviousness, these inquiries may have relevancy."

383 U.S. at 17-18

An obviousness analysis is conducted by comparing the prior art, evaluated as a whole, to the claimed invention taken as a whole. 35 U.S.C. § 103, Panduit Corp. v. Dennison Manufacturing Co., 774 F.2d 1542, 1 U.S.P.Q.2d 1593 (Fed. Cir. 1987). The scope of the prior art is that which is reasonably pertinent to the particular problem facing the inventor. Stratoflex, Inc. v. Aeroquip Corporation, 713 F.2d 1530, 218 U.S.P.Q. 871 (Fed. Cir. 1983). References which fall within one of the prior art categories set forth in 35 U.S.C. § 102 are also prior art for purposes of § 103. Baker Oil Tools, Inc. v. Geo Vann, Inc., 828 F.2d 1558, 4 U.S.P.Q.2d 1210 (Fed. Cir. 1987).

Respondents' burden of proving a patent invalid for obviousness is not reduced by the introduction of prior art which was not considered by the United States Patent and Trademark Office ("PTO"). Uniroyal Inc. v. Rudkin-Wiley Corp., 837 F.2d 1044, 5 U.S.P.Q.2d 1434 (Fed. Cir. 1988). The introduction of such evidence may, however, facilitate the carrying of their

burden. Id. Conversely, a party is less likely to carry its burden when it relies solely upon prior art considered by the PTO. Stratoflex, Inc. v. Aeroquip Corporation, 713 F.2d 1530, 218 U.S.P.Q. 871 (Fed. Cir. 1983).

The comparison between the prior art and the claims at issue is conducted with reference to a hypothetical person of ordinary skill in the art. Such a person is presumed to be aware of all the pertinent prior art, but does not undertake to innovate. Standard Oil Co. v. American Cyanamid Co., 774 F.2d 448, 227 U.S.P.Q. 293 (Fed. Cir. 1985).

When a party asserts that a patent is invalid because it would have been obvious in light of the combined teachings of several prior art references, that party must establish by clear and convincing evidence that there is some teaching, suggestion or inference in the prior art which would have led one of skill in the art to combine the relevant teachings. Ashland Oil, Inc. v. Delta Resins & Refractories, Inc., 776 F.2d 281, 227 U.S.P.Q. 657 (Fed. Cir. 1985).

A court must always consider objective evidence such as commercial success, failure of others, long-felt need, copying, and unexpected results before reaching a conclusion on whether a patent would have been obvious. Hybritech, Inc. v. Monoclonal Antibodies, Inc., 802 F.2d 1367, 231 U.S.P.Q. 81 (Fed. Cir. 1986), cert. denied, 107 S.Ct. 1606 (1987). Such evidence must be weighed along with the other factors of a Graham v. John Deere analysis. See, Truswal Systems Corp. v. Hydro-Air Engineering Inc., 813 F.2d 1207, 1212, 2 U.S.P.Q.2d 1034, 1038 (Fed. Cir. 1987) ("That evidence is 'secondary' in time does not mean that it is secondary in importance.") Commercial success of an invention will only be indicative of nonobviousness if there is a nexus between the success and the merits of the invention. Cable Electric Products.

Inc. v. Genmark, Inc., 770 F.2d 1015, 226 U.S.P.Q. 881 (Fed. Cir. 1985).

2. Scope And Content Of The Prior Art

a. Problem Facing The Inventors

The scope of the prior art is that which is reasonably pertinent to the particular problem facing the inventor. Stratoflex, Inc. v. Aeroquip Corporation, 713 F.2d 1530, 218 U.S.P.Q. 871 (Fed. Cir. 1983). The problem facing Messrs. Birchler and Williams at the time of their work which led to the '027 patent was to develop a process for the encapsulation of a low-cost transistor. FF B 1.

During the 1950's and early 60's, the principal method for encapsulating transistors was known as the "header and can" process. FF A 13. During this process, the device was mounted on a gold-plated metal foundation ("header") and connected to conductor leads with thin "whisker wires". The leads were held in place with a glass filling and came out of the package through the bottom of the header. FF A 13. A metal can was then hermetically welded on top of the header. FF A 13.

In the early 1960's, manufacturers began searching for a means of mass producing inexpensive transistors. FF A 15. Efforts to reduce the costs of manufacturing transistors were undertaken throughout the semiconductor industry. CX 5 at 2, CX 215 at 1. In late 1962 or early 1963, Robert O. Birchler and E.R. Williams commenced working on what eventually became known as TI's Low Cost Transistor Project. FF A 19, A 20. Early in the project, they conducted a cost analysis of the header and can process and determined that in an individual transistor, the header was the second most expensive component. Birchler, Tr. 369. Accordingly, they attempted to devise a process which eliminated the header, and assembled the leads on a "handle"

comprised of two inexpensive steel tabs. Birchler, Tr. 300, 367. Unlike a header, which was encapsulated as part of the finished transistor, the tabs were intended to be discarded after encapsulation. Birchler, Tr. 330. In March, 1963, Mr. Williams stated in his notebook that the ultimate goal of the project was a headerless device. CX 215 at 26-27. One of the problems facing Birchler and Williams was how to mold their headerless devices in a mass production setting without damaging the delicate "whisker wire" components. This work eventually led to the '027 patent.

b. Date Of Invention

Section 103 of Title 35 provides that a patent will not issue if the invention would have been obvious to one of ordinary skill in the art "at the time the invention was made." 35 U.S.C. § 103. Accordingly, an obviousness analysis requires a determination of the date of invention.

The effective filing date of a patent application constitutes a constructive date of invention. Amgen, Inc. v. Chugai Pharmaceutical Co. Ltd., 13 U.S.P.Q.2d 1737, 1762 (D. Mass. 1989). An inventor will be entitled to the benefit of an earlier date of invention by demonstrating by clear and unequivocal evidence that the claimed invention was conceived and reduced to practice by that earlier date. Freeman v. Minnesota Mining & Manufacturing Co. 693 F. Supp. 134, 9 U.S.P.Q.2d 1111 (D. Del. 1988), Polaroid Corp. v. Eastman Kodak Co., 228 U.S.P.Q. 305 (D. Mass. 1985), aff'd 789 F.2d 1556, 229 U.S.P.Q. 561 (Fed. Cir. 1986). Conception is the "formation in the mind of the inventor, of a definite and permanent idea of the complete and operative invention." Hybritech v. Monoclonal Antibodies, Inc., 802 F. 2d 1367, 1376, 231 U.S.P.Q. 81, 87 (Fed. Cir. 1988), cert. denied, 480 U.S. 947 (1989). Reduction to practice requires that the invention be sufficiently tested to

demonstrate that it will work for its intended purpose. Barmag Barmer Maschinenfabrik v. Murata Machinery, Ltd., 731 F.2d 831, 221 U.S.P.Q. 561 (Fed. Cir. 1984).

In determining the date of invention, a finder of fact utilizes a "rule of reason" in which all pertinent evidence is examined. Coleman v. Dines, 754 F.2d 353, 224 U.S.P.Q. 857 (Fed. Cir. 1984), Reese v. Hurst, 661 F.2d 1222, 211 U.S.P.Q. 936 (C.C.P.A. 1981). The inventor must produce independent corroborating evidence in addition to his own statements and documents in order to establish a date of invention earlier than the date the patent application was filed. Hahn v. Wong, 892 F.2d 1028, 13 U.S.P.Q.2d 1313 (Fed. Cir. 1989). However, the rule does not require eye-witness corroboration; sufficient circumstantial evidence can satisfy the corroboration requirement. Knorr v. Pearson, 671 F.2d 1368, 213 U.S.P.Q. 196 (C.C.P.A. 1982), Berges v. Gottstein, 618 F.2d 771, 205 U.S.P.Q. 691 (C.C.P.A. 1980).

The '027 patent issued on August 23, 1977 based on Application No. 384,768, filed July 30, 1973, in continuation of Application No. 738,311 filed October 17, 1968, which was a division of Application No. 331,006 filed on December 16, 1963. CX 1. Thus, the constructive date of invention for the '027 patent is December 16, 1963. Whether Birchler and Williams are entitled to the benefit of an earlier date of invention requires an examination of the evidence regarding the reduction to practice of the process.

As part of the effort to produce a low cost transistor, Birchler advocated utilization of a transfer molding encapsulation process because he believed it might permit high volume production of finished products. Birchler, Tr. 280. He and Williams considered utilizing other methods for encapsulating transistors, such as epoxy casting, but eventually settled on

transfer molding for further experimentation. Williams, Tr. 1463, FF 89.

Based on a sketch supplied by Mr. Lockhart of the Dow Corning Corporation (RPX 109 (Lockhart Dep.) Tr. 14), personnel at TI constructed a small one-cavity mold for the purpose of testing the viability of transfer molding for delicate semiconductor devices. Birchler, Tr. 285. One half of the cavity was situated in the upper half of the mold, and the other half of the cavity was in the lower mold half. FF B 160. The "gate" through which molten plastic would flow was located at the end of the bottom half of the cavity. Id., Birchler, Tr. 360, RX 41.

Mr. Williams brought the mold and about one hundred transistors to the facilities of Dow Corning in Midland, Michigan where he attempted to transfer mold them on May 29, 1963. RPX 109 (Lockhart Dep.) Tr. 14, 16. The transistors Williams brought to Midland had three conductors in a planar arrangement. RX 41. The transistor chip was mounted upon one of the conductors and thin whisker wires ran from the transistor to each of the other two conductors. RX 41. The transistor and whisker wires were located on one side of the plane defined by the three conductors. RX 41. The devices were placed in the cavity with each end of the conductors resting in recesses in the lower half of the mold. FF B 160.

Williams' first attempts to mold the transistors were conducted with the transistor and whisker wires in the bottom of the mold cavity, i.e. on the same side of the conductor plane as the gate. Williams, Tr. 1462-1463, RX 41. Also, because the mold was end-gated, the encapsulating fluid struck the whisker wires at right angles. These initial attempts met with failure, producing no good units. Id., RPX 109 (Lockhart Dep.) Tr. 17. Fifteen or twenty devices were molded and none passed the electrical continuity test.

RPX 109 (Lockhart Dep.) Tr. 17. The devices were thereafter turned over so that the transistor and whisker wires were on the opposite side of the plane from the gate. RX 41. Better results, including good units, were obtained with this arrangement. RX 41, RPX 109 (Lockhart Dep.) Tr. 17. Mr. Williams in his invention disclosure form stated: "The better results are obtained when the unit was in the top half [and the gate was in the bottom half] of the mold so it [the device and whisker wire connections] did not see the plastic as it is initially introduced into the cavity." RX 41.²⁴

Birchler and Williams, decided to further investigate manufacture of semiconductor devices through use of transfer molding. Birchler, Tr. 367; Williams, Tr. 1462-72. Subsequent to the work at Dow, Birchler and Williams built a two-cavity mold. The gate in this mold was located on the side of the cavity and the fluid entered in a direction parallel to the whisker wires and at right angles to the heavier conductor wires. FF B 182a, 186. Further, the gate was offset from the portion of the cavity where the transistor chip was located. Birchler, Tr. 294. An entry in Williams' laboratory notebook dated June 31, 1963 (sic) states that the two cavity mold has been built and tested. RX 41. The "important features" of the two cavity mold are set forth as follows:

²⁴ Mr. Williams' co-inventor, Mr. Birchler, testified at the hearing that Mr. Williams' molding experiments at Dow were a "catastrophe" and the two of them were "absolutely distraught" with the results. Birchler, Tr., 287, 290. On the other hand, Mr. Lockhart, the Dow employee who worked with Mr. Williams during these encapsulation experiments, stated that every transistor molded in the opposite-side gated configuration passed the electrical continuity test, and described Mr. Williams as "elated" with the results. RPX 109 (Lockhart Dep.) at 31, 35. In light of the lack of testimony from Mr. Williams on this point, the indication in his notebook that "good units" were produced at Dow, the diametrically conflicting testimony of Mr. Lockhart, and the fact that opposite-side gating was included as an important feature in the later-written patent disclosure form (RX 51), the Administrative Law Judge finds Mr. Birchler's testimony on this point lacking in credibility.

- A. The molding compound is introduced from the side with individual unit gating. This allows the flow to be parallel to the plane of the emitter & base connections.
- B. The gate is off-center with the device.
- C. The gate is in the bottom half of the mold, and the device in the top.
- D. The construction of the device was double ended to prevent any movement of leads, thus breaking the connections.

Tests of devices from the two cavity mold "yield[ed] ... good devices from transfer molding ... high enough [in number] to preclude any further belief that the molding compound is breaking wires." RX 41, p. 8. The entry also included the statement that samples had been placed on "life test."²⁵
Id.

These entries indicate that delicate transistors have been molded with the two cavity mold, and might evidence a reduction to practice at whatever date this occurred. The deposition testimony of Lockhart indicates that semiconductors were successfully molded in a bottom-gated configuration, but the single cavity mold did not have features A (side-gating) or B (off-center gate). TI has not adduced independent evidence corroborating the assertion that Williams successfully transfer molded semiconductors with a mold containing features A, B and C, and wire arrangements described in feature D and shown in the entry's drawings (last page), as of the date of this entry. See, Hahn v. Wong, 13 U.S.P.Q.2d at 1317 (affidavits of co-inventor's colleagues that they had read and understood entries in a laboratory notebook

²⁵ The date of this latter entry is given as "6/31/63". The same date is indicated as the date it was witnessed and understood by a colleague of Mr. Williams. RX 41 (last page). It is difficult to ascertain the actual date of this entry. There was no clarifying testimony. Some of the possibilities are June 30, 1963, July 1, 1963 or July 31, 1963.

did not corroborate a reduction to practice).²⁶

On August 1, 1963, Mr. Birchler had TI's Special Projects Group prepare a series of viewgraphs showing each step in a production line to transfer mold transistors in accordance with the '027 patent. CX 270; CX 8, Birchler DRAMs Tr. 233-34. These viewgraphs were utilized at some subsequent time, probably in August or September 1963 in a presentation to TI management regarding the low cost transistor project. Id. The viewgraphs display two entire proposed manufacturing lines (the "Gang Concept" and the "Slide Pack Concept"), each of which incorporates encapsulation by transfer molding. CX 270. The first viewgraph is captioned "Carrier Fabrication & Loading" and illustrates that three conductors have been arranged in a common plane with the semiconductor device attached to the middle conductor. CX 270 at 2. The third viewgraph, captioned "Carrier Transfer", illustrates the placement of the planar conductors and die into a transfer molding die that is side-gated with the gate on the other side of the plane formed by the three conductors. CX 270 at 4. The following viewgraph, captioned "Molded 'Gang'", shows the molded product. CX 270 at 5. The viewgraphs captioned "Mechanization Proposal Low-Cost Transistor" illustrate the initial cost estimates of the costs for a production line incorporating each of the two concepts. CX 270 at 17, 18.

At a subsequent presentation to management, probably in September 1963, Birchler and Williams requested the allocation of funds for a commercial

²⁶ In the Initial Determination on remand in DRAMs, it was found that by September 12, 1963, Birchler and Williams had built transistors using their transfer molding process and these transistors had completed a 1,000 hour life test. CX 262 at 28 (Finding No. 82). Because this assertion was based upon the uncorroborated testimony of Mr. Birchler, and TI has not adduced any additional evidence in support of it, the Administrative Law Judge is not adopting this finding.

production line for low cost transistors, submitting a document dated September 12, 1963, entitled "Equipment Requirements". CX 270 at 22; CX 8, Birchler DRAMs Tr. 242-3. This document lists the prices of equipment needed for the proposed production line, including transfer dies and a molding press. CX 270 at 22. Birchler claims that by this time life test data on the transistors had been received. CX-8, Birchler DRAMs Tr. 243.

Mr. Birchler met with Mr. Lawrence Plummer of the Hull Corporation to secure transfer molding equipment for commercial production of the transistors. CX 15, Hull DRAMs Tr. at 1083-1084, 1097. Personnel at Hull worked a great deal with TI on building dies needed to transform the process as demonstrated in the two cavity mold to a commercial scale production process. CX 15, Hull DRAMs Tr. at 1083-1084. An advertisement of the Hull Corporation later touted Hull's contributions to TI's "pioneering" efforts in encapsulating low cost transistors in plastic. CX 201. A few months after the September presentation, TI began sending bulletins to its customers setting forth the technical specifications of its plastic encapsulated SILECT transistors. CX 268 (dated January, 1964). On February 10, 1964, TI issued a general news release announcing the first plastic encapsulated transistors for the consumer market. CX 265.

Mr. Lockhart's deposition testimony provides independent evidence that the feature of opposite side gating was conceived on May 29, 1963, and the viewgraphs described above illustrates all the features of the invention as described in the '027 patent. TI management's decision to go ahead with a commercial production line incorporating the '027 process evidences that management had been convinced that the process worked for the purpose intended. The management decision to take the '027 process out of the

laboratory and place it on a production line constitutes evidence corroborating Mr. Birchler's testimony that the process was reduced to practice in September 1963, but after September 12, 1963.

3. Prior Art

a. U.S. Letters Patent No. 3,367,025 (Doyle)

The Doyle patent is entitled "Method For Fabricating and Plastic Encapsulating a Semiconductor Device." It was issued on February 6, 1968 pursuant to an application which was filed on January 15, 1964. RX 11. During the prosecution of the '027 patent's application, Birchler and Williams were involved in an interference with the Doyle patent. The Board of Patent Interferences determined that Doyle's invention had been conceived and reduced to practice "well prior" to the December 16, 1963 filing of the parent application of the '027 patent. RX 60 at 6. The Board therefore awarded Doyle priority with respect to claims 1, 3, 4 and 6. FF B 281. These claims were cited as prior art during the prosecution of the '027 patent's application. See, Ex parte Birchler, United States Patent and Trademark Office Board of Appeals, Appeal No. 256-14 (RX 49).

In arriving at its decision regarding the reduction to practice of Doyle's invention, the Board relied upon twelve documentary exhibits, ten of which predate September 12, 1963. Accordingly, Doyle's date of invention predates that of the '027 patent, and claims 1, 3, 4 and 6 of Doyle constitute prior art under 35 U.S.C. § 102(g) for purposes of this obviousness analysis.²⁷

²⁷ 35 U.S.C. § 102(g) provides in pertinent part:

A person shall be entitled to a patent unless before the applicant's invention thereof the invention was made in this country by another who had not abandoned, suppressed, or concealed it. In determining priority of invention there shall be considered not only the respective dates of conception and

(continued...)

The Doyle claims disclose a semiconductor device with a plurality of conductor leads held in a "pin circle" (i.e. non-planar) arrangement by a jig. FF B 23, 45. The jig serves as the bottom of a cavity used to transfer mold the device. RX 11. Nail heads are formed on the top of the leads, and these nail heads are raised above the jig. FF B 44, RX 11, Col. 4, line 8 (leads are maintained in the jig, "protruding therefrom"). The semiconductor is placed on one of the nail heads which is slightly lower than the other two. RX 11. "Tiny wires" connect the semiconductor to the other two leads. RX 11, Col. 6 line 11.

During the Doyle process, liquid encapsulation material enters the cavity through a gate located at the parting line between the jig and the upper portion of the mold cavity. Doyle, Tr. 968, 973, RX 11. Because the gate is located on the floor of the mold cavity, and the nail heads (upon which were the semiconductor and whisker wires) are raised above the floor of the cavity, so they could be completely encapsulated, the gate is located beneath the semiconductor and wires. RX 11. Only one end of the leads extends outside the mold cavity. RX 11.

b. U.S. Letters Patent No. 3,235,937 (Lanzl)

The Lanzl patent is entitled "Low Cost Transistor." The application was

²⁷(...continued)

reduction to practice of the invention, but also the reasonable diligence of one who was first to conceive and last to reduce to practice, from a time prior to conception by the other.

Prior work which satisfies the requirements of this provision can be used as prior art in an obviousness analysis. E.I du Pont de Nemours & Co. v. Phillips Petroleum Co., 849 F.2d 1430, 7 U.S.P.Q.2d 1129 (Fed. Cir. 1988), on remand, 711 F. Supp. 1205, 11 U.S.P.Q. 2d 1081 (D. Del. 1989). See also, Ex parte Birchler at 3 ("The rejection before us is one under 35 USC 103. The evidence for obviousness is the prior invention of another in this country under section 102(g)") CX 2 at 32.

filed on May 10, 1963 and the patent was issued on February 22, 1966. RX 7. Because the application for the Lanzl patent was filed before the invention of the '027 process, it constitutes prior art under 35 U.S.C. § 102(e).

Figures 7 and 8 of Lanzl disclose a transistor with planar leads. RX 7. The silicon transistor is mounted upon one of the leads and one mil whisker wires connect it to the other two leads. RX 7, Col. 2 lines 31-42. The semiconductor device and wires are located on the same side of the plane formed by the three leads. RX 7, Figure 8. The Lanzl transistor utilizes a header which stays on the finished product. RX 7; Plummer, Tr. 1403. The Lanzl patent does not disclose transfer molding or any other specific method of encapsulation, stating only that the semiconductor device and wires are "housed by encapsulation in a suitable non-metallic electrically insulative protective material." RX 7, Col. 3 lines 39-41. At the hearing, respondents' expert, Lawrence Plummer, testified that Lanzl transistors were encapsulated by potting. Plummer, Tr. 1403-1404.

c. The Sylvania Transistor/Carruth And Sussman Article

From mid-1958 through mid-1963, Sylvania Electric Products, Inc. conducted a program to develop a process for encapsulating germanium transistors in plastic. Russell, Tr. 1117. Its TF-61 and TF-62 transistors, manufactured in or about March, 1963, were encapsulated by transfer molding and used a header. Russell, Tr. 1109, 1073-74; RX 127 at 58-69. The three conductor wires in the Sylvania transistor were in an in-line configuration, i.e. parallel to each other and in a common plane. FF B 121. The germanium device was mounted on a circular base tab which was then soldered to the center lead in the header. FF B 123. The base tab and transistor were mounted in a plane generally perpendicular to the plane formed by the

conductors. Russell, Tr. 1112, 1114. In contrast to the one mil gold whisker wires utilized in the transistors for which the '027 process was intended, Sylvania's TF-61 and TF-62 transistors utilized nickel bond wires which were on the order of 5-10 mils in diameter. Russell, Tr. 1110-11. The structure of the base tab and germanium die assembly used in the Sylvania transistor was fragile, but it was more rugged than the structure of planar silicon transistors with one mil gold wires typically used in the industry. Russell, Tr. 1115-16.

Sylvania's transfer molded germanium transistor was described in an article by Carruth and Sussman entitled "Epoxy Pellet Encapsulation For Transistors" (RX 24) which appeared in Electronic Packaging And Production in April, 1963 and constitutes prior art under 35 U.S.C. § 102(g). FF B 111. Figure 3 of the Carruth/Sussman article depicts a TF-61 transistor. FF B 112. In the article it is stated that transfer molded transistors were still in the development stage, but offered the advantages of reduced costs, better heat dissipation, and the ability to be packed closely together in low power applications. FF B 116. It is further stated that the moisture resistance of transfer-molded transistors is not as good as solder sealed transistors, but the former passed a standardized moisture test. RX 24 at 3.

TI asserts that the Sylvania transistor was known to the examiner at the time the '027 patent's application was prosecuted. The specification of the '027 patent provides:

"There have been reports that germanium alloy transistors have been encapsulated using transfer molding techniques, but again with the use of expensive headers. Encapsulation of an alloy device is not unusually difficult because mechanically it is inherently relatively strong. However, these plastic encapsulated alloy devices have not been generally accepted on the market because of unacceptably high leakage currents."

CX 1, Col. 1 lines 50-62

The specification does not set forth the details of the lead arrangement or other characteristics of the Sylvania transistor or its encapsulation process, nor does it identify the transistor or process by the manufacturer's name.²⁸ Accordingly, this portion of the '027 patent's specification does not support the conclusion that the examiner was aware of the details of the work performed by Sylvania.

d. The Zecher Article

In July, 1962, IRE Transactions On Product Engineering And Production published an article by Robert F. Zecher of the Hull Corporation entitled "High Production Encapsulation of Electronic Devices." RX 478. Zecher's article discusses the problems and benefits of encapsulating devices by transfer molding. The article states that various devices, including transistors, were being encapsulated by transfer molding. RX 478 at 7. The article also describes reasons manufacturers had not shifted to transfer molding:

"The single drawback to many other new programs is the inherently poor design of a component for encapsulation. Many manufacturers who have been skimming through product development without giving much thought to final packaging are now beginning to wish they had used stiffer leads which could support the device in a mold, that the lead configuration occupied only one plane, so the mold need only have one parting line, that they had not used fiber washers which outgas when heated, and so forth."

RX 478 at 7.

²⁸ In his laboratory notebook Williams states as follows: "The April issue of Electronics Packaging and Production carried an article stating that Sylvania was encapsulating a germanium alloy unit by the transfer molding method. This was accomplished with the use of a header. They did point out the conventional header could be replaced with a plastic type, however they did not consider elimination of same. It should be noted that transfer molding of an alloy device is no more different than molding a resistor, what is common practice." RX 41

e. The Helda-Lincoln Approach

During the early 1960's, Robert Helda and Milan Lincoln were involved in a project at Motorola to develop a low-cost transistor. FF B 66. The work of Helda and Lincoln led to U.S. Letters Patent 3,444,441. RX 330 at 11. The '441 patent issued May 13, 1969 and has an effective filing date of June 18, 1965.

The Helda-Lincoln approach calls for supporting the die at the end of a stamped lead frame. FF B 76. The leads are parallel to each other, and the die and whisker wires are located on one side of the leads. FF B 77. The gate through which the encapsulating fluid enters the molding cavity is located at the end of the cavity opposite to the leads. FF B 76. The fluid enters at right angles to the whisker wires and the gate is not offset from the device. FF B 76.

The '441 patent indicates that the gate is located on the opposite side of the leads from the die and whisker wires. RX 12, fig. 5B. In DRAMs, TI submitted into evidence a sketch prepared by its counsel which was utilized at the deposition of Mr. Lehner. RX 111. It clearly shows that the Helda-Lincoln approach utilized opposite side gating. RX 111.²⁹

²⁹ Mr. Lehner testified that the sketch was not accurate and did not adopt it as an accurate depiction of what it represented to be. DRAMs Order No. 163. It and another exhibit were initially excluded from the DRAMs evidentiary record, but included after TI made an unopposed motion for reconsideration of the rejection. DRAMs, Order No. 163. Order No. 163 states that the exhibits illustrate a point TI wanted to make, but does not state what the point was. Judge Saxon ordered that they not be used "for any purpose that would be inconsistent with the testimony of Mr. Lehner in his deposition." Id. The ALJ takes official notice of the TI Motion for Reconsideration of the Rejection of TI Exhibits 490 and 491, in the DRAMs case, Docket Number 242-237, and designates it as Exhibit ALJX-1 in this proceeding. TI in that motion represented that the only inaccuracy in the sketch is that the gate was offset in the original sketch. Motion at 3. Mr. Lehner corrected the sketch to show that the gate is in-line with the device. TI represented that with

(continued...)

Respondents contend that the Helda-Lincoln approach was invented before the '027 process, and therefore constitutes prior art as to the '027 patent pursuant to 35 U.S.C. § 102(g). An entry from Mr. Helda's laboratory notebook dated May 13, 1963 contains a drawing in which the semiconductor device is located upon a lead and connected by wire bonds to two other leads. RX 75. The entry also contains a notation that the last step in fabricating the finished product is "Plastic Encapsulation (Molded)". RX 75. The entry does not in any way show whether Mr. Helda had conceived of any details of the molding process as of that date.³⁰

On May 17, 1963, Helda and Lincoln submitted a proposal entitled "Proposal for Inexpensive Entertainment Device Package." FF B 67; RX 76. The proposal outlines the production steps for fabrication of the Helda-Lincoln transistor and sets forth that the product will be molded "in a process similar to that used on Motorola's Surmetic Diode." This reference to the process used for the Surmetic Diode meant transfer molding. FF B 76, RX 76. However, nothing in the proposal discloses gate location or indicates that Helda and Lincoln conceived any details of the molding process at that time. RX 76, Plummer, Tr. 1400.

By October 4, 1963, at least twenty-five of the Helda-Lincoln devices had been produced and tested by Motorola. FF B 71. Respondents contend that this establishes a reduction to practice of the Helda-Lincoln proposal as of that date. However, a reduction to practice requires clear and convincing evidence

²⁹(...continued)

this correction, the sketch illustrates the relationship between the device, whisker wire connections and the gate. ALJX-1 at 1. Accordingly, RX 111 is admitted into evidence.

³⁰ The quality of the photocopied entry is too poor to allow one to read most of the notations accompanying the drawing.

that the invention has demonstrated it will work for its intended purpose. Barmag Barmer Maschinenfabrik v. Murata Machinery, Ltd., 731 F.2d 831, 221 U.S.P.Q. 561 (Fed. Cir. 1984). Respondents have not adduced any evidence that these twenty-five devices passed such tests, or in any other way demonstrated that the Helda-Lincoln molding process worked. In light of the strict requirements set down by the Federal Circuit for proving a reduction to practice (Hahn v. Wong, 892 F.2d 1028, 13 U.S.P.Q.2d 1313 (Fed. Cir. 1989)), the fact that some transistors were fabricated does not, in itself, constitute a reduction to practice of the molding process.

On November 19, 1963, Mr. Donald E. Johnson, an industrial engineer at Motorola, prepared a memorandum regarding the Helda-Lincoln project. The memorandum states that as of that date, Helda had manufactured 1,000 plastic package transistors. RX 108. Another memorandum, written by Mr. R.L. Pritchard on November 14, 1963 and summarizing a meeting which took place on November 6, 1963, states that as of the time of the meeting, transistors had been transfer molded and "approximately 600-700 good devices were fabricated." RX 109 (emphasis added). Thus, it appears that at least sixty to seventy percent of the packages manufactured by Helda by this time were "good devices".³¹ These memoranda are evidence that the Helda-Lincoln approach was conceived and reduced to practice on November 6, 1963. Accordingly, it was invented after the date of invention of the process claimed in the '027

³¹ If a portion of the 1,000 devices referred to in the Johnson memorandum were manufactured during the period between November 2 and November 19, the percentage of "good devices" would be greater.

patent, and does not constitute prior art.³²

f. United States Letters Patent 2,757,439 (Burns)

The Burns patent is entitled "Transistor Assemblies". It was issued August 7, 1956 pursuant to an application filed February 25, 1955. RX 3. Burns was cited by the examiner during the prosecution of the '027 patent's parent application as prior art with respect to the claims directed towards

³² In the event this issue is reviewed, the Administrative Law Judge includes the following discussion and finding regarding whether Helda Lincoln was "abandoned, suppressed or concealed":

Motorola did not apply for a patent directed to the Helda-Lincoln approach until June 18, 1965. RX 16. The respondents contend that the Helda-Lincoln invention is § 102(g) prior art. The party asserting invalidity under § 102(g) bears the burden of proving that the prior invention was not abandoned, suppressed or concealed. Oak Industries, Inc. v. Zenith Electronics Corp., 14 U.S.P.Q. 2d at 1420-21 and cases cited therein, 3 Chisum Patents § 10.08[3][c]. A court may find that an invention was abandoned, suppressed or concealed if within a reasonable time after the invention was reduced to practice the inventor took no steps to make the invention publicly known. International Glass Co. v. United States, 408 F.2d 395, 161 U.S.P.Q. 116 (Ct. Cl. 1969) (per curiam) (adopting opinion of Davis, Comm'r, 159 U.S.P.Q. 434), Oak Industries, Inc. v. Zenith Electronics Corp., 726 F. Supp. 1525, 14 U.S.P.Q. 2d 1417 (N.D. Ill. 1989).

The case law on § 102(g) often refers to the plain language of the statute in addressing the issue of whether an earlier invention had been abandoned, suppressed or concealed. In Allen v. W.H. Brady, 508 F.2d 64, 184 U.S.P.Q. 385 (7th Cir. 1974), the court noted that the statute's use of the pluperfect tense - "had not abandoned, suppressed, or concealed it" - requires that a determination of abandonment be made with reference to the date of the patentee's invention. See also, Oak Industries, Inc. v. Zenith Electronics Corp., 14 U.S.P.Q. 2d at 1423, 1424 (abandonment must occur prior to the time of the second invention; determination of suppression or concealment made with reference to date of invention). Because the period between the invention of the Helda-Lincoln approach (November 6, 1963) and the constructive date of invention of the '027 process (December 16, 1963) is only six weeks, Helda-Lincoln was not abandoned, suppressed or concealed for purposes of § 102(g).

the Birchler and Williams encapsulation process. CX 4 at 43, 53-54.

The three leads of the transistor set forth as the preferred embodiment of the Burns patent are inserted into and through a stem base in order to give mechanical support and rigidity during the encapsulation process. RX 3, Fig. 1, Col. 2 lines 3-8. The patent's drawings illustrate that in the preferred embodiment, the holes through which the leads extend are all in the same plane. RX 3, Fig. 6. Thus, the Burns transistor utilizes planar leads.

4. Differences Between The Claimed Invention And The Prior Art

In conducting an obviousness analysis, the claimed invention must be considered as a whole. 35 U.S.C. § 103. When several prior art references are utilized in an attempt to show the patent would have been obvious in light of them, there must be some suggestion in the art to lead one of ordinary skill to combine the references. Lindenmann Maschinenfabrik GmbH v. American Hoist and Derrick Co. 730 F.2d 1452, 1462, 221 U.S.P.Q. 481, 488 (Fed. Cir. 1988). The problem confronted by the inventor must be considered in determining whether it would have been obvious to combine references in order to solve that problem. Diversitech Corp. v. Century Steps, Inc., 850 F.2d 675, 7 U.S.P.Q.2d 1315 (Fed. Cir. 1988). Picking and choosing among the references until all the features of the claimed invention are unearthed will not suffice to invalidate a patent in the absence of such a suggestion. Smithkline Diagnostics, Inc. v. Helena Laboratories Corp., 859 F.2d 878, 8 U.S.P.Q.2d 1397 (Fed. Cir. 1989).

The invention set forth in claims 12, 14 and 17 utilizes a particular arrangement of leads, semiconductor device and gate location to achieve the goal of successfully transfer molding a semiconductor without disturbing the whisker wire connections.

The Doyle patent teaches the utilization of a remote gate to transfer mold a device which has delicate whisker wires leading from the semiconductor to the leads. The semiconductor is mounted on the coined end of a conductor for support and the whisker wires extend to coined ends of the other conductors which are set in a plane slightly above the semiconductor. Doyle's gate is located beneath the device and whisker wires. Because of their pin-circle configuration, Doyle's leads are not in a common plane; however the gate is below the plane of the recessed or lower conductor.

The Lanzl and Burns references are directed toward semiconductor devices, not encapsulation. Like the devices encapsulated by the '027 process, the Lanzl and Burns devices have planar leads with the semiconductor mounted on one of the leads. However, neither patent describes or suggests encapsulating the product by transfer molding.

Zecher discusses in a general sense the utilization of transfer molding in the electronic devices field. Zecher states that device manufacturers were at that time beginning to wish they had used stiffer leads in their devices and had designed the devices with planar leads in order to have one parting line. RX 478 at 7. As evidenced from the prior art, planar lead transistors (Lanzl and Burns patents, Sylvania transistor) were already well-known in the art at that time. CX 10 (Schroen DRAMs testimony) at 84. Zecher's article suggests that one wanting to transfer mold an electronic device should modify the device so the leads are stronger and "in line", i.e. planar. Plummer, Tr. 1378-1380.

The evidence of record establishes that Sylvania successfully encapsulated germanium transistors with leads in a common plane by April, 1963. The Sylvania germanium alloy transistors were more rugged than the

silicon devices described in the specification of the '027 process. The Sylvania device is made of a germanium alloy with a header, utilizing 5-10 mil wire bonds. While the Sylvania device is fragile, it is more rugged than the headerless devices encapsulated by the '027 process which have 1 mil whisker wires. FF B 114.

Claims 12, 14 and 17 of the '027 patent are directed to encapsulation of semiconductors and are not limited to the encapsulation of delicate devices. One utilizing a process described in one of these claims to encapsulate a sturdier device would probably be considered an infringer. Thus, the relative sturdiness of the Sylvania transistor neither removes it from the prior art regarding encapsulation, nor diminishes what Sylvania teaches, namely the transfer molding of a transistor with planar leads.

5. Objective Indicia Of Obviousness

Objective indicia of obviousness such as satisfaction of a long felt need, commercial success, copying, and the failure of others must always to be considered in an obviousness analysis. Hybritech, Inc. v. Monoclonal Antibodies, Inc., 802 F.2d 1367, 231 U.S.P.Q. 81 (Fed. Cir. 1986), cert. denied, 107 S.Ct. 1606 (1987).

From the late 1950's through the early 1960's, several major transistor manufacturers were working on the development of an inexpensive transistor. FF A 15. Texas Instruments, Motorola, Sylvania and others were actively engaged in improving and reducing the cost of packaging transistors, including transfer molding semiconductor devices having fragile whisker wires bonded to the semiconductor and conductor wires. FF A 15, B 1. It was widely recognized that the header was a major contributor to the cost of a transistor. See "Epoxy Pellets Encapsulation for Transistors"

(Carruth/Sussman) at 19-20 (RX 24). Indeed, both Motorola and TI were working on a headerless transistor and accompanying encapsulation process during mid-1963. FF A 19-20, B 66-67. Completely doing away with the header increased the transistor's fragility, making it more susceptible to damage during manufacturing. See Bell Tr. 1002 (leads in Doyle patent use mechanical strength of jig for support during molding). During the early 1960's, an increasing number of electronic devices had been encapsulated by transfer molding, and in 1963 Sylvania transfer molded its germanium alloy transistor. However, transfer molding was generally recognized as a harsh process, and had not been used on something as delicate as a headerless planar transistor. See CX 15, Hull DRAMs testimony at 1019-1021.

At the time the '027 process was invented, there was a tremendous economic incentive to develop a low cost transistor. CX 5, ¶ yyyy. The '027 process met a long felt need in the market for a very low cost transistor because it enabled TI to encapsulate delicate transistors at a low cost. A report issued by Plastics Technology in May 1964 entitled "News in Thermosetting Processing" stated that TI was the first to commercially produce plastic encapsulated transistors and that other major transistor manufacturers were expected to soon follow suit. CX 302. This article is not evidence of direct copying, a factor which can contribute to a finding of nonobviousness, but does evidence that the industry recognized the advantages of a process like that claimed in the '027 patent.

Further, it is apparent that TI enjoyed considerable commercial success in the sale of its plastic-encapsulated transistors in the years following the invention of the '027 patent. CX 297. TI's annual reports for the years 1964-1968 consistently refer to increased sales of semiconductor devices,

particularly those encapsulated in plastic, despite the very competitive nature of the market. CX 297. Indeed, unit and volume sales of TI's semiconductors established record highs in 1965 and 1966 as its high-volume, low-cost plastic packaged transistors were utilized in an increasing number of industrial and consumer products. CX 297. 1967 saw a slight downturn in the semiconductor market in the U.S., but TI improved its market position "[l]argely because of widespread acceptance of its ... digital integrated circuits and additional complex-function circuits in low-cost plastic packages". CX 297. TI's 1968 report stated that plastic encapsulated devices had become "increasingly important" to the company and that TI's plastic packaging had enabled it to produce an inexpensive high-performance silicon transistor. The 1968 report further states that production of SILECT transistors for consumer product applications had increased during the year. CX 297.

The annual reports reflect the expansion in the use of transistors as low-cost plastic encapsulated products entered the market. As noted in the Carruth/Sussman article, plastic encapsulated semiconductors, in addition to being less expensive, had certain unique qualities which allowed their use in a wider array of applications. FF B 116. TI's plastic encapsulation process made it possible to use transistors in an increasing number of applications, particularly in the area of consumer goods such as televisions and radios. The commercial success of TI's low-cost plastic-encapsulated transistors can be attributed to its headerless construction, a feature which would not have been possible without the '027 process, as well as the unique qualities of the product resulting from the use of plastic. Thus, there is the requisite nexus between the '027 patent and the commercial success of TI's plastic-

encapsulated semiconductors.³³ The expanding sales of plastic-encapsulated products, their expanding market, and their unique qualities of relative ruggedness and low cost are strong evidence of nonobviousness.

6. Level Of Ordinary Skill In The Art

The '027 patent is concerned with the arts of transfer molding and semiconductor design. FF B 326. The level of skill in these arts is determined less by educational requirements than by hands-on experience. FF B 326. The parties have not disputed the level of ordinary skill in the art in 1963. At the time the '027 process was invented, the level of ordinary skill was that of a skilled technician. Plummer, Tr. 1375-1376.

7. Conclusion As To Obviousness

The '027 patent resulted from work performed by Birchler and Williams which was designed to produce a low cost transistor by eliminating the header and utilizing transfer molding. While other more rugged electronic products already had been transfer molded, the increased fragility of a headerless transistor made it particularly susceptible to damage by the insulating fluid during molding. Like others in the electronics industry, TI was seeking to eliminate the header in order to lower the production cost of a transistor, and at the same time was working on a complementary encapsulation process.

The Board of Appeals found claims 12, 14 and 17 patentable over Doyle because of the planar leads. Transistors with leads in a common plane were

³³ TI has introduced evidence demonstrating that it has licensed the '027 patent to over [C] CX 421, Donaldson, Tr. 852. Richard Donaldson, a vice-president of TI and its manager of patent licensing, testified that the typical licensing agreement between TI and another did not specify particular patents, but is a [C] license. Donaldson, Tr. 852-853, RX 306. Accordingly, no nexus can be established between TI's success at negotiating these licenses and the '027 patent.

well known in the art in the early 1960's, as evidenced by the Burns patent which issued in 1956. RX 3. Further, the examiner was aware of references describing such transistors having cited Burns during the prosecution of the process claims in the parent application. CX 4 at 53, 73. See also, CX 4 at 138 (TI brought the Lanzl patent to the attention of the examiner).³⁴ However, additional prior art not before the Board of Appeals, particularly the Sylvania transistor and the Zecher article, suggest that one could transfer mold a transistor, as did Doyle, when the transistor had the specific arrangement of leads described in the claims at issue. In reviewing the prior art in light of the suggestion contained in Zecher, that semiconductors should be redesigned to have one parting line (i.e., planar leads) and stronger leads in order to utilize transfer molding,³⁵ the Administrative Law Judge does not discern any appreciable difference between the claims at issue and the prior art considered as a whole.³⁶

The obviousness analysis does not stop with the description of the differences between the claimed invention and the prior art, however.

³⁴ Respondents assert that the Board of Appeals was unaware of the Lanzl and Burns references when it ruled on TI's appeal from the examiner's § 103 rejection because these references were cited in the grandparent application and not mentioned in the '768 application. However, the Board stated in its opinion that application claim 25 was limited to the filing date of the '768 application because "such an embodiment is not found in the parent applications." Ex parte Birchler at 6. The Board could not have made such a finding without reference to the parent applications. Thus it is apparent that, contrary to respondents' assertions, the Board had the parent applications, with their citations to Burns and Lanzl, before it when ruling upon the appeal.

³⁵ See CX 15, Hull DRAMs Tr. 1083-1088.

³⁶ Indeed, Mr. Plummer testified that even in the early days of transfer molding semiconductors, if manufacturers of such devices worked with him in designing the products to be suitable for molding conditions, he could transfer mold even delicate semiconductor devices. Plummer, Tr. 1432-1435.

Concentration upon whether each of the differences between the claimed invention and the prior art would have been obvious is an improper approach in light of the statutory mandate that the invention be considered "as a whole", and the requirement in Graham v. Deere and its progeny requiring an analysis of objective indicia of obviousness. 35 U.S.C. § 103, Graham v. John Deere Co., 383 U.S. 1, 148 U.S.P.Q. 459 (1966).

The objective evidence regarding the '027 patent is very persuasive evidence of its nonobviousness. The evidence regarding the transistor industry in the early 1960's indicates that the market was price sensitive. See RX 109 at 2 (Motorola memorandum describing low price as the "prime factor" in the transistor market). Several major transistor manufacturers had been devoting efforts to lowering the cost of manufacturing transistors. CX 5 at 2, CX 215 at 1. Their efforts illustrate that there were strong economic incentives to develop both such a transistor and an encapsulating process which could package it. However TI's sales of the '027 transistor continued to grow even when the transistor market was in a downturn and in the apparent absence of evidence that TI's sold at a price below its competitors.

TI has enjoyed considerable commercial success as a direct result of the process which is the subject of the '027 patent, thus establishing the requisite nexus between the commercial success of TI's plastic encapsulated products and the patented process. In Akzo N.V. v. U.S. International Trade Commission, 808 F.2d 1471, 1481, 1 U.S.P.Q.2d 1241, 1246 (Fed. Cir. 1987), the Federal Circuit noted the commercial success of the patent at issue had been "enormous" and its range of uses "substantial". The court further stated that commercial success in that instance was a "strong factor favoring non-obviousness." Id.

In Alco Standard Corp. v. TVA, 808 F.2d 1490, 1 U.S.P.Q.2d 1337 (Fed. Cir. 1986), the court addressed a situation analogous to that present in this investigation. The district court had concluded that the prior art did not teach the combination of various references. The Federal Circuit found the court's conclusion clearly erroneous, first stating that the proper inquiry is whether the prior art suggests, not teaches, the desirability of combining references. After comparing the prior art to the invention, the Federal Circuit ruled that the district court was also clearly erroneous with regard to the differences between the prior art and the claim at issue and to what the prior art suggested to one of ordinary skill. The court stated "Thus, standing alone, the prior art provides significant support for the appellants' contention that the '006 patent would have been obvious." 808 F.2d at 1499-1500, 1 U.S.P.Q.2d at 1344.

The Federal Circuit refrained from reaching a conclusion on obviousness at this point, however, and reiterated its holdings regarding the importance of objective indicia in an obviousness analysis.

Prior art, however, cannot be evaluated in isolation, but must be considered in the light of the secondary considerations bearing on obviousness. As we have pointed out:

[E]vidence of secondary considerations may often be the most probative and cogent evidence of record. It may often establish that an invention appearing to have been obvious in light of the prior art was not. It is to be considered as part of all the evidence, not just when the decisionmaker remains in doubt after reviewing the art.

808 F.2d at 1500, 1 U.S.P.Q.2d at 1344, quoting Stratoflex, Inc. v. Aeroquip Corp., 713 F.2d 1530, 1538-39, 218 U.S.P.Q. 871, 879 (Fed. Cir. 1983).

The court reviewed the extensive objective evidence of nonobviousness discussed by the district court and concluded that in light of the district court's findings and the evidence in the record, "including the strong

secondary considerations indicating nonobviousness, which weigh heavily in the determination of obviousness", the patent would not have been obvious in light of the prior art. 1 U.S.P.Q.2d at 1345.

Here also, a comparison of the claimed invention to the prior art, standing alone, would appear to support respondents' contention that the process claimed by the '027 patent would have been obvious to one of ordinary skill in the art at the time it was invented. However, the objective evidence, particularly of commercial success, is strong support of a conclusion that the invention was nonobvious. To quote the Federal Circuit in Alco Standard, "[t]his is one of those cases where evidence of secondary considerations 'may ... establish that an invention appearing to have been obvious in light of the prior art was not.' Stratoflex, 713 F.2d at 1538 [213 U.S.P.Q. at 879]". 1 U.S.P.Q.2d at 1345.

Having considered all of the factors required by the test laid down in Graham v. John Deere, and particularly in light of the strong evidence of commercial success enjoyed by TI as the result of the '027 patent, the Administrative Law Judge has concluded that claims 12, 14 and 17 of the '027 patent would not have been obvious to one of ordinary skill in the art in 1963.

B. The '027 Patent Is Not Anticipated By Helda-Lincoln

Respondents assert that the '027 patent is anticipated pursuant to 35 U.S.C § 102(g) by the work performed by Messrs. Helda and Lincoln. Because the Helda-Lincoln invention was not reduced to practice until November 6, 1963, it is not prior art and cannot anticipate the '027 patent. Accordingly, the '027 patent is not invalid for anticipation.

C. The '027 Patent Discloses The Best Mode Known To The Inventors At The Time

Under 35 U.S.C. § 112, an applicant for a patent must disclose the best mode for practicing the patented invention known to him at the time the application was filed. 35 U.S.C. § 112. A patent will be found invalid for failure to disclose the best mode if the inventor is aware of, but conceals, a better mode of practicing the invention than that disclosed in the patent. Chemcast Corp. v. Arco Industries Corp., 913 F.2d 923, 16 U.S.P.Q.2d 1033 (Fed. Cir. 1990). The party asserting invalidity for failure to disclose the best mode must prove by clear and convincing evidence that the applicants were aware of a better mode and concealed it, either intentionally or by accident. Dana Corp. v. IPC Limited Partnership, 860 F.2d 415, 8 U.S.P.Q.2d 1692 (Fed. Cir. 1988).

The Federal Circuit in Chemcast described the proper best mode analysis as consisting of two components. First, it must be determined whether, at the time the inventor filed his patent application, he knew of a mode of practicing the invention that he considered better than any other. If so, the patent must then be examined to determine whether its disclosure is adequate to enable one skilled in the art to practice the preferred mode. If the disclosure is insufficient, the inventor is considered to have concealed his preferred mode. 16 U.S.P.Q.2d at 1036-1037.

Respondents assert that the '027 patent is invalid for the inventors' failure to disclose the molding parameters such as temperature, ram pressure and transfer speed of the plastic encapsulating fluid, as well as the type of plastic material best suited for use in the process.

During their experiments in 1963, Messrs. Birchler and Williams utilized the molding parameters provided by the vendors of molding compound. FF A 85.

These parameters were specific to the equipment and products used and were supplied by the vendor. FF A 104. It was Williams' belief during the time he was working on the development of the '027 process that parameters as provided by the vendors were typically sufficient to utilize the products. Williams, Tr. 1502-1503. He did not set forth these parameters in his laboratory notebook because they were not "a particular issue." Williams, Tr. 1503.

The evidence does not support a conclusion that Birchler and Williams were aware of any single set of parameters which was a better mode for practicing their invention than any other. Williams apparently believed that the process could be utilized with the molding parameters supplied by vendors. Accordingly, the '027 patent is not invalid for failing to disclose the best mode.

D. The '027 Patent Is Not Invalid For Obviousness-Type Double Patenting

The California respondents contend that claims 1, 12, 14 and 17 of the '027 patent are invalid by reason of obviousness type double patenting in light of claims 16 and 17 of U.S. Letters Patent 3,716,764 ('764 patent) because consonance with the examiner's restriction requirements was not maintained throughout the prosecution of the '764 and '027 patents. If their contention is correct, 35 U.S.C. § 121 would not protect the '027 patent from double patenting claims.

The inventors, Birchler and Williams filed patent application serial no. 331,006 ('006 application) on December 16, 1963. FF D 1. On September 18, 1968 the patent examiner determined that the claims of the '006 application, as amended, described three distinct inventions and required restriction to one of the following three groups of claims:

- I. Claims 14 to 20, 23 and 45 to 52 drawn to a semiconductor device with an integrally molded mass of insulating material.
- II. Claims 1 to 13, 21, 22 and 35 to 43 drawn to an injection molding process for semiconductor devices.
- III. Claims 24 to 34, 44 and 53 to 55 drawn to a lead frame for semiconductor devices and a method for securing semiconductor crystals to that frame, i.e., an intermediate product for use in producing the final semiconductor device.

FF D 2. The examiner distinguished the three groups as follows:

The claims of group II are distinct from those of groups I and III because the products and processes claimed in those groups do not require an injection molding process but can be made by other processes. Additionally, such a process as claimed in group II has acquired separate status in the art and requires a different field of search. The claims of group I are distinct from those of group III because the latter claims in no way involve molded encapsulation and relate to an intermediate product only.

FF D 3. (Emphasis added).

Complainant elected to continue prosecution of the group I claims which resulted in patent number 3,439,238 patent. Complainant filed divisional application serial number 768,325 ('325 application) on October 17, 1968 for the group III claims, which resulted in the issuance of the '764 patent on February 13, 1973. Complainant also filed divisional application number 768,311 ('311 application) on October 17, 1968 directed to the group II claims. The '311 application was abandoned, however, on July 30, 1973 complainant filed application number 384,768 ('768 application), as a continuation of the '311 application on the group II claims, which application resulted in the issuance of the '027 patent on August 23, 1977. FF D 4, FF D 5, and FF D 6.

At the time of the restriction the '006 application included a claim 26³⁷ which read as follows:

26. A method as defined in claim 24, comprising the further steps of embedding the semiconductor body and the strip regions to which the body and the semiconductor electrodes are conductively connected in a mass of insulating material prior to separating the strips from one another.

FF D 7. (Emphasis added). After the restriction and during the prosecution of the '325 application the applicants added claims 16 and 17. FF D 8. These claims read, in pertinent part, as follows:

16. A method for providing electrical connections to and encapsulating a semiconductor device comprising the steps of:

* * * *

(d) enclosing the central region of the assembly in plastic insulating material to surround the wafer and lead wires and parts of the conductor strips;

* * * *

17. A method according to claim 16 wherein enclosing in encapsulating means includes the step of transfer molding the plastic insulating material.

(Emphasis added). FF D 9, FF D 10.

The law recognizes two kinds of double patenting. The first, "same invention" double patenting, is not at issue in the instant investigation. The second kind, "obviousness type," has been raised by the California respondents as an invalidating argument against claims 1, 12, 14 and 17 of the '027 patent. Obviousness type double patenting is "a judicially created doctrine grounded in public policy (a policy reflected in the patent statute) rather than based purely on the precise terms of the statute," the purpose of

³⁷ Claim 26 subsequently became claim 3 in the '325 application and appears as claim 3 in the '764 patent.

which is to "prevent the extension of a term of a patent...by prohibiting the issuance of the claims in a second patent not patentably distinct from the claims of the first patent." In re Paolo Longi, 759 F.2d 887, 892, 225 USPQ 645, 648 (Fed. Cir. 1985). Where there has been a restriction pursuant to 35 U.S.C. § 121, however, the third sentence of section 121 provides protection from double patenting allegations by prohibiting use of a patent of "either the parent or any divisional application thereof" which adheres to the requirements of the restriction as a reference against the other.³⁸ Manual of Patent Examining Procedure § 804.01. The protection of section 121 does not apply when "[t]he claims of the different applications or patents are not consonant with the requirement made by the examiner, due to the fact that the claims have been changed in material respects from the claims at the time the requirement was made." Id. See also, Chisum, Chisum on Patents, § 12.05. The Federal Circuit has held that once it is determined that particular claims are not consonant with the restriction requirements, and that the protections of Section 121 do not apply, one must then determine whether the invention claimed in the second patent would have been obvious in light of the invention claimed in the first patent. Symbol Technologies, Inc. v. Opticon, Inc., 935 F.2d 1569, 1579 (Fed. Cir. 1991) ("Symbol Technologies").

³⁸ The third sentence of section 121 reads as follows:

A patent issuing on an application with respect to which a requirement for restriction under this section has been made, or on an application filed as a result of such a requirement, shall not be used as a reference either in the Patent and Trademark Office or in the courts against a divisional application or against the original application or any patent issued on either of them, if the divisional application is filed before the issuance of the patent on the other application.

35 U.S.C. § 121.

The consonance requirement was extensively discussed in a recent Federal Circuit case involving obviousness type double patenting, Gerber Garment Technology, Inc. v. Lectra Systems, Inc., 916 F.2d 683, 16 USPQ2d 1436 (Fed. Cir. 1990) ("Gerber"). The patents in Gerber related to "automated fabric cutting and disclose the use of a vacuum to hold a stack of multiple layers of fabric...while a vertically reciprocating cutting blade cuts the fabric." Id., 916 F.2d at 684, 16 USPQ2d at 1437. Gerber filed a patent application in May of 1969 on which a restriction requirement was imposed by the examiner between claims 1-11 and 16-28 "drawn to a cutting apparatus" and claims 12-15 "drawn to a work holding means." Id. Gerber elected to pursue claims 1-11 and 16-28, and patent 3,495,492 ('492 patent) issued on February 17, 1970. Also in February of 1970 Gerber began prosecution of an application directed to the remaining group of claims, which resulted in the February 5, 1974 issuance of patent number 3,790,154 ('154 patent). Id. During its prosecution of the application leading to the '154 patent "Gerber incorporated as a limitation the cutting blade of elected claim 23 of the '492 patent" into claims 15 and 16 of the '154 patent "and thereby rendered claims 15 and 16 non-consonant with those not elected in its response to the restriction requirement." Id., 916 F.2d at 689, 16 USPQ2d at 1441. In describing the demands of consonance, the Court held that "consonance requires that the line of demarcation between the 'independent and distinct inventions' that prompted the restriction requirement be maintained," that claims may be amended, but "must not be so amended as to bring them back over the line imposed in the restriction requirement" and that when "that line is crossed the prohibition of the third sentence of Section 121 does not apply." Id., 916 F.2d at 688, 16 USPQ2d at 1440, citing In re Ziegler, 443 F.2d 1211, 1215, 170 USPQ 129,

131-32 (CCPA 1971). Accordingly, the Court held that in making "the cutting blade a limitation of claims 15 and 16 Gerber crossed back over the line of demarcation between the 'cutting apparatus' claims and 'work holding means' claims drawn by the examiner in the restriction requirement," and that "[i]nvalidation of the '154 patent for obviousness-type double patenting was therefore appropriate." *Id.*, 916 F.2d at 689, 16 USPQ2d at 1441.

In the instant investigation, it is contended that claims 1, 12, 14 and 17 of the '027 patent should be held invalid on the grounds of obviousness type double patenting. This argument is made in two parts. First, respondents argue that the "[n]ewly added claim 17 of the '764 patent was directed to a transfer molding process, and thus overlaps with the subject matter of the '027 patent" and that "there is no longer consonance and the protection of § 121 no longer applies." Posthearing brief of the California respondents at 46-47. Second, respondents argue that claim 16 and 17, which claims "the step of encapsulating by transfer molding," together "read directly on what is shown in Figs. 9 and 10 of both the '027 and '764 patents" and that, when considered in the light of Doyle or Sylvania, claims 16 and 17 of the '764 patent render obvious claims 1, 12, 14 and 17 of the '027 patent. Posthearing brief of the California respondents at 47-48.

At the time of the restriction, claim 26 of the '006 application claimed the step of "embedding the semiconductor in a mass of insulating material." FF D 11. Claim 26 of the '006 application was added as part of an amendment dated "received May 25, 1967." The amendment, which added claims 24 through 34 to the '006 application, specifies that those claims were "submitted under Rule 116 for the purpose of preparing the application for interference," and states that the claims were "copied from Patent No. 3,281,628 issued to Bauer

et al on October 25, 1966." FF D 12.³⁹ In the remarks section of the amendment, where "the copied claims are specifically applied to the disclosure of the present invention," claim 3 of the Bauer patent (claim 26 of the '006 application) is described as follows:

Fig. 9 shows further that semiconductor body 142 and conductively connected strips 136, 138 and 140 are placed in a mould cavity, indicated by dotted outline 148, and embedded in encapsulating material to form the insulating mass 158 shown in Fig. 10. Page 16, lines 23-26 state that transfer moulding is completed prior to separating the strips from one another along the dotted lines 154 and 156 of Fig. 9.

(emphasis added). FF D 13.

The above-quoted portion of the amendment adding claim 26 to the '006 application, demonstrate that the application associated the terms "embedding" and "transfer moulding" before the restriction requirement was imposed by the examiner.⁴⁰ Respondents' argument that transfer molding was introduced to the group III claims only upon addition of claim 17 to the '325 application, after the restriction requirement, is incorrect. The concept of transfer molding was made part of the group III invention when the examiner placed claim 26 in the third group of claims as part of the restriction requirement.

³⁹ Claim 3 of the Bauer patent was copied and submitted as claim 26 in the amendment to the '006 application. RPX 87 at 63.

⁴⁰ Although the term "transfer molding" does not appear in claim 26 itself, but appears in the remarks, the remarks should be considered in determining the scope of the restriction requirements because they are "necessary to give meaning to the claim and properly define the invention." Perkin Elmer Corp. v. Computervision Corp., 732 F.2d 888, 896, 221 USPQ 669,675 (Fed. Cir. 1984), cert. denied, 469 U.S. 857 (1984) (relying on claim limitations appearing in the preamble to define invention). See also, Gerber, 916 F.2d at 689, 16 USPQ2d at 1441 (relying on claim limitations appearing in remarks of an amendment to define invention).

Accordingly, the post-restriction addition of claim 17, drawn to a transfer molding process, should be held to be consonant with the examiner's restriction requirement, and no double patenting should be found.

Respondents argue that the examiner's restriction requirement itself states that the difference between group II and groups I and III is that the latter "do not require an injection molding process, but can be made by other processes," and that the claims of group III, in particular, "in no way involve molded encapsulation." Respondents argue that the addition of claim 17 is therefore contrary to the language of the restriction requirement. Posthearing brief of the California respondents at 45-46.

As discussed above, the remarks to the May 25, 1967 amendment adding claim 26 indicate that claim 26 contemplates use of transfer or injection molding to accomplish encapsulation of the semiconductor body. Accordingly, the actual grouping of claim 26 in group III apparently conflicts with the examiner's description of the three groups. There are no cases deciding whether it is the actual grouping of claims or the examiner's written description of the restriction that define the requirements of the restriction. Section 121 allows for restriction to "independent and distinct inventions," and it is clear that it is the claims which define the invention. See, 35 U.S.C. § 120 and Manual of Patent Examining Procedure §§ 806.01 (claimed subject matter must be compared in questions of double patenting and restriction) (emphasis in original) and 806.03 (claims define essential features of an invention). Moreover, the courts have looked only to the claims of the various groups in the restriction to construe the consonance of subsequently added claims. See Symbol Technologies, 935 F.2d at 1579; Gerber, 916 F.2d 688-89, 16 USPQ2d at 1440-41; and Lerner v. Ladd, 216 F. Supp. 81,

82-84, 136 USPQ 624, 625-26 (D. D.C. 1962). Accordingly, to the extent that there is any conflict between the examiner's description of the restriction requirement and the actual grouping of claims therein, the grouping of claims, because the claims define the inventions, should be given decisive weight.

In addition, even if added claims 16 and 17 of the '764 patent were not consonant with the examiner's restriction requirement, claims 1, 12, 14 and 17 of the '024 patent would not be invalid by reason of obviousness type double patenting because the claims of the '027 patent at issue are "patentably distinct" from the at issue claims of the '764 patent. Symbol Technologies, 935 F.2d at 1569. Claim 1 of the '027 patent discloses a process by which the "opposite ends of the conductors" are held and extend from the mold cavity while the insulating material is injected into the mold. This feature of claim 1 is nowhere disclosed in either claim 16 or 17 of the '076 patent, nor is it obvious in light of claims 16 or 17. Similarly, claims 12, 14 and 17 of the '027 patent disclose the injection of the insulating material from a gate on the opposite side of the conductors. This opposite side injection is not disclosed in either claim 16 or 17 of the '764 patent, nor is it obvious in light of claims 16 or 17 of the '764 patent.

Thus, claims 1, 12, 14 and 17 of the '027 patent are not invalid by reason of obviousness type double patenting. The post-restriction addition of claims 16 and 17 to the '325 application leading to the '764 patent, even though drawn to a transfer molding process, was consonant with the examiner's restriction requirement. Accordingly, the protections of Section 121 apply and the claims of the later issued '027 patent are protected from a double patenting allegation. Moreover, even if there was no consonance, claims 1, 12, 14 and 17 of the '027 patent are not rendered obvious in light of claims

16 and 17 of the '764 patent.

IV. THE '027 PATENT IS NOT UNENFORCEABLE

Respondents asserted that the '027 patent is unenforceable for inequitable conduct before the PTO. To establish inequitable conduct, respondents must establish by clear and convincing evidence that the applicants made false material statement or withheld information with intent to mislead the PTO. Kingsdown Medical Consultants, Inc. v. Hollister, Inc., 863 F.2d 867 (Fed. Cir. 1988), cert. denied, 490 U.S. 1067 (1989); FMC Corp. v. Manitowac Co., 835 F.2d 1141 (Fed. Cir. 1987).

Respondents adduced no evidence that the applicants acted in a manner that would constitute inequitable conduct. Indeed, respondents post hearing briefs do not address the issue. Accordingly, they have failed to prove that the '027 patent is unenforceable.

V. ALL RESPONDENTS IMPORT ACCUSED PRODUCTS

The California Respondents have stipulated that they import into the United States plastic encapsulated integrated circuits which TI alleges infringe one or more of the claims at issue. CX 400.

Analog has continually imported plastic encapsulated integrated circuits from its Philippines facility since 1982, and from its Ireland facility since 1976. Hinchey, Tr. 1282, 1280.

VI. A DOMESTIC INDUSTRY EXISTS WITH RESPECT TO THE '027 PATENT

A. Texas Instruments' Domestic Activities Are Sufficient To Demonstrate The Existence Of A Domestic Industry

A complainant in a patent-based investigation is afforded relief under Section 337 only when there exists a domestic industry devoted to the

exploitation of the patent at issue. 19 U.S.C. § 1337(a)(2). Under Section 337, a domestic industry exists if one of the three prongs set forth in the statute is satisfied. Section 337(a)(3) provides:

(3) [A]n industry in the United States shall be considered to exist if there is in the United States, with respect to the articles protected by the patent...

(A) significant investment in plant and equipment;

(B) significant employment of labor or capital; or

(C) substantial investment in its exploitation, including engineering, research and development, or licensing.

19 U.S.C. § 1337(a)(3).

Because the statute uses the disjunctive term "or", a complainant can demonstrate the existence of a domestic industry by satisfying any one of the three tests set forth therein. TI asserts that it satisfies the criteria under each of these three tests.

1. Plant And Equipment/Labor Or Capital

TI's only domestic production facility for plastic encapsulated integrated circuits is the Flexible Assembly Module ("FAM") facility in Sherman, Texas. FF E 13 The FAM was established in 1983 with an initial start up cost of [C] FF E 15 When the FAM began operations, the thrust of its charter was to compete with offshore encapsulation centers, which had lower labor costs, by becoming a high-volume, automated encapsulation center. FF E 27-28 It was unable to realize this goal and in 1988, TI amended its charter to concentrate on making small lots of high pin count devices and servicing customers who demanded quick supply of their product requests. FF E 35, 237-42. Consequently, the annual number of units built at the FAM for the years 1989 and 1990 is less than earlier years. FF E 75-81. The FAM currently encapsulates 20, 24 and 28 pin DIP, 20, 24 and

28 pin SOIC and 28, 48 and 56 pin SSOP packages types. FF E 54. The 28 pin DIP, 28 pin SOIC and 28 pin SSOP are currently made only at the FAM. FF E 58. The FAM also has responsibility for large pin type plastic packages. FF E 55, 57. Since January, 1991, average monthly production at the FAM is a little less than [C] FF E 74.

The FAM occupies a total of [C] square feet, approximately [C] of which is devoted to the production area. FF E 51. The FAM also utilizes an additional [C] square feet of warehouse space at another location in Sherman. FF E 52.

TI initially owned the Sherman facility's buildings and land, but on December 29, 1986, TI sold the Sherman facility to Atlantic Properties, Inc. for [C] and leased it back. SX-22 (TI's Amended Resp. Int. Nos. 87 and 88(b)); CX 409. The cost to TI of the Sherman facility's lease per year is about [C] is attributable to the FAM. SX-10 (TI Resp. to Staff's Second Set of Interrogatories, Int. No. 36). The total capital approved for the FAM from 1983 through 1990 was [C] FF E 84.

Currently, there are five molding presses and seven molds in operation at the FAM. FF E 69. All of these molds and presses are bottom gated. FF E 70. The equipment currently located at the FAM was purchased by TI at a cost of at least [C] SX 23, Exhibit A; RX 414; SX 10, Attachment 5; SX 103 at 24.

When TI filed the complaint in this investigation in July, 1990, the FAM employed [C] who were directly involved in the plastic encapsulation of integrated circuits. FF E 59. Because of a slow financial period for TI during late 1990 and early 1991, employee reductions took place at the FAM as

well as at offshore TI facilities. FF E 60-61. Currently, the FAM employs about [C] people for the plastic encapsulation of integrated circuits, although this number may increase if the demand for the 100/120 pin devices increases. FF E 62-63.

2. Engineering And Research And Development

From 1976 to 1990, TI expended approximately [C] on research and development projects which are related to the '027 patent. FF E 203, 205, CX-424. The projects which account for the [C] were all performed within the United States, and many of them involved the FAM. FF E 208, 209.

The numerous research and development projects undertaken by TI during this time period in support of its exploitation of the '027 patent are set forth in CX 424. Many of the projects are directly related to the '027 patent in that they concerned an aspect of the molding process itself, such as 1) designing molds for new products (e.g. "44 Pin Plastic Leaded Chip Carrier, CX 424 at 2); 2) laboratory work for developing plastic molding equipment, evaluating products and selecting molding materials (e.g. "Assembly Lab", CX 424 at 12, 15); and 3) evaluating molding materials and the quality of plastic product (e.g. "Test Structure Fab", CX 424 at 19). Many other projects are also directly related to the exploitation of the '027 patent because they concerned an aspect of an integrated circuit which is closely related to the molding process such as 1) lead frame design (e.g. "Lead Frame Design and Finish", CX 424 at 16) and 2) lead conditioning (e.g. "SOIC Lead Conditioner", CX 424 at 12).

These research and development projects include projects totalling [C] [C] relating to equipment for die mounting and wire bonding. FF E 213. The patent does not contain any discussion of the techniques of die mounting

and wire bonding. FF E 216. However, both of these operations are an integral part of the manufacturing of a semiconductor, and the location of the die and the delicate nature of the wire bonds are both mentioned in the '027 patent's specification. CX-1, Col. 4, lines 26-35. It is difficult in situations such as that presented in this investigation to draw a bright line dividing those projects which exploit the patent at issue from those which do not. Some relate more directly to the patented process, and others seem somewhat indirectly or remotely related. Since there are many processes which could be used in die mounting or wire bonding from manual to highly automated techniques, evidence of research and development into these areas appears rather indirect to the exploitation of the '027 patent. Accordingly, the Administrative Law Judge has not given the evidence of this [C] as much weight as that regarding other engineering and research projects which are more directly related to the patented claims in determining whether a domestic industry exists.

3. Licensing

Texas Instruments has an extensive licensing program with approximately [C] in its patent portfolio. FF E 145. TI has spent approximately [C] since 1981 on its licensing activities. FF E 142. TI employs [C] to work in connection with its licensing program, and one of its patent attorneys spends essentially all of his time on licensing the '027 patent. FF E 158, 159. In the last five years, TI has received approximately [C] in royalties from licenses that include the '027 patent. FF E 162.

Mr. Donaldson, a Texas Instruments vice president and manager of patent licensing, testified that the '027 patent plays a "key role" in TI's licensing

program because it covers a broad range of products. FF E 141. In recent licensing negotiations with [C

] Donaldson, Tr. 864-867. However, while TI's overall licensing program is substantial, the [C

] FF E 148. All of the TI licenses that involve the '027 patent [C] FF E 143, 147. TI did not adduce evidence demonstrating the extent of its licensing investment in the '027 patent individually, nor was documentary evidence adduced to support Mr. Donaldson's assertion regarding the importance of the '027 patent in the negotiation of a [C] cross-license agreement. In light of the difficulty in segregating TI's licensing activities with respect to the '027 patent from its overall licensing activities, the Administrative Law Judge is ascribing little weight to the TI licensing program as evidence of a domestic industry exploiting the '027 patent.

4. TI's Overseas Activities

The respondents assert that TI's domestic operations when compared to its overseas operations, cannot constitute a domestic industry as required by the statute. Respondents argue that because products encapsulated by the '027 process at the FAM facility account for a small proportion of TI's overall sales of products encapsulated by the '027 process, the FAM facility does not satisfy the domestic industry requirement of Section 337.

TI sold almost [C] in plastic encapsulated integrated circuits in the United States in 1989. FF E 12. Over [C] of these circuits were encapsulated overseas. FF E 12. The circuits encapsulated in the United States at the FAM were encapsulated by a process which practiced the entire

'027 process from start to finish.

In investigations where the article protected by the patent was partially produced abroad and partially produced in the United States, the Commission has assessed the relative importance of domestic activities to the total activities conducted. In Certain Concealed Cabinet Hinges And Mounting Plates, Inv. No. 337-TA-289, the Commission examined the complainant's domestic finishing operations to complainant's operations in Europe to determine whether there was a domestic industry with respect to the product covered by the patent. The Commission stated that the statute's utilization of the term "significant" denoted an assessment of the relative importance of the two segments of the single manufacturing operation. Cabinet Hinges, Comm. Op. at 22. The product as imported was covered by the patent at issue. Id. at 22-23. The domestic operations contributed only a small percentage of the product's finished value, and also consisted of the addition of a feature which was not covered by the patent's claims. Id. The Commission declined to adopt what it characterized as the administrative law judge's "heavy reliance" on domestic value added, but agreed with him that complainant's domestic operations were insufficient to constitute a domestic industry. Cabinet Hinges, Comm. Op. at 24.

The circumstances in this investigation are distinguishable from those in Cabinet Hinges. Here, TI practices the entire process claimed in the '027 patent in the United States. Unlike the product in Cabinet Hinges which was produced partially in the United States and partially overseas, an integrated circuit encapsulated by the '027 process is not partially encapsulated overseas and partially encapsulated domestically. Rather, 100% of the value created by the encapsulation of an integrated circuit at the FAM is created

domestically. Accordingly, it is not possible to conduct a relative assessment of the importance of two segments of a single operation as was done in Cabinet Hinges.

Congress enacted 19 U.S.C. § 1337(a)(3) in 1988 as part of the Omnibus Trade and Competitiveness Act. The Commission has not had an opportunity in the intervening years to apply the statute to a situation analogous to that present in this investigation, i.e. a complainant practices all the steps of a patented process both domestically and overseas. Language from the statute's legislative history and the Commission's decision in DRAMs, however, supports a conclusion that the domestic industry analysis in such a situation is to focus on the nature and significance of the domestic operations without resorting to a mere mathematical calculation.

The report of the House Committee on Ways and Means regarding 19 U.S.C. § 1337 (a)(3) evidences that the Congress intended to codify existing Commission practice with respect to the first two factors and expand the definition of domestic industry by adding the third factor:

The Committee is concerned, however, that in some recent decisions the Commission has interpreted the domestic industry requirement in an inconsistent and unduly narrow manner. In order to clarify the industry standard, a definition is included which specifies that an industry exists in the United States with respect to a particular article involving an intellectual property right if there is, in the United States --

1. significant investment in plant and equipment;
2. significant employment of labor or capital; or
3. substantial investment in the exploitation of the intellectual property right including engineering, research and development or licensing.

The first two factors in this definition have been relied on in prior Commission decisions finding that an industry exists in the United States. The third factor, however, goes beyond the ITC's recent decisions in this area. This definition does not require actual production of the article in the United States if it can be demonstrated that substantial investment and activities of the type enumerated are taking place in the United States. Marketing and

sales in the United States alone would not, however, be sufficient to meet this test. The definition could, however, encompass universities and other intellectual property owners who engage in extensive licensing of their rights to manufacturers.

H.R. Rep. No. 40, 100th Cong., 1st Sess., pt. 1 at 157 (1987).
(emphasis added)

The touchstone of the prior Commission decisions referred to in the legislative history was the nature and significance of the activities alleged to constitute the domestic industry. DRAMs, Comm. Opn. at 68. The "significance" half of the test has now been expressly incorporated into § 337. Further, as illustrated in Cabinet Hinges where the Commission's decision was based in part on the fact that the operations performed in the United States were adding a feature not covered by the patent, the "nature" of a complainant's activities are to also be considered.

The respondents in DRAMs, like the respondents here, argued that TI did not have a domestic DRAM industry because of its extensive overseas operations. The Commission addressed this argument, first describing both the nature and significance of TI's domestic operations:

Complainant TI's operations in the United States cover every aspect of DRAM production, from initial product and process research and development, through prototype development, to commercial wafer fabrication. Although TI's primary assembly operations are conducted in the Far East, TI does prototype assembly, and some assembly of DRAMs for military applications, in the United States. In addition, TI performs substantial service operations such as modification of products for specific customer requirements.

DRAMs, Comm. Opn. at 68-69.

Having established that TI's "primary operations" were conducted overseas, the Commission nevertheless rejected respondents' argument:

Respondents argue that TI is primarily a Japanese DRAM manufacturer, alleging that TI's Japanese operations are far more significant than its U.S. operations, and that having made the choice to produce in Japan, TI cannot avail itself of section 337. We do not believe that TI's substantial, and to some extent

greater, production-related activities at its Japanese DRAM facilities, vitiate the domestic character of its DRAM operations in the United States. ... We have focused solely on the activities which take place in the United States in connection with DRAMs which are at least partially manufactured in the United States. That TI has manufacturing operations abroad, and the extent of those activities, are not relevant to the question of whether there is a domestic industry.

DRAMs, Comm. Opn. at 71. (emphasis added)

The Commission concluded that a domestic DRAM industry existed after examining both the operations of TI and its licensees which cover every aspect of DRAM production, as well as those which added value to imported DRAMs. Comm. Opn. at 66-74.

Nothing in the legislative history of 19 U.S.C. § 1337 (a)(3) or the Cabinet Hinges opinion suggests that an analytical framework different from that utilized in DRAMs should be employed in this investigation. Accordingly, the question of whether TI's domestic activities relating to the '027 patent constitute a domestic industry will be determined by examining the nature and significance of the activities. The nature and extent of a TI's overseas activities will be a factor in this analysis, but the presence of extensive overseas operations will not, taken alone, be dispositive.

5. Conclusion As To Domestic Industry

TI's Sherman facility is a true manufacturing site, housing not only the FAM but a wafer fabrication facility as well. FF E 113. The vast majority of the products the FAM encapsulates are manufactured by Sherman General Purpose Logic Wafer Fab, one of the larger wafer fab sites in the world. FF E 114, 115. Further, the presence of design engineers, product engineers and administrative personnel in one location allows the FAM to provide a quick turnaround time in response to customers' requests. FF E 116-117. The FAM's location in the United States also contributes to its ability to respond to a

customer's requests more rapidly than an overseas facility. FF E 118.

Another important function of the FAM is its work performed on proposed new products. FF E 125. It tests new packages and devices and is able to implement laboratory results on a true manufacturing line. FF E 122-131.

In addition to its function as a major test center, the FAM is also responsible for encapsulating several package types, many of which were all developed at the FAM. FF E 54, 56. Further, the FAM has responsibility for packaging large pin type plastic packages and in trying to market them ahead of the competition. FF E 55. Two such large pin types are currently under development and are expected to be available shortly. FF E 57.

Thus, the FAM is not simply another TI encapsulation facility. Unlike TI's other facilities, the FAM works closely with the Dallas PAC⁴¹ on the design and testing of new equipment and the encapsulation of new products which are still in the development stage. Further, several of the already-developed packages produced by TI are encapsulated at the FAM alone, and not at any of TI's facilities elsewhere in the world. Finally, the FAM utilizes its encapsulation facilities as an integral part of its quick turnaround services to TI's customers.

In addition to the FAM's activities which utilize the '027 process, TI's Dallas PAC conducts considerable research and development activities which exploit the '027 patent. While some evidence was adduced that TI conducts limited research and development at its Singapore PAC (FF E 167-168), the majority of TI's research and development activities relating to the '027

⁴¹ The PAC is TI's "Process Automation Center" in Dallas where TI performs its research and development activities. FF 164-166.

process apparently take place within the United States.⁴²

In light of the important role the FAM plays in TI's operations as a facility for the testing of equipment, processes and devices under full production conditions, as the sole source of certain package types, and as a source for products for domestic customers on short notice, it is of a nature and significance that belie its relatively small output volume. Because of its importance to TI's operations as a whole, TI's investment in the FAM is "significant". Similarly, the related research and development activities that occur at the PAC are "significant". Consequently, a domestic industry devoted to the exploitation of the '027 patent exists.

B. Texas Instruments Practices The '027 Patent

In a patent-based investigation, a threshold issue of whether a domestic industry exists is whether the complainant is exploiting the patent at issue as required by 19 U.S.C. § 1337(a)(2). Certain Doxorubicin and Preparations Containing Same, USITC Inv. No. 337-TA-300, Commission Opinion (Public Version) at 21 (May 2, 1991).

Both TI and respondents presented witnesses to testify on whether TI practices the '027 patent at its FAM facility. TI's witness, Dr. Seiling, testified that he had visited the FAM facility and witnessed molding operations. Seiling, Tr. 392, 693-695. In his witness statement, Dr. Seiling stated that TI encapsulates PDIP, SOIC and SSOP packages at the FAM. CX 600, ¶ 197. Dr. Seiling sponsored exhibits CPX 489-499, and 505-508 which are claim charts purporting to demonstrate how TI's bottom-gated processes are

⁴² Respondents have adduced evidence regarding TI's overall investment in research and development activities at home and overseas, but have not provided a breakdown as to how much of this figure is related to the '027 process. FF 257.

entered into a cross-license agreement with TI.

TI and [C] entered into a cross-license agreement [C]
[C] that had an effective date of April 1, 1974, and that covers the
'027 patent. FF F 1, 4. On August 8, 1990, Analog acquired all of [C]
stock, and [C] became a wholly-owned subsidiary of Analog. On November 3,
1990, Analog and [C] formally merged, with articles of merger having been
filed with the Massachusetts Secretary of State on October 31, 1990. FF F 7.

Patent licenses are not assignable or transferable unless they are
expressly made so. PPG Industries, Inc. v. Guardian Industries Corp., 597
F.2d 1090, 1093-1096 (6th Cir.), cert. denied, 444 U.S. 930 (1979) ("PPG
Industries"); Unarco Industries, Inc. v. Kelley Co., 465 F.2d 1303, 1306 (7th
Cir. 1972), cert. denied, 410 U.S. 929 (1973). Whether or not Analog is
licensed under the '027 patent depends on how Article VII, Section 3 of the [C]
license agreement should be applied to the facts of this case. See PPG
Industries, 597 F.2d at 1095. Article VII, Section 3 provides in part:

[C]

Analog is a third party that has acquired [C]

] of [C] FF F 7. Analog claims that since it has met that condition
under the [C] license agreement, it is licensed to the extent of the annual

sales of licensed products being made by [C] at the time it was acquired, and that even if Analog was required to obtain the consent of TI, TI has unreasonably withheld its consent. The staff supports Analogs' position in this respect. TI denies that Analog can be a licensee without its consent or that it has unreasonably withheld its consent.

A contract is unambiguous when it is reasonably open to just one interpretation given the rules of construction and the surrounding circumstances. Technical Consultant Services, Inc. v. Lakewood Pipe of Texas, Inc., 861 F.2d 1357, 1362 (5th Cir. 1988). No party has alleged that Article VII, Section 3 of the [C] license agreement is ambiguous, and very little evidence other than the [C] license agreement itself has been put forth by any party concerning construction of that provision. No party has tried to show that the terms at issue of that provision have anything but their ordinary meaning. Accordingly, Article VII, Section 3 of the [C] license agreement should be construed as a matter of law. Id.; Barstow v. State, 742 S.W.2d 495, 510 (Tex. App. 1988); Community Development Services, Inc. v. Replacement Parts Manufacturing, Inc., 679 S.W.2d 721, 723 (Tex. App. 1984).⁴⁴ The intention of the parties should be followed, as it is expressed or as it is apparent in the writing. Community Development, 679 S.W.2d at 723. In this case, the parties have centered their arguments on the plain language of

⁴⁴ The [C] license agreement provides that it is to be construed in accordance with Texas law. FF F 2. Questions with respect to the assignability of a patent license are controlled by federal law. PPG Industries, 297 F.2d at 1093; Unarco Industries, 465 F.2d at 1306. However, according to the terms of a license agreement, it can be construed under state law. Southwire Co. v. USITC, 629 F.2d 1332, 1338, 207 U.S.P.Q. 189, 193-94 (C.C.P.A. 1980); Certain Fluidized Supporting Apparatus and Components Thereof, Inv. No. 337-TA-182/188, Commission Opinion at 12 (1984) [225 U.S.P.Q. 1211, 1216].

Article VII, Section 3 itself. The provision at issue should receive a reasonable construction, and its terms should be given their ordinary meaning. L.S.S. Leasing Corp. v. United States, 695 F.2d 1359, 1363-64 (Fed. Cir. 1982).

The second sentence [C] clearly addresses the issue of the [C] in the event that [C] [C] were acquired [C] party. The parties in this investigation disagree as to whether the consent of the licensing (non-acquired) party must be obtained to effect the [C] [C]⁴⁵ [C] TI contends that the license [C] be transferred, and that thus it [C] [C]. The word [C] is capable of several meanings in English. In this case, it is reasonable to ascribe to the word the meaning of ability or power (i.e., "can"), rather than]that of possibility, likelihood or permission as is seemingly urged by TI.⁴⁶ More importantly, rather than linking an [C] [C] [C] under the second sentence to the restrictions found in other parts of the provision.

⁴⁵ [C]

⁴⁶ See Webster's New World Dictionary 909 (1966).

the [C] license agreement is found [C]
[C] The first sentence of the provision addresses [C]
[C] in a general way. If it stood alone, the first sentence might have
the effect that TI ascribes to it, i.e., [C]
[C].⁴⁷ But the first sentence
does not stand alone. [C]
[C]
[C]
[C] It is not reasonable to suppose that
the second sentence is merely different wording for the same idea expressed in
the first sentence, or that it is in conflict with the first sentence.
Rather, [C]
[C]
[C]
[C]
[C]

If the [C] required by the first sentence covered the situation
contemplated by the second sentence [C]
[C] the restriction imposed by the second
sentence upon [C] parties [C] would
be superfluous at best. For example, in this case, inasmuch as Analog would
have [C] there would be no need to state that

⁴⁷ This is especially likely given the law as discussed in PPG Industries, supra, that basically prohibits the assignability or transferability of patent licenses absent provisions to the contrary.

]

In Article VII, Section 3, it would not be reasonable to have three separate sentences and two distinct "provided" clauses expressing different restrictions upon [C], if all three sentences applied in the same circumstances and created ambiguities and conflicts. Analog's current position as a licensee is addressed clearly and unambiguously by the second sentence, which does not require [C].

Analog contends that even if [C] were required in the current situation, TI [C] unreasonably. At the time that [C] was acquired by Analog, Analog had already been sued for patent infringement in a U.S. District court. FF F 16. In such circumstances in which TI was already suing Analog, it is difficult to prove that TI was unreasonable in [C] [C], especially when the motive for such licensing seems not to be settlement of litigation per se but rather Analog's desire to expand its business and to indemnify itself from TI's infringement suit.⁴⁹

⁴⁹ Analog's annual sales were about [C] as [C] sales at the time that Analog acquired [C]. FF F 14; see also discussion below on amount of sales by [C] and Analog. Furthermore, Analog has two of its own encapsulation facilities offshore, whereas [C] did not have any offshore
(continued...)

Although Analog is licensed under the [C] license agreement for sales [C] being made by [C] at the time that it was acquired, it must be determined whether Analog's sales are in fact at or below the amount for which it is licensed. [C] total worldwide sales of all of its products were over [C] in the twelve months preceding its merger with Analog. FF F 9. At the time that it merged with Analog, [C] entire product line was covered by the [C] license agreement. FF F 10.

Analog's sales of plastic encapsulated integrated circuits for its fiscal year, which ended at the end of October of 1990, were about [C] FF F 13. The combined sales of Analog's and [C] plastic encapsulated integrated circuits for 1990 were about [C] FF F 17. The amount of Analog's [C] is therefore below the amount of

⁴⁹(...continued)

encapsulation facilities at the time it was acquired by Analog. FF F 15. These are facts that, along with the existence of the prior litigation against Analog, would explain why TI would not want to negotiate with Analog for [C] pursuant to the third sentence of Article VII, Section 3. However, Analog did not contend in the post-hearing phase of this investigation that TI failed to negotiate. Rather, its arguments appear limited to the issue of whether TI unreasonably [C] [C].

[C] annual sales at the time it was acquired, and thus Analog's sales after it acquired substantially all of the assets of [C] have been licensed under the [C] license agreement.⁵⁰

⁵⁰ In addition to that portion of Article VII, Section 3 quoted above, the provision also provides:

[C]

]

[C]

]

Analog contends that a comparison of the [C] license agreement with another license agreement entered into by TI supports Analog's position that the [C] license agreement [C]

] [C]

]

[C]

]

* * *

[

C

]

(continued...)

Analog argues that inasmuch as it has a fully paid up license under the patent at issue, this investigation should be dismissed because possession of a license under the patent in suit is an absolute defense in a section 337 proceeding, relying on Order No. 52 of Order No. 71 in Certain Cardiac Pacemakers and Components Thereof, Inv. No. 337-TA-162 (May 25 and July 3, 1984). TI and the staff oppose Analog's argument. The orders relied on from the Cardiac Pacemakers investigation are not controlling in this investigation, and they do not state that any previous violation becomes irrelevant upon acquisition of a license.⁵¹ The facts in this investigation are more analogous to those in Certain Fluidized Supporting Apparatus and Components Thereof, Inv. No. 337-TA-182/188 (1984), in which the Commission

⁵⁰(...continued)

[

C

]

TI contends that Analog's findings with respect to the [C] are irrelevant and that they "are in violation" of that Article X of the [C] license agreement that states in essence [C

] Yet the [C] agreement serves as an illustration of how a patent license can be written to cover [C]

In contrast, it has not been shown that the [C] license agreement restricts [C]

⁵¹ For example, the ruling in Order No. 52 was based on the claim of certain respondents that they had acquired a license from those with rights in the patent at issue that were superior to those of the complainant. It was also established that sales of certain products occurred after respondents became licensed and that sales of other products had ceased or would cease. Order No. 52; Notice of Commission Determination Not to Review an Initial Determination Terminating Certain Patent Claims as to Certain Respondents (June 26, 1984) The motion for termination of another respondent that brought about Order No. 71 was unopposed by the complainant, and was based on a claim to have been licensed before institution of the investigation, and to have rights superior to those of the complainant. Cardiac Pacemakers, Order No. 71 at 1-2.

found reason to believe that there was violation of section 337 despite the fact that the respondents in that investigation may have had a partial license under the patent in issue and may have made allegedly infringing sales as well as licensed sales. Commission Opinion at 9, 15, 225 U.S.P.Q. at 1215, 1218. While Analog is correct that it does not have a partial license in a geographical sense, as in Fluidized Supporting Apparatus, or a partial license that covers only a certain amount of its current sales of licensed products,⁵² Analog has been licensed for only part of the time that it was allegedly making sales of accused products and for only part of the time during which this investigation has been pending.

In Monumental Wood Windows, Inv. No. 337-TA-40, the Commission investigative attorney filed a motion to terminate the investigation with prejudice by reason of there being no violation of section 337. The motion was not opposed by the complainant. In fact, the complainant admitted that there was no present violation of section 337 and indicated that it would not present any case to prove a past violation. The motion to terminate was supported by the respondents. The Commission granted the motion to terminate with a finding that there was no violation of section 337, but stated that the finding was based on the fact that complainant conceded that there was no present violation and failed to sustain its burden of proof that a past violation existed. Commission Determination and Action at 2-3 (January 8, 1979). Thus, the Commission left open the possibility that it would in the

⁵² Analog, even after acquiring [C], projects [C
this projection on [C] Analog bases

] FF F

18.

future find a violation of section 337 based on past conduct even when no present conduct constituted an unfair act.⁵³

The Commission instituted this investigation to determine "whether there is a violation" of section 337, and that is taken to refer at least to the question of whether there was a violation as of the date of institution. Notice of Investigation (Aug. 8, 1990). TI's complaint was filed on July 19, 1990, and this investigation was instituted on August 7, 1990, before Analog acquired its license under the '027 patent by means of the [C] license agreement. Even if Analog became licensed as early as August 8, 1990, that is still a day after institution of the investigation and a considerable period of time after violation of section 337 is alleged to have begun. In the event that a violation is found, a decision as to whether, how, and on what basis the Commission will fashion a remedy in view of the fact that Analog is now licensed under the '027 patent is not under the jurisdiction of the administrative law judge. This investigation should not be dismissed on the basis that Analog has become licensed under the [C] license agreement.⁵⁴

⁵³ See also Certain Rotary Printing Apparatus Using Heated Ink Composition, Components Thereof, and Systems Containing Said Apparatus and Components, Inv. No. 337-TA-320, Order No. 1 (January 14, 1991) ("Neither importation nor sale during the pendency of the investigation is required to support a Section 337 violation, and discontinuance of an unfair practice is not an adequate defense." Id. at 1).

⁵⁴ Analog's brief argument, without citation to authority, that this investigation as concerns Analog should be dismissed now because the dispute between TI and Analog it is at most a contract dispute, is not adopted here. This investigation was instituted to determine whether there is an unfair act in the importation or sale of products made by an allegedly infringing process. The contract to which Analog refers is the [C] license agreement that is used as a defense to TI's charge of infringement, which charge is central to the purpose of this investigation, and as discussed at the outset of this opinion, is within the jurisdiction of the Commission.

VIII. ANALOG'S "GRANDFATHER CLAUSE" DEFENSE IS REJECTED

Part of the Omnibus Trade and Competitiveness Act of 1988, Pub. L. No. 100-418, 102 Stat. 1107 ("the Trade Act") is the Process Patent Amendments Act of 1988, Pub. L. No. 100-418, 102 Stat. 1563 (Trade Act, Title IX, Section 9001)("the Patent Amendments"). Subtitle A of the Patent Amendments contains section 9003 (codified at 35 U.S.C. § 271(g))("section 271(g)"), which provides in part:

Whoever without authority imports into the United States or sells or uses within the United States a product which is made by a process patented in the United States shall be liable as an infringer, if the importation, sale, or use of the product occurs during the term of such process patent.

Exceptions to that liability are specified in section 9006(b) of the same subtitle of the Patent Amendments, which provides in part:

The amendments made by this subtitle shall not abridge or affect the right of any person or any successor in business of such person to continue to use, sell, or import any specific product already in substantial and continuous sale or use by such person in the United States on January 1, 1988, or for which substantial preparation by such person for such sale or use was made before such date, to the extent equitable for the protection of commercial investments made or business commenced in the United States before such date. This subsection shall not apply to any person or any successor in business of such person using, selling, or importing a product produced by a patented process that is the subject of a process patent enforcement action commenced before January 1, 1987, before the International Trade Commission, that is pending or in which an order has been entered.

The Commission, and section 337 in particular, is further addressed in section 9006(c) of the same subtitle, which provides:

The amendments made by this subtitle shall not deprive a patent owner of any remedies available under subsections (a) through (f) of section 271 of title 35, United States Code, under section 337 of the Tariff Act of 1930, or under any other provision of law.

Analog takes the position that even if its encapsulation method is

covered by the '027 patent, it cannot be committing an unfair act under section 337 by importing plastic encapsulated circuits due to equitable rights that it has to continue its practices pursuant to the "grandfather clause," i.e., section 9006(b), of the Patent Amendments. The staff takes the position that section 9006(b) does not apply to investigations such as this.

By 1988, Analog had already built facilities overseas for plastic encapsulation, and had begun selling imported plastic encapsulated circuits. FF G 1-7. Analog might have substantial and continuous sales or use that started before 1988, or substantial preparation for use or sale before 1988, as contemplated by section 9006(b). But there is a threshold question of law as to whether the "grandfather clause," section 9006(b), can serve as an affirmative defense to the allegations made by TI that are the subject of this investigation.

This investigation was instituted to determine, in part, whether there is a violation of subsection (a)(1)(B) of section 337 in the importation, sale for importation or sale after importation of certain products that are manufactured, produced or assembled abroad by a process covered by certain claims of the '027 patent.⁵⁵ Notice of Investigation (Aug. 8, 1990). Even before section 271(g) was added to extend the powers of the courts, the

⁵⁵ 19 U.S.C. § 1337(a)(1) provides, among other things, that the following is unlawful:

(B) The importation into the United States, the sale for importation, or the sale within the United States after importation by the owner, importer, or consignee, of articles that -

* * *

(ii) are made, produced, processed, or mined under, or by means of, a process covered by the claims of a valid and enforceable United States patent.

Commission, through 19 U.S.C. §§ 1337 and 1337a, had the authority to investigate and issue remedies with respect to certain importations and sales of articles covered by process patents.⁵⁶

The plain language of section 9006(b) of the Patent Amendments ensures that its exception from liability under section 271(g) does not apply in certain Commission actions begun before a specified date.⁵⁷ Section 9006(b), especially when read in conjunction with section 9006(c), does not provide any exception for acts that are separately specified as unlawful under section 337. Section 337 explicitly states that actions may be taken thereunder "in addition to any other provision of law." 19 U.S.C. § 1337(a)(1). As seen from the plain language of Section 9006(c) of the Patent Amendments, quoted above, the Patent Amendments recognized section 337 as an independent cause of action in that the addition of section 271(g) did not deprive a patent owner of any remedies available under section 337.⁵⁸ This investigation was not

⁵⁶ As amended by the Trade Act, subsection (a) of section 337 makes it unlawful to make certain importations and sales of articles that are made, produced or processed under or by a process covered by a valid United States patent. See Trade Act, § 1342(a), 102 Stat. at 1212; 19 U.S.C. § 1337(a)(1)(B)(ii). In amending subsection (a) of section 337, the Trade Act, by means of a conforming amendment, also repealed section 337a which had also provided for coverage under section 337 of articles covered by process patents. See Trade Act, § 1342(c), 102 Stat. at 1215-16; 19 U.S.C.A. § 1337a (1980).

⁵⁷ The starting point in statutory interpretation is the language of the statute itself. United States v. James, 478 U.S. 597, 604 (1986).

⁵⁸ The fact that section 337 and section 271(g) constitute separate causes of action was recognized by the court in Bristol-Myers Co. v. Erbamont Inc., 723 F. Supp. 1038 (D. Del. 1989), a case involving a counterclaim based on section 271(g). The court stated upon consideration of a motion for summary judgment of non-infringement:

Before passage of the [Trade] Act, the only remedy a patent process holder had in this situation was the International Trade Commission ("ITC") pursuant to 19 U.S.C. §§ 1337 and 1337a. The

(continued...)

instituted to make an infringement determination with respect to section 271(g), but to make a determination as to whether there is a violation of section 337. Analog cannot rely on section 9006(b) of the Patent Amendments to defend against allegations that it is in violation of section 337.

The Commission already made a determination with respect to the applicability of the "grandfather clause," section 9006(b) of the Patent Amendments, to a Commission action taken under section 337(a)(1)(B)(ii), in Certain Methods of Making Carbonated Candy Products, Inv. No. 337-TA-292 (1989) ("Carbonated Candy"). The instant investigation, as explained above, is also based on that provision of section 337. In Carbonated Candy, the complainant moved for partial summary determination that the Commission deny, as a matter of law, respondents' affirmative defenses that even if the Commission were to determine that there was patent infringement, section 9006(b) of the Patent Amendments would except respondents from a Commission exclusion order due to their continuous and substantial sales in the United States prior to January 1, 1988 of products covered by a U.S. process patent. In granting the motion for partial summary determination, and thereby rejecting the affirmative defenses as a matter of law, the administrative law judge found that the Patent Amendments did not eliminate any preexisting process patent remedy found under section 337, but rather that they afford

⁵⁸(...continued)

ITC, however, could only grant non-monetary relief in the form of an in rem exclusion order against goods. 35 U.S.C. § 271(g), by its terms, permits a federal district court to award a patent process holder damages for infringement and issue any other relief against an infringer. 35 U.S.C. § 271(g), therefore, provides an in personam remedy as compared to the in rem remedy of 19 U.S.C. §§ 1337 and 1337a.

Id. at 1041 n.10.

process patent holders an additional remedy against process patent infringement. Notice of Commission Not to Review an Initial Determination Rejecting As a Matter of Law Respondents Zeta and Confex's Affirmative Defenses Involving Process Patent Legislation (Oct. 2, 1989) ("Notice Not to Review"); Carbonated Candy, Order No. 19 (Sept. 1, 1989) (initial determination on partial summary determination).

The Commission determined not to review the initial determination (Order No. 19), thus, pursuant to Commission Rule 210.53(h) (19 C.F.R. § 210.53(h)), the initial determination became the determination of the Commission. Notice Not to Review.⁵⁹ The Commission's determination in Carbonated Candy with respect to the applicability of the "grandfather clause," section 9006(b) of the Patent Amendments, is still binding on this investigation, and therefore, Analog's affirmative defense under section 9006(b) must be rejected.

⁵⁹ The Commission stated that its action in not reviewing the initial determination (Order No. 19), should not be interpreted as holding that the Patent Amendments (or "Process Patent Legislation") can never be applicable to section 337 investigations. That statement by the Commission reinforces the finding that the Patent Amendments provide an additional remedy for process patent holders, and suggests that the Patent Amendments could play a part in determining the definition of an unfair act or patent infringement in other actions under section 337. See Notice Not to Review.

FINDINGS OF FACT

FF A 1. On July 9, 1990, Texas Instruments, Incorporated ("TI") filed a complaint with the U.S. International Trade Commission under section 337 of the Tariff Act of 1930, as amended, 19 U.S.C. § 1337, alleging that the importation and sale of plastic encapsulated integrated circuits by the Respondents constituted infringement of claims 12, 14 and 17 of U.S. Letters Patent No. 4,043,027 ("the '027 patent"). TI's complaint sought permanent relief in the form of exclusion orders and cease and desist orders. Complaint, ¶¶ 1, 2.

FF A 2. The Commission instituted an investigation of TI's complaint and issued a Notice of Investigation on August 7, 1990. 55 Fed. Reg. 33388 (August 15, 1990).

FF A 3. On January 9, 1990, the Administrative Law Judge issued an initial determination: (1) amending the complaint by revising paragraph 36 of the complaint and substituting Exhibit 49a for Exhibit 49, (2) adding claim 1 of the '027 patent to the investigation, and (3) designating the investigation "more complicated" by a full six months. The Commission determined not to review the initial determination. Notice of Commission Decision Not to Review an Initial Determination Amending the Complaint and Notice of Investigation and Designating the Investigation "More Complicated," 56 Fed. Reg. 4851 (Feb. 6, 1991).

FF A 4. A hearing on TI's complaint was held before the Administrative Law Judge from May 13 to May 22, 1991. Tr. 1-1579.

FF A 5. The '027 patent, in addition to nine other patents, was asserted by TI before the Commission in 1986 in Certain Dynamic Random Access Memories.

Components Thereof and Products Containing Same, Inv. No. 337-TA-242

("DRAMs"). On appeal from a Commission determination finding the '027 patent invalid, the Federal Circuit reversed the findings of invalidity on the grounds of 35 U.S.C. §§ 101 and 112, vacated the finding of obviousness under 35 U.S.C. § 103, and remanded. Texas Instruments, Inc. v. U.S. International Trade Commission, No. 87-1627 (Fed. Cir. July 12, 1988) (unpublished). On remand, the Commission assigned the investigation to an Administrative Law Judge for findings on the issues of obviousness and infringement. Notice of Remand of Investigation to Administrative Law Judge, 53 Fed. Reg. 39159 (Oct. 5, 1988). After a review of the original record, the Administrative Law Judge found claims 12-15 and 17 of the '027 patent to be nonobvious and infringed. DRAMs, Initial Determination (March 29, 1989). The Commission determined not to review. Notice of Commission Decision Not to Review Initial Determination on Remand, 54 Fed. Reg. 22633 (May 25, 1989).

FF A 6. On July 9, 1990, Texas Instruments filed a parallel proceeding in the United States District Court for the Northern District of Texas asserting that the five respondents named in this investigation have infringed claims 12, 14 and 17 of the '027 patent. Texas Instruments, Inc. v. Analog Devices, Inc. et. al, Civil Action No. 90-1590-H (N.D. Tex. 1990). TI did not allege infringement of claim 1 of the '027 patent in this proceeding.

FF A 7. Complainant TI is a Delaware corporation having its principal place of business at 13500 North Central Expressway, Dallas, Texas.

Complaint, ¶ 3.

FF A 8. Analog Devices, Inc. is a Massachusetts corporation having its principal place of business at One Technology Way, Norwood, Massachusetts.

Response of Analog to Complaint, ¶ 4.

FF A 9. Integrated Device Technology, Inc. ("IDT") is a Delaware corporation having its principal place of business at 2975 Stender Way, Santa Clara, California. Complaint, ¶ 5; Response of the California Respondents to Complaint, ¶ 5.

FF A 10. LSI Logic Corporation ("LSI") is a Delaware corporation having its principal place of business at 1551 McCarthy Boulevard, Milipitas, California. Complaint, ¶ 6, p. 4; Exhibit 41. Response of the California Respondents to Complaint, ¶ 6.

FF A 11. Cypress Semiconductor Corporation ("Cypress") is a Delaware corporation having its principal place of business at 3901 North First Street, San Jose, California. Complaint, ¶ 8, p. 5; Exhibit 45. Response of the California Respondents to Complaint, ¶ 8.

FF A 12. VLSI Technology, Inc. ("VLSI") is a Delaware corporation having its principal place of business at 1509 McKay Drive, San Jose, California. Complaint, ¶ 7, pp. 4-5; Exhibit 43. Response of the California Respondents to Complaint, ¶ 7.

FF A 13. In the late 1950s and early 1960s, the principal method of encapsulating transistors was the header and can process. The header and can method involved placement of a semiconductor chip on a foundation or handle called a header. After the chip was mounted on top of the header, wire connections to conductor leads were made. The header was a metal plate on which the leads of the device were held in place with a glass filling. The leads came out of the package through the bottom of the header. A metal can was hermetically welded on top of the header. These steps were performed by hand inside a small environmental chamber and were very labor intensive. The gold-plated header and the can were expensive components. DRAMs Finding No.

10: Admitted by Analog and California Respondents.

FF A 14. The primary manufacturing cost of transistors packaged in a header and can was the cost of defective units. The labor-intensive assembly step was the second largest cost component, and the cost of the gold plated header was the third largest cost component of manufacturing the finished product. CX 8, Birchler Wit. Stmt. at 189-191.

FF A 15. Beginning in the early 1960s, semiconductor manufacturers began searching for means to mass produce inexpensive transistors. Plastic encapsulation of integrated circuits substantially reduced the component and labor cost of manufacturing finished products. Russell, Tr. at 1118; Seiling, Tr. at 421.

FF A 16. The semiconductor industry's early attempts to transfer mold integrated circuits suffered problems with high velocity molding compound entering the mold cavity and damaging the semiconductor device and whisker wires. Designers of molding equipment were always concerned with holding the components in proper position during molding and possible breakage of the devices and the connection. When the problem was solved, transfer molding became the encapsulation method of choice in the industry. Plummer, Tr. at 1433-1434.

FF A 17. In September of 1959, Robert O. Birchler was developing a mass production method for encasing transistors in header and can packages. DRAMs
Finding 70: Admitted by California Respondents and Analog; CPX 11.

FF A 18. While working on mass production techniques for header and can packaging of transistors, and at least by May 1, 1961, Mr. Birchler designed a flat metal strip as a header for transistor packaging. CX 5, ¶ 111; CX 215, ¶ 111.

FF A 19. Following Mr. Birchler's developmental work on mass production of inexpensive transistors, he began working with E.R. Williams on means for packaging transistors without the use of expensive headers and cans, a project that would eventually be called TI's Low Cost Transistor Project. CX 5, ¶ nnn, CX 215, ¶ nnn.

FF A 20. TI's Low Cost Transistor Project began in late 1962 or early 1963 with the goal of developing an inexpensive process to assemble and encapsulate transistors. CX 5, ¶ 000; CX 215, ¶ 000.

FF A 21. As a first step in developing low cost transistors, Birchler and Williams identified the cost of each component and process involved in the manufacture of header and can packaged transistors. That cost analysis revealed that the header and can components and the labor required to assemble those parts were a significant cost of the finished product. They therefore proposed the development of a headerless transistor assembly encapsulated in plastic. Birchler, Tr. at 367, 369.

FF A 22. Prior to the Low Cost Transistor Project, Mr. Birchler had no "hands-on" experience, and Mr. Williams had no experience at all, with transfer molding. Mr. Williams therefore began researching the packaging technology available in the plastic industry. Birchler, Tr. at 279-280; CX 5, ¶ 000; CX 215, ¶ 000.

FF A 23. Mr. Williams' lab notebook contains drawings dated May 29, 1963 of two single cavity mold experiments which he conducted at Dow Chemical in Midland, Michigan. In the first experiment, as depicted in the drawing labeled "Unit In Top", the semiconductor device, whisker wires and gate were all located in the top of the mold cavity, a configuration which the notebook entry describes as "most unsatisfactory with the .001" emitter and base

connection being broken during the transfer operation." In the second experiment, as depicted in the drawing labeled "Unit in Bottom", the semiconductor device and whisker wires were located in the bottom half of the mold cavity with the gate located on the opposite side of the conductors in the top half of the mold cavity, a configuration which the notebook entry describes as producing "better results (good units)". RX 041 (enlarged at RPX 34); Birchler, Tr. at 281-285.

FF A 24. In the same-side gated experiment at Dow Chemical, every transistor failed electrical continuity tests, apparently due to broken bond wires. RPX 109 (Lockhart, Dep.), Tr. 17; CX 8 (Birchler Wit. Stmt.) at 225-227.

FF A 25. Birchler and Williams's first experiments at Dow Chemical used a transistor mounted on a plastic header in order to determine whether a transistor could be successfully transfer molded. Elimination of the header component was delayed until there was some initial indication of whether transfer molding operations could be conducted without damaging the bond wires. CX 8 (Birchler Wit. Stmt.) at 230-231; Birchler, Tr. at 282.

FF A 26. By no later than November 1963, Mr. Birchler made drawings illustrating the transfer molding process shown in Figure 5 of the '027 Patent. RX 44 (Rule 131 Affidavit); Birchler, Tr. at 297.

FF A 27. United States Letters Patent No. 4,043,027 issued on August 23, 1977 based on Application No. 384,768, filed July 30, 1973, in continuation of Application No. 738,311 filed October 17, 1968, which was a division of Application No. 331,006 filed on December 16, 1963. CX 1.

FF A 28. TI is owner by assignment of the '027 patent. CX 1; CX 2.

FF A 29. A variety of differently shaped and structured plastic packages

can be configured by changing the location of the conductors, the geometry of the conductors outside the plastic package, and the shape and dimensions of the plastic package. Schroen, Tr. at 40-42.

FF A 30. Common plastic package types include Dual In-line Packages (DIPS), Plastic Leaded Chip Carriers (PLCC), Small Outline Integrated Circuits (SOIC) and Quad Flat Packs (QFP). These package types can accommodate a range of conductors or pins for conducting electrical signals or loads between the semiconductor device and the outside circuitry connected to the conductors. The conductors themselves can be further bent or formed into a variety of shapes, including J-type leads, gull wing configurations, and surface mounts. Seiling, Tr. at 416-419; CX 567-A; CX 567-B.

FF A 31. Processes for transfer molding various package types can be described as "opposite-side gated", where the semiconductor device and bond wires are located on the opposite side of the lead frame from the portion of the mold cavity containing the plastic injection gate, or as "same-side gated", where the semiconductor device, bond wires, and gate are all located on one side of the mold cavity from the lead frame. Williams, Tr. at 1461-1463; RX 41; Birchler, Tr. at 334-335.

FF A 32. TI, Cypress, IDT and LSI have produced both same-side gated and opposite-side gated plastic encapsulated integrated circuits. Schroen, Tr. at 65; CX 400 (Respondent Import Stipulations).

FF A 33. Multiple plastic encapsulated integrated circuits are sometimes combined into assemblies or modules of individually packaged components. Schroen, Tr. at 37-38.

FF A 34. Claim 1 provides:

1. A process for encapsulating a miniaturized semiconductor device having a multiplicity of electrical terminals comprising the steps

of:

electrically connecting each of the electrical terminals of the device to an intermediate point of a conductor and mechanically attaching each component of the device to at least one of the conductors for support,

disposing the device and the adjacent intermediate portions of the conductors in a mold cavity with the opposite ends of each of the conductors extending from generally opposite side of the mold cavity, and

holding the opposite ends of the conductors extending from the mold cavity while injecting a fluid insulating material into the mold cavity which will subsequently solidify, the fluid insulating material being injected into a portion of the mold cavity remote from the device and the means electrically connecting the terminals of the device to the conductors,

whereby the fluid will not directly engage the device and electrical connection means at a high velocity and the conductor will be secured against appreciable displacement by the fluid which would be likely to break or displace a connection means in such a manner to cause a failure of the device. (Emphasis added to identify principal elements where infringement is contested.)

CX 1 (the '027 patent) at Col. 9, lines 1-27.

FF A 35. Claim 1 of the '027 patent requires attachment of the bond wires at an intermediate point between opposite ends of the conductors, while Respondents' processes attach bond wires to the ends or tips of cantilevered conductors. CX 1 (the '027 patent) at Col 9, lines 1-28; Plummer, Tr. at 1335

FF A 36. The "electrical connections" of the '027 patent are described in the specification as very fine wire leads which provide an electrically conductive path between the terminals of the semiconductor device and the relatively larger conductors which extend outside the finished package. CX 1 (the '027 patent) at Col. 4, lines 34-45.

FF A 37. The terms "whisker wires" and "wire bonds" are interchangeably used to refer to the means for electrically connecting the terminals of the semiconductor device to the conductors. See, Seiling, Tr. at 678.

FF A 38. The "leads" described in Birchler and Williams' TI invention disclosure and in Mr. Williams' laboratory notebook were later described in the '027 patent as "conductors". RX 51 (Birchler and Williams Invention Disclosure); RX 41 (Williams Laboratory Notebook); Birchler, Tr. at 318.

FF A 39. The claims at issue refer to "conductors", which are defined in the '027 patent as a plurality of individual conductors to which the transistor is mechanically and electrically connected. Williams, Tr. at 1482-1487.

FF A 40. Claim 1 is literally limited to those processes where the conductors extend through, and are held by, opposite sides of the mold cavity wall, whereby they are secured against displacement by the flow of molding compound. CX 1 ('027 patent, Claim 1) at Col. 9, lines 1-27.

FF A 41. The electrical connections between the semiconductor device and conductors are explained in the specification as "connecting each of the electrical terminals to a midpoint of a conductor wire . . .". CX 1 (the '027 patent), at Col. 2, lines 19-20.

FF A 42. The conductors described in Claim 1 are illustrated in Figures 1, 2, 3, 4, 9 and 10 of the '027 patent, wherein semiconductor devices and bond wires are attached to intermediate portions of conductors whose ends extend through, and are held by, the mold cavity walls. CX 1 (the '027 patent); Birchler, Tr. at 299, 307.

FF A 43. The Claim 1 limitations of "an intermediate point of a conductor . . . with the opposite ends of each of the conductors extending from generally opposite sides of the mold cavity" refers to the "double-ended" conductors which Birchler and Williams produced in their two-cavity mold and described in their invention disclosure. Birchler, Tr. at 307, 317;

CX 41 (Williams Laboratory Notebook) at page dated 6/31/63; CX 51 (Birchler and Williams Invention Disclosure) at subparagraph D.

FF A 44. In Respondents' processes one end of each conductor is cantilevered freely in space near to the die pad, while the other end of each conductor extends through, and is held by, the mold. CX 50 (Representative Lead Frame) at "Step A"; CX 8 (Seiling Wit. Stmt.) at ¶ 12; CX 400 (Stipulations Regarding Respondents Commercial Imports) see Seiling, Tr. at 397-398, 529 (equating lead frame fingers with conductors), 603.

FF A 45. Respondents' expert Mr. Plummer correctly interpreted the literal language of Claim 1 of the '027 patent as requiring attachment of the bond wires to intermediate points of the conductors whose ends extend through and are held by the opposite sides of the mold cavity walls. Respondents' processes do not utilize the "double-ended" structure; instead the bond wires are attached to the ends of conductors which are cantilevered freely in space adjacent to the die pad, while the other end of the conductor extends through and is held by the mold cavity walls. Plummer, Tr. at 1386.

FF A 46. In Claim 1, the "double-ended" conductors are described in the "whereby" clause as secured against appreciable displacement by the fluid insulating material, and therefore function as a stabilized support for the bond wires which otherwise might be broken or displaced in such a manner as to cause a failure of the device. CX 1 ('027 Patent) at Col. 9, lines 1-27; Birchler, Tr. at 317-318, 346; Williams, Tr. at 1472-1473; Schroen, Tr. at 98.

FF A 47. The cantilevered conductors used in Respondents' processes have bond wires attached to an unrestrained end of the conductor. Seiling, Tr. at 596-597.

FF A 48. The unrestrained ends of cantilevered conductors can be

stabilized by attaching around the inside of the conductor tips a strip of "lead frame tape". Seiling, Tr. at 597.

FF A 49. TI and its witnesses contend that two or more cantilevered conductors, while still attached by dam bars and side rails during the molding step, can be read as a single "double-ended" conductor under Claim 1 of the '027 patent. Seiling, Tr. 640-644.

FF A 50. TI's expert witness, Dr. Carl Seiling, had not reviewed the '027 patent prosecution history and art cited therein, and was therefore unable to construe the '027 patent claims with respect to prior art cited during prosecution of the patent or with respect to arguments made during prosecution of the patent. The testimony of TI's expert regarding construction of the '027 claim language is thus limited to interpreting the claims, read in light of the specification, as understood by persons skilled in the relevant arts. Seiling, Tr. 543-548.

FF A 51. U.S. Patent No. 3,171,187, issued on March 2, 1965 to Ikeda, disclosed and claimed a method of attaching semiconductor devices to conductors formed as "inwardly projecting fingers." RX 5 (Ikeda Patent), Col. 2, lines 15-20.

FF A 52. Attachment of bond wires to the tips of conductors is a technique disclosed in the Ikeda patent. Plummer, Tr. at 1340.

FF A 53. The Ikeda patent claims priority from a Japanese application filed May 4, 1962, and therefore constitutes prior art under 35 U.S.C. 102(e) over the '027 patent which has a December 17, 1963 filing date. RX 5; CX 1; Williams, Tr. at 1461-1463; RX 41.

FF A 54. The Birchler and Williams '027 patent and '238 patents issued from divisional applications restricted from the parent application Ser. No.

331,006, filed December 16, 1963. CX 1; CX 4.

FF A 55. In reply to the patent examiner's prior art rejection of Claim 1 in the parent application; TI argued

"Applicants' Claim 1 recites a process of encapsulating a miniaturized semiconductor device and recites the steps of connecting each of the electrical terminals of the semiconductor device to an intermediate point of an appropriate semiconductor disposing the device together with adjacent intermediate portions of the conductor in a mold cavity with the opposite end of each of the conductors extending from opposite sides of the mold cavity and also holding or restraining the portion of the conductors extending from opposite sides of the mold cavity while injecting fluid insulating material into the mold cavity. Increased mechanical stability and reduced risk of breakage were achieved since the terminal connection is at an intermediate point of a conductor whose opposite ends are held at the opposite sides of the mold cavity. Such a process is in no way shown or suggested by Ikeda et al."

4 (Birchler and Williams '238 patent file wrapper) at 82-83 (emphasis in original).

FF A 56. Birchler and Williams further distinguished their Claim 1 over the prior art by arguing:

"Ikeda, et al., show the attachment of the ends of the conductors to the terminals of the semiconductor device. Similarly, Burnes shows the securement of the ends of conductors to a semiconductor device. It is quite clear that neither of these references in any way show or suggest connecting terminals of the semiconductor device to an intermediate point of an appropriate conductor so that the conductors may be arranged to extend from opposite sides of a mold cavity with the portions of the conductors extending from opposite sides of the cavities being restrained."

CX 4 (Birchler and Williams' '238 patent file wrapper) at 83 (emphasis in original).

FF A 57. RX 169 is a demonstrative exhibit which illustrates a modern lead frame comprised of a die pad and surrounding cantilevered conductors. The bond wires are attached to one end of the conductors at the tips located adjacent to the die pad. The conductors are held at the other end by the dam bars. Plummer, Tr. at 1343-1344; RX 169.

FF A 58. Respondents' lead frame conductors are more similar to the Ikeda cantilevered conductors than to the "double-ended" conductors described in Claim 1 of the '027 patent. Seiling, Tr. at 593.

FF A 59. TI's SILECT transistors were switched from a "double-ended" conductor configuration to a more economical single ended, cantilevered configuration within six months of its introduction into the marketplace. Birchler, Tr. at 328, 330, 347.

FF A 60. SILECT transistors based on single-ended, cantilevered conductors did not incorporate the features of "double-ended" conductors described in the Williams lab notebook, the '027 patent disclosure, or in the '027 patent, of securing the conductors against displacement by the injected plastic fluid. Birchler, Tr. at 331-332; RX 41 (Williams Lab Notebook Entry Dated 6/31/63); RX 51 (Patent Disclosure), page 2, subparagraph D.; RPX 87 (Application maturing as the '027 patent); CX 1 ('027 patent).

FF A 61. Dr. Schroen described bond wires as attached "to the fingers of the metallic lead frame" in TI's DRAM products. CX 10 (Schroen Wit. Stmt.) at 54.

FF A 62. Claim 12 reads:

12. The process for encapsulating a semiconductor device comprising:

electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support;

disposing the conductors generally in a common plane;

disposing the device and a major portion of the means for making electrical connection between the terminals and the conductors generally on one side of the place;

disposing the device and portion of the conductors in a mold cavity; and

holding the ends of the conductors extending from the mold cavity while injecting a fluid insulating material into the mold cavity one the other side of the plane to subsequently solidify and embed said device, the fluid insulating material being injected into a portion of the cavity remote from the device and the means electrically connecting the terminals of the device to the conductors,

whereby the fluid will not directly engage the device and electrical connection means at high velocity, and the conductors will be secured against appreciable displacement by the fluid. emphasis added to identify principal elements where infringement is contested

CX 1 at Col. 9, lines 1-27.

FF A 63. Claim 12 of the '027 patent discloses conductors with a semiconductor device connected by bond wires to the conductors on one side of the plane, and with the injection of liquid plastic taking place on the other side of the plane. CX 1, the '027 patent, at Col. 12, lines 26-51.

FF A 64. In the basic processes used by Respondents to plastic encapsulate integrated circuits, the semiconductor device is mounted on a lead frame, the terminals of the device are electrically connected to the lead frame conductors, and the assembly is then encapsulated in plastic via a transfer molding operation. CX (Seiling Witness Stmt.) at 3-4.

FF A 65. The Claim 12 limitation of "electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support" literally requires electrical and mechanical attachment of the semiconductor to a conductor. CX 1 (the '027 patent) at Col. 12, lines 26-51.

FF A 66. In Respondents' processes the semiconductor device is mounted on the "die pad" portion of a lead frame rather than to a conductor. Prior to molding, the die pad is mechanically supported in the mold cavity by "tie bars" which extend outside the mold cavity to the lead frame rails. After

molding, the die pad is supported by the solidified plastic and the tie bars are then severed at the edge of the plastic package. Seiling, Tr. 430, 441, 571, 573.

FF A 67. Figure 3 of the '027 patent shows a transistor 40 attached to a "conductor wire" 12. Fig. 9 shows an assembly, similar to a modern lead frame, with a transistor 142 attached to a "conductor wire" 138. Since transistors require at least three electrodes, each of the three "conductors" shown in Figs. 3 and 12 must act as electrically conductive leads. The '027 drawings and specification therefore identify "conductors" as structures which transmit electrical loads or impulses in the finished product. CX 1; Birchler, Tr. 318-320.

FF A 68. In the accused products, the die pads and tie bars do not act as electrical conductors during manufacture nor during operation of the finished product in that they do not conduct electrical loads or impulses. Seiling, Tr. at 573.

FF A 69. Integrated circuits are commonly attached to die pads by adhesives which contain silver fillers. Those fillers help dissipate heat generated by the device. Plummer, Tr. at 1342.

FF A 70. TI uses die attach compounds which glue the semiconductor chip to the die pad and also contain silver fillers for heat dissipation. Such compounds have low concentrations of silver filling and would be highly resistant to electrical conductivity. Schroen, Tr. at 169-174.

FF A 71. Figure 3 of the '027 patent shows a transistor 40 attached to a "conductor wire" 12. Fig. 9 shows an assembly, similar to a modern lead frame, with a transistor 142 attached to a "conductor wire" 138. Each of the three "conductors" shown in Figs. 3 and 12 must act as an electrically

conductive lead. The '027 drawings and specification therefore indicate that "conductors" are structures which transmit electrical loads or impulses in the finished product. "Conductors" in the '027 patent do not include die pads which do not conduct electrical loads or impulses in the finished product. CX 1; Birchler, Tr. 318-20.

FF A 72. The Claim 12 step of "mechanically attaching a portion of said [semiconductor] device to at least one of the conductors for support" has the function of mechanically supporting the semiconductor in the mold, thereby enabling plastic fluid to flow around all sides of the device, and preventing dislocation of the device by the plastic fluid flow. Seiling, Tr. 430, 441, 571, 573.

FF A 73. In Respondents' processes the die pad functions to mechanically suspend the semiconductor in the mold cavity. The mechanical suspension is accomplished by way of supporting tie bars rigidly extending from the die pad through the cavity wall and attaching to the lead frame rails. Suspension of the semiconductor device in the mold cavity results in plastic flow around all sides of the device, with the result of preventing dislocation of the device by the plastic flow. Plummer, Tr. at 1341, 1418.

FF A 74. Claim 12 requires electrical connection and mechanical attachment of the semiconductor to a conductor, serving a dual function of suspending the device in the mold cavity and conducting electrical loads and signals between the device and the conductors. CX 1 (the '027 patent), at Col. 12, lines 26-51.

FF A 75. Each of the drawings in the '027 patent depicts the relative positions of the gate, semiconductor device and whisker wires and all show opposite-side gated configurations. Plummer, Tr. at 1387-1390; CX 1, Figs. 5,

9 and 10.

FF A 76. The '027 patent does not show or explicitly describe any configuration of the gate, semiconductor device and whisker wires other than opposite-side gated configurations. Plummer, Tr. at 1390.

FF A 77. Claim 12 is limited to those processes where the conductors are disposed in a plane, the semiconductor devices and bond wires are attached to the conductors generally on one side of that plane, and the insulating fluid is injected through a gate on the opposite side of the plane. CX 1 (the '027 patent), at Col. 12, lines 26-51.

FF A 78. The '027 specification explains that the insulating material is injected through the gate 88 in Fig. 5 into the lower mold cavity, that the conductor wires are clamped between the upper and lower molds, and that attached to the conductors are the semiconductor and bond wires which are positioned in the upper mold cavity. CX 1 (the '027 patent), Col. 5, lines 34-59.

FF A 79. Respondents manufacture plastic encapsulated integrated circuits by processes using both same-side gated and opposite-gated molds. CX 95, CX 145, CX 395, CX 400.

FF A 80. Figure 10 of the '027 patent shows a gate scar on the opposite side of the conductors from the semiconductor and whisker wires shown in corresponding Figure 9. Birchler, Tr. at 293.

FF A 81. Respondents' opposite-side gated processes literally embody the Claim 12 element of injecting the plastic on the opposite side of the conductors from the device and bond wires. CX 8 (Seiling Wit. Stmt.), ¶¶ 200-201.

FF A 82. On June 15, 1989, TI argued to the Commission that a DRAM gate

scar revealed the "place of injection being below the plane of the lead frame and, therefore, on the opposite side of the lead frame from the device and the electrical connections. DRAMs, Brief Of Complainant Texas Instruments Incorporated On Remedy, Public Interest And Bonding Issues, Exhibit 5 "Affidavit Of John W. Orcutt" (June 15, 1989).

FF A 83. INTENTIONALLY OMITTED

FF A 84. The transfer molding work leading to the invention claimed in the '027 patent was primarily conducted by Mr. Williams in conjunction with molding equipment and product vendors. Williams, Tr. at 1460-1461; Birchler, Tr. at 276, 285, 358

FF A 85. Mr. Williams utilized processing parameters for the Low Cost Transistor Project experiments, including mold temperature, RAM speed and ram pressure which were given to him by the vendors of the molding compound. Williams, Tr. at 1502.

FF A 86. On May 29, 1963, Mr. Williams traveled to Dow Chemical Corporation in Midland, Michigan to attempt transfer molding of transistors mounted on a header. In the first set of experiments the semiconductor, the connecting wires and the gate were in the bottom portion of the mold, a same-side gated configuration. In these experiments, none of the devices were successfully encapsulated. In the second set of experiments, the semiconductor and the connecting wires were in the top portion of the mold while the gate remained in the bottom portion, an opposite-side gated configuration. These experiments succeeded in producing good, working units. Williams, Tr. at 1461-1463; RX 41

FF A 87. Birchler and Williams had not decided how to encapsulate their low cost transistors prior to Mr. Williams' experiments at Dow Chemical.

Williams, Tr. at 1463.

FF A 88. Mr. Williams first conceived of the opposite-side gating configuration during his trip to Dow Chemical and, based on those experiments, Williams and Birchler decided to incorporate that configuration in subsequent molds. Williams, Tr. at 1463-1464.

FF A 89. Birchler and Williams decided to pursue transfer molding as the packaging means for the Low Cost Transistor Project. Birchler, Tr. at 287, 367; Williams, Tr. at 1463.

FF A 90. The invention disclosure statement that "Better results are obtained when the unit was in the top half of the mold so it did not see the plastic as it is initially introduced into the mold" reflected Mr. Williams' belief that the molding compound after entering the mold, went across the bottom half so as not to initially engage the device located in the top half of the mold. Williams, Tr. at 1466, 1469-1470.

FF A 91. In 1963 Mr. Williams had no direct means of knowing how molding compound filled his mold cavities. However, he did observe short shots which provided some idea of how the molding compound flowed. He conducted experiments and tested the damage which results from same-side gated configurations and opposite-side gated configurations, and he believed that while some molding compound might directly enter the top half of the mold cavity, the molding compound basically flowed as shown by the arrows in Figure 5 of the '027 patent. Williams, Tr. at 1468, 1466, 1462-1463, 1468, 1471, 1505-1506.

FF A 92. While Mr. Birchler has not observed the flow of plastic through a mold cavity, the flow pattern shown in Figure 5 and the description at Col. 5, lines 46-50 reflected his understanding that the plastic flow started

out across the bottom of the mold cavity and progressed to fill the remaining portion of the cavity. Birchler, Tr. at 310, 354-355.

FF A 93. Birchler and Williams knew from their experiments that as the plastic entered the mold cavity there was some substantial region of high velocity which damaged the whisker wires, which they later avoided by placing the whisker wires outside the path of that high velocity plastic. Birchler, Tr. at 309-310.

FF A 94. Birchler and Williams found that gate location was a critical element of a successful transfer molding process for transistors. Birchler, Tr. at 348-349.

FF A 95. Birchler and Williams did not measure the plastic fluid's flow velocity during their experiments. Birchler, Tr. at 352.

FF A 96. Mr. Hightower's 28 years of experience in plastic encapsulating integrated circuits at TI has demonstrated that gate location is a critical element of successful plastic encapsulation of integrated circuits. CX 12, (Hightower Wit. Stmt.) at 1828-1829.

FF A 97. Whisker wires will be damaged if the plastic is injected through a gate which directs the plastic flow against the side of the whisker wires. CX 12 (Hightower Wit. Stmt.), DRAMs Tr. at 1829.

FF A 98. During the time frame of Birchler and Williams' developmental work on low cost transistors, there were no automatic transfer speed controls on the Hull Company presses. CX 12 (Hightower Wit. Stmt.), DRAMs Tr. at 1844-1845.

FF A 99. During the transfer molding step, several interrelated factors can result in damaged semiconductors or wire bonds. Schroen, Tr. at 175.

FF A 100. High speed, high ram pressure, or high temperatures can cause

the molding compound to "squirt" or "jet" into the mold cavity. Schroen, Tr. at 182-183, 186.

FF A 101. "Jetting" plastic can damage delicate semiconductor device and wire bonds. Schroen, Tr. at 188-189.

FF A 102. If the molding compound "jets" on the same-side of the lead frame as the side on which the wire bonds are located, there is a good probability that the jet could cause damage to those wires. Schroen, Tr. at 189.

FF A 103. The relatively high viscosity of current molding compounds at normal operating temperatures, and the low ram speed and pressure used in normal molding operations avoid the "jetting" of plastic flow which might damage the semiconductor device and wire bonds. Schroen, Tr. at 195.

FF A 104. Mr. Williams generally recorded in his laboratory notebook all information necessary to replicate his experiments, but because molding process parameters are specific to the particular equipment and products in use, and because the molding equipment and product vendors supplied process specifications, Williams felt it was unnecessary to record the process parameters used in the experiments conducted at Dow Chemical. Williams, Tr. at 1503.

FF A 105. Mr. Williams selected experimental molding conditions or parameters based on information he obtained from vendors of transfer molding equipment and plastic molding compounds. Birchler, Tr. at 276.

FF A 106. Mr. Birchler does not recall knowing the molding temperatures, ram speeds or ram pressures which Mr. Williams selected for their transfer molding experiments. Birchler, Tr. at 277, 358.

FF A 107. The primary factors which determine the velocity at which the

molding compound engages the semiconductor device are ram speed, ram pressure and the viscosity of the molding compound. Plummer, Tr. at 1334.

FF A 108. Birchler and Williams discovered that transfer molding processes for delicate transistors and bond wires could be improved by not directing the plastic at the bond wires. They avoided that direct contact by locating the gate on the opposite side of the mold cavity from the semiconductor device and bond wires, off-setting the gate from the center line of the package where the transistor was located, and placing the gate as remotely as possible from the transistor and bond wires. Birchler, Tr. at 303-304

FF A 109. The arrows shown in Figure 5 of the '027 patent illustrate the inventors' understanding, as of the date of their patent application, of how the molding compound flowed through the mold cavity. Birchler, Tr. at 308-309.

FF A 110. To an engineer skilled in the art of transfer molding, the arrows shown in Figure 5 of the '027 patent illustrate the flow of molding compound through the mold cavity. Williams, Tr. at 1499-1500.

FF A 111. Mr. Birchler created the sketch which appears in Figure 5 of the '027 patent. Birchler, Tr. at 308.

FF A 112. Mr. Williams currently does not know how molding compound moves through mold cavities, therefore he does not know if Respondents' "jetting" short shot exhibit (RPX 90-A) accurately illustrates how molding compound moves through an integrated circuit mold cavity. Williams, Tr. at 1501-1502; RPX - 90A; See SF 85, p. 26.

FF A 113. When Mr. Plummer was performing developmental work in 1963 on transfer molding of integrated circuits, he observed half-filled molds where

the molding compound had "kicked over" the mold cavity, a process that he now recognizes as jetting. Plummer, Tr. at 1436-1437.

FF A 114. In Fig. 5 of the '027 patent, the arrows shown in the bottom half of the mold cavity are consistent with the jetting of molding compound across the bottom of the mold before migrating to the top half of the mold. Plummer, Tr. at 1328-1329, 1437-1438.

FF A 115. A major teaching of the '027 patent is that locating the die and bond wires on the opposite side of the lead frame from the gate avoids damaging those delicate components by removing them from the pathway of the injected plastic. Plummer, Tr. at 1438.

FF A 116. Short shots demonstrate that, under TI's recent processing conditions, flipping the semiconductor device between the same and opposite side of the lead frame makes no difference in how the molding compound flows through the mold cavity. Schroen, Tr. at 34, 225-226; CPX 568-A; CPX 568-B.

FF A 117. [C

] Seiling, Tr. at 489-492.

FF A 118. In his twenty years of experience in plastic encapsulating integrated circuits, Mr. Hightower has seen short shots which indicated a range of patterns by which plastic flows through mold cavities. While simultaneous filling of the top and bottom cavities is very desirable, this is rarely achieved. Hightower, Tr. at 257, 3.

FF A 119. Respondents can now inject plastic into the mold on either side of the lead frame without damaging the semiconductor device and bond

wires, a process accomplished by controlling a variety of process parameters, in particular ram speed, ram pressure and the temperature of the molding compound. Plummer, Tr. 14.

FF A 120. In the parent application, Ser. No. 331,006, the applicants distinguished claim 12 over Ikeda in light of Burns and the GE literature by stating "none of these references alone or in combination in any way show or suggest the step of injecting fluid insulating material into a mold cavity on an opposite side of the common plane defined by the conductor wires from the side on which the device and a major portion of the means making electrical connection between the device and the conductor wires are disposed." CX 87, Amendment, December 16, 1963 at File Wrapper 93.

FF A 121. TI has stated in the past to the Commission, that opposite-side gate locations result in "injection on the opposite-side of the plane". DRAMs, Brief Of Complainant Texas Instruments Incorporated On Remedy, Public Interest And Bonding Issues, Exhibit 5 (Affidavit Of John W. Orcutt) June 15, 1989.

FF A 122. TI argued to the Commission that a DRAM gate scar revealed the "place of injection being below the plane of the lead frame and, therefore, on the opposite side of the lead frame from the device and the electrical connections." DRAMs, Brief Of Complainant Texas Instruments Incorporated On Remedy, Public Interest And Bonding Issues, Exhibit 5 "Affidavit Of John W. Orcutt" June 15, 1989 [emphasis added].

FF A 123. When the Patent Office initially rejected Claim 12 as obvious over certain prior art, TI argued that Claim 12 was limited to processes injecting the plastic on the opposite side of the conductors from the device and bond wires, whereas in the prior art the plastic was injected on the same

side of the conductors as the semiconductor and bond wires. In the parent application of the '027 patent, the applicants distinguished claim 12 over Ikeda in light of Burns and the GE literature by stating

"none of these references alone or in combination in any way show or suggest the step of injecting fluid insulating material into a mold cavity on an opposite side of the common plane defined by the conductor wires from the side on which the device and a major portion of the means making electrical connection between the device and the conductor wires are disposed."

CX 87 (Amendment, December 16, 1963) at File Wrapper 93.

FF A 124. In both opposite-side gated and same-side gated molds, under currently employed "normal operating conditions" the plastic is injected through a gate into the mold cavity and quickly expands to form a plug which flows across the cavity to the opposing cavity wall. However, at higher injection pressures, at higher injection speeds, and perhaps at higher temperatures, the plastic can enter the cavity at a higher velocity and squirts or "jets" in a direct stream across the cavity, only then expanding to meet the cavity walls. Plummer, Tr. at 1423-14, 1436; Seiling, Tr. at 490-491.

FF A 125. In Respondents' current transfer molding operations, molding compound assumes a plug flow within a very short distance after entering the mold cavity. That plug flow forms regardless of whether the gate is on the top or bottom of the mold cavity and before the molding compound reaches the semiconductor device. Plummer, Tr. at 1423-14.

FF A 126. Under proper process conditions, once the molding compound assumes a plug flow, it is no longer moving at a high velocity so as to damage the semiconductor device. Plummer, Tr. at 14.

FF A 127. Claim 14 reads:

14. A process of encapsulating a semiconductor device comprising:

providing electrical connections between electrical terminals of the device and a plurality of conductors arranged in a substantially common plane, said device and the thusly provided electrical connections thereto being disposed on one side of said plane,

holding the conductors while injecting a fluid insulating material into the mold cavity for subsequently solidifying and embedding said device,

the fluid insulating material being injected into a portion of the cavity on the opposite said of said plane to preclude direct high velocity engagement between the fluid and the device and the electrical connections thereto. (emphasis added to identify principal elements where infringement is contested)

CX 1 at Col. 13, lines 3-21.

FF A 128. Claim 14 is limited to processes in which the semiconductor device is electrically connected to one side of a plurality of conductors where the electrical connections are disposed on the side of the plane and where the conductors are held while insulating fluid is injected into the mold cavity on the opposite side of the conductors from the device and the bond wires. CX 1, the '027 patent, at Col. 13, lines 3-20.

FF A 129. Claims 14 and 17 are broader than Claim 12. Claim 12 is limited to processes where the semiconductor device is mechanically attached to one of the conductors arranged in substantially the same plane as the other conductors. CX 1 (the '027 patent), at Col. 12, lines 26-51, Col. 13, lines 3-20, Col. 14, lines 6-23.

FF A 130. Respondents' opposite-side gated products embody the claim limitation of injecting the plastic fluid on the opposite side of the plane of the conductors from the semiconductor device and bond wires, but Respondents' same-side gated products do not meet that limitation. CX 8 (Seiling Wit. Stmt.) ¶¶ 200-01; Plummer, Tr. 1384.

FF A 131. Claim 17 reads:

17. A process of encapsulating a semiconductor device comprising:

providing electrical connections between electrical terminals of the device and a plurality of conductors arranged substantially parallel to one another, said device and the thusly provided electrical connections thereto being provided on one side of said conductors,

disposing the device and portions of the conductors in a mold cavity, and

holding the conductors while injecting a fluid insulating material into the mold cavity for subsequently solidifying and embedding said device,

the fluid insulating material being injected into a portion of the cavity on the opposite side of said conductors to preclude direct high velocity engagement between the fluid and the device and the electrical connections thereto. (emphasis added to identify principal elements where infringement is contested).

CX 1 at Col. 14, lines 6-23.

FF A 132. The plain language of claim 17 is met when all, not only two, of the conductors are substantially parallel to one another. Plummer, Tr. 1422-1423.

FF A 133. Respondents' products do not incorporate conductors all of which are substantially parallel to one another. CX 40, 49-52, 55, 76-77, 107-110, 122-124, 155, 183-185, 205.

FF B 1. In the late 1950's and early 1960's, the principal semiconductor devices being produced in any quantity were diodes and transistors. Many companies were engaged in the design and manufacture of these devices, including Texas Instruments, Motorola, Inc., Sylvania Electric Products, Inc., Radio Corporation of America, International Business Machines Corporation, Fairchild, General Electric, Bell Laboratories and Western Electric. CX 5 (admitted Partial Mathias Finding of Fact 9) p. 2.¹

FF B 2. RX 32 is a 1962 handbook entitled "ELECTRICAL ENCAPSULATION" authored by employees of Emerson Cuming. In a section entitled "MOLDING" (page 81 et seq.), the book states:

Direct encapsulation of small components by transfer molding techniques is now possible. Sparking this advance has been the development of epoxy powders (Fig. 7.6) and of automatic equipment for low - and moderate - pressure transfer molding (Fig. 7.7) (Emphasis in original).

CX 5, p. 8 [admitted Mathias Finding of Fact 23].

FF B 3. Figure 7.6 of the book is a photograph (courtesy of the Hull Corporation) with the caption: "Epoxy Transfer Molding Components are Available in a Variety of Forms." Figure 7.7 entitled "Horizontal Transfer Molding Press for Small Components" and related photographs from Hull (see Figs. 7.8A-H) provides:

Extremely delicate elements have been processed successfully at lower plunger head pressures. These include diodes and rectifiers, deposited carbon and metal film resistors, and miniature wire wound devices. Recently developed and now in use on a production basis is processing for encapsulation of fragile diodes using very

¹ CX 5 is the California Respondents' Response to TI's First Request for Admissions, which requested the California Respondents to admit or deny many of Judge Mathias' findings of fact from the second Initial Determination in the DRAMs investigation. USITC Investigation No. 337-TA-242. Where only part of an admitted Mathias Finding is set forth as a Proposed Finding, the citation will read, as here, "admitted partial Mathias Finding #."

low viscosity epoxy transfer molding compounds at a plunger head pressure of 200 psi.

CX 5, p. 8 [admitted Mathias Finding of Fact 1].

FF B 4. Transfer molding is defined as the "process of forming articles, in a closed mold, from a thermosetting material that is conveyed under pressure, in a hot plastic state, from an auxiliary chamber." A thermosetting plastic (i.e., a plastic that first melts with the application of heat and then sets or hardens in an irreversible reaction) is first melted in a cylinder and then "transferred" or forced out of the cylinder through a pipe-like runners into one or more mold cavities. The transfer of the plastic occurs under controlled pressure and velocity conditions and at low plunger head pressures. The device to be encapsulated is held or supported in the cavity and the plastic is made to follow around the device and encapsulate it. After hardening, the encapsulated device is removed from the mold and the process is repeated. CX 5 (admitted Mathias Finding of Fact 28) pp. 11-12.

FF B 5. Transfer molding was introduced by the Shaw Insulator Company in 1926. Following WWII, the introduction of high-frequency dielectric preheating and steam preheating greatly accelerated the growth of transfer molding. The speed of transfer and cure times were markedly increased, and lower pressures could be used. CX 5 (admitted Mathias Finding of Fact 29) p. 12.

FF B 6. In 1957, when Plummer joined the Hull Corporation, Hull had a line of molding presses for molding thermosetting plastics. Plummer, Tr. 1309.

FF B 7. Mr. Hull testified [in the DRAMs investigation] that among the reasons for the acceptance of transfer molding was its ability to mold very thin parts and to mold around inserts which might be needed in a final molded

part. In the early days, inserts were often nuts or bolts, so that threaded parts could be available in the molded part for the ultimate use of the molded part. This insert molding application of transfer molding was further refined by the Hull Corporation when it recognized that transfer molding was also a viable way to encapsulate electrical and electronic devices. Hull Corporation started electrical device encapsulation in the late fifties on fairly simple items such as resistors and certain types of capacitors. Hull Corporation consulted with manufacturers of electronic components to develop plastic encapsulations for their devices, with the idea that it would provide a cheaper way to produce such devices in very high production quantities. CX 5 (admitted Mathias Finding of Fact 30) pp. 12-13.

FF B 8. During the period between 1957 and 1963, the semiconductor field embraced quite aggressively the technique of packaging components in plastic by transfer molding. Plummer, Tr. 1313.

FF B 9. In 1958, Bell Labs approached Hull Corporation to transfer mold a double diode device. Plummer and Hull told Bell Labs that the part was too delicate; that it would not survive the transfer molding process. Bell Labs indicated the importance of attempting to transfer mold the double diode device, and Hull attempted to transfer mold sixty pieces. Fifty six pieces tested positive, beginning a long commercial relationship between the Hull Corporation and Bell Labs and Western Electric. CX 5 (admitted Mathias Finding of Fact 31) p. 13. This showed that delicate semiconductor diode devices could be transfer molded successfully.

FF B 10. During the period of time from 1958 to 1963, Hull had the opportunity to work with virtually every manufacturer of semiconductors and went from transfer molding axial lead diodes to transistors to integrated

circuits. Plummer, Tr. 1314.

FF B 11. Robert Zecher was a sales engineer working for Mr. Plummer at the Hull Corporation in 1962. Plummer, Tr. 1379.

FF B 12. Robert Zecher's article, entitled "High Production Encapsulation of Electronic Devices," published in 1962, refers to the desirability of planar leads when encapsulating electronic devices by transfer molding. In the article, Mr. Zecher states on page 7: "Many manufacturers who have been skimming through product development without giving much thought to final packaging are now beginning to wish that they had used stiffer leads which could support the device in a mold, that the lead configuration occupied only one plane, so the mold need only have one parting line..." Plummer, Tr. 1377-79; RX 478.

FF B 13. In 1962 Dow Corning offered to the industry silicone molding compounds which it suggested for use in transfer molding transistors. RX 22; RX 23.

FF B 14. George Doyle, an engineer at Motorola, transfer molded rectifiers and diodes as early as 1961 using a twenty-five ton Hull transfer press, model 359D, at least for experimental purposes. Doyle later constructed his own transfer press, and by July of 1962, Doyle sought to purchase a transfer press for his laboratory with better controls such as speed, pressure and temperature. Doyle, Tr. 954-55; RX 330 (admitted Partial Mathias Finding of Fact 42) p. 7 .²

FF B 15. In 1962, after Doyle had developed plastic encapsulated diodes and rectifiers for Motorola, he became interested in finding out whether

² RX 330 is TI's Response to the California Respondents' First Request for Admissions, which requested TI to admit or deny many of Judge Mathias' Findings of Fact.

transistors could be transfer molded. Doyle, Tr. 960; RX 113.

FF B 16. Doyle decided to attempt to transfer mold the TO-18 transistors that Motorola was making at that time, which were enclosed using a steel can hermetically sealed to a glass header. Doyle, Tr. 957-58.

FF B 17. Doyle built a transfer molding press to transfer mold the TO-18 transistors. Doyle, Tr. 958.

FF B 18. From the production line at Motorola, Doyle obtained some of the TO-18 transistors with just the header, i.e., before the metal can had been sealed to the header. Doyle, Tr. 957-58.

FF B 19. Between the time that Doyle first decided to try to transfer mold a transistor with a header and the time actual transfer molding occurred, a couple of months elapsed, because Doyle had to build and design the mold and fixtures to do the actual molding. Doyle, Tr. 963-64.

FF B 20. By the end of 1962, Doyle had successfully transfer molded these transistors with headers. Doyle, Tr. 958-60; Bell, Tr. 996-98; RPX 67.

FF B 21. These transistors were initially subjected to tests, which they successfully passed to determine if there were any shorts or opens. Doyle, Tr. 958-59; Bell, Tr. 997.

FF B 22. These transistors with headers were subsequently subjected to life tests, which they successfully passed. Doyle, Tr. 958-59; Bell, Tr. 997-98.

FF B 23. The transistors with headers had their leads arranged in a pin circle configuration, i.e., the leads were non-planar. Doyle, Tr. 957-58.

FF B 24. In these transistors with headers, two of the terminals of the device were connected to two of the leads through the use of one-mil diameter gold wires. Doyle, Tr. 957-58.

FF B 25. Transfer molding was successfully carried out without damage to these bond or whisker wires. Doyle, Tr. 958-59.

FF B 26. Doyle then designed a transistor to be transfer molded without a header, and a mold to be used in this project. Doyle, Tr. 961; Bell, Tr. 998.

FF B 27. By May 1963, Doyle successfully transfer molded a transistor without a header. RX 113.

FF B 28. Between the time that transistors with headers were successfully molded and the time that headerless transistors were successfully molded, several months elapsed. During this time Doyle was building and designing a mold and a mold press for use in the headerless project. Doyle, Tr. 964.

FF B 29. After his first attempts at transfer molding headerless transistors, Doyle knew almost immediately that he had a working process, because when the units came off the press they were tested for continuity and shorts, and they passed these tests. Doyle, Tr. 963.

FF B 30. This headerless transistor included a semiconductor device mounted on one lead and fine one-mil bond wires running from the device to two other leads. Doyle, Tr. 961, 975-76; RPX 83.

FF B 31. Hundreds of transistors were made by this process and subjected to environmental and life tests. The yield of good units was very high. Doyle, Tr. 962-63, 975-76; RX 113.

FF B 32. Doyle submitted an invention disclosure to the Motorola Patent Committee describing this invention. Doyle, Tr. 962; RX 113.

FF B 33. In Doyle's invention disclosure, dated May 22, 1963, the name of the invention is given as "Surmetic Headerless Transistor (TO-18) and

method of assembling and handling the device without using a header." RX 113.

FF B 34. Between the time in early 1963 when Doyle first transfer molded transistors without headers, and May, 1963, when he submitted the invention disclosure on that invention (RX 113), Doyle made hundreds of headerless units and put them on life and environmental tests with good results. Doyle, Tr. 962-63.

FF B 35. At the time of submitting the patent disclosure on May 22, 1963, the transfer molded headerless transistors had been built and tested and this is indicated in the disclosure. Doyle, Tr. 962-63; RX 113.

FF B 36. The Motorola Patent Committee approved filing of a patent application on Doyle's invention on October 25, 1963. The patent application was filed on January 15, 1964. RX 60, pp. 15-16.

FF B 37. Doyle's invention disclosure indicates that he conceived his idea for transfer molding a transistor in June, 1962. RX 113.

FF B 38. Doyle's invention disclosure notes that the invention was disclosed to Harold Bell in June, 1962. RX 113.

FF B 39. INTENTIONALLY OMITTED

FF B 40. Doyle indicated in his invention disclosure that the absence of header was an important aspect of his invention. In the invention disclosure, he stated: "The most salient features of this device are: 1. No header." In the disclosure Doyle also stated that "special gating techniques permit filling of the cavity without exerting damaging forces on the fragile wire bonds," but he disclosed no specific technique in his Invention Disclosure on the '025 patent. RX 113; RX 11.

FF B 41. Mr. Doyle stated that by use of the term "special gating techniques permit filling of the cavity without exerting damaging forces on

the fragile wire bonds" he meant that the gate was placed on the other side of the plane formed by the device and whisker wires so as to prevent direct engagement of these fragile parts by the fluid entering the cavity. Doyle, Tr. 977-78; Bell, Tr. 1003-04; RX 113.

FF B 42. The patent disclosure led to a patent application which became U.S. Patent No. 3,367,025. Doyle, Tr. 964; RX 11.

FF B 43. The patent accurately describes the mold used by Doyle to make headerless transistors such as RPX 83. Doyle, Tr. 964; Bell, Tr. 1001.

FF B 44. As shown in the Doyle '025 patent, the Doyle headerless transistor had three leads with nail heads formed on their tops. Doyle, Tr. 965-66; Bell, Tr. 1001-02; RX 11; RX 172; RPX 13.

FF B 45. The leads were held in a triangular or "pin circle" arrangement by a jig which formed the floor of the mold. Doyle, Tr. 965-66; 975-83; RX 11.

FF B 46. Although distances are not set forth in the '025 patent, all of these nail heads were raised up approximately 50 mils from the bottom of the mold. One lead however was lower by 10-15 mils from the other two leads. Doyle, Tr. 966-67; Bell, Tr. 1002-03; Plummer, Tr. 1350-51; RX 320(j); RPX 98(j).

FF B 46a. Figure 4 of the Doyle '025 patent shows the gate being located at the parting line between the jig (24) and the upper portion of the mold (45). The specification discloses that "[t]he flats 30, 31, and 32 [i.e., nail heads] on the wires are positioned a given distance above the surface formed by the top portion of the three clamping parts [of the jig]." Col. 3, lines 1-4. The '025 specification does not disclose any particular length or purpose of the "given distance" in the molding process, but does show the nail

heads, semiconductor device or whisker wires as situated above the flow of plastic through the gate and into the upper mold cavity. RX-11.

FF B 47. The nail head lead on which the device was mounted was located beneath the other two nail head leads because at the time it was conventional practice to wire bond uphill so that the bond wires would not sag onto the device or the lead on which the device was mounted, thereby causing a short. Doyle, Tr. 967; Bell, Tr. 1003.

FF B 47a. Leads in a pin circle arrangement are not in a common plane. Doyle Tr. 984.

FF B 48. The representation on the right-hand side of RPX 98(j) accurately represents the lead arrangement in the transistors that Doyle molded. It shows the nail heads raised off the floor of the mold by about 50 mils with the lead on which the device is mounted about 10-15 mils below the others. Doyle, Tr. 966; RX 320(j); RPX 98(j).

FF B 49. Figures 3C and 3D of the Doyle '025 patent show the nail head leads being raised off the floor of the mold. This is illustrated by the additional ring under the nail head leads 31 and 32 in Figure 3C and 3D. Under this arrangement the plastic completely encapsulated the ends of the leads, the device and its connecting wires. Doyle, Tr. 968-969; RX 11.

FF B 49a. The Board of Appeals also noted that appealed Claims 15, 18 and 21-24 (issued as 12, 13, and 14-17) was distinguishable over Doyle because:

These appealed claims recite specific arrangements of the connectors, connections and semiconductor wafer within the cavity. Specifically, the conductors, not parts of them, are defined to be in a parallel or common plane. [Emphasis added]. Doyle's flats 31 and 32 are described as being in a plane slightly above flat 30. These appealed claims when given the broadest reasonable interpretation in light of the specification . . . are not rendered obvious by the invention

of Doyle.

CX-2, Paper No. 20 (Nov. 30, 1976).

FF B 50. In the Doyle '025 patent the silicon chip (or device) was mounted and electrically bonded to the lower nail head. Doyle, Tr. 965-68, 975; RX 320(j); RPX 98(j).

FF B 51. Fine one mil bond wires were run from the device to the other nail heads. Doyle, Tr. 961, 965-68, 975-76; RX 320(j); RPX 98(j).

FF B 52. This structure was then enclosed by the top half of the mold which contained the entire mold cavity. Doyle, Tr. 965, 975; RX 320(j); RPX 98(j).

FF B 53. The gate was located at the parting line between the upper portion of the mold containing the entire cavity and the jig, thus, putting it on the floor of the mold cavity. Doyle, Tr. 968; RPX 98(vv).

FF B 54. INTENTIONALLY OMITTED

FF B 55. INTENTIONALLY OMITTED

FF B 56. The gate was thus below the three nail head leads. Doyle, Tr. 978; RPX 98(j); RPX 98(vv); RX 11.

FF B 57. INTENTIONALLY OMITTED

FF B 58. Doyle designed his gate location so that as the plastic came into the cavity, it would not impinge directly on the fine bond wires. Doyle, Tr. 977-78; RX 113.

FF B 59. Once the mold had been closed, a plunger forced plastic material through a gate into the cavity to encapsulate the transistor. The mold was subsequently opened and the transistor was removed. Doyle, Tr. 972-73.

FF B 60. The Doyle '025 patent describes a process of encapsulating a

transistor in which three leads are held a given distance above the floor of the mold cavity. The end of each of these leads which is within the mold cavity is coined, or flattened. Two of these flattened ends are held in one plane, while the third one, on which the device rests, is held slightly below the other two. At column 3, lines 4-5, the patent states: The flats 30, 31 and 32 on the wires are positioned a given distance above the surface formed by the top portion of the three clamping parts. The flats 31 and 32 on wires 15 and 16 are in the same plane slightly above the flat 30 on wire 14. RX 11.

FF B 61. Doyle testified that in his process the mold gate was located between the emitter lead and the base lead. Doyle, Tr. 970.

FF B 62. At the hearing, Doyle labeled figures 2 and 3D of the Doyle '025 patent (RPX 13) to show his understanding of how the plastic flowed through the mold gate in his process. The path of the fluid he showed in labeling these figures was parallel to the whisker wires 18 and 19. Doyle, Tr. 972-973; RX 172; RPX 13.

FF B 63. At the hearing Doyle identified samples of transistors, both one with a header (RPX 67) and one without a header (RPX 83) which he had transfer molded in 1962 and 1963. Doyle, Tr. 959-61, 961-62. He also identified an x-ray (RX 320(i); RPX 84; RPX 98(i)) of the headerless transistor showing the leads raised up off the bottom. Doyle, Tr. 974.

FF B 64. INTENTIONALLY OMITTED

FF B 65. INTENTIONALLY OMITTED

FF B 66. During the early 1960's, Robert Helda and Milan Lincoln worked at Motorola to develop a low-cost transistor. William Lehner was one of their supervisors. CX 5 (admitted Mathias Finding of Fact 56) p. 25 ; CX 16 (Doyle, DRAM, Tr. 1225).

FF B 67. In May of 1963, Helda and Lincoln prepared and submitted a proposal at the direction of Lehner entitled "Proposal for Inexpensive Entertainment Device Package." CX 5 (admitted Partial Mathias Finding of Fact 57) p. 26.

FF B 68. This proposal (at p.2, par. 6) dated May 17, 1963, mentioned, in general their approach to transfer molding a transistor. RX 76.

FF B 69. In the proposal, Helda and Lincoln estimate that the unit cost of each transistor, when the transistors are produced in quantities of ten million units, should be sixteen cents each. RX 76.

FF B 70. On August 28, 1963, Motorola had its first meeting on the implementation of the Helda-Lincoln approach. At the August 28th meeting, Motorola discussed the need to make some units so that those units could be tested and the process evaluated. The projection on August 28 was that "finished transistors should be forthcoming 6-8 weeks from the date of the meeting, i.e., by 10- October 1963." RX 330 (admitted Mathias Finding of Fact 59) p. 11.

FF B 71. The device depicted in the May 1963 Helda-Lincoln proposal was in the experimental stage in August of 1963. By October 4, 1963, at least twenty-five of the Helda-Lincoln devices had been produced and tested by Motorola. RX 330 (admitted Mathias Finding of Fact 60) p. 11.

FF B 72. On November 6, 1963, Motorola held a second meeting to discuss their progress on the Helda-Lincoln approach. One thousand of the units had been produced by November 19, 1963. RX 330 (admitted Mathias Finding of Fact 61) p. 11.

FF B 73. Helda and Lincoln filed an application for a patent on June 18, 1965. On May 13, 1969, the Helda-Lincoln application matured into U.S.

Letters Patent 3,444,441. RX 330 (admitted Partial Mathias Finding of Fact 62) pp. 11-12.

FF B 74. The Helda-Lincoln proposal sets forth eight steps to be used in manufacturing a transfer molded transistor. RX 76.

FF B 75. The eight steps are as follows: 1. Selecting a strip of nickel from which a lead frame will be punched. 2. Punching a lead frame from the strip of nickel. 3. Placing a gold substrate on the tips of the leads to facilitate wire bonding. (Helda and Lincoln note that this step is optional, in that the strip of nickel could be purchased with a ribbon of gold already on it.) 4. Bonding the die to the center lead. 5. Wire bonding the die to the two outer leads. (Helda and Lincoln note that "this system is also compatible with the recently developed high speed wire bonding with only minor modifications to handle the greater belt width."). 6. Transfer molding the transistors. 7. The end rail on the lead frame is clipped off. 8. The transistors, which are still held to each other by the plastic, are tested and then separated. RX 76.

FF B 76. The Helda and Lincoln approach called for supporting the die at the end of the conductor in a stamped lead frame with a gate location opposite the end of the center lead. The gate was located perpendicular to the whisker wires and directly in line with the device. The finished product was to be encapsulated using the encapsulating techniques being used in Omar Sturm's diode assembly area. This meant transfer molding. RX 330 (admitted Mathias Finding of Fact 58) pp. 10-11.

FF B 77. The Helda-Lincoln gate was in the bottom of the cavity and the semiconductor and bond wires were in the upper half of the cavity. Plummer, Tr. 1368-69; RX 111; RPX 98(f); ALJX 1; RX 12.

FF B 78. The Helda-Lincoln work is an indication of the level of skill in the art at the time Birchler and Williams did their work. It is also indicative of how the concept of transfer molding progressed at Motorola from the pin circle configuration to the lead frame design. FF B 66-77.

FF B 79. The Helda-Lincoln patent is directed to the use of a tie-strip which acts as a closing point for the mold. RX 12: col. 3, lns. 53-56.

FF B 79a. The Helda-Lincoln project resulted in the issuance of U.S. Patent No. 3,444,441 on May 13, 1969. RX 12. The Helda-Lincoln patent is directed to "a device which will lend itself to indexed continuous automatic assembly and to encapsulation in multiple units, and to a method for assembling such devices." RX 12, Col. 1, lines 47-50.

FF B 79b. The Helda-Lincoln patent discloses the following method for assembling a semiconductor device, including the steps of: mounting the semiconductor device directly on a portion of an external lead (Col. 3, ll. 11); holding the leads together in a precise orientation by the lead mounting portion and a tie-strip which are integral with the leads (Col. 3, lines 24-25); and molding the devices in strips of 50 units in a multiple cavity mold (Col. 3, lines 27-32).

FF B 79c. The method for encapsulating devices disclosed in Helda-Lincoln patent is nowhere reflected in the May 17, 1963 Helda-Lincoln proposal. RX 12; RX 76. In particular, the Helda-Lincoln patent sets forth Figures 5A and 5B, which are perspectives of a transfer mold used to encapsulate devices. RX 12. Neither figure appeared in the May 17, 1963 proposal. RX 76.

FF B 79d. The Helda-Lincoln patent discloses a transfer molding process that is nowhere found in the May 17, 1963 proposal: "The mold closes on the

tie strip 26, thereby avoiding the necessity of the mold mating in the areas between the external leads . . . A thermosetting epoxy plastic material is forced into the mold through the cylindrical passage 30, and the combination of the pressure from the piston 31 and the mold temperature results in the epoxy material entering the cavities 33 through the gates 32 at the lowest viscosity of the epoxy. Because of this low viscosity, the shortness of the fine wires and the position of the gates, the fine wires are not broken during this encapsulating process." RX 12, Col. 4, 11. 29-39

FF B 80. The commercial product manufactured by Motorola has the configuration shown in U.S. Patent No. 3,431,092 to Lehner. RX 13; CX 5 (admitted partial Mathias Finding of Fact 64) p. 29.

FF B 81. As stated at column 2, lines 6-9, the Lehner patent is directed to a construction which permits automatic wire bonding. The Lehner construction also arranges the collector on the right-hand side of the transistor rather than in the middle, duplicating the lead arrangement of the prior TO-18 and TO-5 transistors. RX 13.

FF B 82. In the design shown in the Lehner patent, the plastic is injected into the mold cavity in a direction generally parallel to the orientation of the whisker wires connecting the die to the emitter and base leads. CX 5 (admitted Partial Mathias Finding of Fact 64) p. 29.

FF B 83. The application which matured into the Lehner '092 patent was filed on October 22, 1965. The patent was issued on March 4, 1969, and the invention contained therein is described as an improvement over the Helda-Lincoln approach. RX 13.

FF B 84. The Lehner approach, marketed by Motorola, also included a tie-strip as described in the Helda-Lincoln patent. RX 12; RX 13.

FF B 85. The Lehner arrangement had a depressed die pad. RX 13.

FF B 86. The commercial Motorola product also utilized features of the Doyle process such as a recessed pad on which the device was located, injection on the opposite side from the device and injection substantially parallel to the whisker wires. RPX 98(vv).

FF B 86a. Motorola never marketed transistors of the type shown in the Doyle '025 patent, and indeed the arrangement in Fig. 4 was acknowledged by Mr. Doyle to be experimental. CX-16, Doyle DRAM Tr. 1251-52; CX-262, DRAM FF 47: CX-5 at 21-22 ¶ (mm) admitted with comment; CX-215 at 17 ¶ (mm) admitted with comment.

FF B 87. Instead of leads in a pin circle configuration, the commercial Motorola transistors had flat leads arranged in a straight line. Doyle, Tr. 980; RX 12.

FF B 88. At the time Doyle left Motorola in November 1964, Motorola was tooling up for mass production of headerless transistors with planar leads. Doyle, Tr. 979.

FF B 89. The Motorola transistor utilizing the approach shown in the Lehner patent was first marketed in late 1964 or early 1965. RPX 62 (Lehner, DRAM, Tr. at 1415-16.

FF B 90. Motorola was the first company to utilize a stamped lead frame in a transfer molded plastic package. Corrigan, Tr. 1043.

FF B 91. By the early 60's, Sylvania was making germanium transistors in a TO-22 configuration with a solder seal (header and can) package. Russell, Tr. 1074-75.

FF B 92. A memo dated March 20, 1962 from Donald M. Russell, Jr. to H.M. Luhrs sets forth the April, 1962 price schedule of Sylvania transistors

encapsulated using the header and can method which Sylvania attempted to sell to Arvin Industries. The range of prices shown is 15 to 43 cents. Russell, Tr. 1099-1100; RX 127 (CAL RESPS 0098-0099).

FF B 93. Another memo from Donald M. Russell, Jr. to H.M. Luhrs sets forth the prices different for kits (or sets) of Sylvania transistors attempted to be sold to Arvin. The range in prices shown is \$1.42 to \$2.33 for kits which have anywhere from 5 to 8 transistors. Russell, Tr. 1101; RX 127 (CAL RESPS 0100-0102).

FF B 94. In 1961, Sylvania Electric Products obtained from the Hull Corporation a forty cavity production mold manufactured by the KRAS Corporation. Russell, Tr. 1083-84; RX 126.

FF B 95. This mold was used by Sylvania at its Hillsboro, New Hampshire plant. Russell, Tr. 1083.

FF B 96. Sylvania used this mold to make at least 20,000 transfer molded transistors over the period from June, 1961, to approximately June or July, 1963. Russell, Tr. 1092-93.

FF B 97. The Sylvania transfer molded transistors were assigned numbers TF-61 and TF-62. Russell, Tr. 1079.

FF B 98. There is only a very small difference electrically between the TF-61 and TF-62 transistors. The TF-61 is a higher frequency unit designed for I.F. and mixer use, and therefore has a lower collector capacitance and high frequency gain. Thus, the collector dot is a little bit larger on the TF-62. Otherwise the structures of the TF-61 and TF-62 are identical. Russell, Tr. 1083.

FF B 99. The Sylvania Product Review Committee voted to put the TF-61 and TF-62 transistors into the Sylvania product list on May 26, 1961. A memo

dated January 26, 1962, from W. Hogan to "List" indicates that the TF-61 and TF-62 transistors were "activated 5/26/61." Russell, Tr. 1088-89; RX 127 (CAL RESPS 0048).

FF B 100. The yield of transistors encapsulated by transfer molding at Sylvania was at least equal to and usually superior to that for the TO-22 solder-sealed (header and can) package. Russell, Tr. 1094.

FF B 101. The transistors molded by Sylvania known as the TF-61 and TF-62 successfully passed all these tests and were reported in May, 1962 as being "...completely satisfactory for the intended class of service in the stages of entertainment portable radios..." Russell, Tr. 1096-98; RX 127 (CAL RESPS 0056-0057, 0073-0074).

FF B 102. Samples of the transistors molded at Sylvania were sent to certain key Sylvania customers (Arvin, Emerson, Warwick and Zenith) from May, 1962 to April, 1963 to make these customers aware of what was coming so they would not be taken by surprise. Russell, Tr. 1101-02.

FF B 103. The feedback from these customers concerning the transfer molded transistors was generally enthusiastic. Russell, Tr. 1102.

FF B 104. A set of samples (RPX 98(yy), 98(zz), 98(aaa), 98(bbb), 98(ccc) and 98(ddd)) of the Sylvania TF-61 and TF-62 transistors were manufactured and subjected to electrical parameter tests by April 12, 1963. Russell, Tr. 1073-75; RX 127 (CAL RESPS 0058-0069).

FF B 105. Mr. Russell at the hearing identified transistor samples (RPX 98 (yy), (zz), (aaa), (bbb), (ccc) and (ddd)) which were forwarded from the Hillsboro plant to Russell by Ralph Carruth. Thus transistors were transfer molded in about April of 1963. Russell, Tr. 1075-76.

FF B 106. Ralph Carruth was the engineer in charge of transistor product

engineering at the Hillsboro plant. Russell, Tr. 1077.

FF B 107. The customers to whom the transistors were sent were not put under any kind of restrictions as to whom they could show the transistors, or as to whom they could tell about them. Russell, Tr. 1102.

FF B 108. On April 15-16, 1963, the Sylvania plant at Hillsboro where the transfer molding was carried out was visited by representatives of a key customer, the Arvin Corporation -- specifically, the Chief Engineer and Purchasing Manager. Russell, Tr. 1105-06; RX 127 (CAL RESPS 0083-0084).

FF B 109. During the plant visit, the Purchasing Manager and Chief Engineer observed both the TF-61 and TF-62 transistors being transfer molded at Sylvania. Russell, Tr. 1106.

FF B 110. The Chief Engineer and Purchasing Manager were under no requirements of confidentiality and were free to disclose the transfer molding process that they had seen at the Sylvania factory. Russell, Tr. 1106.

FF B 111. In April, 1963, Ralph Carruth, along with Vincent Sussman, published an article describing the transfer molded transistors that had been made at Sylvania in the magazine Electronic Packaging and Production. Russell, Tr. 1102-03; RX 24.

FF B 112. Figure 3 of the Carruth and Sussman article depicts a TF-61 transistor. Russell, Tr. 1103; RX 24.

FF B 113. At the time the Carruth and Sussman article was published, the TF-61 and TF-62 transistors had been made successfully and were ready to be sold to customers. Russell, Tr. 1104.

FF B 114. The structure of the base tab and germanium die assembly used in the Sylvania transistor was fragile, but it was more rugged than the 1 mil gold wires typically used in the industry when encapsulating planar silicon

transistors in plastic. Russell, Tr. 1115-1116.

FF B 115. The Carruth and Sussman article notes that Sylvania's transfer molded transistors were the same electrically as its header and can transistors. The article states: "Since the most expensive part of the entire transistor is the header, cost reduction in this area is quite desirable. This objective was achieved by Sylvania without derating the transistor in any way by redesigning the header and transfer-molding the transistor thereby producing an all-epoxy package". RX 24.

FF B 116. The Carruth and Sussman articles notes many of the advantages of transfer molded transistors, as opposed to transistors encapsulated using the header and can method. The article states: "Although transfer molded transistors are still in the development stage they promise some very interesting advantages. In addition to reducing cost, transfer-molded units have better heat dissipation and therefore can be used at higher power ratings." Later, the article states: "For low power applications, the [transfer molded] transistors can be packed closely together, even touching one another or other components without danger of shorting from one unit to another. Transistors are smaller in size, have better operating life characteristics and the package can be molded into different configurations for easy identification of the collector or emitter." RX 24.

FF E 117. The Sylvania TF-61 and TF-62 transistors were never sold because Sylvania was unable to develop companion units needed to make a full kit at a suitable price soon enough to meet the design schedule of manufacturers. Russell, Tr. 1098-99.

FF B 118. Customers in the entertainment transistor business at that time, i.e., those buying transistors for radios, insisted on buying a complete

kit or complement of units needed in a radio. Russell, Tr. 1098.

FF B 119. Customers insisted on buying a complete kit because it gave them tremendous leverage on price, delivery and quantity. Russell, Tr. 1098.

FF B 120. The structure of the transistor which was transfer molded at Sylvania included a header. Russell, Tr. 1081, 1086; Plummer, Tr. 13; RPX 63B.

FF B 121. In the Sylvania transistor, the three conductor wires were supported by the header in an in-line configuration, i.e., parallel, and in a plane. Russell, Tr. 1086-87; Plummer, Tr. 13-25; RX 126; RPX 63B.

FF B 122. This in-line configuration was what was known as the TO-22 configuration. In this arrangement, a base lead is located in the middle and an emitter lead is located on one side and a collector lead is located on the other side, with the emitter lead spaced closer to the base lead than the collector lead. Russell, Tr. 1081; RX 127 (CAL RESPS 0028).

FF B 123. A square piece cut from a germanium wafer with indium dots alloyed to it on both sides was mounted on a base tab, which was in the nature of a circular washer, was approximately 5 mils thick, and supported the transistor. That assembly was then soldered to the metal base lead (the center lead) in the header. Russell, Tr. 1081, 1089, 1113-16; RX 320(o); RPX 98(o).

FF B 124. The square piece of germanium is 3 to 5 mils thick. Russell, Tr. 1082.

FF B 124a. The square piece of germanium (the germanium device) and the bond wires are mounted in a plane generally perpendicular to the plane of the leads, located partly on each side of the plane defined by the conductors. Russell, Tr. 1112; RPX 98(o), RPX 98(ww).

FF B 125. Electrical connections were made between the collector and emitter indium dots on the germanium transistor wafer and the emitter and collector leads. Russell, Tr. 1081; RX 320(o); RPX 98(o). The diameter of each electrical connections was about 6 mils. However, Mr. Russell stated that the bond wires used in the Sylvania germanium transistor were on the order of 10 mils more or less. Russell Tr. 1110-1111. In comparison, at Column 4, 11. 41-45, the '027 patent discloses that "the whisker wire leads 52 and 54 are very small and will customarily be on the order of one mil in diameter as compared to the conductor wires 10, 12 and 14 which will be on the order of 10 mils in diameter." CX 1. The bond wires used to assemble germanium alloy transistors were approximately the size of the conductor wires used to assemble the planar silicon transistors disclosed in the '027 patent. Schroen, Tr. 113.

FF B 126. None of the claims in suit (claims 1, 12, 14, and 17) refer to the diameter of the electrical connector means, although the specification does refer to the size of various wires and leads. Seiling, Tr. 628; RX 40.

FF B 127. INTENTIONALLY OMITTED

FF B 128. INTENTIONALLY OMITTED

FF B 129. INTENTIONALLY OMITTED

FF B 130. The structure so formed, with its three leads parallel and planar was placed in the transfer mold with the header, germanium transistor, electrical connections and portions of the leads inside the cavity. Russell, Tr. 1086; RX 126.

FF B 131. After all of the forty transistors were placed in the bottom half of the cavity, the top half of the cavity was closed, clamping the leads in a planar arrangement. Russell, Tr. 1086-87; Plummer, Tr. 1322; RX 126.

FF B 132. In the Sylvania mold, the distance from the mold gate to the top edge of the base tab was about 50 mils. Russell, Tr. 1092.

FF B 133. In the Sylvania mold, the distance from the mold gate to the center of the device was about 150 mils. Russell, Tr. 1092.

FF B 134. With the transistors clamped in place, the transfer press ram was operated to force the epoxy material through gates into the mold cavities to encapsulate each of the transistors. Russell, Tr. 1086-87; Plummer, Tr. 1322-23; RX 126.

FF B 135. The gates were located in the bottom half of the mold. Russell, Tr. 1087; Plummer, Tr. 1323; RX 126.

FF B 136. The transistor itself and the electrical connections were perpendicular to the conductor leads, partially in the top half of the mold and partially in the bottom half. RX 126; Russell Tr. 1086-88.

FF B 137. During the molding, the electrical connections were exposed to the fluid plastic. Russell, Tr. 1088; RPX 98(o).

FF B 138. When the Sylvania transfer molded transistors were first removed from the mold, the leads were planar and at least 9/16 inches in length, or, in other words, the transistors were in the TO-22 configuration. Russell, Tr. 1078; RPX 63B.

FF B 139. Bottom-gating (locating the gate in the bottom half of the mold) was conventional. Birchler, Tr. 295-96; Plummer, Tr. 1323-, 1386; Doyle, Tr. 978; Seiling, Tr. 672; RX 41.

FF B 140. It is clear from the testimony at this hearing, and confirmed by documentation, that the leads in the Sylvania device were in a common plane and parallel, and that the transfer molding of transistors was carried out successfully. Donald Russell's testimony was credible; amply corroborated by

the testimony of Lawrence Plummer, contemporaneous documents and physical exhibits; and established that Sylvania successfully transfer molded the transistors he described at the indicated times in 1961 through early 1963. FF B 91-138.

FF B 141. U.S. Patent No. 3,235,937 to R.H. Lanzl et al. was filed May 10, 1963. RX 7.

FF B 142. The structure shown by Lanzl et al. in Figs. 7 and 8 and described in the specification includes a header 40, with three leads 32, 34 and 36. Plummer, Tr. 1366; RX 7.

FF B 143. The silicon transistor 2 mounted on carrier 20 is connected to the middle lead 34, which forms the collector. Extremely fine wire leads 26 and 28 extend from the transistor to the other two leads, 32 and 36. Plummer, Tr. 1366; RX 7.

FF B 144. The conductors or leads 32, 34 and 36 are in the same plane. Plummer, Tr. 1366; RX 7.

FF B 145. The device 2 and the extremely fine bond wires 26 and 28 are disposed on one side of the plane of the conductors after being so assembled. Plummer, Tr. 1366; RX 7.

FF B 146. The Lanzl et al. patent does not set forth any specific method of encapsulation; the transistor was embedded in insulation by "casting" or "potting," liquid epoxy into an open mold which contained the semiconductor. Plummer, Tr. 1376. The patent state that the assembly "is then housed by encapsulation in the suitable non-metallic electrically insulative protective material 50". RX 7, col. 3, lns. 39-41.

FF B 147. The Lanzl et al. patent has a lead configuration similar to the Sylvania lead configuration. RX 7, Fig. 7; RX 320(o); RPX 98(o).

FF B 148. INTENTIONALLY OMITTED

FF B 149. Prior to the transfer molding work done by Birchler and Williams, General Electric and Fairchild were producing encapsulated low-cost transistors. Corrigan, Tr. 1041-42.

FF B 149a. Fairchild's transistor was made by "glop-top" application of a drop of plastic. Corrigan, Tr. 1042.

FF B 150. In 1962, General Electric advertised transistors made by the casting process priced at 23 cents each. Corrigan, Tr. 1041.

FF B 151. When purchased in large quantities, these transistors sold for 23 cents or less, Corrigan, Tr. 1041-42.

FF B 152. In May, 1962, entertainment transistors were selling for 25 to 35 cents apiece. Russell, Tr. 1099.

FF B 153. In contrast, transistors for the industrial and military market were selling for several dollars apiece. Russell, Tr. 1099.

FF B 154. In the early 1960's, the price of transistors was determined more by the application to which the transistors would be put than by the encapsulation technique. Corrigan, Tr. 1042.

FF B 155. Thus by the time Birchler and Williams began their work, the prior art included the encapsulation in plastic of transistors, both silicon planar and germanium, including encapsulation by transfer molding as had been done by Sylvania and Doyle. Further, as taught by Zecher, it was known that transfer molding could best be carried out with planar leads as Sylvania had done. That encapsulation of devices with fine bond wires was possible had been shown by Doyle. Doyle, Tr. 961, 975-76; Bell, Tr. 999; Russell, Tr. 1092-93; RX 478.

FF B 156. Both in-line (planar lead) (Russell, Tr. 1086-87; Plummer, Tr.

13-25; RX 126; RPX 63B) and pin circle transistors (Doyle, Tr. 965-66; 978-79; RX 11) had existed in the art before Birchler and Williams started their work.

FF B 156a. In late 1962 or early 1963, Robert Birchler and E.R. Williams began working on a low-cost transistor project at TI. CX 5 (admitted Partial Mathias Finding of Fact 75) p. 34.

FF B 157. Birchler did not have ordinary skill in the art of transfer molding in 1963, and does not have ordinary skill in the art of transfer molding today. Birchler, Tr. 285. At the time Birchler and Williams got into the low-cost transistor project, Williams had no previous experience with transfer molding. Bircher, Tr. 279-80.

FF B 158. On or prior to May 29, 1963, one of the co-inventors, E. R. Williams, Jr., went to Dow Corning Corporation in Midland, Michigan, taking with him a one cavity mold for molding a transistor. Birchler, Tr. 285-87; Williams, Tr. 1461; RX 41.

FF B 159. The one-cavity mold taken to Dow Corning was made by people at TI. Birchler, Tr. 285.

FF B 160. The one cavity mold used by Mr. Williams had half of the mold cavity in an upper mold half and the other half of the mold cavity in a lower mold half, and included recesses between which the leads of the transistor were clamped. A runner and gate were formed in the bottom half of the cavity. Birchler, Williams, Tr. 281; Birchler, Tr. 1462.

FF B 161. Before this trip to Dow, Birchler and Williams had not settled on transfer molding as the way to proceed with the low-cost transistor project. Williams, Tr. 1463.

FF B 162. Prior to going to Dow, Birchler and Williams did not have a

transfer mold press available to them at Texas Instruments. Birchler, Tr. 281-85; Williams, Tr. 1461-63; RX 41; RX 206; RPX 34.

FF B 163. Williams took approximately one hundred unencapsulated devices to Dow Corning. RPX 109 (Lockhart Dep. Tr. 14).

FF B 164. Frederic Lockhart worked at Dow Corning in the Technical Service and Development Department in the 1962-1963 time frame. RPX 109 (Lockhart Dep. Tr. 7-10).

FF B 165. While at Dow, Mr. Williams, assisted by Frederic Lockhart, and utilizing equipment at Dow, molded a number of the transistors which Mr. Williams had brought with him. Williams, Tr. 1461; RPX 109 (Lockhart Dep. Tr. 14); RX 41.

FF B 166. The transistors included a plastic header on which three wires were supported in a planar arrangement. The transistor was mounted on one of the wires and thin whisker or bond wires ran from the transistor to the other two wires. The device and the bond wires were on one side of the plane of the three conductors. Birchler, Tr. 282-84, 360-62; Williams, Tr. 1461; RX 41.

FF B 167. Williams brought the equipment with him to measure electrical continuity of the transistors. RPX 109 (Lockhart Dep. Tr. 21).

FF B 168. At Dow, Williams tried transfer molding with the device in two different locations: one with the device and the connecting wires in the top half of the mold and the gate in the bottom half, and one with the device and connecting wires in the bottom half, and the gate in the bottom half. Williams, Tr. 1462.

FF B 168a. Williams' May 29, 1963 notebook entry observed that the gate of the single cavity mold was located at the top of the mold cavity, which "is conventional for end gating." RX 41. He noted, however, that he obtained

better results and some good units when he turned the transistor device over "so that it did not see the plastic as it is initially introduced into the cavity." RX 41.

FF B 169. The first 15-20 devices that were molded at Dow were failures. RPX 109 (Lockhart Dep. Tr. 17). These devices were molded with the device and wires in the bottom on the same side as the gate. Williams, Tr. 1462-63.

FF B 170. Subsequently, the device was turned over so that, according to Lockhart, "the plastic flowed into the mold . . . at a point where it did not impinge directly on the gold wires." Lockhart Dep. Tr. 17. The plastic "enveloped the device without rupturing the gold wires". RPX 109 (Lockhart Dep. Tr. 39).

FF B 171. Before trying flipping the device over to improve yield, Williams and Lockhart did not vary any of the mold parameters. RPX 109 (Lockhart Dep. Tr. 21).

FF B 172. After flipping the device over, Williams and Lockhart managed to make at least 50 or 60 good devices, i.e., devices with electrical continuity. RPX 109 (Lockhart Dep. Tr. 17).

FF B 173. As Williams recalls, when the arrangement was molded with the device and wires in the bottom on the same side as the gate, all of the units were bad, i.e., all of the units had opens or shorts. On the other hand, when the device and wires were in the top and the gate in the bottom, good units were obtained. The yield was improved. Williams, Tr. 1462-63; RX 41.

FF B 174. Birchler got his information about the experiments at Dow from Williams. Birchler, Tr. 285.

FF B 175. Lockhart remembers that Williams was elated following the experiments at Dow. RPX 109 (Lockhart Dep. Tr. 30-31).

FF B 176. The feature of opposite-side gating was discovered during this trip to Dow. Williams, Tr. 1463-64.

FF B 177. The inventors decided that opposite-side gating was worth pursuing in subsequent molds. Williams, Tr. 1464.

FF B 178. Williams was encouraged by the results at Dow. Williams, Tr. 1466.

FF B 179. INTENTIONALLY OMITTED

FF B 180. INTENTIONALLY OMITTED

FF B 181. INTENTIONALLY OMITTED

FF B 182. Subsequent to the trip to Dow, Birchler and Williams built a second experimental two-cavity mold. Birchler, Tr. 286; Williams, Tr. 1465; RX 41; RX 51.

FF B 182a. The new double-cavity mold was "side-gated." CX-8, Birchler DRAM Tr. 228. Like the single cavity mold, it was built in-house at TI by Birchler's staff. CX-8, Birchler DRAM Tr. 232, 7; Birchler Tr. 366. However, unlike the single-cavity mold, the new double-cavity mold was designed to have plastic injected from the side, in a direction generally parallel to the whisker wires, and the gate was located at a point offset from the device and on the bottom mold half. CX-8, Birchler DRAM Tr. 228, 230; Birchler Tr. 286, 291-95, 299-300; RX 41, 51; Williams Tr. 1465-66.

FF B 183. The two-cavity mold carried forward the concept of having the gate on the bottom and the device on the top. Williams, Tr. 1466.

FF B 184. INTENTIONALLY OMITTED

FF B 185. Using this mold, experiments were carried out with a structure in which the three wires of the transistor were held in parallel relationship in a single plane by tabs welded to their ends. The device and whisker wires

were mounted on one side of the wires. The unit was then placed in a mold cavity with the wires extending from both sides of the mold cavity. The top half of the mold cavity was placed over the bottom half and the wires were clamped on both sides during the molding. Birchler, Tr. 286, 291-94, 299-300; Williams, Tr. 1465; RX 41; RX 51.

FF B 186. As a result of the change in gate location, the injection of the fluid was parallel to the whisker wires of the two-cavity mold, whereas, it had been perpendicular to the whisker wires in the one-cavity mold. Birchler, Tr. 292-94; RX 51.

FF B 187. An entry in Williams' lab notebook dated June 15, 1963 notes that "a one cavity transfer mold of the book type has been built in which transfer molding around .001" gold wire is planned." Since the following entry is dated May 29, and since the May 29 entry concerns work already done with a one cavity mold, it appears that either the June 15 or the May 29 entry is dated incorrectly. RX 41.

FF B 188. A drawing included in the entry dated June 15, 1963 shows a one cavity transfer mold with the gate in the bottom half of the mold. RX 41.

FF B 189. In a notebook entry dated May 29, 1963, Williams noted that the transfer molding experiments at Dow were unsuccessful with same-side gating, but successful with opposite-side gating. Williams wrote: "The results were most unsatisfactory with the .001" emitter and base connections being broken during the transfer operation. These units were built on plastic headers... However, during the same experiment it was found that better results (good units) were obtained when the unit was in the top half of the mold so it did not see the plastic as it is initially introduced to the cavity." RX 41.

FF B 190. The entry dated May 29, 1963 has two figures at the bottom of the page. The figure on the left shows the unit and gold wires in the top of the mold and the gate in the bottom. The figure on the right shows the unit and the gold wires in the bottom of the mold, and the gate in the bottom. Williams, Tr. 1462; RX 41; RPX 34. These illustrate the two configuration used by Williams at Dow. Williams, Tr. 1462-63.

FF B 191. An entry dated June 31, 1963 notes that a new two cavity mold has been built and tested. The entry states: "The important features of the new mold are:

- A. The molding compound is introduced from the side with the individual unit gating. This allows the flow to be parallel to the plane of the emitter and base connections.
- B. The gate is off center with the device.
- C. The gate is in the bottom half of the mold and the device is in the top.
- D. The construction of the device was double-ended to prevent any movement of leads, thus breaking the connection. See drawing."

At the bottom of this page are two drawings. The drawing on the left shows the gate in the bottom half of the mold and the gold wires and device in the top half of the mold. RX 41.

FF B 192. The drawings on the page of Williams' lab notebook dated June 31, 1963 (the last page) show the double-ended feature (Feature D) of the alleged invention by Birchler and Williams. Birchler, Tr. 306; RX 44. Williams identified the ends of the conductors as those portions most distant from the device, which was located intermediate of the ends. RX 55.

FF B 193. Birchler believed that if the leads were held on both sides that they would be secure as the fluid entered the mold cavity. Birchler, Tr. 307.

FF B 194. Birchler thought the fluid plastic would initially flow across the bottom of the mold cavity. Birchler, Tr. 310.

FF B 195. Williams believed that if the gate was located in the bottom half of the mold and the device on the top half, the fluid plastic would go into the bottom first so that the device would not initially see it, and that the fluid plastic would tend to fill the bottom cavity first if the gate was located in the bottom half. Williams, Tr. 1470-71.

FF B 196. INTENTIONALLY OMITTED

FF B 197. Birchler and Williams were trying to achieve as much distance between the entry of plastic and the whisker wires as possible. Williams, Tr. 1488.

FF B 198. At the time Bircher and Williams were doing the work which led up to their patent, they understood that it was not good to shoot directly at the wires. Birchler, Tr. p. 303.

FF B 199. Putting the gate on the other side from the wires helps in not shooting directly at the wires. Birchler, Tr. p. 303.

FF B 200. Locating the gate offset also helps in not shooting directly at the wires. Birchler, Tr. pp. 303-304.

FF B 201. It would be common sense not to shoot directly at the wires. Birchler, Tr. p. 306.

FF B 202. There is a greater possibility of damage to the bond wires when they are located in the path of the mold gate. Schroen, Tr. 179.

FF B 203. The inventors were concerned that the fluid plastic would hit the whisker wires at high velocity and break them. Birchler, Tr. 310.

FF B 204. Consequently, the inventors put the gate at a location where the fluid plastic would not hit the whisker wires as it initially entered the

mold cavity. Birchler, Tr. 310.

FF B 205. According to TI's Dr. Seiling, remote gating is the key to the '027 patent (Seiling, Tr. 619):

"Q: Haven't you said on more than one occasion that remoteness is the most important consideration in the 027 patent?

A: I probably have, yes. It is important.

Q: Most important, correct, of all the matters we've discussed?

JUDGE HARRIS: Well, do you agree now that that's correct?

THE WITNESS: Yes, I think it is probably the most important." Seiling, Tr. 634.

Dr. Seiling would define "remote" as any gate location which produces a good product. All of the claims in issue that refer to gate location (claims 12, 14, 17) specify opposite-side injection of plastic. Opposite-side gating makes the gate more remote from the device and bond wires. As Dr. Seiling stated:

"A. (By the witness) The other side of the plane as an injection point would further remove the injection point from the device and wires.

Q. Your saying it would make it more remote?

A. Correct." RPX 57 (Seiling Dep. Tr. 30). Similarly opposite-side gating satisfies the whereby clause in the claim which states that the "fluid will not directly engage the device" at high velocity. As Dr. Seiling testified:

Q. Does having the gate remote as you've previously defined it have any relationship to the "whereby the fluid will not directly engage the device and electrical means at high velocity"?

A. Yes.

Q. And what relationship does it have?

A. If the gate is farther away it will not engage directly. RPX 57, (Seiling Dep. Tr. 30-31).

Similarly, emphasis on opposite-side gating was a factor in the DRAMs

proceeding:

"Q. Would you explain to me how injection into the other side of the mold cavity prevents direct high velocity engagement?

A. Well, it is part of the distance away from the portions of the wires and the die that you want. We are talking about a microworld. It certainly doesn't seem like much in real physical terms, but if you put the gate in the bottom, you are just that much farther away from the wire." CX 7 (Seiling, DRAM Tr. 764).

FF B 206. An invention disclosure was submitted to the TI Patent Department by Birchler and Williams. The test results at Dow, specifying some good units with opposite-side gating and total failure with same-side gating, were noted as were the four features, A to D (side-gating, off-center gating, bottom-gating with device in top, and double-ended). Williams, Tr. 1464-66; RX 51.

FF B 207. In the description of their invention in the invention disclosure, Birchler and Williams noted that: "The problem solved by the invention was a method of gating the mold and holding the transistor such that the velocity of transfer molding would not disrupt the .001" gold emitter and base connections [i.e. whisker wires]." RX 51.

FF B 208. In the invention disclosure, the indication was made that "gate location is critical". Also attached to the invention disclosure was a figure indicating the manner in which the inventors thought the fluid flowed: entry of the plastic into the bottom of the mold cavity with the device in the top of the mold cavity. Birchler, Tr. 291-92, 309; Williams, Tr. 1464, 1467-69; RX 51.

FF B 209. Birchler drew the figure attached to the invention disclosure showing the flow of fluid plastic in the mold cavity, which eventually became Figure 5 of the '027 patent. Birchler, Tr. 308.

FF B 210. In the invention disclosure (RX 51), the statement that "the

results were most unsatisfactory... " refers to the first experiments at Dow with same-side gating. Williams, Tr. 1465.

FF B 211. Feature A of Birchler and Williams' invention disclosure (RX 51) refers to side gating. Seiling, Tr. 636; Birchler, Tr. 298.

FF B 212. Feature B of Birchler and Williams' invention disclosure (RX 51) refers to the gate being located in a place, where, if one looks through the gate, one would not see the whisker wires. Seiling, Tr. 637. It refers to the gate offset. Birchler, Tr. 294, 333.

FF B 213. Feature C of Birchler and Williams' invention disclosure (RX 51) is illustrated in Figure 5 of the '027 patent, where the gate is in the bottom of the mold and the device and whisker wires are in the top. Birchler, Tr. 294-95; Seiling, Tr. 637.

FF B 214. Feature D of Birchler and Williams' invention disclosure (RX 51) is illustrated in Figure 3 of the patent, where the opposite ends of the conductors are held i.e. the double-ended configuration. Seiling, Tr. 637. For reference purposes, Feature D was also shown in a model identified as RPX 98(t). Seiling, Tr. 637; Birchler, Tr. 299-300.

FF B 215. In their patent application, filed on December 16, 1963, refiled on October 17, 1968, and filed again on July 30, 1973, the only configuration depicted or described was opposite-side gating. Fig. 5 depicts bottom- or opposite-sidegating and is described at column 5, lines 41-50. Figures 9 and 10 also depict bottom- or opposite-side gating as shown by the gate scar in Fig. 10 and as explained at column 10, lines 58-62 and column 7, line 67 - column 8, line 3. Among the configurations for opposite-side gating, a preference is stated for bottom gating. Bottom gating was most common, since the molded part could be more easily seen and handled when in

the bottom half of the mold. Birchler, Tr. 295-96.

FF B 216. During the prosecution of application Serial No. 331,006, Birchler and Williams submitted an affidavit under Rule 131 in order to establish a date of invention prior to the November 1, 1963 publication of a reference entitled "Semiconductor Products Department, Supplement to Active Discrete Pellet Functional Device," published by the General Electric Company. As evidence of the date of their invention, Birchler and Williams submitted their invention disclosure (RX 51), which, on the third and fourth pages stated: "the important features of the new mold are ... C. The gate is in the bottom half of the mold, and the device in the top". Birchler and Williams also attached the page from Williams' lab notebook dated June 31, 1963, setting forth the four features of the new mold, including "C. The gate is in the bottom half of the mold, and the device in the top." This same document, submitted to the Patent Office, explained how same-side gating was a failure whereas opposite-side gating gave improved results. RX 44.

FF B 217. In their preliminary statement in the interference with Doyle, Birchler and Williams noted that the trip to Dow was "the first act or acts [other than those mentioned in the lab notebook], which, if proven, would establish conception of the invention." RX 48.

FF B 218. In their preliminary statement in the interference with Doyle, Birchler and Williams attached the page from Williams' lab notebook dated May 29, 1963, describing the trip to Dow, and failure with same-side gating, but better results, including good units with opposite-side gating, and noted that it contained the first drawing of their invention. RX 41; RX 48.

FF B 219. INTENTIONALLY OMITTED

FF B 220. The double-ended feature was incorporated in the first plastic

encapsulated transistors made commercially at TI. Birchler, Tr. 328.

FF B 221. In these double-ended transistors, the leads extending from one end were cut off and painted over after encapsulation. CX 8 (Birchler, DRAM Tr. 237-38).

FF B 222. Within six months, TI switched to single-ended SILECT transistors in which the conductor wires were only held at one end. Birchler, Tr. 328-30.

FF B 223. Single-ended SILECT transistors did not have their leads extending from both ends during molding. Birchler, Tr. 330-32; RX 50.

FF B 224. Thus, these single-ended SILECT transistors did not incorporate Feature D ("the device was double-ended") of the alleged invention by Birchler and Williams set forth in their invention disclosure. Birchler, Tr. 332; RX 51.

FF B 225. The first single-ended SILECT transistors had an in-line configuration, i.e., the leads were all in a plane. Birchler, Tr. 328-29; RX 50, p. 2.

FF B 226. Subsequently, TI also molded single-ended SILECT transistors in a pin-circle arrangement. RPX 1 (Smith Dep. Tr. 14-16 -- December 19, 1990).

FF B 227. In a pin circle arrangement, the leads are not all in the same plane, but are instead in a triangular arrangement. RPX 1 (Smith Dep. Tr. 14 -- December 19, 1990).

FF B 228. SILECT transistors with the pin-circle configuration did not have all of their leads in the same plane. RPX 1 (Smith Dep. Tr. 14 -- December 19, 1990).

FF B 229. For many years, TI continued to use round wires as conductors.

Birchler, Tr. 332; RPX 126 (Pritchard Dep. Tr. 13).

FF B 230. TI initially employed a reel-to-reel system using wires instead of a lead frame. Corrigan, Tr. 1043.

FF B 231. Motorola was skeptical about the TI reel-to-reel approach, and therefore did not change its design when TI came out with that approach. Corrigan, Tr. 1043-44.

FF B 232. In 1970 or 1971, when Birchler left the SILECT operation, TI was not yet using lead frames in its process for encapsulating transistors in plastic. Birchler, Tr. 332-33; RPX 126 (Pritchard Dep. Tr. 13); CX 8 (Birchler, DRAM Tr. 279).

FF B 233. Even after TI began making plastic encapsulated transistors, wire bonding had to be done by hand under microscopes. Birchler, Tr. 337.

FF B 234. A TI lead frame drawing showing a lead frame with a dam bar dated March, 1971, suggests TI was making its transistors with a lead frame having a dam bar by that time. RPX 126 (Pritchard Dep. Tr. 19-22, Ex. 2).

FF B 235. By 1977, TI was utilizing a lead frame with a double rail. RPX 126 (Pritchard Dep. Tr. 20-).

FF B 236. TI also switched to automatic bonding at some point. RPX 126 (Pritchard Dep. Tr. 16).

FF B 237. Switching to lead frames aided the use of automatic bonding equipment. RPX 126 (Pritchard Dep. Tr. 16).

FF B 238. In the original TI SILECT configuration, the collector was in the middle. RPX 98(t).

FF B 239. At least some of the transistors subsequently molded by TI using lead frames utilized a configuration with the collector on the side rather than in the middle. RPX 126 (Pritchard Dep. Tr. 21-22, Pritchard Dep.

Ex. 2).

FF B 240. As of 1975, TI was still encapsulating some transistors using the header and can method. Adams, Tr. 1164.

FF B 241. U.S. Patent Application Serial No. 331,006 was filed December 16, 1963 by Robert O. Birchler and E.R. Williams. The '006 application was followed by two subsequent applications which led to the '027 patent. The '006 application is therefore known as the "grandparent" application of the application that lead to the '027 patent. RPX 87; RX 40.

FF B 242. The '006 application, as originally filed, contained eighteen claims. Thirteen claims were directed to the process for encapsulating a semiconductor device for manufacturing a transistor and seven claims were directed to an improved transistor made by the process. RPX 87, pp. 19-33.

FF B 243. The first office action on the application was mailed February 11, 1966. In this office action, the examiner rejected Claims 1-20 as unpatentable over Ikeda et al. alone or in combination with Burns and Cotton. RPX 87, pp. 42, 43.

FF B 244. Ikeda, U.S. Patent 3,171,187 (filed 5/1/63) discloses a method of manufacturing semiconductors which are encapsulated in a ceramic-type material such as glue or porcelain (col. 2, lines 39-41). The semiconductor may comprise three "projecting fingers" (reference numbers 3, 5 and 6) to which are attached a "transistor element" 2 (on finger 3) and lead wires 7 and 8 going from the tips of fingers 5 and 6 to the transistor element 2. RX 5, col. 2, lines 27-34, Figs. 1A, 4.

FF B 245. Burns, U.S. Patent No. 2,757,439, issued August 1, 1956, discloses a plastic encapsulated transistor. The leads or conductors (Fig. 1, Reference numbers 5, 6 and 7) are attached directly to and terminate at the

emitter, collector and base areas of the semiconductor. (Reference numbers 2, 3 and 4). A mold (14) is filled with a casting resin (col. 2, lines 21-2) and allowed to harden, after which the "stem base" (header 8) is removed. (col. 2, lines 23-27) (RX 3).

FF B 246. Cotton, U.S. Patent 3,221,089 describes a method for making capacitors by injecting a thermoplastic material into a mold to surround the capacitor. (col. 2, lines 23-31). A capacitor has two leads 12 and 14 which are held in a mold 22. The leads extend from the mold at each side and terminate at the capacitor. (col. 3, lines 9-16, 38-43, col. 5, lines 1-3) (RX 6).

FF B 247. In a response dated May 6, 1966 while arguing for the allowance of claim 1, the applicants emphasized the importance to their invention of keeping the whisker wires out of the path of the fluid plastic as it is injected into the mold cavity. They made the following statement to the Patent Office: "The Examiner has further alleged that the location and direction of the injected fluid is not critical. . . . In contrast, the whisker wires of the present invention would be demolished should they be directly in the injected stream of high velocity plastic." RPX 87, p. 48.

FF B 248. In its response to the first office action, TI argued that there was no teaching in the reference that would indicate the use of the same lead extending in different directions from outside the package, saying: "Likewise there is no teaching or suggestion in any of the cited references which would indicate use of the same lead extending in different directions." (emphasis in original). RPX 87, p. 49. Note that in each of Ikeda, Cotton and Burns the lead terminates near the semiconductor device. Ikeda has a lead finger which approaches the device. Cotton and Burns have conductors which

terminate at their devices. RX 3; RX 5; RX 6.

FF B 249. After receiving a final rejection from the examiner that was mailed January 25, 1967, TI filed an amendment under Rule 116 copying claims from U.S. Patent No. 3,281,628 issued to Bauer et al. in order to try to provoke an interference. At the same time TI appealed to the Board of Appeals the rejection of Claim 1-23 by the examiner. RPX 87, pp. 59-68.

FF B 250. On August 18, 1967 the examiner issued an action withdrawing the final rejection and entering the claims applicant copied from the Bauer patent. In this action, the examiner rejected all of the outstanding claims as unpatentable under 35 U.S.C. 103 over Ikeda et al. in view of Burns and a new piece of prior art, a pamphlet published by General Electric Corporation referred to as "The GE Literature" [this document was lost by the Patent Office and respondents attempts to obtain this document by subpoena, have been unsuccessful.] RPX 87, p. 73-75.

FF B 251. Applicants submitted their response to the August 18, 1967 Office Action on December 18, 1967. RPX 87, pp. 82-83.

FF B 252. TI emphasized to the Patent Office that holding both ends of each conductor and attaching a semiconductor device to an intermediate point of one of the conductors were important features of their invention. In distinguishing the prior art, including the Ikeda patent, they stated:

"Applicant's claim 1 recites a process of encapsulating a miniaturized semiconductor device and recites the steps of connecting each of the electrical terminals of the semiconductor device to an intermediate point of an appropriate conductor, disposing the device together with adjacent intermediate portions of the conductors in a mold cavity with the opposite ends of each of the conductors extending from opposite sides of the mold cavity and also holding or restraining the portions of the conductors extending from the opposite sides of the mold cavity, while injecting fluid insulating material into the mold cavity.

"Increased mechanical stability and reduced risk of breakage are achieved since a terminal connection is at an intermediate point of a conductor whose

opposite ends are held at the opposite sides of the mold cavity. Such a process is in no way shown or suggested by Ikeda et al, Burns, or the GE literature.

"Ikeda et al show the attachment of the ends of the conductors to the terminals of the semiconductor device. Similarly, Burns shows the securement of the ends of conductors to a semiconductor device. It is quite clear that neither of these references in any way show or suggest connecting terminals of the semiconductor device to an intermediate point of an appropriate conductor so that the conductors may be arranged to extend from opposite sides of a mold cavity with the portions of the conductors extending from opposite sides of the cavities being restrained. The GE literature similarly shows devices in which the ends of a plurality of conductors are connected to a semiconductor device, and does not show or suggest connecting the terminals of the semiconductor device to intermediate points of appropriate conductors."

Emphasis in original. RPX 87, pp. 82-83.

FF B 253. In the December 18, 1967 response, TI also argued that Claim 2 of the '006 application [that became Claim 1 of the '027 patent (see RX 56-59)] was patentable in that it specified that the fluid insulating material is injected into a portion of the mold cavity remote from the semiconductor device and the means electrically connecting the terminals of the semiconductor device to the conductors so that fluid insulating material does not directly engage the device and the electrical connection means. TI argued that none of the cited references show or suggest the remote injection of a fluid insulating material. RPX 87, p. 84, 85.

FF B 254. In their December 18, 1967 response to the office action, TI stated, in talking about Claim 3 of the '006 application:

"More particularly Claim 3 specifies that the conductor wires are disposed in a common plane while the device and a major portion of the means making electrical connection between the device and the conductor wires are disposed generally on one side of this plane and that the fluid insulating material is injected into the mold cavity on the other side of the plane. As clearly explained in Applicant's specification, this prevents direct contact between the fluid insulating material as it is initially injected into the mold cavity and the relatively fragile connections between the semiconductor device and the conductors."

RPX 87, p. 86.

FF B 255. In arguing for allowance of application claim 9, TI distinguished the alleged invention from several prior art references on the grounds that while TI's conductor wires extended between both sides of a frame, the leads shown in the prior art extended inwardly toward a semiconductor device, and then ended. TI stated:

"Claim 9 is also generally similar to the preceding claims, but specifies punching four generally parallel slots from a metallic plate to form a generally rectangular frame with three conductor wires disposed generally in parallel relationship and extending between two sides of the frame. As previously explained in detail, both Ikeda et al. and Burns references show mutually perpendicular lead wires, the ends of which extend to the semiconductor device but do not show the conductor wires extending between two sides of a frame. Furthermore, it is clear that the GE literature does not show or suggest such an arrangement, since, in the GE reference, the conductor wires extend inwardly toward the center with each terminating before reaching the other side. Thus, the GE literature does not show or suggest a particular arrangement of conductor wires extending between two sides of the frame. Furthermore, claim 9 recites that the opposite ends of the conductor wires extend from the mold cavity and are held, while injecting the fluid insulating material into the mold cavity, so as to prevent excessive movement of the conductor wires. This is in no way shown or suggested in any other references. Consequently, it is respectfully submitted that claim 9 is also clearly patentable over the cited references alone or in combination."

RPX 87, pp. 89-90.

FF B 256. In further distinguishing claims, TI argued Claim 12 is generally similar to Claim 9 and further specifies that an assembly is formed having a rectangular frame and three conductor wires disposed generally in parallel relationship and extending between two sides of the frame. RPX 87, p. 91-92.

FF B 257. In its December 18, 1967 response TI further emphasized the feature of holding the "ends of the conductors extending from the mold cavity" as well as the remote injection feature:

"Claim 21 specifies a process for encapsulating the semiconductor

device including electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of the device to at least one of the conductors for purposes of support. The claim also specifies its device and portions of the conductors are disposed in a mold cavity and fluid insulating material is injected into a portion of the cavity remote from the device and the means electrically connecting the terminals of the device while restraining ends of the conductors extending from the mold cavity as a result of injecting the fluid insulating material into a portion of the cavity remote from the device and the means electrically connecting the terminals of the device of the conductors so fluid does not directly engage the device and electrical connection so as to avoid unduly stressing the connections."

Emphasis in original. RPX 87, p. 91-92.

FF B 258. In referring to Claim 22, [which became Claim 12 of the '027 patent (see RX 56-59)], TI argued that the prior art did not suggest injecting on the opposite side from the device and its bond wires:

"Claim 22 is dependent on '21 and further specifies that the conductor wires are disposed generally in a common plane with the device and a major portion of the means making electrical connection between the terminals and conductor wires being disposed generally on one side of this plane while the fluid insulating materials injected into the mold cavity on the opposite side of this plane. Consequently, the device and its electrical connections are arranged such that they are not directly engaged by the fluid insulating material injected into the mold cavity. Such an arrangement, of course, is in no way shown or suggested by any of the cited references None of these references alone or in combination in any show or suggest the step of injecting the fluid insulating material into a mold cavity on an opposite side of the common plane defined by the conductor wires from the side on which the device and a major portion of the means making electrical connections between the device and conductor wires are disposed."

RPX 87, p. 92-93.

FF B 259. On December 15, 1967, Birchler and Williams executed an Affidavit under Rule 131, which was submitted to the Patent Office. Mr. Birchler and Mr. Williams swore the claimed invention in their application was described in their invention disclosure form and their laboratory notebook pages. RPX 87, pp. 104-107.

FF B 260. Attached to this Affidavit was a copy of their invention disclosure and a copy of a page from Williams' lab notebook which showed the double-ended arrangement with opposite-side gating. RPX 87, pp. 108-112.

FF B 261. In this Affidavit, Birchler and Williams relied upon Fig. 5 of their patent application which showed the initial flow of encapsulating fluid into the bottom of the mold cavity. They stated:

we conceived and reduced to practice in the United States of America the invention described in said patent application as evidenced by the following:

- a) The Texas Instruments Invention Disclosure Form labeled Exhibit 1, showing that the invention was disclosed to the Patent Department of Texas Instruments Incorporated prior to November 1, 1963.
- b) A pencil drawing labeled Exhibit 2 drawn by Robert O. Birchler to show that the device and lead structure situated in a die suitable for injection of molding fluid. This drawing is signed by the undersigned and corresponds to Figure 5 of the above said patent application.

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RPX 86, pp. 104-105.

FF B 262. The invention disclosure included the following statement, noting the importance of opposite-side gating to the inventors: "The important features of the new mold are: . . . C. The gate is in the bottom half of the mold and the device is in the top. . . ." RX 51; RPX 86, pp. 110-11.

FF B 263. INTENTIONALLY OMITTED

FF B 264. Subsequently, during this prosecution, in an action dated September 18, 1968, after claims had been added by amendment, the examiner found that the claims were directed to three distinct inventions, and thus required restriction between the following three groups of claims:

"I. Claims 14 to 20, 23 and 45 to 52 drawn to a semiconductor device with an integrally molded mass of insulating material.

II. Claims 1 to 13, 21, 22 and 35 to 43 drawn to an injection molding process for semiconductor devices.

III. Claims to 34, 44 and 53 to 55 drawn to a lead frame for semiconductor devices and a method for securing semiconductor crystals to that frame, i.e., an intermediate product for use in producing the final semiconductor device."

Bjorge, Tr. 15-26; RPX 87, pp. 127-28.

FF B 265. In imposing the restriction requirement, the Examiner noted that the reason that the claims of Group II were patentably distinct from the claims of Groups I and III was that, while the former [Group II] contained an injection molding limitation, the latter [Groups I and III] could be molded by any process, stating:

"While the inventions appear related, they are obviously distinct, i.e., they would not be subject to any double-patenting rejection if claimed in separate applications. The claims of Group II are distinct from those of Groups I and III because the products and processes claimed in those Groups do not require an injection molding process, but can be made by other processes. Additionally, such a process as claimed in Group II has acquired separate status in the art and requires a different field of search. The claims of Group I are distinct from those of Group III because the latter claims in no way involve molded encapsulation and relate to an intermediate product only. The claims of Group I, on the other hand, contain many patentably distinct final product embodiments not recited in the claims of Group III. Restriction for the purpose of examination is, therefore, deemed proper."

RPX 86, p. 127-28.

FF B 266. In a response dated September 27, 1968, the applicants elected to maintain Group I, which was directed to a semiconductor device with an integrally molded mass of insulating material, in the original application, and this application issued as U.S. Patent No. 3,439,238. Bjorge, Tr. 1526-27; RPX 87, cover, p. 131.

FF B 267. The Group II claims, which were directed to the transfer molding process, were refiled in a divisional application (Serial No. 768,311) on October 17, 1968. Bjorge, Tr. 1527; RPX 86. After being refiled again, as

Serial No. 384,768 on July 30, 1977, certain of these claims issued as U.S. Patent 4,043,027. CX 1.

FF B 268. The Group III claims, which were directed to a lead frame, were also refiled in a divisional application (Serial No. 768,325) on October 17, 1968 which became the '764 patent. Bjorge, Tr. 1527; RPX 88.

FF B 269. In application Serial No. 768,311, the applicants copied claims 1, 3, 4, 6, 7 and 8 from the Doyle '025 patent in an attempt to provoke an interference. Bjorge, Tr. 1531; RPX 86, pp. 46-58.

FF B 270. By copying the Doyle claims, Birchler and Williams asserted that their disclosure supported the copied claims. Bjorge, Tr. 1531; RPX 86, pp. 51-58.

FF B 271. In addition to TI's claims 25-28, which eventually got into the interference with claims 1, 3, 4, and 6 of the Doyle '025 patent, TI's claims 29 and 30, corresponding to claims 7 and 8 of Doyle, were also presented. The Examiner permitted the interference to proceed, as to claims 25-28, (Claims 1, 3, 4 and 6 of Doyle), but rejected TI's claims 29 and 30 as lacking support in its patent application. The Examiner stated that the portion of each conductor which was flattened in the alleged invention by Birchler and Williams was towards the middle of the conductor, while the portion which was flattened in the Doyle '025 patent was clearly on one end. With regard to claim 29, the examiner stated "Copied claims (sic) 7 (claim 29) contains the limitations that the metal lead has a flattened portion at one end thereof. Applicants' flattened (sic) portion is clearly intermediate ends of lead wires 10, 12 and 14 (but admittedly they are off-center and thus closer to one end)." Bjorge, Tr. 1532; RPX 86, p. 62.

FF B 272. In the interference with Doyle, TI never established a date of

invention earlier than the filing date (December 16, 1963) of the original patent application (SN 331,006). RX 60.

FF B 273. In the interference proceeding, Doyle, the junior party (the party with the later filing date), had the burden of establishing an invention date prior to that of Birchler and Williams. Bjorge, Tr. 1533-34; RX 60.

FF B 274. Doyle established a date of invention sometime prior to May, 1963. RX 60, pp. 12-17.

FF B 275. In the interference proceeding, the date of Doyle's invention was corroborated by documentary and physical evidence. The interference decision states: "The Doyle record of some 1100 pages includes a testimony of Doyle and 9 corroborating witnesses with reference to some 40 documentary and physical exhibits." RX 60, p. 3.

FF B 276. INTENTIONALLY OMITTED

FF B 277. Before the Board of Interferences, TI argued that Doyle's work in the late 1962 and early 1963 time frame was not covered by claims 1, 3, 4 and 6 of the Doyle '025 patent. The Board rejected this argument. RX 60, pp. 7-8.

FF B 278. The Board of Interferences found that Doyle used "tiny wires," as the phrase "tiny wires" was used in the interference counts. The Board stated: "The record is clear beyond any doubt that Doyle and those working on his behalf had available and did work with either 0.7 mil or one mil wire; predominantly with 0.7 mil wire as was conventional." RX 60 p. 10.

FF B 279. The Board of Interferences noted that Doyle did extensive testing on his headerless devices. The Board stated: "The conclusion is inescapable from a reading of the entire record for Doyle that, though a precise number cannot be determined, many devices, greatly in excess of the 10

or 20 admitted by TI were made and tested in a multiplicity of ways during the period between January and May of 1963 and certainly before December 16, 1963." RX 60, p.12.

FF B 280. The Board of Interferences did not feel that Doyle's continued testing of the headerless devices after submission of his invention disclosure suggested that these devices had not been reduced to practice before May 22, 1963. The Board stated: "Further we see nothing in the fact that Doyle and Heinle both continued working with the transistors and investigating various kinds of plastics during 1963 and after May 22, 1963, tending to disprove an actual reduction to practice of the method in issue prior to Birchler et al.'s filing date." RX 60, p.15

FF B 281. The interference was decided in favor of Doyle, who was granted priority of invention with respect to claims 1, 3, 4 and 6. Bjorge, Tr. 1535; RX 60; RPX 86.

FF B 282. Subsequently, claims 1-8 and 14-30 were canceled by TI. RPX 86, pp. 81-82.

FF B 283. In application Serial No. 384,768, first on May 23, 1971 and again on November 20, 1971, the examiner rejected claims 1-6 and 14-25 as obvious over Doyle either alone, or in view of the Otis patent. Bjorge, Tr. 1535; RPX 85, pp. 42, 50.

FF B 284. Otis U.S. Patent 2,436,597, issued February , 1948, discloses a method for making a capacitor imbedded in plastic from which two capacitor leads extend (col. 1, lines 3-11). The capacitor is placed in a cavity and thermosetting plastic performs flow into and fill up the cavity (col. 9, lines 2-27). RX 2.

FF B 285. In response to the first of these rejections, Birchler and

Williams argued that: "The Examiner's description of the Doyle disclosure as purportedly showing the injection of fluid at a location remote from his device seems to be based on pure speculation . . ." RPX 85, p. 48.

FF B 286. TI also asserted to the Patent Office that Doyle did not disclose the feature of injecting the fluid plastic parallel to the whisker wires: "Still further, with respect to claims 4, 5, 17, 18, and 25, the references [including Doyle] do not teach or suggest the feature of directing the fluid injection in a direction parallel to the connecting wires of the device." RPX 85, p. 49. Parallel flow is not a requirement of any claim in issue in this proceeding.

FF B 287. Claim 2 of the application Serial No. 384,768 corresponds to claim 1 in issue here. Claims 15, 20-21, and 24, correspond to claims 12, 14 and 17 in issue here. RX 56-59; RPX 85, p. 19, 20, 30, 31, 86 and 87.

FF B 288. After these rejections and corresponding responses, (RPX 85, pp. 43-56), the applicants appealed the examiner's rejection to the Board of Appeals. RPX 85, p. 57.

FF B 289. After submission of a Brief by applicants and an Answer by the Examiner, the Board of Appeals, in its decision, sustained some of the rejections and reversed others. Bjorge, Tr. 1536-38; RPX 85, p. 81.

FF B 290. The only prior art references mentioned by the Board were the Otis (RX 2) and Doyle '025 patents (RX 11). Bjorge, Tr. 1538. The Board also expressly stated: "References are:

Otis	2,436,597	Feb. , 1948
Doyle	3,367,025	Feb. 8, 1968." RX 49, p.81.

FF B 291. The Board of Appeals allowed application claim 2, which became claim 1 (which is in issue here) (see RX 56-59) because of the limitation in the claims that the conductors are disposed within the mold cavity in such a

way that opposite ends of each of the conductors extend from opposite sides of the mold cavity. In reversing the rejection of what became claim 1, the Board of Appeals stated: "The examiner's position, in rejecting claims 2 and 3, is that to encapsulate Otis' device using the particular transfer molding means of Doyle is considered obvious. However, with the combined teachings of all that is disclosed in these two patents we do not see where the claimed step of

'disposing the device and the adjacent intermediate portions of the conductors in a mold with the opposite ends of each of the conductors extending from generally opposite sides of the mold cavity.' (emphasis supplied)

is within the admit of the combined teachings or rendered obvious thereby. Accordingly, the rejection of claims 2 and 3 is reversed." RX 49; RPX 85, pp. 81-82.

FF B 292. The Board of Appeals, in affirming the rejection of claims 14, 16, 17, 19 and 20, stated: "In any event, even without the benefit of Doyle's figure 4, it is merely a matter of common sense to one of ordinary skill in the art to not inject the full force of the fluid directly on a fragile semiconductor wafer and its tiny connecting wires. Thus, one would inject the fluid remote or offset from the vicinity of the semiconductor assembly." RX 49; RPX 85, pp. 84.

FF B 293. In allowing the claims which became claims 12, 14 and 17 of the patent, which are in issue here, (see RX 56-59) the Board gave great weight to the "common plane" limitation. The Board stated as follows: "The subject matter of claims 15, 18 and 21 through , we do not see as being obvious over the invention defined in claims 1, 3, 4 and 6 of Doyle. These appealed claims recite specific arrangements of the conductors, connections and semiconductor wafer within the cavity. Specifically, the conductors, not parts of them, are defined to be in a parallel or common plane. Doyle's flats

31 and 32 are described as being in a plane slightly above flat 30. These appealed claims when given the broadest reasonable interpretation in light of the specification, In re Okuzawa, supra, are not rendered obvious by the invention of Doyle. RX 49; RPX 85, pp. 84.

FF B 294. The Board of Appeals noted that one of Doyle's nail head leads (or flats) was located in a plane slightly below the other two nail head leads (or flats). RX 49, p.84.

FF B 295. The claims the Board of Appeals allowed (claims 15, 18 and 21 through) (see RX 56-59) were allowed because of the configuration of the leads, the whisker wires, and the semiconductor device, within the mold cavity. RX 49, p.84.

FF B 296. The Ikeda patent (RX 5), the Lanzl patent (RX 7) and the Burns patent (RX 3), prior art references showing planar leads were cited during the prosecution of an earlier application SN 331,006. RPX 85, pp. 42, 75, 147.

FF B 297. Neither the Burns patent nor the Lanzl patent nor the Ikeda patent was cited or referred to in later applications or before the Board of Appeals. RX 60; RPX 85; RPX 86.

FF B 298. The Board of Appeals noted that it could only consider the claims on which Doyle had been awarded priority (with the disclosure available to help define the claims) as prior art. RX 85, p. 82; RX 60, p. 3.

FF E 299. INTENTIONALLY OMITTED

FF B 300. U.S. Patent 4,043,027 issued August 23, 1977. Robert O. Birchler and E.R. Williams, Jr. are named as inventors. The Patent is assigned to Texas Instruments, Inc. RX 40, p. 1.

FF B 301. The '027 Patent, issued from Application No. 384,768 filed July 30, 1973, that was a continuation of abandoned Serial No. 768,311 filed

October 17, 1968, that was a division of Serial No. 331,006 filed December 16, 1963, now U.S. Patent No. 3,439,238. RX 40, p. 1.

FF B 301a. The '027 patent discloses an invention entitled "Process for Encapsulating Electronic Components in Plastic." CX-1; CX-262, DRAM FF 116.

FF B 301b. The '027 specification states that:

The present invention is concerned with plastic encapsulation of very tiny and very delicate electrical circuit devices by transfer molding techniques, and in particular relates to a process for manufacturing an improved planar type transistor or the like on an economical, mass production basis without the use of a header.

CX-1, col. 2, ll. 10-16. See also id. at col. 1, ll. 63-66.

FF B 301c. The drawings of the '027 patent relate to the assembly and encapsulation of a transistor. The '027 specification clearly discloses, however, that the claimed process may be used to encapsulate other types of semiconductor devices, including integrated circuits. Seiling Tr. 517-518; CX-15, Hull DRAM Tr. 1667-1668. See, e.g., CX-1, col. 1, l. 14. See also CX-262, DRAM FF 117.

FF B 301d. In particular, the '027 specification discloses that "[t]he process is particularly adapted to the manufacture of transistors, but can be used, in its broader aspects, for manufacturing various other electrical devices such as integrated circuits." CX-1, col. 8, ll. 34-37.

FF B 301e. Another object of the invention is to provide a process for transfer molding a planar semiconductor device. CX-1, col. 2, ll. 67-68.

FF B 301f. Planar transistors are used exclusively today, and are truly integrated circuits. CX-10, Schroen DRAM Tr. 79. Figures 3 and 3A of the '027 patent depict a cross-section of a planar transistor. CX-10, Schroen DRAM Tr. 79-80.

FF B 301g. A planar transistor uses very delicate 1 mil whisker wires

because the geometries of such miniaturized semiconductor devices are so small that only very delicate wires can be used. CX-10, Schroen DRAM Tr. 79.

FF B 301h. As is observed in the '027 specification, "the planar transistor is very small and delicate, and successful encapsulation in plastic, particularly by transfer molding techniques, constitutes a considerable problem. Nearly all commercially available planar transistors are manufactured by using a header and transistor can substantially as heretofore described." CX-1, col. 1, 1. 68 through col. 2, 1. 6.

FF B 301i. In 1962 and 1963, planar transistors were not commercially available in a plastic, transfer molded package. CX-10, Schroen DRAM Tr. 82.

FF B 301j. As observed in the '027 specification, high quality and practical semiconductor devices must generally be constructed so as to withstand high mechanical shock loads. The active components must be encased in an electrically non-conductive environment and should be protected from light. The environment should also be such as will conduct heat away from the active regions of the device. CX-262, DRAM FF 87; CX-5 at 39-40 ¶ (aaaa); CX-215 at 30-31 ¶ (aaaa).

FF B 301k. In one of the embodiments of the invention described in the specification, three conductor wires 10, 12, 14 are held in an assembled, generally planar relationship by tabs 16, 18 at either end, and a semiconductor die or transistor wafer 40 is mechanically attached to the mid-point of one of the wires so as to make electrical contact between an active region of the wafer and the conductor wire. Each of the other active regions of the wafer are then interconnected with one of the other conductor wires by very small "whisker wire" leads 52, 54. This arrangement is illustrated in Figure 3 of the '027 patent. CX-262, DRAM FF 88; CX-5 at 40

¶ (bbbb); CX-215 at 31 ¶ (bbbb).

FF B 3011. Alternatively, the separate conductor wires 10, 12, 14 in Figure 3 can be formed by punching elongated slots from a generally rectangular sheet of thin metal. As illustrated in Figure 9 of '027 patent this alternative forms a rectangle support 134, or "lead frame," which interconnects the ends of the conductor wires 136, 138, 140. A suitable transistor wafer 142 may then be alloyed to the center conductor wire 138, whisker wire leads 144 and 146 connected to the appropriate active regions of the wafer and to the other conductor wires 136 and 140, respectively. CX-262, DRAM FF 89: CX-5 at 40-41 ¶ (cccc); CX-215 at 31 ¶ (cccc).

FF B 301m. The '027 patent specification teaches that "[a]llthough specific embodiments of the invention have been described in detail, it is to be understood that various changes, substitutions and alterations can be made therein without departing from the spirit and scope of the invention" CX-1, col. 8, 11. 63-67.

FF B 302. INTENTIONALLY OMITTED

FF B 303. INTENTIONALLY OMITTED

FF B 304. The center portions of the conductors, the transistor wafer, and the whisker wire leads are then disposed within a mold cavity with the opposite ends of the conductor wires extending from the mold cavity. The ends of the conductor wires are clamped on each side of the mold cavity to prevent movement of the conductor wires as a fluid plastic material is injected into the mold cavity to encapsulate the transistor. RX 40, col. 2, lines 20-40.

FF B 305. An important aspect of what the inventors considered to be their invention is the manner in which the fluid plastic material is gated into the mold so as to prevent damage to the delicate whisker wire leads and

transistor wafer. RX 40, col. 2, lines 41-43.

FF B 306. Figure 1 of the '027 Patent is a perspective view of an assembly illustrating an initial step in the process of plastic encapsulation. RX 40, col. 3, lines 7-8.

FF B 307. Figure 1 discloses three conductor wires 10, 12, and 14 disposed within a common plane. Intermediate portions of the conductors are flattened at 10(a), 12(a) and 14(a). A transistor 40 in Fig. 3 is electrically and mechanically connected to the flattened portion of 12(a) of each of the conductor wires. The electrical connections to conductors 10 and 14 are shown in Fig. 3 by numerals 52 and 54. RX 40, col. 3, lines 46-49, lines 51-53, col. 4, lines 15-18, and col. 4, lines 48-50.

FF B 308. The tabs used to hold the wires together, as illustrated in the '027 patent, perform the same function as a header, giving a handle to keep the wires together as you are putting the die and whisker wires on during the alloy and ball-bonding operations. Birchler, Tr. p. 300.

FF B 309. Figure 5 depicts the conductor wires 10, 12, and 14, which are clamped at opposite ends between the upper and lower halves of the mold cavity. As stated in the patent, "It will also be noted that since the transistor wafer 40 and the whisker wire leads 52 and 54 are connected to the tops of the flattened portions 10(a), 12(a) and 14(a), the wafer and whisker wire leads are positioned in the upper mold cavity half 66. On the other hand, the Gate 88 is located in the lower mold cavity half 64 and, as previously mentioned, is offset from the center of the mold cavity so as to direct material into the mold cavity at a point remote from the transistor device and its connecting whisker wire leads." RX 40, col. 5, lines 34-46.

FF B 310. Figure 5 of the '027 patent indicates that the plastic enters

the bottom half of the cavity and then swirls around to the top half.

Williams, Tr. 1500.

FF B 311. In the early 1960's, the semiconductor industry was a very empirical industry. By trial and error, engineers figured what worked and what did not work. Quite frequently, the theoretical understanding of the reason why something worked came two or three years later. Corrigan, Tr. 1055.

FF B 312. Fig. 9 of the '027 patent is a top view of an intermediate article for use in practicing the invention of the '027 patent. In Fig. 9, an assembly 120 is formed by punching four slots 1, 126, 128 and 130 from a generally rectangular sheet of thin metal - 132. This forms a rectangular support - 134 - that interconnects the ends of conductor wires 136, 138 and 140 that correspond to the conductor wires 10, 12, and 14 of the assembly 20 depicted in Fig. 1. RX 40, col. 7, lines 39-45.

FF B 313. During the transfer molding operation, the conductor wires 136, 138, and 140 are again tightly clamped between the dies on either side of the mold cavity 148 to hold the conductor wires against the force of injected plastic. RX 40, col. 7, lines 52-56.

FF B 314. A gate 152 is shown by the dashed lines in Fig. 9. Gate 152 is wholly located within the portion of the mold cavity formed by the lower die such that the flattened conductor wires 136, 138, and 140 may be received in that upper die so that they will be disposed above the gate. The patent specification states: "Then, as the encapsulated material is injected into the mold cavity 148 at a high velocity, it will first enter the cavity below the conductor wires at a point offset from the fragile whisker wire leads 144 and 146. The leads are securely clamped between the dies on opposite sides of

the mold cavity to ensure that the leads are not displaced to such an extent as to part one of the whisker leads or to cause a short by the injected encapsulating material." (emphasis supplied) RX 40, col. 7, lines 58-69; col. 8, lines 1-2; col. 8, lines 6-10.

FF B 315. After transfer molding is completed, the conductor wires 136, 138, and 140 may be severed along the dotted lines 154 and 156 to produce the structure illustrated in Fig. 10. The ends of the conductor wires shown as 136(a), 138(a), 140(a) extend outside the package. RX 40, col. 8, lines 13-

FF B 316. Figure 10 of the '027 patent shows a gate scar, indicative of bottom gating. Birchler, Tr. 293; Plummer, Tr. 1387-89.

FF B 317. The gate scar of Fig. 10 is located on the opposite side of the plane from the device and whisker wires. Birchler, Tr. 293; Plummer, Tr. 1389.

FF B 318. Integrated circuits are not shown in any of the illustrations in the '027 patent, or described in that patent in any detail. Seiling, Tr. 517.

FF B 319. The '027 patent issued with seventeen claims all of which are method claims. RX 40.

FF B 320. Claim 1 is directed to a process for encapsulating a semiconductor.

FF B 321. Claims 2 - 4 are dependent on claim 1 and add the features of opposite-side gating and off-set gating. RX 40, col. 9, line 29 to col. 10, line 2.

FF B 322. Claims 5 - 11 are directed to a process for making a transistor and include the presence of three "conductors" or "conductor wires". RX 40, col. 10, lines 5-16.

FF B 323. Claims 12, 14 and 17 are directed to encapsulating a semiconductor.

FF B 324. Claims 13, 15 and 16 are directed to encapsulating a semiconductor and include features of an off-set gate, parallel flow, and a mold adopted to provide a flat reference surface on the semiconductor, and conductors arranged in parallel. RX 40, cols. 11-14.

FF B 325. The prior art which Respondents rely upon to show obviousness of claims 12, 14 and 17 includes the prior invention of Doyle and his patent claims (RF 91-112); the prior invention of Sylvania and the Carruth and Sussman publication (RF 169-189); the Lanzl patent (RF 190-197); and the Zecher article.

FF B 326. The '027 Patent is concerned with the art of transfer molding and semiconductor design. Several inventors named in patents in these fields did not have formal college training. Others had graduate degrees in engineering. The level of skill in the arts of transfer molding and semiconductor design is determined less by educational requirements than by hands-on experience, common sense and ingenuity. CX 5, p. 53 (Mathias Finding of Fact 109).

FF B 327. The Doyle process is a process for encapsulating a semiconductor device which is the type of process of each of the '027 claims in issue. Doyle, Tr. 961-64; RX 11; RX 113.

FF B 328. The Doyle process performs the step of "connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support." RX 40, Fig. 3D, col. 12, lines 28-30; Doyle, Tr. 966-67, 975; RPX 98(j).

FF B 329. The Doyle process includes the step of "disposing the device

and a major portion of the mass for making electrical connection between the terminals and the conductors generally on one side of a plane, which is defined by the lowest nail-head conductor to which the die is attached."

RX 40, col. 12, lines 34-37; RPX 98(j). See also Fig. 3D of Doyle. RX 11.

FF B 330. The Doyle process also includes the step of "holding the ends of the conductors extending from the mold cavity while injecting a fluid insulating material into the mold cavity on the other side of the plane to subsequently solidify and imbed said device." RX 40, col. 12, lines 40-44; Doyle, Tr. 975, 978. The conductors are held in the jig (mold base), while the fluid is injected at the base of the mold below the device and its bond wires. Doyle, Tr. 968-70.

FF B 331. In the Doyle process, the fluid insulating material is injected into a portion of the cavity "remote from the device and the means electrically connecting the terminals of the device to the conductors," since there was no damage to the wires. Doyle, Tr. 975-76, 978; Plummer, Tr. 1364; RX 40, col. 12, lines 45-47.

FF B 332. As a result of these steps, the fluid in the Doyle process "will not directly engage the device and electrical connection means at high velocity and the conductors will be secured against appreciable displacement by the fluid." Doyle, Tr. 977-78; Plummer, Tr. 1364. Doyle like Birchler and Williams injects below the device and its bond wires and obtains a useful encapsulated product. RX 11, 40.

FF B 333. In the Patent Office, Birchler and Williams argued that: "The Examiner's description of the Doyle disclosure as purportedly showing the injection of fluid at a location remote from his device seems to be based on pure speculation . . ." RPX 85, p. 48. However, the Board of Appeals pointed

out that the gate shown in the Doyle '025 patent was located "remote" from the device and whisker wires. The Board stated: "...it is clear that the Doyle claims are directed to a process using the transfer mold shown in his figure 4. The claims expressly require that the semiconductor be completely encapsulated which would certainly lead one to a process configuration wherein the semiconductor is disposed in the cavity interior. RX 49, pp. 4-5.

FF B 334. INTENTIONALLY OMITTED

FF B 335. The only element of claim 12 which may not be found in the Doyle process is the step which calls for disposing the conductors generally in a common plane. Doyle, Tr. 978-79; Plummer, Tr. 1364; RX 40, col. 12, lns. 26-51. Doyle does not show conductors in a common plane because one of his flats or nail heads 31, is below 30, and 32.

FF B 336. The only element of claim 14 which may not be found in the Doyle process is the requirement that the plurality of conductors are "arranged in a substantially common plane". Doyle, Tr. 978-79; RX 40, col. 13, lns. 3-20.

FF B 337. The only element of claim 17 which may not be found in the Doyle process is the requirement that the conductors be "substantially parallel," since, despite the fact that the leads are parallel for most of their lengths, the nail heads to which the device and whisker wires are connected are not parallel; two are in one plane and the other is in a different plane. Doyle, Tr. 966; RX 40, col. 14, lns. 6-23; RPX 98(j).

FF B 338. INTENTIONALLY OMITTED

FF B 339. The process used by Sylvania was a process for encapsulating a semiconductor device. Russell, Tr. 1081; Plummer, Tr. 1318.

FF B 340. In the Sylvania process, the step of "electrically connecting

each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support" was carried out as shown by the transistor configuration, although in the Sylvania configuration the device is attached to a basetab and the tab and device are attached to a conductor. RX 40, col. 12, lines 28-31; Russell, Tr. 1081; RPX 98(o).

FF B 341. In the Sylvania process, the step of disposing the conductors generally in a common plane was carried out. Each of the conductors or leads are in a straight line and thus in a common plane. Russell, Tr. 1087; Plummer, Tr. 13-25; RX 126.

FF B 342. In the Sylvania process, the step of "disposing the device and portions of the conductors in a mold cavity" was carried out as established by testimony, the mold drawing and the final product. Russell, Tr. 1086-87; Plummer, Tr. 1322-23; RX 126.

FF B 343. INTENTIONALLY OMITTED

FF B 344. INTENTIONALLY OMITTED

FF B 345. INTENTIONALLY OMITTED

FF B 346. In the Sylvania process, the step of "providing electrical connections between electrical terminals of the device and a plurality of conductors arranged in a substantially common plane" was carried out. Russell, Tr. 1081, 1087; RPX 98(o); Plummer, Tr. 1370-71.

FF B 347. INTENTIONALLY OMITTED

FF B 348. In the Sylvania process, the step of "arranging a plurality of conductors substantially parallel to each other" was carried out. Russell, Tr. 1086; Plummer, Tr. 1325; RX 126; RPX 63B.

FF B 349. INTENTIONALLY OMITTED

FF B 350. INTENTIONALLY OMITTED

FF B 351. Lanzl et al. describes a process for encapsulating a semiconductor device. Plummer, Tr. 1366; RX 7.

FF B 352. Lanzl et al. discloses disposing the conductors generally in a common plane. Plummer, Tr. 1366; RX 7.

FF B 353. Lanzl et al. discloses the step of electrically connecting each of the electrical terminals of the device to a conductor and mechanically attaching a portion of said device to at least one of the conductors for support. Plummer, Tr. 1366; RX 7.

FF B 354. Lanzl et al. discloses surrounding the conductors, device and electrical connections with a fluid insulating material which subsequently solidifies and embeds the device. Plummer, Tr. 1366; RX 7.

FF B 355. The conductors in Lanzl et al. are arranged parallel to one another. Plummer, Tr. 1366; RX 7.

FF B 356. Thus, Lanzl et al. performs the steps of claims 12, 14 and 17, with the exception of the steps relating specifically to transfer molding, i.e., disposing the device and portions of the conductors in a mold cavity, and holding the ends of the conductors extending from the mold cavity while injecting a fluid insulating material into the mold cavity on the other side of the plane formed by the conductors from the device and whisker wires. RX 7; RX 40.

FF C 1. When encapsulating semiconductor devices in plastic, respondents employ a rectangular metal frame (referred to as a "lead frame"), which provides a structure for mounting, assembling and handling one or more semiconductor devices at the same time. CPX 10 (Roberts Dep.) at 29-31; CPX 7 (Funcell Dep.) at 58-70, 94-97; CPX 1 (Camarda Dep.) at 4649; CPX 5 (Fehr Dep.) at 62-65; CPX 3 (Liang Dep.) at 16-18.

FF C 2. Respondents' lead frames are typically made of either a [C] [C]. The metal strip is stamped or etched to form slots or openings in the metal. CPX 1 (Camarda Dep.) at 50, 52, 55, 93, 104-05; CPX 7 (Funcell Dep.) at 63-65, 94-95; CPX 5 (Fehr Dep.) at 84, 87, 89; CPX 3 (Liang Dep.) at 38-39, 49-50, 52-53; CPX 10 (Roberts Dep.) at 35-36. Portions of the metal portions which remain after the slots are formed will serve as conductors in the finished product, and the metal structure connecting them is referred to as a "dam bar." RX 320-1.

FF C 3. The portions of the lead frame that remain after stamping or etching (i.e., the dam bar and leads, the die pad/tie bars structure, and the "end rail" structures) are bodies capable of transmitting electricity. CPX 10 (Roberts Dep.) at 54-60; CPX 7 (Funcell Dep.) at 64-65; CPX 1 (Camarda Dep.) at 52-53; CPX 5 (Fehr Dep.) at 68-70; CPX 3 (Liang Dep.) at 39.

FF C 4. Respondents electrically connect the terminals on the semiconductor device to points on the lead frame with whisker wires (referred to in the industry as a "wire bonding"). Typically, respondents use [C] [C] wire when wire bonding semiconductor devices to the conductors. CPX 10 (Roberts Dep.) at 54-60; CPX 7 (Funcell Dep.) at 104-05; CPX 1 (Camarda Dep.) at 123, 129; CPX 5 (Fehr Dep.) at 60, 75-76 & Ex. 11; CPX 3 (Liang Dep.) at 56-57.

FF C 5. Respondents mechanically attach the semiconductor device to the die pad portion of the lead frame (often referred to in the industry as "die attach"). Typically, respondents use a [C] adhesive to attach the die to the die pad. CPX 10 (Roberts Dep.) at 37-38; CPX 7 (Funcell Dep.) at 70-72; CPX 1 (Camarda Dep.) at 58-61; CPX 5 (Fehr Dep.) at 92-95; CPX 3 (Liang Dep.) at 16, 22-23.

FF C 6. Respondents attach the semiconductor device and the whisker wires generally on one side of the lead frame. CPX 10 (Roberts Dep.) at 70-71, 89-103 & Exs. 6, 7, 8, 9; CPX 7 (Funcell Dep.) at 1-26, 154-57 & Exs. 11, 12, 16; CPX 1 (Camarda Dep.) at 123-29 & Exs. 13, 14; CPX 5 (Fehr Dep.) at 111 & Ex. 9; CPX 3 (Liang Dep.) at 15-17, 62-63 & Exs. 6, 7, 8, 9, and Vol. II, CPX 4 at 11-12.

FF C 7. Respondents place the lead fingers in a mold cavity. After placing them in the mold, portions of the conductors extend from sides of the mold cavity. CPX 10 (Roberts Dep.) at 89-103 & Exs. 8, 9; CPX 7 (Funcell Dep.) at 69-70; CPX 2 (Camarda Dep. Vol. II) at 172-73; CPX 5 (Fehr Dep.) at 110-12, Vol. II, CPX 6 at 16; CPX 3 (Liang Dep.) at 61-64.

FF C 8. Respondents clamp the upper and lower dies of the mold together during encapsulation, firmly holding the dam bar and one end of each conductor. The conductors extend from the mold cavity between the dies. CPX 10 (Roberts Dep.) at 89-103 & Exs. 8, 9; CPX 2 (Camarda Dep. Vol. II) at 172-73; CPX 5 (Fehr Dep.) at 110-12, Vol. II, CPX 6 at 16; CPX 3 (Liang Dep.) at 64; RX 320-1.

FF C 9. While holding the dam bar, respondents inject a fluid insulating material (referred to in the industry as a "molding compound") into the mold cavity. Typically, respondents use an epoxy transfer molding compound. CPX

10 (Roberts Dep.) at 40-42, 94; CPX 7 (Funcell Dep.) at 70-72; CPX 1 (Camarda Dep.) at 103; CPX 5 (Fehr Dep.) at 112; CPX 3 (Liang Dep.) at 45-46.

FF C 10. In the majority of integrated circuits encapsulated by respondents, the gate is located at the other or opposite side of the lead frame from the semiconductor device and the whisker wires. Given conventional industry practice, this is referred to in the industry as a "bottom-gated" or "opposite side gated" mold. CPX 10 (Roberts Dep.) at 88, 93, 94, 96; CPX 7 (Funcell Dep.) at 75-85; CPX 1 (Camarda Dep.) at 83-88; CPX 5 (Fehr Dep.) at 136-38; CPX 4 (Liang Dep. Vol. II) at 11.

FF C 11. Some of the respondents (Cypress, IDT and LSI) have manufactured and imported products in which the gate was located on the same side of the lead frame as the semiconductor device and the bond or "whisker" wires. This is referred to as a "top-gated" or "same side gated" mold. CX 441 (Seventh Set); CPX 10 (Roberts Dep.) at 112-16 & Ex. 13; CPX 7 0 (Funcell Dep.) at 74-79; CPX 1 (Camarda Dep.) at 20-21; CPX 5 (Fehr Dep.) at 141-47.

FF C 12. In today's transfer molding processes, upon exiting the gate, the mold compound very quickly expands into both the upper and lower mold cavities to form a plug flow shape. In plug flow the flow of molding compound moves in a more or less uniform wave front in the mold and is not affected by whether the gate is located in the upper or lower portion of the mold cavity. Schroen, Tr. 184-185; CX 7; Seiling DRAM Tr. 497, 596-97, 967; Hightower Tr. 253.

FF C 13. INTENTIONALLY OMITTED

FF C 14. The fluid insulating material subsequently solidifies and embeds the semiconductor device. CPX 2 (Camarda Dep. Vol. II) at 34-35.

FF C 15. Cypress Semiconductor Corp. ("Cypress") has encapsulated

integrated circuits in plastic outside of the United States and imports the resulting products for sale in the United States. CPX 1 (Camarda Dep.) at 17-18.

FF C 16. Cypress imports plastic encapsulated integrated circuits in the following package types: Plastic Dual In Line Packages ("PDIPs"); Plastic Leaded Chip Carriers ("PLCCs"); Small Outline Integrated Circuits ("SOICs"), including Small Outline "J-lead" ("SOJ") package types. CX 400.

FF C 17. The following package types are encapsulated by the following foreign subcontractors: PDIPs [C] and [C]; SOICs, including J lead packages, at [C], [C], and [C] [C]; and PLCCs at [C]. CPX 1 (Camarda Dep.) at 19-21.

FF C 18. Although different subcontractors might encapsulate the same product using different process parameters - such as the use of different mold presses or temperatures, - Cypress considered the resulting products to be the same insofar as their functionality was concerned. CPX 1 (Camarda Dep.) at 133.

FF C 19. Cypress' subcontractors develop their own detailed parameters with respect to many assembly steps -- such as wafer saw, die attach, and wire bonding -- depending on the particular machinery being used at their facilities. CPX 1 (Camarda Dep.) at 137.

FF C 20. Once the subcontractor demonstrated to Cypress that it could assemble parts that passed Cypress' reliability tests, Cypress did not care about the subcontractor's process parameters as long as results were consistent. CPX 1 (Camarda Dep.) at 142-43.

FF C 21. Cypress' subcontractor specifications do not require any

particular relationship between the location of the gate, die pad, bond wires, and semiconductor die. CPX 1 (Camarda Dep.) at 143.

FF C 22. Cypress has encapsulated the following PDIP packages at [C] [C]: 16 pin [C], 20 pin [C], 22 pin [C], pin .300 [C], pin .600 [C], 28 pin .600 [C], 40 pin [C], 48 pin [C], and 64 pin [C]. CPX 1 (Camarda Dep.) at 34-35, 40-43.

FF C 23. With regard to the PDIPs imported by Cypress, except as noted to the contrary: (a) all PDIPs are made in a mold that has a gate; (b) all PDIPs are end-gated, as exemplified in Cypress Document No. 003851-52; (c) on approximately [C] of the PDIPs imported and sold by Cypress, said gate was located on the same side of the lead frame as the bond or "whisker" wires," as exemplified in Cypress Exemplars [C] and [C] and [C]; (d) on the remainder of the PDIPs imported by Cypress PDIPs, said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400, RPX 123, p. 39, Exh. 2.

FF C 24. Cypress has encapsulated the following SOIC packages at [C], [C]: 18 pin [C], 20 pin, pin, 28 pin. CPX 1 (Camarda Dep.) at 36-37, 43-45.

FF C 25. With regard to the SOICs imported by Cypress, except as noted to the contrary: (a) all SOICs are made in a mold that has a gate; (b) all SOICs are end-gated, as exemplified in Cypress Document No. 003849; (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 26. Cypress encapsulates the following PLCC packages at either [C] [C]: 20 pin, 28 pin, 32 pin [C], 44 pin, 52 pin [C],

68 pin, and 84 pin. CPX 1 (Camarda Dep.) at 33-34, 39-40; CPX 2 (Camarda Dep. Vol. II) at 18.

FF C 27. With regard to the PLCCs imported by Cypress, except as noted to the contrary: (a) all PLCCs are made in a mold that has a gate; (b) all PLCCs are gated on a corner, as exemplified in Cypress Document No. 003850; (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 28. All of the portions of the lead frames used to assemble and encapsulate Cypress' PDIP, SOIC and PLCC packages, regardless of subcontractor, are stamped or etched from a single sheet of [C]. CPX 1 (Camarda Dep.) at 50, 52, 55, 93, 104-05. If the foreign subcontractor can provide a suitable lead frame, i.e., one with an adequate die pad and lead arrangement for wire bonding, Cypress will not provide a lead frame design. CPX 1 (Camarda Dep.) at 56.

FF C 29. To manufacture a Cypress lead frame, a vendor starts with raw sheet stock of flat [C] which is slotted down to achieve the desired width. CPX 1 (Camarda Dep.) at 95-96. The lead frame pattern is formed either by a stamping operation or an etching operation. CPX 1 (Camarda Dep.) at 96. The central region of each unit on the lead frame strip is then plated and the die pad is downset through a tooling operation. CPX 1 (Camarda Dep.) at 96. The [C] strip is then cut into individual lead frames of a desired length. CPX 1 (Camarda Dep.) at 96.

FF C 30. The central portion of each lead frame is plated with [C]. CPX 1 (Camarda Dep.) at 51, 105. The purpose of the [C] plating is to provide a bondable surface on the metal lead frame for the [C] bond wires. CPX 1 (Camarda Dep.) at 51, 101.

FF C 31. Cypress has used two epoxy die attach materials, [C] [C], which is its present material of choice, and the now-discontinued [C], in connection with all plastic packages. CPX 1 (Camarda Dep.) at 57-60, 91-92.

FF C 32. Both the [C] and [C] adhesives are [C] [C] that are [C] conductive. CPX 1 (Camarda Dep.) at 59-60. The presence of the [C] makes these adhesives somewhat electrically conductive, but they do not serve as conductors. Plummer Tr. 1342.

FF C 33. Cypress expressly specifies the epoxy to be used as a die attach adhesive by its subcontractors. CPX 1 (Camarda Dep.) at 61.

FF C 34. Cypress uses [C] wire to connect the semiconductor device to the lead frame. CPX 1 (Camarda Dep.) at 129.

FF C 35. Cypress has used three molding compounds to encapsulate its integrated circuit packages: [C], which is its current material of choice, [C], and [C]. CPX 1 (Camarda Dep.) at 62-63, 73, 88-90. [C] is a low stress compound which minimizes the internal package stresses that are exerted on the die. CPX 1 (Camarda Dep.) at 63.

FF C 36. Cypress expressly specifies the molding compound to be used by its subcontractors in encapsulating integrated circuits. CPX 1 (Camarda Dep.) at 91.

FF C 37. After die attach and wire bonding, the lead frame strips are placed in a mold. CPX 1 (Camarda Dep.) at 102. When the mold is closed, portions of the lead frame extend from the mold cavity. CPX 1 (Camarda Dep.) at 103.

FF C 38. The top and bottom portions of the mold are clamped together on

the lead frame outside of the dam bar, including the dam bar, the side rails and the portions of the lead frame that eventually will be formed into the leads. CPX 2 (Camarda Dep. Vol. II) at 172, 174.

FF C 39. While the lead frame is held, encapsulating material is transferred into the mold cavity. CPX 1 (Camarda Dep.) at 103. After the material has gone through an initial cure, the die is opened and the molded strip is removed. CPX 1 (Camarda Dep.) at 103.

FF C 40. After encapsulation, the molded devices (which remain on the lead frame) may be subjected to cleaning steps. CPX 2 (Camarda Dep. Vol. II) at 34. The molded devices are then sent to "post mold cure," where they are placed in an oven at temperature for a period of time to permit full cross-linking of the molecular structure of the molding compound. CPX 1 (Camarda Dep.) at 73; CPX 2 (Camarda Dep. Vol. II) at 34.

FF C 41. Following mold cure, dam bar portions of the lead frame are trimmed away and the leads are plated with solder. CPX 2 (Camarda Dep. Vol. II) at 37. Finally, the units on the lead frame are singulated, i.e., divided into individual units, and the leads may be formed into any desired shape, such as a "gullwing" or "J" shaped lead. CPX 1 (Camarda Dep.) at 104; CPX 2 (Camarda Dep. Vol. II) at 37.

FF C 42. Cypress' subcontractors [C] encapsulate using conventional or "chase" molds having a gate located in the lower mold die, i.e., on the "opposite side" of the lead frame from the normal location of the die and bond wires. CPX 1 (Camarda Dep.) at 86. [C] uses both conventional and plate molds. CPX 1 (Camarda Dep.) at 85.

FF C 43. Typically PLCC packages are encapsulated in molds having a gate located in a corner of the package and on the other side of the lead frame

from the die and whisker wires. CPX 2 (Camarda Dep. Vol. II) at 38-39, 44, 46-47.

FF C 44. Typically, PDIPs and SOICs are encapsulated in molds that have a gate located at the end of the mold cavity and on the opposite side of the lead frame from the die and whisker wires. CPX 2 (Camarda Dep. Vol. II) at 43, 48.

FF C 45. In none of the opposite side gated molding processes used to encapsulate Cypress' integrated circuits does the top portion of the semiconductor die lie within the cross-section of the gate into the mold cavity. CPX 1 (Camarda Dep.) at 153.

FF C 46. Hermetic and ceramic packaging materials cost more than the packaging materials used in plastic encapsulated integrated circuits, and therefore result in a greater manufacturing cost and a higher selling cost to the consumer. CPX 2 (Camarda Dep. Vol. II) at 104.

FF C 47. Cypress Exemplar [C] is a "top gated" device that was molded by Cypress' [C] subcontractor, [C], on a conventional mold. CPX 1 (Camarda Dep.) at 82-85; CPX 2 (Camarda Dep. Vol. II) at 191. Exemplar [C] bears a date code [C] which indicates that the device was marked and tested in the [C] work week of [C]. CPX 1 (Camarda Dep.) at 86-88. Exemplar [C] was produced by inverting the lead frame in a conventional mold. CPX 2 (Camarda Dep. Vol. II) at 114-15.

FF C 48. Approximately [C] top-gated Exemplar [C] devices were produced and sold to two U.S. customers, [C] CPX 2 (Camarda Dep. Vol. II) at 22. The customers were not informed that any changes had been made to the product they received. CPX 2 (Camarda Dep. Vol. II) at 146, 186, 208.

FF C 49. Cypress did not requalify the top-gated products sold to [C] [C] CPX 2 (Camarda Dep. Vol. II) at 128. Joel Camarda, Cypress' representative, stated that no requalification was necessary because these devices were produced in a qualified mold, and the thermomechanical stress due to the expansion and contraction of the silicon die and the [C] leadframe in that mold were already known for bottom-gated products. CPX 2 (Camarda Dep. Vol. II) at 128, 130. Camarda testified that the thermodynamic and mechanical stresses are equivalent for bottom- and top-gated products made in the same mold. CPX 2 (Camarda Dep. Vol. II) at 208.

FF C 50. Cypress subjected its top-gated Exemplar [C] products to x-ray testing to test for wire sweep and delamination of the die. CPX 2 (Camarda Dep. Vol. II) at 130-31. It determined that assembly yields were essentially standard, in the [C] percent range, and met Cypress' in-house product specifications for form, fit, function and reliability. CPX 2 (Camarda Dep. Vol. II) at 131, 146-47.

FF C 51. After producing the [C] Exemplar [C] devices, Cypress reverted to opposite side gating for subsequent production runs. CPX 570b (Camarda Dep. Vol. III) at 62-63.

FF C 52. Cypress has decided that all new molds it purchases will be "same side gated". CPX 2 (Camarda Dep. Vol. II) at 123. One of its subcontractors, [C], has already purchased a same side gated mold for Cypress' [C] pin [C] PDIP package. CPX 2 (Camarda Dep. Vol. II) at .

FF C 53. In April 1991, Cypress discovered that a [C] pin PDIP package that its subcontractor, [C], had been encapsulating since [C] was a "same side gated" device. CPX 570b (Camarda Dep. Vol. III) at 38-40, 44.

FF C 54. [C] produced the same-side devices by turning the lead frame upside down in a conventional, bottom gated mold. CPX 570b (Camarda Dep. Vol. III) at 42.

FF C 55. The reason for molding the [C] pin PDIP package upside down were historical: the particular device (a logic circuit) originally was packaged in a ceramic DIP package in a "cavity down" position, and customers for this product were locked into a "cavity down" pin-out so that the device fit on their circuit boards. CPX 570b (Camarda Dep. Vol. III) at 55. The lead frame was inverted to achieve this ceramic pin-out in a plastic package. CPX 570b (Camarda Dep. Vol. III) at 55.

FF C 56. In assembling and encapsulating the [C] pin PDIP, the process parameters for lead frame material, [C] plating, die attach material, [C] wire, and molding compound remain the same as for conventional bottom-gated products. CPX 570b (Camarda Dep. Vol. III) at 46, 49, 51.

FF C 57. Since discovering that the [C] pin PDIP was top-gated, Cypress has not instructed [C] to make any changes in the molding process. CPX 570b (Camarda Dep. Vol. III) at 44-45. Cypress' representative, Joel Camarda, stated that the top-gated [C] pin PDIP package had historically passed all of Cypress' reliability and qualification standards. CPX 570b (Camarda Dep. Vol. III) at 64, 66, 71-72.

FF C 58. In December [C], a Cypress engineer, Brian West, noticed a "jetting" fill pattern of molding compound in an accidental short shot for a [C] package. CPX 570b (Camarda Dep. Vol. III) at 10-12. The jetting pattern occurred on a conventional, opposite side gated mold which Cypress was trying to qualify for production. CPX 570b (Camarda Dep. Vol. III) at 12.

FF C 59. West and Camarda concluded that the fill pattern did not "look

healthy," and was not desirable because it could lead to voids or delamination in the finished package. CPX 570b (Camarda Dep. Vol. III) at 12, 16.

FF C 60. Cypress subsequently reproduced a jetting pattern in a series of experiments on [C] packages run on [C]. CPX 570b (Camarda Dep. Vol. III) at 9-10 and Ex. 1; RPX 90a.

FF C 61. Cypress jetting experiments were conducted using a multiplunger automatic molding system and a mold having a gate on the opposite side of the lead frame from the die and whisker wires. CPX 570b (Camarda Dep. Vol. III) at 20-21.

FF C 62. To produce jetting, Cypress used a normal amount of molding compound, but set the plunger of the press to travel for only part of the normal cycle. CPX 570b (Camarda Dep. Vol. III) at 31. The plunger velocity was set at 10 millimeters per second, which was the maximum setting permitted by the press. CPX 570b (Camarda Dep. Vol. III) at 32-33.

FF C 63. Integrated Device Technology, Inc. ("IDT") imports plastic encapsulated integrated circuits in the following package types: Plastic Dual In Line Packages ("PDIPs"); Plastic Leaded Chip Carriers ("PLCCs"); Small Outline Integrated Circuits ("SOICs"), including Small Outline "J-lead" ("SOJ") package types; Plastic Quad Flat Packs ("PQFPs"). CX 400.

FF C 64. IDT has encapsulated integrated circuits in plastic outside of the United States and imports the resulting products for sale in the United States. CPX 7 (Funcell Dep.) at 12.

FF C 65. IDT integrated circuits are encapsulated in plastic by the following foreign assemblers and/or subcontractors: [C]; [C], in [C]; and [C], in [C]. CPX 7 (Funcell Dep.) at 14, 31. [C], [C] and [C] have assembled all of the plastic

encapsulated integrated circuits that IDT has imported into the United States from [C] to the present. CPX 7 (Funcell Dep.) at 14.

FF C 66. IDT has entered into agreements with its foreign subcontractors specifying each of the steps to be used in assembling its integrated circuit products. CPX 7 (Funcell Dep.) at 12.

FF C 67. IDT generally ships semiconductor wafer to [C], which "scribes" the wafer, separating it into individual die, and performs all steps through the complete assembly and encapsulation process. CPX 7 (Funcell Dep.) at 111-12. Occasionally, however, individual semiconductor die may be shipped to [C] for assembly and encapsulation. CPX 7 (Funcell Dep.) at 115-16.

FF C 68. IDT began encapsulating integrated circuits in plastic during [C] as part of an overall drive to enter the commercial market. CPX 7 (Funcell Dep.) at 128. By switching from ceramic to plastic encapsulation, IDT could reduce the cost of assembling and encapsulating an integrated circuit from [C] to [C] per unit -- or by approximately [C]. CPX 7 (Funcell Dep.) at 133.

FF C 69. Since at least [C], IDT has encapsulated the following PDIP packages at one or more offshore locations: 16 pin [C], 18 pin [C], 20 pin [C], 22 pin [C], pin [C] [C], pin-2 [C]; 28 pin [C]; 48 pin [C]; and 64 pin [C]. CPX 7 (Funcell Dep.) at 37-42.

FF C 70. With regard to the PDIPs imported by IDT, except as noted to the contrary: (a) all PDIPs are made in a mold that has a gate; (b) all PDIPs are end-gated, as exemplified in IDT Document No. 001214, 1217-18; 001169, 1173-74; and 001239, 12-43 (see CX 160, Funcell Dep.) Exs. 15A, B & C; (c) on approximately [C] PDIPs imported by IDT, said gate was located on the same side of the lead frame as the bond or "whisker" wires, as exemplified in IDT

Exemplars [C]; (d) on the remainder of the PDIPS imported by IDT, said gate is located on the opposite side of the lead frame from the bond or "whisker" wires, as exemplified in IDT Document No. 001214, 1217-18; 001169, 1173-74; and 001239, 12-43 (see CX 160; Funcell Dep.) Exs. 15A, B & C; CX 166; CX 168; CX 400.

FF C 71. IDT recently transferred molds for encapsulating its [C] [C] pin PDIP packages from its Santa Clara, California facility to its [C] facility. CPX 7 (Funcell Dep.) at 57. The reason cited for the transfer was the lower costs associated with foreign encapsulation. CPX 7 (Funcell Dep.) at 58.

FF C 72. Since at least 1988, IDT has encapsulated the following SOIC packages at one or more offshore locations: 16 pin [C], 18 pin [C], 20 pin [C], pin [C], and 28 pin [C]. CPX 7 (Funcell Dep.) at 42-45. A pin SOIC package currently is being qualified at [C]. CPX 7 (Funcell Dep.) at 49. Although these products normally are offered in a "gull-wing" lead configuration, the 20-, -, and 28 pin SOICs manufactured by [C] currently are being offered in a J-lead configuration. CPX 7 (Funcell Dep.) at 53-56.

FF C 73. With regard to the SOICs imported by IDT, except as noted to the contrary: (a) all SOICs are made in a mold that has a gate; (b) all SOICs are end-gated, as exemplified in IDT Document No. 001189, 1191-92; (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 74. IDT recently transferred molds for encapsulating its 20 pin SOIC package from Santa Clara to [C]. CPX 7 (Funcell Dep.) at 57. The reason cited for the transfer was the lower costs associated with foreign

encapsulation. CPX 7 (Funcell Dep.) at 58.

FF C 75. Since at least [C], IDT has encapsulated the following PLCC packages at [C]: 20 pin, 28 pin, 32 pin, 44 pin, 52 pin, 68, and 84 pin. CPX 7 (Funcell Dep.) at 46-47. A 32 pin PLCC package currently is being qualified at [C]. CPX 7 (Funcell Dep.) at 49.

FF C 76. With regard to the PLCCs imported by IDT, except as noted to the contrary: (a) all PLCCs are made in a mold that has a gate; (b) all PLCCs are gated on a corner, as exemplified in IDT Document No. 002102 (Funcell Dep.) Ex. 17); (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 77. Since at least [C], IDT has encapsulated a 132 pin PQFP at [C]. CPX 7 (Funcell Dep.) at 48. IDT also has a 144 and 208 pin PQFP package in qualification at [C]. CPX 7 (Funcell Dep.) at 48.

FF C 78. With regard to the PQFPs imported by IDT, except as noted to the contrary: (a) all PQFPs are made in a mold that has a gate; (b) all PQFPs are gated on a corner, as exemplified in IDT Document No. 002101; (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 79. All of the lead frames used by Analog to encapsulate its PDIP, SOIC (including J-lead) and PLCC packages are made from [C] [C]. CPX 7 (Funcell Dep.) at 59, 94, 101. The lead frames used by Analog to encapsulate its PQFP packages are either made from [C] [C]. CPX 7 (Funcell Dep.) at 95-97.

FF C 80. IDT obtains its PDIP lead frames from a variety of sources. CPX 7 (Funcell Dep.) at 59. Some lead frames are obtained directly from foreign lead frame manufacturers including [C]. CPX

7 (Funcell Dep.) at 60. Some lead frames are supplied by the foreign subcontractor. CPX 7 (Funcell Dep.) at 60-61. IDT purchases its PQFP lead frames from [C]. CPX 7 (Funcell Dep.) at 95.

FF C 81. Generally, IDT provides lead frames to its foreign subcontractors where a special proprietary lead frame design is required; otherwise, it normally relies on the foreign subcontractor to select an appropriate design. CPX 7 (Funcell Dep.) at 61-63.

FF C 82. All of the PDIP, SOIC and PLCC lead frames used by IDT are stamped or etched out of a single piece of [C]. CPX 7 (Funcell Dep.) at 63-65, 94-95. The lead frame and the tie bar connected to the die pad and the leads are all made of the same material. CPX 7 (Funcell Dep.) at 94-95.

FF C 83. On all of its PDIP, SOIC, PLCC and PQFP lead frames, IDT employs a [C] plating on the die attach pad and adjacent leads. CPX 7 (Funcell Dep.) at 65, 95, 97. The purpose of the plating is to promote corrosion resistance so that the wire bond will adhere better. CPX 7 (Funcell Dep.) at 66-67.

FF C 84. When the PDIP is encapsulated, the plastic material will cover everything between the dam bars on the lead frame. CPX 7 (Funcell Dep.) at 70. After encapsulation, the leads will extend outside of the plastic, and subsequently will be plated or coated with a lead or tin material. CPX 7 (Funcell Dep.) at 70.

FF C 85. IDT's representative, Ms. Funcell, testified that, prior to mechanical debar and deflash, it would be possible to conduct electricity between a lead emerging from one side of a PDIP package and a lead emerging from the opposite side of a PDIP package through the integrated structure of

the lead frame. CPX 8 (Funcell Dep. Vol. II) at 83-84. After mechanical debar and deflash, however, the conductive pathway would be broken. CPX 8 (Funcell Dep. Vol. II) at 83-85.

FF C 86. IDT specifies the use of [C], an epoxy die attach material, in assembling all of its PDIP, SOIC, PLCC and PQFP plastic packages. CPX 7 (Funcell Dep.) at 70-73, 97, 1-25; CPX 8 (Funcell Dep. Vol. II) at 117.

FF C 87. IDT uses [C] wire to wire bond the semiconductor die to the lead frame. CPX 7 (Funcell Dep.) at 104-05.

FF C 88. IDT currently specifies the use of [C] in assembling all of its PDIP, SOIC, PLCC and PQFP plastic packages. CPX 7 (Funcell Dep.) at 72, 97, 125. Before [C], IDT specified [C] for all of its encapsulating requirements. CPX 7 (Funcell Dep.) at 73; CPX 8 (Funcell Dep. Vol. II) at 117.

FF C 89. IDT products assembled at [C] and [C] are encapsulated using a "conventional" or chase mold. CPX 8 (Funcell Dep. Vol. II) at 29. All of the molds at [C] have a gate on the lower mold chase. CPX 8 (Funcell Dep. Vol. II) at 30. IDT uses both conventional presses and [C] multiplunger "conventional" presses at its [C] facility. CPX 8 (Funcell Dep. Vol. II) at 21-22.

FF C 90. After encapsulation, an IDT device is subjected to the following manufacturing steps: chemical deflash, to remove unwanted plastic; back marking of the device; mold cure; mechanical deflash to remove unwanted portions of the lead frame, such as the dam bar portions; lead plating; and trim and form. CPX 8 (Funcell Dep. Vol. II) at 31-32.

FF C 91. During the second half of [C], following consultation with its

attorneys, IDT produced three packages at its [C] facility -- a [C] pin PDIP, a pin PDIP [C], and a pin PDIP [C] -- using a conventional or "chase" mold having a gate located on the same side of the lead frame as the bond wires. CPX 7 (Funcell Dep.) at 75-86, 88, 91. The date code on the packages [C] indicates that they were manufactured during the [C] work week of [C].

FF C 92. All of the IDT top-gated devices were manufactured during the same period, resulting in several commercial shipments. CPX 7 (Funcell Dep.) at 82, 84. None of the "top-gated" devices was sold to a customer. CPX 8 (Funcell Dep. Vol. II) at 118.

FF C 93. To manufacture its top-gated packages, IDT's technicians put the lead frames "upside down" in the mold. CPX 7 (Funcell Dep.) at 87-88.

FF C 94. IDT did not impose any requalification requirements on the devices produced by this method. CPX 7 (Funcell Dep.) at 87-89. Nor did IDT's technicians observe anything abnormal in the resulting devices. CPX 7 (Funcell Dep.) at 92.

FF C 95. The Exemplars [C] devices are the only integrated circuits made and imported to date by IDT in a mold having a gate located on the same side of the lead frame as the bond wires and device. CPX 7 (Funcell Dep.) at 92-93.

FF C 96. In IDT's top-gated process, a portion of the die and the bond wires lie above the level of the gate into the mold cavity. CPX 7 (Funcell Dep.) at 156-57 and Ex. 16.

FF C 97. Prior to this investigation, all of the molds used at [C] were built having a gate located in the lower mold chase. CPX 8 (Funcell Dep. Vol. II) at 23. Recently, however, IDT purchased a mold from [C], a

[C] mold maker, having a gate located in the upper mold chase. CPX 8 (Funcell Dep. Vol. II) at 23-. IDT is presently in the process of qualifying two packages at [C], a [C] integrated circuit, on its new [C] molds. CPX 8 (Funcell Dep. Vol. II) at 25, 41.

FF C 98. After the first three top-gated devices were tested, it was directed that top-gated devices be qualified for production. CPX 8 (Funcell Dep. Vol. II) at 46, 98. Pursuant to this direction, IDT built qualification lots of between 1,500-2,000 devices of five packages: a 20 pin PDIP, a pin PDIP .300, a pin PDIP .600, a 28 pin PDIP, and a 32 pin PLCC. CPX 8 (Funcell Dep. Vol. II) at 47.

FF C 99. The qualification devices were encapsulated in the same way as the earlier top-gated devices -- by inverting the lead frames in a bottom gated mold. CPX 8 (Funcell Dep. Vol. II) at 48. The inversion of the lead frame required only a minor modification of the mold in which the alignment and/or locator pins were removed or relocated. CPX 8 (Funcell Dep. Vol. II) at 99-102, 131.

FF C 100. Ms. Funcell testified that it would be possible to design a "universal" lead frame with alignment holes in the rail that would permit the lead frame to be used interchangeably in a "top-gated" or "bottom-gated" mold. CPX 8 (Funcell Dep. Vol. II) at 100.

FF C 101. The qualification devices were assembled and encapsulated using the same lead frame material, the same [C] plating, the same die attach material, the same molding compound, and the same process specifications used for IDT's "bottom-gated" devices. CPX 8 (Funcell Dep. Vol. II) at 86, 90-93.

FF C 102. The devices were then subjected to reliability and electrical

tests, including temperature cycle tests, x-ray analysis, pressure pot tests, life tests, die penetration tests, and dimensional testing. CPX 8 (Funcell Dep. Vol. II) at 47-48.

FF C 103. On the basis of its experiments, IDT concluded that there were no reliability implications if the mold was gated on the top portion of the mold cavity or on the bottom portion of the mold cavity. CPX 8 (Funcell Dep. Vol. II) at 56, 69. Ms. Funcell stated that, from a quality and performance standpoint, the devices were the same. CPX 8 (Funcell Dep. Vol. II) at 87-88.

FF C 104. LSI Logic Corporation ("LSI") encapsulates integrated circuits in plastic at facilities located outside of the United States and imports the resulting devices into the United States. CPX 5 (Fehr Dep.) at 18, 20, 22.

FF C 105. LSI Logic Corporation ("LSI") imports plastic encapsulated integrated circuits in the following package types: Plastic Dual In Line Packages ("PDIPs"); Plastic Leaded Chip Carriers ("PLCCs"); Plastic Quad Flat Packs ("PQFPs"). CX 400.

FF C 106. LSI encapsulates PDIP, SOIC, PLCC, and PQFP plastic packages at one or more of the following foreign locations: [C], [C], [C], and [C] [C]. CPX 5 (Fehr Dep.) at 20, 22; CPX 6 (Fehr Dep. Vol. II) at 35, 71, 95.

FF C 107. LSI typically manufactures "application specific integrated circuits," or ASICs. CPX 5 (Fehr Dep.) at 17. ASIC wafer is sorted, tested, and subsequently sent to overseas assemblers. The assembler saws the wafer into individual dice, which it subsequently attaches to a lead frame selected to produce a particular integrated circuit. CPX 5 (Fehr Dep.) at 61-62.

FF C 108. The choice of lead frame typically is left to the assembler,

[C] mold maker, having a gate located in the upper mold chase. CPX 8 (Funcell Dep. Vol. II) at 23-. IDT is presently in the process of qualifying two packages at [C], a [C] integrated circuit, on its new [C] molds. CPX 8 (Funcell Dep. Vol. II) at 25, 41.

FF C 98. After the first three top-gated devices were tested, it was directed that top-gated devices be qualified for production. CPX 8 (Funcell Dep. Vol. II) at 46, 98. Pursuant to this direction, IDT built qualification lots of between 1,500-2,000 devices of five packages: a 20 pin PDIP, a pin PDIP .300, a pin PDIP .600, a 28 pin PDIP, and a 32 pin PLCC. CPX 8 (Funcell Dep. Vol. II) at 47.

FF C 99. The qualification devices were encapsulated in the same way as the earlier top-gated devices -- by inverting the lead frames in a bottom gated mold. CPX 8 (Funcell Dep. Vol. II) at 48. The inversion of the lead frame required only a minor modification of the mold in which the alignment and/or locator pins were removed or relocated. CPX 8 (Funcell Dep. Vol. II) at 99-102, 131.

FF C 100. Ms. Funcell testified that it would be possible to design a "universal" lead frame with alignment holes in the rail that would permit the lead frame to be used interchangeably in a "top-gated" or "bottom-gated" mold. CPX 8 (Funcell Dep. Vol. II) at 100.

FF C 101. The qualification devices were assembled and encapsulated using the same lead frame material, the same [C] plating, the same die attach material, the same molding compound, and the same process specifications used for IDT's "bottom-gated" devices. CPX 8 (Funcell Dep. Vol. II) at 86, 90-93.

FF C 102. The devices were then subjected to reliability and electrical

tests, including temperature cycle tests, x-ray analysis, pressure pot tests, life tests, die penetration tests, and dimensional testing. CPX 8 (Funcell Dep. Vol. II) at 47-48.

FF C 103. On the basis of its experiments, IDT concluded that there were no reliability implications if the mold was gated on the top portion of the mold cavity or on the bottom portion of the mold cavity. CPX 8 (Funcell Dep. Vol. II) at 56, 69. Ms. Funcell stated that, from a quality and performance standpoint, the devices were the same. CPX 8 (Funcell Dep. Vol. II) at 87-88.

FF C 104. LSI Logic Corporation ("LSI") encapsulates integrated circuits in plastic at facilities located outside of the United States and imports the resulting devices into the United States. CPX 5 (Fehr Dep.) at 18, 20, 22.

FF C 105. LSI Logic Corporation ("LSI") imports plastic encapsulated integrated circuits in the following package types: Plastic Dual In Line Packages ("PDIPs"); Plastic Leaded Chip Carriers ("PLCCs"); Plastic Quad Flat Packs ("PQFPs"). CX 400.

FF C 106. LSI encapsulates PDIP, SOIC, PLCC, and PQFP plastic packages at one or more of the following foreign locations: [C], [C], [C], and [C] [C]. CPX 5 (Fehr Dep.) at 20, 22; CPX 6 (Fehr Dep. Vol. II) at 35, 71, 95.

FF C 107. LSI typically manufactures "application specific integrated circuits," or ASICs. CPX 5 (Fehr Dep.) at 17. ASIC wafer is sorted, tested, and subsequently sent to overseas assemblers. The assembler saws the wafer into individual dice, which it subsequently attaches to a lead frame selected to produce a particular integrated circuit. CPX 5 (Fehr Dep.) at 61-62.

FF C 108. The choice of lead frame typically is left to the assembler,

who is provided with a bonding diagram showing the type of package selected, lead count, style of frame, and correct cavity size. CPX 5 (Fehr Dep.) at 62-63. Where the assembler does not have a suitable lead frame in its inventory, LSI will purchase a suitable lead frame from a third party manufacturer [C] [C]. CPX 5 (Fehr Dep.) at 63-64.

FF C 109. The foreign assembler would then attach a die to each unit on the lead frame, wire bond, and encapsulate. CPX 5 (Fehr Dep.) at 60.

FF C 110. LSI's subcontractors have used both conventional "chase" molds and plate molds to encapsulate all plastic package types. CPX 5 (Fehr Dep.) at 107, 114, 121 and Ex. 8.

FF C 111. When the lead frame is placed in the plate or chase mold, it is positioned on a series of alignment pins and then clamped or sandwiched between the upper and lower halves of the mold. CPX 5 (Fehr Dep.) at 110, 112.

FF C 112. Typically, when using a plate mold, the die and whisker wires are inverted in the mold cavity and the gate is located somewhere in the top of the end of the package. CPX 5 (Fehr Dep.) at 108, 111. The gate on a plate mold generally does not run along the full width of the top portion of the package, but can appear at one or more locations along that width. CPX 5 (Fehr Dep.) at 119; CPX 6 (Fehr Dep. Vol. II) at 63-64.

FF C 113. PLCC packages are generally made in a conventional mold having a gate on the opposite side of the lead frame from the die and bond wires. CPX 5 (Fehr Dep.) at 122.

FF C 114. PQFP packages are made in both conventional and plate molds.

CPX 5 (Fehr Dep.) at Ex. 1.

FF C 115. Following encapsulation, the assembler would mark the resulting devices, subject them to mold cure (with an optional temperature cycle), plate the leads, trim and form, and subject the units to electrical testing. CPX 5 (Fehr Dep.) at 60-61.

FF C 116. Since at least 1988, LSI has encapsulated the following PDIP packages at either [C] and imported the resulting products into the United States: 16 pin, 18 pin, 20 pin, 22 pin, pin, pin "skinny DIP," 28 pin, 40 pin, and 48 pin. CPX 5 (Fehr Dep.) at 32-35, 43-44, 46-47 and Ex. 3.

FF C 117. With regard to the PDIPs imported by LSI, except as noted to the contrary: (a) all PDIPs are made in a mold that has a gate; (b) all PDIPs are end-gated, as exemplified in LSI Document No. 004337 (Fehr Dep.) Ex. 1); (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires." CX 400.

FF C 118. Since at least 1988, LSI has encapsulated the following PLCC packages at either [C] and imported the resulting products into the United States: 28 pin, 44 pin, 68 pin, 84 pin, 120 pin and 132 pin. CPX 5 (Fehr Dep.) at 36-37, 44-45, 47-48 and Ex. 3.

FF C 119. With regard to the PLCCs imported by LSI, except as noted to the contrary: (a) all PLCCs are made in a mold that has a gate; (b) all non-plate molded PLCCs are gated on a corner, as exemplified in LSI Document No. 004333 (Fehr Dep.) Ex. 1); (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 120. Since at least 1988, LSI has encapsulated the following PQFP packages at either [C] and imported the

resulting products into the United States: 44 pin, 64 pin, 80 pin, 100 pin, 128, 144 pin, 160 pin, 184 pin, and 208 pin. CPX 5 (Fehr Dep.) at 38-39, 42, 45, 49-53, 57-59 and Ex. 3.

FF C 121. With regard to the PQFPs imported by LSI, except as noted to the contrary: (a) all PQFPs are made in a mold that has a gate; (b) all PQFPs are gated on a corner, as exemplified in LSI Document No. 004384 (Fehr Dep.) Ex. 1); (c) on approximately [C] PQFPs imported and sold by LSI, said gate was located on the same side of the lead frame as the bond or "whisker" wires; (d) on the remainder of the PQFPs imported by LSI, said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 122. The lead frames used to encapsulate LSI's PDIP and PLCC packages are stamped or etched entirely out of a single sheet of [C] [C]. CPX 5 (Fehr Dep.) at 65-66, 73, 79.

FF C 123. The lead frames used to encapsulate LSI's PQFP packages are stamped or etched out of a single piece of either [C] [C]. (Fehr Dep.) CPX 5 at 84, 87, 91.

FF C 124. LSI's stamped lead frames typically are made from a continuous reel of metal sheet. (Fehr Dep.) CPX 5 at 67. LSI's etched lead frames are manufactured by placing a photoresistive material on top of a [C] sheet, exposing the material with a mask so that certain portions of the photoresistive material can be removed, after which the exposed [C] can be chemically etched away. (Fehr Dep.) CPX 5 at 67-68.

FF C 125. [C] are materials that conduct electricity. (Fehr Dep.) CPX 5 at 65, 85, 91.

FF C 126. The upper and lower edge of a typical LSI lead frame is bordered by two edge rails, which are perforated with circular and oblong

5; CX 59; CX 26. The presence of the [C] makes the adhesive somewhat [C] conductive, but it does not serve as a [C]. Plummer, Tr. 1342.

FF C 133. LSI connects the die to the lead frame by [C] bonding with [C] wire. (Fehr Dep.) CPX 5 at 75 and Ex. 5) CX 59); CX 26).

FF C 134. LSI's subcontractors use one or more of three basic molding compounds: [C] compound for PQFP packages. (Fehr Dep.) CPX 5 at 97-100. These molding compounds are generally described as [C] and are used for all plastic packages. (Fehr Dep.) CPX 5 at 97-98.

FF C 135. During the second half of 1990, LSI [C] modified a conventional bottom gated mold to direct molding compound through a gate located on the same side of the lead frame as the die and bond wires. (Fehr Dep.) CPX 5 at 143-44.

FF C 136. The mold modification included closing the existing bottom gate, machining a new gate in the top mold chase, and drilling a hole through the lead frame to permit the flow of material to proceed through the bottom runner to the top gate. (Fehr Dep.) CPX 5 at 144-46, Fehr Dep.) Vol. II, CPX 6 at 15-19, 37.

FF C 137. [C] PQFPs were produced in this mold, electrically tested, and sold to [C]. (Fehr Dep.) Vol. II, CPX 6 at 21-22. LSI did not requalify the devices before they were shipped to [C], and has no firm plans to requalify top-gated parts. (Fehr Dep.) CPX 5 at 30, 44-45.

FF C 138. LSI has decided to convert its molding operations at LSI [C] so that the gate will be located in the upper mold cavity. (Fehr Dep.) Vol. II, CPX 6 at 38, 48-49. LSI also has had discussions with at least two of its

subcontractors, [C], concerning a change to top-gated molds. (Fehr Dep.) Vol. II, CPX 6 at 46.

FF C 139. As a result of this investigation, LSI switched its plastic encapsulation production from a bottom-gated process to a top-gated process. Corrigan Tr. 1051-1052.

FF C 140. There is no difference in terms of product yields by switching from a bottom-gated process to a top-gated process. (Corrigan Tr. 1053.

FF C 141. VLSI Technology, Inc. ("VLSI") encapsulates integrated circuits in plastic at facilities located outside of the United States and imports the resulting devices into the United States. (Liang Dep.) CPX 3 at 11.

FF C 142. Respondent VLSI Technology, Inc. ("VLSI") imports plastic encapsulated integrated circuits in the following package types: Plastic Dual In Line Packages ("PDIPs"); Plastic Leaded Chip Carriers ("PLCCs"); Small Outline Integrated Circuits ("SOICs"), including Small Outline "J-lead" ("SOJ") and Small Outline "Gull Wing-lead" ("SOG") package types; Plastic Quad Flat Packs ("PQFPs"). CX 400.

FF C 143. VLSI has employed [C] subcontractors to assemble and encapsulate integrated circuits in PDIP, SOIC, PLCC, and PQFP packages. These foreign subcontractors include [C], [C], [C] [C], [C], [C], and [C]. (Liang Dep.) CPX 3 at 11-12, 32-33, 37; Liang Dep.) Vol. II, CPX 4 at 11.

FF C 144. VLSI manufactures and sorts semiconductor wafer which it later ships, usually in wafer form, to its subcontractors for assembly and plastic encapsulation. (Liang Dep.) CPX 3 at 14-16.

FF C 145. After receipt, the subcontractor places the wafer in its warehouse, subject to a later release upon VLSI's request to encapsulate.

(Liang Dep.) CPX 3 at 16, 76-77. The wafers are then put through a rough incoming inspection. (Liang Dep.) CPX 3 at 16. They are subsequently mounted on a tape and diced, after which the resulting dice are attached to lead frames, wire bonded, and encapsulated in plastic. (Liang Dep.) CPX 3 at 16.

FF C 146. After encapsulation, the units are dejunked (i.e., unwanted plastic and metal are removed), singulated, marked, and the remaining leads are plated. The finished units may be inspected or tested prior to importation. (Liang Dep.) CPX 3 at 16.

FF C 147. Since at least [C], VLSI has encapsulated the following PDIP packages at one or more offshore locations and imported such packages into the United States: 8 pin [C], 14 pin [C], 18 pin [C], 20 pin [C], 22 pin [C], pin [C], 28 pin [C], 32 pin [C], 40 pin [C], and 64 pin [C]. (Liang Dep.) CPX 3 at 25-27, 32-35 and Ex. 3.

FF C 148. With regard to the PDIPs imported by VLSI, except as noted to the contrary: (a) all PDIPs are made in a mold that has a gate; (b) all PDIPs are end-gated, as exemplified in VLSI Document No. 004730 (Liang Dep.) Ex. 11); (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires." CX 400.

FF C 149. Since at least [C], VLSI has encapsulated the following SOIC packages at one or more offshore locations and imported the resulting such packages into the United States: 20 pin [C], pin [C], and 28 pin [C]. (Liang Dep.) CPX 3 at 30-31, 36-37 and Ex. 3.

FF C 150. With regard to the SOICs imported by VLSI, except as noted to the contrary: (a) all SOICs are made in a mold that has a gate; (b) all SOICs are end-gated, as exemplified in VLSI Document No. 004808-09 (Liang Dep.) Ex. 13; CX 109); (c) said gate is located on the opposite side of the lead frame

from the bond or "whisker" wires. CX 400.

FF C 151. Since at least [C], VLSI has encapsulated the following PLCC packages at one or more offshore locations and imported such packages into the United States: 20 pin [C], 28 pin [C], 32 pin [C], 44 pin [C], 52 pin [C], 68 pin [C], 84 pin [C] [C]. (Liang Dep.) CPX 3 at 27, 35-36, 37 and Ex. 3.

FF C 152. With regard to the PLCCs imported by VLSI, except as noted to the contrary: (a) all PLCCs are made in a mold that has a gate; (b) all PLCCs are gated on a corner, as exemplified in VLSI Document No. 004794-95 (Liang Dep.) Ex. 12; CX 108); (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400.

FF C 153. Since at least [C], VLSI has encapsulated the following PQFP packages at one or more offshore locations and imported such packages into the United States: 100 pin [C], 128 pin [C], 144 pin [C], 160 pin [C], and 208 pin [C]. (Liang Dep.) CPX 3 at 28-29, 36 and Ex. 3.

FF C 154. With regard to the PQFPs imported by VLSI, except as noted to the contrary: (a) all PQFPs are made in a mold that has a gate; (b) all PQFPs are gated on a corner, as exemplified in VLSI Document No. 004798-99 (Liang Dep.) Ex. 14; CX 110) (c) said gate is located on the opposite side of the lead frame from the bond or "whisker" wires. CX 400)

FF C 155. VLSI specifies the lead frames to be used by all of its subcontractors except [C]. (Liang Dep.) CPX 3 at 17. VLSI would provide [C] with a bonding diagram, and [C] would inform VLSI what lead frame was available. (Liang Dep.) CPX 3 at 18.

FF C 156. If a subcontractor does not have a lead frame meeting VLSI's

specifications, VLSI would purchase suitable lead frames from a third party manufacturer -- such as [C] [C] -- which would be delivered to the subcontractor. (Liang Dep.) CPX 3 at 18-21.

FF C 157. Today, VLSI uses lead frames that are stamped or etched from a single piece of [C] to encapsulate its DIP, SOIC and PLCC packages. (Liang Dep.) CPX 3 at 38-39, 49-50, 52-53. In the past, VLSI also has used lead frames made of [C] for some of its PDIP/PLCC/SOIC encapsulation work. (Liang Dep.) CPX 3 at 47-48.

FF C 158. The lead frames for PQFP packages are stamped or etched from a single sheet of [C]. (Liang Dep.) CPX 3 at 54.

FF C 159. [C] does not have the electrical and thermal performance as [C], but is a stiffer material and provides for a better coplanarity among the external lead of the finished package. (Liang Dep.) CPX 3 at 55-56.

FF C 160. Mr. Liang of VLSI testified at deposition that he did not know of any VLSI lead frames where the die pad was not downset. (Liang Dep.) CPX 3 at 59, 122-23.

FF C 161. The leads on the lead frame are conductors. (Liang Dep.) CPX 3 at 39.

FF C 162. The die pad and adjacent portions of the lead frame are plated with [C]. (Liang Dep.) CPX 3 at 40, 50, 53, 54, 109. The purpose of the plating is to promote the electrical connection between the bond wire and the conductors because [C] oxidizes very quickly. (Liang Dep.) CPX 3 at 40.

FF C 163. The leads on the finished integrated circuit are plated with a [C] solder. (Liang Dep.) CPX 3 at 48, 109. This coating provides better solderability, or wetting, of the device onto a PC board. (Liang Dep.) CPX 3

at 49.

FF C 164. VLSI specifies an epoxy die attach material to be used by each of its subcontractors except [C]. (Liang Dep.) CPX 3 at 22-23, 40.

FF C 165. VLSI typically uses one of two die attach materials: [C] [C]. (Liang Dep.) CPX 3 at 43, 51, 53, 54.

FF C 166. Both the [C] die attach materials are [C] and [C] conductive. (Liang Dep.) CPX 3 at 44.

FF C 167. The wire bonds in all VLSI plastic packages are made of [C] mil [C] wire. (Liang Dep.) CPX 3 at 56-57, 108. In some circuits, VLSI grounds the semiconductor chip with a [C] wire down bond onto the die pad or die pad supports. (Liang Dep.) CPX 3 at 85.

FF C 168. VLSI specifies the molding compound to be used by each of its subcontractors. (Liang Dep.) CPX 3 at 22-23.

FF C 169. Typically, during the recent past VLSI has used either [C] [C] (which differ from one another primarily in the shape and size of the fillers in the epoxy resin base). (Liang Dep.) CPX 3 at 45-46, 51, 53, 55.

FF C 170. All PDIP, SOIC, PLCC and PQFP products imported by VLSI are made in a conventional or "chase" mold having a gate located on the opposite side of the lead frame from the device and bond wires. (Liang Dep.) CPX 3 at 60-64; Liang Dep.) Vol. II, CPX 4 at 7-9, 11.

FF C 171. In PDIP and SOIC packages, which are rectangular in shape, the gate is located at the end of the package. (Liang Dep.) Vol. II, CPX 4 at 7-8. In PLCC and PQFP packages, which are square in shape, the gate is located at a corner of the package. (Liang Dep.) Vol. II, CPX 4 at 8-9.

FF C 172. VLSI may offer the same semiconductor product in either a

ceramic or a plastic package. (Liang Dep.) CPX 3 at 70.

FF C 173. The plastic package is cheaper to manufacture, and has a lower selling cost to the end purchaser. (Liang Dep.) CPX 3 at 72. One of the reasons for the lower manufacturing cost of plastic is the difference in cost between the plastic and the ceramic materials used to encapsulate. (Liang Dep.) CPX 3 at 72. Ceramic parts also have greater reliability and performance. (Liang Dep.) CPX 3 at 72.

FF C 174. One of VLSI's reasons for packaging integrated circuits in plastic is that plastic packaging is cheaper. (Liang Dep.) CPX 3 at 74.

FF C 175. Typically, during the recent past VLSI has used either [C] [C] (which differ from one another primarily in the shape and size of the fillers in the epoxy resin base). (Liang Dep.) CPX 3 at 45-46, 51, 53, 55.

FF C 176. INTENTIONALLY OMITTED

FF C 177. INTENTIONALLY OMITTED

FF C 178. INTENTIONALLY OMITTED

FF C 179. INTENTIONALLY OMITTED

FF C 180. INTENTIONALLY OMITTED

FF C 181. Analog Devices, Inc. ("Analog") has encapsulated integrated circuits in plastic at facilities located outside of the United States and imports the resulting products for sale into the United States. (Roberts Dep.) CPX 10 at 8, 42.

FF C 182. Analog imports plastic encapsulated integrated circuits in the following package types: Plastic Dual in Line Packages ("PDIPs"); Plastic Leaded Clip Carriers ("PLCCs"); Small Outline Integrated Circuits ("SOICs"); and Plastic Quad Flat Packs ("PQFPs"). (Roberts Dep.) CPX 10 at 15-20.

FF C 183. Analog also employs Asia-based subcontractors to assemble and encapsulate its integrated circuit products. [C] [C]. (Roberts Dep.) CPX 10 at 9-10.

FF C 184. Respondents' expert, Mr. Lawrence Plummer, testified that, regardless of whether a plate mold or conventional mold is used, the way Analog produces its products at issue in this investigation is almost identical to the way DRAM products are produced. Plummer Tr. 1408.

FF C 185. The assembly plant for Analog's Boston, Massachusetts semiconductor division is located at Analog Devices Phillipines, Inc. ("ADPI"). (Roberts Dep.) CPX 10 at 9, . Analog also maintains a second manufacturing plant, Analog Devices BV ("ADBV"), in Limerick, Ireland, which functions as its own encapsulating facility. (Roberts Dep.) CPX 10 at 9, .

FF C 186. After semiconductor wafer comes out from "wafer fab," it is subjected to gross electrical testing. (Roberts Dep.) CPX 10 at 76. The wafer is then shipped uncut to one or more offshore assemblers for encapsulation. (Roberts Dep.) CPX 10 at 76.

FF C 187. After the semiconductor wafer is received by the offshore assembler, it is put through a wafer sawing operation. The resulting semiconductor die are subjected to visual inspection and a quality control gate. Die which pass visual inspection are attached and wirebonded to lead frames and encapsulated in plastic. (Roberts Dep.) CPX 10 at 12, 76-77.

FF C 188. The resulting devices are then sent to mold cure, cutting and bending, lead finishing with tin or solder plate, and occasionally to branding and some electrical testing. The finished devices are then imported into the United States, subjected to outgoing quality control testing, and packaged for

shipping to customers at Analog's Wilmington, Delaware facility. (Roberts Dep.) CPX 10 at 12-14.

FF C 189. ADPI encapsulates the following PDIP packages: 8 pin, 14 pin, 16 pin, 20 pin, pin, 28 pin, and 40 pin. (Roberts Dep.) CPX 10 at 15.

FF C 190. ADPI encapsulates the following SOIC packages: 8 pin and 16 pin. (Roberts Dep.) CPX 10 at 16.

FF C 191. ADPI encapsulates the following PLCC types: 20 pin, 28 pin, and 44 pin. (Roberts Dep.) CPX 10 at 16.

FF C 192. ADBV encapsulates the following PDIP packages: 14 pin, 16 pin, 20 pin, pin, and 28 pin. (Roberts Dep.) CPX 10 at 18. ADBV does not make SOIC, PLCC or PQFP packages. Id.

FF C 193. [C] encapsulates a pin PDIP package, a 44 pin PLCC package, and a 20 pin SOIC package. (Roberts Dep.) CPX 10 at 18-19. Integrated circuits encapsulated by [C] in each of the foregoing packages have been imported by Analog into the United States. (Roberts Dep.) CPX 10 at 19.

FF C 194. [C] encapsulates 20 and 28 pin PLCC packages, as well as and 28 pin SOIC packages. (Roberts Dep.) CPX 10 at 19. Integrated circuits encapsulated by [C] in each of the foregoing packages have been imported by Analog into the United States. (Roberts Dep.) CPX 10 at 19-20.

FF C 195. [C] encapsulates PQFP packages, [C] [C] (Roberts Dep.) CPX 10 at 20.

FF C 196. [C] encapsulates 14 and 16 pin SOIC "gullwing" packages. (Roberts Dep.) CPX 10 at 20.

FF C 197. Analog purchases the lead frames used to encapsulate devices at its ADPI and ADBV facilities from [C] (Roberts Dep.) CPX 10 at 30.

FF C 198. [C] furnish the lead frames used to encapsulate Analog integrated circuits at their offshore facilities. (Roberts Dep.) CPX 10 at 30-31.

FF C 199. The lead frames used to encapsulated Analog's integrated circuits in PDIP packages are either stamped out of a continuous roll of metal or etched from a single metal sheet. (Roberts Dep.) CPX 10 at 34. Stamped lead frames are generally preferred. (Roberts Dep.) CPX 10 at 35.

FF C 200. The metal used for Analog's PDIP lead frames may be either [C]. (Roberts Dep.) CPX 10 at 31. [C] [C] (Roberts Dep.) CPX 10 at 33-34.

FF C 201. All of the SOIC and PLCC lead frames used by Analog are made out of a [C] (Roberts Dep.) CPX 10 at 35-36.

FF C 202. The portion of the lead frame to which the die is mounted is called the "die attach pad." (Roberts Dep.) CPX 10 at 50 and Ex. 5; CX 205. On some of Analog's lead frames, the die attach pad is not downset. (Roberts Dep.) CPX 10 at 57 and Ex. 5; CX 205. On other lead frames, the die attach pad is downset by 15 thousandths of an inch, or "15 mils". (Roberts Dep.) CPX 10 at 58 and Ex. 5; CX 205.

FF C 203. The top and bottom portion of each lead frame used by Analog is bordered with a solid metal portion called a "rail." (Roberts Dep.) CPX 10 at 55 and Ex. 5; CX 205. Each rail is pierced by circular and oblong holes used as reference and positioning points during assembly operations to align the lead frame in the mold. (Roberts Dep.) CPX 10 at 55-56 and Ex. 5; CX 205.

FF C 204. The lead frame consists of a plurality of fingers or leads ("conductors") that radiate 360° outwardly from the center of the lead frame. Plummer Tr. 1360, CX 205.

FF C 205. The leads on Analog lead frames are joined by portions of metal called a "dam bar." (Roberts Dep.) CPX 10 at 59 and Ex. 5; CX 205. The dam bar is used to keep the plastic confined in the mold during the molding process, and defines the outer edge of the plastic package. (Roberts Dep.) CPX 10 at 60 and Ex. 5; CX 205.

FF C 206. The die attach pad and surrounding leads on Analog's lead frames are plated either in [C]. (Roberts Dep.) CPX 10 at 31-32.

FF C 207. Analog formerly used a eutectic die attach process which required the use of a [C] die attach pad. (Roberts Dep.) CPX 10 at 33. Recently, however, Analog has switched to a [C] [C] (Roberts Dep.) CPX 10 at 33.

FF C 208. As a general rule, Analog's production lead frames now employ [C] [C] (Roberts Dep.) CPX 10 at 33, 35-36.

FF C 209. Analog uses [C] a polyamide die attach material, at its ADPI facility. (Roberts Dep.) CPX 10 at 37, 40. Analog uses [C] [C] at its ADBV facility. (Roberts Dep.) CPX 10 at 37.

FF C 210. Analog's subcontractors all use [C] (Roberts Dep.) CPX 10 at 37.

FF C 211. Analog does not specify which [C] is used by its subcontractors so long as its yield and reliability requirements are met. (Roberts Dep.) CPX 10 at 39-40.

FF C 212. The [C] is both electrically and thermally conductive. (Roberts Dep.) CPX 10 at 38. The [C] is both electrically and thermally conductive. (Roberts Dep.) CPX 10 at 37.

FF C 213. Analog's products are typically wire bonded with a piece of gold wire. (Roberts Dep.) CPX 10 at 70. A machine attaches one end of the wire to a silvered inner end of a lead and the other end to an electrical junction, or terminal, on the semiconductor device. (Roberts Dep.) CPX 10 at 70-71; Plummer, Tr. 1335-1337; CX 206; CX 251(a).

FF C 214. Presently, all of Analog's products are encapsulated using [C]. (Roberts Dep.) CPX 10 at 41-42. Analog employed [C] [C] [C] at its ADPI facility. (Roberts Dep.) CPX 10 at 83-85.

FF C 215. Analog molds PDIPs at its ADPI facility using a plate molding process. (Roberts Dep.) CPX 10 at 47. Analog molds SOICs and PLCCs at its ADPI facility using a conventional or "chase" molding process. (Roberts Dep.) CPX 10 at 47.

FF C 216. Analog molds PDIPs at its ADBV facility using a conventional or "chase" molding process. (Roberts Dep.) CPX 10 at 47.

FF C 217. During encapsulation, the lead frame and the bonded integrated circuit are placed in a mold cavity with the outer end of each of the conductors extending outside of the cavity. CX 251(a).

FF C 218. The inner ends of the conductors to which the whisker wires are connected do not extend from the sides of the mold cavity and are not supported by the mold cavity. Rather, the inner, free ends of the conductors extend into the mold cavity and are unsupported and cantilevered much like a diving board. (Plummer Tr. 1343, 1344.

FF C 219. In general, none of Analog's PDIP, SOIC and PLCC packages are made in a mold having a gate located on same side of the lead frame as the

device and whisker wires. (Roberts Dep.) CPX 10 at 88-89.

FF C 220. With respect to plate-mold PDIP packages encapsulated at ADPI, the lead frame is turned upside down so that the package "top" is located in the lower part of the mold, while the runner and gate system are located on the top half of the mold and inject plastic into what will become the package bottom. (Roberts Dep.) CPX 10 at 93-94 and Ex. 8; CX 208.

FF C 221. In all of Analog's conventional molding processes, the gate was located on the opposite side of the lead frame from the die and whisker wires. CPX 10 (Roberts Dep.) at 105-06 and Ex. 10; CX 209.

FF C 222. With respect to all PLCC packages, the gate is located on the opposite side of the lead frame from the bond wires and in a corner of the package. (Roberts Dep.) CPX 10 at 96 and Ex. 8; CX 208.

FF C 223. In mid-September, 1990, Analog concluded an evaluation of 8-pin PDIP and 8-pin SOIC devices manufactured in a mold where the gate was located on the same side of the lead frame as the bond wires and device. (Roberts Dep.) CPX 10 at 114, 118 and Ex. 12; CX 212.

FF C 224. These experimental top-gated devices were manufactured by loading the lead frames in the mold "upside down." CPX 10 (Roberts Dep.) at 114.

FF C 225. The electrical test data obtained from the top-gated devices showed no significant difference between these products and similar bottom-gated devices as far as the effect of molding is concerned. CPX 10 (Roberts Dep.) at Ex. 12 at 000221-22; CX 212.

FF C 226. Today's molding processes utilize an upwardly angled gate to help obtain simultaneous filling in the top and bottom halves of the mold. Hightower Tr. 4-6, 8, 250.

FF C 227. The technique for transfer molding integrated circuits as practiced by Analog creates a plug flow of the plastic. Plummer Tr. 1331.

FF C 228. In plug flow, as distinguished from spurting, the plastic first fills the cavity at the end where the gate is located and then, as a plug, moves to the opposite end of the cavity. The plug moves at the same velocity across the top and bottom of the cavity and directly engages the whisker wires. Plummer Tr. 1331, Schroen Tr. 184.

FF D 1. U.S. Patent Application Serial No. 331,006 was filed December 16, 1963 by Robert O. Birchler and E.R. Williams. The '006 application was followed by two subsequent applications which led to the '027 patent. The '006 application is therefore known as the "grandparent" application of the application that lead to the '027 patent. RPX 87; RX 40.

FF D 2. Subsequently, during this prosecution, in an action dated September 18, 1968, after claims had been added by amendment, the examiner found that the claims of the '006 application were directed to three distinct inventions, and thus required restriction between the following three groups of claims:

I. Claims 14 to 20, 23 and 45 to 52 drawn to a semiconductor device with an integrally molded mass of insulating material.

II. Claims 1 to 13, 21, 22 and 35 to 43 drawn to an injection molding process for semiconductor devices. [Note that the Examiner refers to the claims, which now appear in the '027 patent, as being 'injection molding,' whereas such claims have been referred to at the hearing as being for transfer molding. The name used is not material to this issue; the claims of Group II refer to "injecting" the fluid, which occurs in transfer molding.]

III. Claims to 34, 44 and 53 to 55 drawn to a lead frame for semiconductor devices and a method for securing semiconductor crystals to that frame, i.e., an intermediate product for use in producing the final semiconductor device.

Bjorge, Tr. 15-26; RPX 87, pp. 127-28.

FF D 3. In imposing the restriction requirement, the Examiner noted that the reason that the claims of Group II were patentably distinct from the claims of Groups I and III was that, while the former [Group II] contained an injection molding limitation, the latter [Groups I and III] could be molded by any process, stating:

While the inventions appear related, they are obviously distinct, i.e., they would not be subject to any double-patenting rejection if claimed in separate applications. The claims of Group II are distinct from those of Groups I and III

because the products and processes claimed in those Groups do not require an injection molding process, but can be made by other processes. Additionally, such a process as claimed in Group II has acquired separate status in the art and requires a different field of search. The claims of Group I are distinct from those of Group III because the latter claims in no way involve molded encapsulation and relate to an intermediate product only. The claims of Group I, on the other hand, contain many patentably distinct final product embodiments not recited in the claims of Group III. Restriction for the purpose of examination is, therefore, deemed proper.

RPX 86, p. 127-28.

FF D 4. In a response dated September 27, 1968, the applicants elected to maintain Group I in the original application, and this application issued as U.S. Patent No. 3,439,238. Bjorge, Tr. 1526-27; RPX 87, cover, p. 131.

FF D 5. The Group II claims, which were directed to the transfer molding process, were refiled in a divisional application (Serial No. 768,311) on October 17, 1968. Bjorge, Tr. 1527; RPX 86. After being refiled again, as Serial No. 384,768 on July 30, 1977, certain of these claims issued as U.S. Patent 4,043,027. RF 332, 350.

FF D 6. The Group III claims, which were directed to a lead frame, were also refiled in a divisional application (Serial No. 768,325) on October 17, 1968 which became the '764 patent. Bjorge, Tr. 1527; RPX 88.

FF D 7. Claim 26 of the '006 application provides as follows:

A method as defined in claim , comprising the further steps of embedding the semiconductor body and the strip regions to which the body and the semiconductor electrodes are conductively connected in a mass of insulating material prior to separating the strips from one another.

Emphasis added. RPX 87 at 60; RPX 88 at 37.

FF D 8. During the prosecution of application Serial No. 768,325, leading to the '764 patent, claims 16- were added. RPX 88, pp. 61-62. Claim 17, a claim dependent upon claim 16, claimed the step of encapsulating by the

transfer molding technique. Plummer, Tr. 1393; RPX 88, pp. 61-62.

FF D 9. Claim 16 of the '764 patent states:

16 A method for providing electrical connections to and encapsulating a semiconductor device comprising the steps of

a) providing the substantially flat metal sheet having recesses therein which divide the sheet into a plurality of conductor strips which are spaced apart from one another for least a major portion of their length and which are joined together at least one of their ends by at least one side piece, which is spaced from a central region of the assembly, a plurality of the conductor strips extending from the side piece parallel to one another for at least part of their lengths;

b) conductively connecting one face of a semiconductor wafer to one of said conductor strips in the central region;

c) conductively connecting electrodes on the opposite face of the wafer to conductor strips at the central region by separate lead wires;

d) enclosing the central region of the assembly in plastic insulating material to surround the wafer and lead wires and parts of the conductor strips; and

e) severing the conductor strips at positions spaced from the central region to eliminate the remainder of the sheet including the side piece."

Emphasis added. RPX 88; RX 17.

FF D 10. Claim 17 of the '764 patent states:

"17. A method, according to Claim 16, where an enclosing and encapsulating means includes the step of transfer molding the plastic insulating material."

RPX 88; RX 17.

FF D 11. At the time of the restriction requirement, application Claim 26 (which was included in Group III) specifically referred to "embedding the semiconductor body" in a "mass of insulating material." The claim language necessarily relates to molding in general, and transfer molding in particular, which were the embedding processes disclosed in the '764 specification.

RPX-88.

FF D 12. Claim 26 of the '006 application was "submitted under Rule 116 for the purpose of preparing the application for interference" and was copied from Patent No. 3,281,628 issued to Bauer et al on October 25, 1966." RPX 87 at 59 and 62; RPX 88 at 36 and 39.

FF D 13. Copied claim 3 of the Bauer patent (claim 26 of the '006 application) is "specifically applied to the disclosure of the present invention" in the remarks section of the May 25, 1967 amendment as follows:

Figure 9 shows further that semiconductor boy 142 and conductively connected strips 136, 138 and 140 are placed in a mould cavity, indicated by dotted outline 148, and embedded in encapsulating material to form the insulating mass 158 shown in Figure 10. Page 10, lines 23-26 state that transfer moulding is completed prior to separating the strips from one another along the dotted lines 154 and 156 of Fig. 9.

Emphasis added. RPX 87 at 64; RPX 88 at 41.

FF E 1. TI's method of plastic encapsulation is essentially the same as respondents. (Plummer Tr. 1380-1381, CX-7 at 120, CX-600 at 120).

FF E 2. Integrated Circuit Engineering Corporation is a consulting company and data source by the integrated circuit industry. Corrigan Tr. 1041.

FF E 3. Worldwide sales of semiconductors encapsulated in plastic and non-plastic were approximately \$62 billion in 1989. (RX-232A).

FF E 4. Over 92% of integrated circuits sold worldwide in 1989 were plastic encapsulated (RX-232F).

FF E 5. American semiconductor manufacturing companies made over \$21 billion worth of semiconductors in 1989. RX-232C and RX 232E.

FF E 6. LSI will have total sales of approximately [C] million this year. Corrigan Tr. 1039-40.

FF E 7. VLSI will have total sales of approximately [C] million this year. Corrigan Tr. 1040.

FF E 8. Cypress will have total sales of approximately [C] million this year. Corrigan Tr. 1040.

FF E 9. IDT will have total sales in excess of [C] million this year. Corrigan, Tr. 1040.

FF E 10. Analog will have total sales in excess of [C] this year. RX 278, RX 465.

FF E 11. Most plastic encapsulation of integrated circuits is done offshore because of the significant labor cost savings obtained thereby. Labor costs are ten times higher in the United States than they are overseas. (Wilson Tr. 729-731, Adams Tr. 1181, Corrigan Tr. 1036).

FF E 12. TI sold over [C] worldwide in plastic encapsulated

integrated circuits in 1989 of which [C] were encapsulated abroad and [C] (approximately [C]) were encapsulated domestically. TI sold almost [C] in plastic encapsulated integrated circuits in the United States in 1989. CX 436, SX-109.

FF E 13. TI's only domestic production facility for plastic encapsulated integrated circuits is the Flexible Assembly Module located in Sherman, Texas ("the FAM"). Schroen Tr. 155, Wilson Tr. 721.

FF E 14. The FAM occupies a very small portion of TI's Sherman facility. Wilson Tr. 765.

FF E 15. The FAM was established in 1983 with an initial start up cost of [C]. Wilson Tr. 752-754, CX 413.

FF E 16. The type of activity conducted at the FAM is generally referred to as the "back-end" manufacturing operations of encapsulated integrated circuit production. (Schroen Dep.) SPX 5 at 44-45.

FF E 17. In 1983 the only mold press in the FAM was a TOWA machine which is a top-gating machine. All integrated circuits plastic encapsulated in the FAM in 1983 were made using a top-gating process. Wilson Tr. 747, RX-382.

FF E 18. Approximately 52% of all integrated circuits manufactured at the FAM between 1983-1990 were plastic encapsulated by a top-gating process. RX-382.

FF E 19. At the FAM, the steps performed on products after encapsulation include: curing, laser marking for some products, trim and form, singulation, inspection and electrical testing. (Wilson Dep.) RPX-106 at 46-48.

FF E 20. The FAM manufactures only plastic encapsulated devices. It does not perform ceramic encapsulation. (Wilson Dep.) RPX 106 at 16-17.

FF E 21. Primarily, the FAM encapsulates logic products. Wilson Tr.

804-05.

FF E 22. The FAM is part of TI's General Purpose Logic Department ("GPL"). The GPL department covers different products in the logic family as opposed to products in the linear, MOS, or memory family. Wilson Tr. 739; (Wilson Dep.) RPX-106 at 17.

FF E 23. TI alleges a cumulative investment from 1983-present in the FAM of [C] Wilson Tr. 750, CX-412.

FF E 24. TI alleges that the current book value of the FAM is approximately [C] although this figure also includes the value of some equipment that has been removed to other locations. RX-238.

FF E 25. The reason for placing an assembly site next to a United States wafer fabrication plant was to achieve quick cycle time in finished products. Wilson Tr. 769.

FF E 26. The alternative to having a full size assembly facility next to a domestic wafer fabrication facility was to continue to plastic encapsulate and test semiconductors abroad and forego the reduced cycle time necessary to meet current market requirements. Wilson Tr. 769, CX 413.

FF E 27. When the FAM began operations, it had an aggressive charter to compete with offshore encapsulation centers which had much lower labor costs. Wilson Tr. 728-29.

FF E 28. This early charter was to automate the process to lower labor costs and make the FAM a high volume production facility. Wilson Tr. 729-30.

FF E 29. The FAM was originally intended to be a full scale production facility producing 20% of the United States demand for general purpose logic products which would be about [C] units a month. Wilson Tr. 770-771, CX-413 at p. 3.

FF E 30. The FAM's early attempts to automate proved ineffective as a cost reduction measure. Wilson Tr. 729.

FF E 31. By March 1, 1985, the FAM had one conventional bottom-gating mold press and five TOWA top-gating mold presses. Wilson Tr. 776, RX 417.

FF E 32. The FAM added more equipment and by 1988 was using 5 conventional mold presses, 3 FICO Automated Molding Systems and 5 TOWA mold presses. RX 417.

FF E 33. TI's goal was to increase the volume of domestic production in order to spread its fixed costs and achieve economies of scale. The alternative was to continue molding offshore and forego the reduced cycle time necessary to meet current market demand. Wilson Tr. 784, RX 375.

FF E 34. Although early on the FAM was effective in coming up with good designs and equipment, it could not compete with the lower costs of offshore high volume production facilities. Wilson Tr. 729-31.

FF E 35. In 1988, TI changed the FAM's charter from being a high volume assembly operation to making small lots of high pin count devices. Wilson Tr. 724, 731.

FF E 36. After 1987, the number of units built dropped off pursuant to the decision to change the charter from high-volume production to higher pin count, more specialized production. Wilson Tr. 731.

FF E 37. In 1987-1988 the FAM shifted its focus to "quick turn capability" of products and stressing quality and customer satisfaction. Wilson Tr. 732.

FF E 38. Thus, today, the FAM charter includes the quick turnaround of customers' product requests made possible by the design, engineering and production capabilities of the FAM. In such a way, the customer can receive

an ordered product within a few days and get the customer's line [production activities] up [operating]. Wilson Tr. 718-19, 758-59; (Wilson Dep.) RPX-106 at 17; CX-427.

FF E 39. The FAM's current charter is exemplified in a brochure which it distributes to its customers. This brochure explains how the FAM meets its customers' requirements and discusses the quality of the products made at the FAM. Wilson Tr. 722; CX-402.

FF E 40. This brochure, called "Customer Satisfaction Through Total Quality," explains that as "TI's only plastic encapsulated Integrated Circuit assembly facility located in the United States . . ." it is "designed from front to back to provide our customers with top quality IC devices." CX-402 at 1-2.

FF E 41. Additionally, it stresses the primary focus of the FAM: the customer and total commitment to quality. "That sense of commitment is the foundation of FAM and it ensures our ability to meet the every-increasing expectations of our customers." CX-402 at 1-3.

FF E 42. TI conducts audits to ensure the quality of the processes used at the FAM and to ensure that they are in conformance with customer specifications. Wilson Tr. 723.

FF E 43. Pursuant to the change in the FAM's charter, TI off-loaded the production of [C] to its plants in Malaysia and Taiwan. Wilson Tr. 731, 788-789, RX-382.

FF E 44. Production of plastic encapsulated chips at the FAM fell from almost [C] RX-382.

FF E 45. Production in 1991 has been less than [C]

month. Wilson Tr. 744.

FF E 46. From its peak employment in 1987, over [C] at the FAM were eliminated with the change in charter and down-sizing of the FAM. RPX-108 at Ex. 8, Wilson Tr. 737-738.

FF E 47. The numbers of employees at the FAM has decreased from [C] in January, 1990 to about [C] at the time of the hearing. Current plans are to keep the number of employees around [C]. Wilson Tr. 737-738, 740.

FF E 48. Millions of dollars worth of equipment was removed from the FAM as a result of the transfer of 14/16 pin DIP and SOIC production offshore, some of which was relocated in foreign facilities. Wilson Tr. 801-803, RX-398, RX-417.

FF E 49. The FAM is a true manufacturing site. Schroen Tr. 50-51.

FF E 50. CX-408, a floor plan of the FAM, describes the allocation of the FAM floor space to particular operations conducted at the FAM. Wilson Tr. 732-34.

FF E 51. The FAM occupies a total of approximately [C] square feet with approximately [C] of that devoted to the production area. Wilson Tr. 732-34; (Wilson Dep.) RPX-106 at 12; CX-408.

FF E 52. The FAM utilizes additional warehouse space of approximately [C] square feet at another location in Sherman which operates as the FAM's product distribution center and a storage area for excess equipment. Wilson Tr. 733-34; (Wilson Dep.) RPX-106 at 57-58.

FF E 53. Over [C] square feet of the FAM is devoted to final testing and packaging of chips. CX-408, Wilson Tr. 805, 812.

FF E 54. Currently, the FAM plastic encapsulates the following package types: 20, and 28 pin DIP; 20, and 28 pin SOIC; and 28, 48 and 56 pin SSOP.

Wilson Tr. 716A.

FF E 55. The FAM has responsibility primarily for large pin type plastic packages and in trying to market new devices ahead of the competition. Wilson Tr. 7-25.

FF E 56. Products such as the 28, 48 and 56 pin SSOPs as well as the 28 pin DIP and 28 pin SOIC were all developed at the FAM. Wilson Tr. 720.

FF E 57. Two new large pin count packages currently under development at the FAM are the [C] Wilson Tr. 719-20; 725. Mechanical samples of these new devices are expected to be available at the end of the third quarter of 1991 with production commencing by 1992. Wilson Tr. 719-20.

FF E 58. The 28 pin DIP, 28 pin SOIC and 28 pin SSOP are currently made only at the FAM and no other TI facility produces them. Wilson Tr. 720, 725.

FF E 59. In July of 1990, the FAM employed [C] people who were directly involved in the plastic encapsulation of integrated circuits. Wilson Tr. 737.

FF E 60. The employee numbers at the FAM were reduced after a slow financial period for TI during late 1990 and in the beginning of 1991. Wilson Tr. 738.

FF E 61. In the early months of 1991, employee reductions not only took place at the FAM but also at offshore TI facilities such as in Portugal and in Malaysia. Wilson Tr. 738, 740.

FF E 62. Currently, the FAM employs about [C] people for the plastic encapsulation of integrated circuits. Wilson Tr. 737-38.

FF E 63. The FAM's current plans are to keep employee levels at a constant unless the demand for new products [C] requires more employees. Therefore, the only expected change would be a potential

increase in employee numbers. Wilson Tr. 740-41.

FF E 64. The FAM is the only nucleus technical production facility in the United States. Its employees include the whole gamut of engineers: product engineers, process engineers, equipment engineers, production operators, and equipment technicians. Wilson Tr. 741-42; (Wilson Dep.) RPX-106 at 61-67; CX-410.

FF E 65. Among the FAM's present [C] production operators who run the equipment (Wilson Tr. 742, 804); process engineers who develop the processes and make sure they are run within specifications (Wilson Dep.) RPX-106 at 23; and equipment engineers who design modifications to equipment and work with the Process Automation Center ("PAC") designing new equipment for TI. (Wilson Dep.) RPX-106 at 22.

FF E 66. The engineering staff at the FAM is highly qualified and capable of implementing ideas generated in a laboratory setting. Schroen Tr. 46-47.

FF E 67. Suggestions for improving the FAM's operations are encouraged and can be submitted by FAM employees through Method Improvement Reports or "MIR." Wilson Tr. 749; CX-411.

FF E 68. Employee participation is also encouraged through publication of a Quarterly Newsletter which provides employee recognition and emphasizes the importance of quality and customer service to the FAM's operations. Wilson Tr. 736; CX-403.

FF E 69. Currently, there are five molding presses in operation at the FAM. Wilson Tr. 734.

FF E 70. The presses currently operating at the FAM are all bottom-gated. Wilson Tr. 745. These include 3 Stokes conventional molding

presses and three LaRose conventional molding presses. Wilson Tr. 734.

FF E 71. However, in previous years the FAM used a TOWA multiplunger molding press which used a top-gated process; in fact, in 1983 the FAM's production was all top-gated. Wilson Tr. 744-47.

FF E 72. In 1991, the FAM shipped out its last TOWA Multiplunger molding press. Wilson Tr. 734. The TOWA molding presses were gradually removed from the FAM because they required a high level of maintenance and more labor to run than the conventional presses. Wilson Tr. 734-35.

FF E 73. Removal of the last TOWA molding press in 1991 did not affect the FAM's capacity. Wilson Tr. 735-36.

FF E 74. Since January 1991, average monthly production at the FAM is a little less than [C] Wilson Tr. 744.

FF E 75. In 1990, net units built at the FAM totalled [C] Wilson Tr. 744; RX-383.

FF E 76. In 1989, net units built at the FAM totalled [C] RX-383.

FF E 77. In 1988, net units built at the FAM totalled [C] RX-383.

FF E 78. In 1987, net units built at the FAM totalled [C] RX-383.

FF E 79. In 1986, net units built at the FAM totalled [C] RX-383.

FF E 80. In 1985, net units built at the FAM totalled [C] RX-383.

FF E 81. In 1984, net units built at the FAM totalled [C] RX-383.

FF E 82. In 1983, net units built at the FAM totalled [C] RX-383.

FF E 83. The FAM built a total of [C] units from 1983 to 1990. (RX-383; Wilson Tr. 744).

FF E 84. Total capital approved from 1983 through 1990 for the FAM was [C] Wilson Tr. 750; CX-412-419.

FF E 85. CX-412 is a summary report of all capital packages that were authorized for installation at the FAM from 1983-1990. Wilson Tr. 749-50; CX-412.

FF E 86. Once capital is approved, that is the amount the FAM is authorized to use. Wilson Tr. 750-52; CX-413.

FF E 87. An example of a project which makes up this [C] capital investment is the "FAM Auto Tape Attach" project which represents an expenditure of [C] for equipment used to mount the wafer on a tape. Wilson Tr. 754-56; CX-419.

FF E 88. The FAM Impact Repair EQ, a 1990 project representing an expenditure of [C] involved a piece of equipment for testing the impact of certain procedures on plastic encapsulated products. Wilson Tr. 756; CX-419.

FF E 89. The FAM Video Editor, also a 1990 project representing an expense of [C] was the purchase of a video editor to replace one that was destroyed. Wilson Tr. 756; CX-419.

FF E 90. The Video Editor was needed because the FAM does a lot of video taping for training. They have a computer enhanced video training module set up for their employees and also use it for time studies. Wilson Tr. 756-57.

FF E 91. Another 1990 project, the SGPL FAM SSOP Incremental Capacity, involved the second capital expenditure to fill a need that arose after an

initial expenditure was used to purchase some molding equipment. Once the equipment and process were installed, an additional [C] was authorized to buy more equipment to use with the first equipment purchased. Wilson Tr. 757-58; CX-419.

FF E 92. When the FAM makes a request for capital, it has to submit an equipment list associated with it to verify what would be purchased and installed. Examples of such equipment lists are contained in CX-413-419. Wilson Tr. 752; CX-413-419.

FF E 93. In 1984 the following types of equipment were installed at the FAM: [C

] The total cost of this equipment was [C] (Equipment List contained in CX-413).

FF E 94. In 1985, capital projects were approved. CX-414. The first, [C

] (Equipment List contained in CX-414). The total cost of this equipment was [C] CX 414.

FF E 95. The second 1985 project, the FAM Line Balance, involved the following equipment: [C]]. CX-414.

FF E 96. The third project from 1985 for which an equipment list was submitted was the FAM Abacus III Bonders. This project involved the purchase of bonder equipment costing [C] CX-414.

FF E 97. For the capital projects approved in 1986, the FAM ASDIP Solder Machine necessitated the purchase of [C] worth of equipment including a [C] CX-415.

FF E 98. Another 1986 project, the FAM Productivity Improvement, involved the expenditure of [C] for a [C] CX-415.

FF E 99. A third 1986 project, the FAM S.O. Production Phase I utilized equipment costing [C] This equipment included: [C] [C] CX-415.

FF E 100. The FAM S.O. Taping Machine, another 1986 project necessitated the purchase of two taping machines, at a cost of [C] CX-415.

FF E 101. In 1987, [C] was spent on equipment purchased for a 28 pin Capability Project. This project utilized the following types of equipment: [C] CX-416.

FF E 102. The FAM ASDIP Transfer, a 1987 project necessitating [C] worth of equipment, utilized the following types of machinery: [C] [C] CX-416.

FF E 103. The FAM Laser Strip Handler was also a 1987 project which involved [C] costing [C] CX-416.

FF E 104. The FAM Conventional Mold Control was a 1987 project which involved the purchase of a [C] at the cost of [C] CX-416.

FF E 105. Other equipment purchased for capital projects in 1987

includes: [C
] CX-416.

FF E 106. 1988 Expenditures for equipment included the expenditure of [C
] CX-417.

FF E 107. Other equipment approved and purchased for use in 1988 capital projects includes: [C
] CX-417.

FF E 108. A Tape/Reel Machine Project, authorized in 1989, utilized a [C
] CX-418.

FF E 109. Other equipment purchased for 1989 capital projects includes: [C
] CX-418.

FF E 110. A capital project approved in 1990, called "FAM Auto Tape Attach," involved the purchase of a [C
] CX-419.

FF E 111. Other equipment purchased for 1990 capital projects includes a [C
] CX-419.

FF E 112. An additional [C] of capital was approved in April 1991 to purchase equipment for new products TI intends to introduce in early 1991, the [C] Wilson Tr. 719-20.

FF E 113. The Sherman FAM is important in that it is probably the only place in the world where one can start with raw silicon and complete the assembly of a finished product in one location. Wilson Tr. 725-726; RPX-106

(Wilson Dep.) at 21. This is because TI's Sherman facility not only houses the FAM but it also houses a wafer fabrication facility. Wilson Tr. 726.

FF E 114. The vast majority of the wafers that are encapsulated at the FAM come from Sherman General Purpose Logic Wafer Fab. Wilson Tr. 718; RPX-106 (Wilson Dep.) at 186.

FF E 115. The wafer fabrication operations at the Sherman General Purpose Logic is one of the larger wafer fab sites in the world. Wilson Tr. 726.

FF E 116. The FAM is the only TI facility that has, in one location, a design area with engineers, administrative staff to make decisions concerning the introduction of new packages, and product engineers for qualification of new devices. Wilson Tr. 726; RPX-106 (Wilson Dep.) at 21.

FF E 117. The FAM is unique because it has a design function, a qualification function, and quick turnaround capabilities, all in one location to meet customer demands and to work closely with customers regarding new or different products. Wilson Tr. 718-19, 726.

FF E 118. The FAM has an advantage in cycle time over foreign facilities in the ability to get the product to the customer in just a few days because of its U.S. location and the different functions the FAM can perform in one location. Wilson Tr. 726-29.

FF E 119. Because it is the only TI plastic encapsulating facility located in the United States, the FAM has many visiting customers that tour the facility to see its operations. Wilson Tr. 722.

FF E 120. Recently, one TI customer, [C] visited the FAM as part of [C] efforts to improve operations. Wilson Tr. 723-.

FF E 121. TI keeps track of customers such as [C] [C]

] who have called upon the FAM to shorten the product cycle time, avoiding the need for the customer to shut down its production line awaiting for product from offshore locations. Wilson Tr. 759-60; CX-427.

FF E 122. The "FAM" in Sherman, Texas, is important from a technical standpoint because it can implement laboratory results on a true manufacturing line. Schroen Tr. 46-47, 50.

FF E 123. FAM is also the testing ground for the next generation of General Purpose Logic Production, including new packages, new devices and assembly technology developments. CX-402 at 2; Wilson Tr. 747.

FF E 124. The FAM also tests products that are assembled at other TI assembly facilities. Wilson Tr. 812.

FF E 125. New product introduction is a function of the FAM. RPX-106 (Wilson Dep.) at 17. About [C] of the activity at the FAM is devoted to new devices. Wilson Tr. 748-49. The remaining [C] of the FAM's activity consists of assistance to customers who have a line down, and back end type support. Wilson Tr. 818-19.

FF E 126. New product introduction is also known as "quick cycle time." RPX-106 (Wilson Dep.) at 17.

FF E 127. When a new product is designed at the FAM, the main concerns are turnaround and quick cycle time. Wilson Tr. 727.

FF I 128. One new device, for example, had to be tested extensively by the FAM because the wafer fab facility could not get the process in control to meet the customer's need. The FAM did testing in an effort to control this process. Wilson Tr. 748.

FF E 129. The FAM has extensive listings of new devices tested within its facility CX-428). There are two general types of tests conducted on new 1

evices. They are electrical testing and mechanical testing to ensure that it is functioning properly. Wilson Tr. 747; CX-428.

FF E 130. Many of these tests involve compact devices. These devices are important because they can provide speed that customers are now demanding. Wilson Tr. 748.

FF E 131. New equipment for packaging is also tested at the FAM. Schroen Tr. 52.

FF E 132. The FAM projects bear an important relationship to its goal of customer satisfaction. All of FAM's processes are continually studied to ensure its ability to meet the ever-increasing expectations of its customers. CX-402.

FF E 133. In addition to the [C] spent on the FAM between 1983-1990, the semiconductor group had capital projects totalling over [C] from 1983-1990. RX-373-380.

FF E 134. TI presently encapsulates plastic semiconductor devices in at least 11 foreign facilities located at Kuala Lumpur, Malaysia; Taipei, Taiwan; Oporto, Portugal; Hiji, Japan; Miho, Japan; Hatogaya, Japan; Aguascalientes, Mexico; Brazil; Baguio, Philippines; Singapore; and Rieti, Italy. SX-109, RX-405).

FF E 135. TI encapsulates over [C] of its plastic integrated circuits at its foreign facilities. SX-109.

FF E 136. TI's foreign assembly plants occupy approximately [C] square feet of space. RX-405.

FF E 137. Approximately [C] people are employed at TI's foreign plastic encapsulation facilities. RX-405.

FF E 138. The current net book value of the land, buildings and

equipment in TI's foreign assembly plants is over [C] RX-405.

FF E 139. TI licenses the '027 patent. Donaldson Tr. 850-51.

FF E 140. The number of TI licenses involving the '027 patent is a constantly changing number because TI is continually negotiating new agreements. Donaldson Tr. 851.

FF E 141. [C

] Donaldson Tr. 879.

FF E 142. TI has spent approximately [C] since 1981 on its licensing activities. Donaldson Tr. 869-871, 876, CX 421, CX 423.

FF E 143. All of TI's semiconductor related licenses [C

] Donaldson Tr. 875, 888-889,

RX-286, RX-423.

FF E 144. TI has approximately [C] patents in its patent portfolio. Donaldson Tr. 880.

FF E 145. CX-421 is a list of a number of companies with whom TI has semi-conductor patent license agreements involving the '027 patent. However, the list omits [C] Donaldson Tr. 852; CX-421.

FF E 146. CX-421 reflects over [C] which include the '027 patent. CX-421; Donaldson Tr. 852.

FF E 147. All of the TI licenses that involve the '027 patent are [C] Donaldson Tr. 875.

FF E 148. The '027 patent has [C] Donaldson Tr. 879, 880, CX-421.

FF E 149. Both before and after a license is executed, various activities take place in the licensing department at TI. These activities include [C

] Donaldson Tr. 870-74; 908.

FF E 150. TI cannot state with precision what portion of the administrative licensing activity relates to the '027 patent alone. Donaldson Tr. 875.

FF E 151. TI's licensing department expenditures include direct salaries, benefits, cost center allocations based on the number of people working in the licensing department, allocations for office space, telecommunications equipment, computers and general overhead. Donaldson Tr. 878-879, CX 423.

FF E 152. The expenses also include the cost of an engineering lab in which other companies' products are decapped and reverse engineered in order to analyze the circuitry to determine whether it utilizes any of TI's proprietary technology. Expenses incurred in analyzing a product's circuitry are unrelated to the '027 patent. Donaldson Tr. 854, 875, 909.

FF E 153. There are substantial expenditures involved with the administrative activity to monitor a license including one involving the '027 patent. Donaldson Tr. 875.

FF E 154. The licensing group for TI is located in Dallas, TX. Donaldson Tr. 879.

FF E 155. The approximate square footage of the area used by the licensing group at TI is over [C] square feet of office space and [C] square feet of laboratory space. Donaldson Tr. 879.

FF E 156. In 1990, the licensing group at TI billed approximately [C] on licensing activities. Donaldson Tr. 925; CX-423.

FF E 157. Some of the expenses of the licensing group are not included in the [C] These include litigation costs, some activities relating to the evaluation of products, and a few other activities. Donaldson Tr. 926; CX-423.

FF E 158. In connection with licensees involving the '027 patent, TI has [C]. Also, [C] assist them. Donaldson Tr. 877.

FF E 159. One TI attorney spends essentially all of his time on licensing the '027 patent. Donaldson Tr. 918.

FF E 160. Additional personnel is involved in licensing activity involving the '027 patent, including lab personnel. Donaldson Tr. 877-78.

FF E 161. The licensing department at TI also gets assistance from design engineers on a case-by-case basis. Donaldson Tr. 877-78.

FF E 162. In the last five years, TI has received approximately [C] [C] from licenses that include the '027 patent. Donaldson Tr. 880.

FF E 163. INTENTIONALLY OMITTED

FF E 164. The PAC, or "Process Automation Center", is located in Dallas, Texas. Schroen Tr. 44; Wilson Tr. 720; Adams Tr. 1127.

FF E 165. At the Dallas PAC, TI carries out research and development activities related to the commercial production of plastic encapsulation of semiconductor devices. Schroen Tr. 47, Adams, Tr. 1127, 1131.

FF E 166. TI conducts research at the PAC into the development of automated machinery and the expansion of TI's technology. Schroen Tr. 49-50,

204, RX 474 (a).

FF E 167. There is also a PAC or "Process Automation Center" located at TI's facility in Singapore. Schroen Tr. 72.

FF E 168. Limited R&D work is performed by TI at the Singapore PAC, including a small amount of tooling design and some die attach research and development. Schroen 72; Adams Tr. 1191.

FF E 169. Approximately [C] people are employed at the Singapore PAC today. Adams Tr. 1190.

FF E 170. The PAC has three major areas. The first one is packaging and process development where packages and processes for new packages are developed and the existing packages are worked on for cost reduction and improvements. The second is the development of assembly equipment. The third is new processes developed for the packages and test equipment. Adams Tr. 1127.

FF E 171. Because the FAM is so close to the PAC, it is a very convenient site for equipment and process testing. Adams Tr. at 1142; Schroen Tr. 46-47.

FF E 172. Many of the products on equipment design and on processes are sent to the FAM for beta testing. Therefore, the PAC uses the FAM as its initial site for taking a concept into production. Adams Tr. at 1142.

FF E 173. Currently, the auto align programs are tried out first at the FAM. Adams Tr. at 1142-43.

FF E 174. The FAM performs substantial design work, working with the Dallas PAC on equipment and processes. Wilson Tr. 719.

FF E 175. The Dallas PAC works in conjunction with TI production sites to eliminate process problems and difficulties, ensuring that the process runs

under control at high yield. Schroen Tr. 47-49.

FF E 176. Dr. Schroen's laboratory is a part of the Dallas PAC. Approximately [C] people are employed in Dr. Schroen's laboratory today. Schroen Tr. 52, 68.

FF E 177. The FAM line in Sherman is the primary ground where the PAC tries out new innovations related to plastic packaging. Schroen Tr. 52-53.

FF E 178. If the FAM has a problem in its processes, the PAC is called on for assistance. Schroen Tr. 70-71.

FF E 179. For example, a recent research effort, conducted by the Dallas PAC and FAM together, consisted of an attempt to eliminate steps which could be harmful to a plastic package. Schroen Tr. 51.

FF E 180. The Dallas PAC conducts research aimed at anticipating customer needs and expanding existing technology to satisfy customer needs. Schroen Tr. 49-50.

FF E 181. All of the [C] employees at Dr. Schroen's PAC laboratory work on the plastic encapsulation of integrated circuits. Schroen Tr. 68-69.

FF E 182. The employees of Dr. Schroen's laboratory include computer specialists, package designers, trim and form equipment designers, metallurgy specialists, chemistry specialists and reliability specialists. Schroen Tr. 44-46.

FF E 183. The computer specialists who work with Dr. Schroen set up software programs so that phases of the molding process can be computer simulated. Schroen Tr. 44-45.

FF E 184. The package designers who work with Dr. Schroen determine the design of the molds by laying out the lead frames, determining the size of the package, and making sure they follow industry standards. Schroen Tr. 45.

FF E 185. The package designers who work with Dr. Schroen also design trim and form equipment. Schroen Tr. 46.

FF E 186. The metallurgy specialists who work with Dr. Schroen help to determine the characteristics of the gold, copper or aluminum wire bonds to the chip and to the lead frame. Schroen Tr. 46.

FF E 187. The chemistry specialists who work with Dr. Schroen determine the chemical effects of molding compound polymerization within the package which may release chemicals affecting the lead frame on the chip. Schroen Tr. 46.

FF E 188. Other chemical specialists who work with Dr. Schroen are dedicated specifically to the study of plastic materials for molding compounds. Schroen Tr. 47.

FF E 189. The reliability specialists who work with Dr. Schroen test the molded packages in atmospheres of varied moisture and temperature to insure the integrity of the molded packages. Schroen Tr. 46.

FF E 190. Assembly and packaging are integral steps involved in a finished semiconductor device, because the steps which have been performed before the actual molding step have an effect on molding and the finished product. Schroen Tr. 69-70.

FF E 191. Dr. Schroen's group at the Dallas PAC has designed most of the lead frames for all packages at TI as well as out lines of packages. Schroen Tr. 74-75.

FF E 192. At the Dallas PAC, research is conducted on molding compounds and fillers. Schroen Tr. 165.

FF E 193. Current research and development relating to plastic encapsulation includes work on molding materials for high thermal dissipation,

molding materials for thinner packages, and lower cost molding materials.

Schroen Tr. 53.

FF E 194. Some of the research conducted at the Dallas PAC is directed to the existence of trace radioactive materials in the molding compound.

Schroen Tr. 166.

FF E 195. The PAC conducts research on the fillers of molding compounds. Schroen Tr. 27-28.

FF E 196. TI has conducted research at the Dallas PAC that continues today to ensure that there are no voids or cracks in the molding compound and to make sure the molding compound does not separate from the metallic lead frame and expose itself to corrosive elements. In general, TI has conducted research to ascertain under which conditions the integrity of a plastic package is guaranteed. Schroen Tr. 35-37.

FF E 197. TI has conducted extensive research at the Dallas PAC to make sure that the stress exerted on the lead frame caused by polymerization of the plastic material does not affect the operation of the chip or harm the thin whisker wires. Schroen Tr. 39.

FF E 198. The design of trim and form equipment, also called tooling, is intimately related to TI's efforts to encapsulate and assemble semiconductor chips. Schroen Tr. 46.

FF E 199. Dr. Schroen testified that his PAC laboratory is about [C] larger than Hearing Room 100A at the U.S. International Trade Commission. Schroen Tr. 44-45.

FF E 200. The PAC employs a [C]]

RX 337 at p. 118-120.

FF E 201. In 1989 and 1990, the PAC sold over [C] worth of equipment to third parties. Adams Tr. 1193, TI's Supplemental Response to Analog Interrogatory No. 127, dated May 8, 1991.

FF E 202. There are [C

] Adams Tr. 1128-29.

FF E 203. TI initially alleged that it has expended approximately [C] [C] on research and development projects relating to the '027 patent from 1976 to 1990. Adams Tr. 1131, CX 425, CX 426.

FF E 204. CX-4 is a summary listing all of these projects and reflects a brief description of each. CX-425 and CX-426 are TI financial records that support the expenditures for the projects summarized in CX-4. Adams Tr. 1131-32; CX-425; CX-426.

FF E 205. Although CX-4 adds up to approximately [C] dollars, Mr. Adams testified that projects relating to four (4) research projects relating to SIP package tooling totalling approximately [C] should be excluded, thereby reducing the total to approximately [C] Adams Tr. 1218-1219, TI's Supplemental Response to Commission Investigative Staff's Second Set of Interrogatories, April 15, 1991; TI's Posthearing Statement [Attachment C].

FF E 206. TI's investment in research and development relating to the

'027 patent was calculated by going back through project records from 1976 to 1990 and picking out projects that were easily identifiable as plastic-related. Adams Tr. 1130.

FF E 207. The amount arrived at in CX-4 is conservative. Adams Tr. 1130.

FF E 208. The projects listed in CX-4 do not include any work done off-shore. It only includes work done in Dallas. Adams Tr. 1232.

FF E 209. Many of the projects listed in CX-4 involved the Sherman FAM. Adams Tr. 1142.

FF E 210. The Dallas PAC also carries out projects that are specifically for research and development of ceramic packages. Adams Tr. 1134.

FF E 211. No ceramic projects were included in the CX-4 as expenditures related to the '027 patent. Adams Tr. 1134.

FF E 212. Five criteria were used to determine which products should be included in CX-4. They include products which are plastic encapsulated, two-sided, wire-bonded, use a two-sided mold, and planar in nature. Adams Tr. 1134, 1143-44, 1177.

FF E 213. Included in TI's [C] for R&D is [C] relating to research and development of equipment offered for sale by the PAC. This includes [C] relating to development of electrical test equipment; [C] relating to development of die mount equipment; [C] relating to marketing and visual and mechanical inspection equipment; [C] relating to trim and form, lead finish and lead conditioning equipment; [C] relating to development of several generations of ABACUS bonders; and [C] relating to general factory automation projects including development of hardware and software. Adams Tr. 1135, 1138, 1220-1231, RX 475, CX 4, CX 425,

CX 426.

FF E 214. The equipment involved in TI's Abacus Bonders projects includes: Copper Bonder, Copper Bonding Program, Auto Align Abacus Bonder, Auto Align Bonder, Abacus III and IV software and other programs, and Abacus Tech Development. CX-4 at 11, 17, 22-, 30-33.

FF E 215. The '027 patent does not cover the Abacus bonder. Adams Tr. 1138.

FF E 216. The '027 patent does not discuss techniques of die mounting or wire bonding, both of which were done manually when the original application was filed in 1963. Neither the Abacus bonder nor automated die attach equipment are covered by the '027 patent. Birchler Tr. 337, Adams Tr. 1138-1140, 1223, SPX-7 at p. 361-362.

FF E 217. Other Bonding Equipment which TI asserts were the subject of R&D relating to the '027 patent includes: Aluminum Copper Bonder, Wire Bonder, Standalone Auto Align, Base Metal Bonding, Low Cost Base Metal Plastic, PICS Pattern Recognition, Product Quality Support, Auto Align Upgrade, Standalone Bonding, Polar Bond Head, and Auto Assy & AA Upgrade/Process. CX-4 at 9, 19, 25-27, 30-32.

FF E 218. TI's plastic encapsulation R&D also included projects relating to an Auto/Visual Mechanical Inspection, TO-220 Tooling, Laser Symbolizer, and Quick Cure Equipment. CX-4 at 8, , 34.

FF E 219. Automation Projects included in CX-4 involved research and development of the following kinds of equipment: Automated Factory Assembly, Assy/Test Equipment Development, Advanced Assembly Development and Surface Mount Automation. CX-4 at 28-29, 32.

FF E 220. Automation projects all relate to manufacturing plastic

packages. Adams Tr. 1229.

FF E 221. Ball Bonding Equipment projects listed in CX-4 includes: research and development on Aluminum Ball Bond Lead Frame, and Aluminum/Copper Ball Bonders. CX-4 at 4-7.

FF E 222. The Ball Bonding Projects involve wire bonding. CX-4 at 4-7.

FF E 223. Other projects related to plastic encapsulation and included in TI's [C] expenditure for R&D include the following categories: Standardizing Bond Parameters and Package Design, Assembly Process Labs, Flux Evaluation, Semiconductor Evaluation and Design, General Package Improvement, Bonding Task Force, Electronic Assembly, Wafer Mapping and Engineering Studies. CX-4 at 1, 6-7, 9, 12, 14-15, 18-20, 26-28, 30, 34.

FF E 224. These projects are all related to the '027 patent in that they fit the five criteria applicable to the patent. Adams Tr. 1143-44.

FF E 225. The current budget for research and development for 1991 at the Dallas PAC is approximately [C] Greater than [C] of this amount will be used for research and development relating to plastic encapsulation. Adams at 1129, 1190.

FF E 226. The '027 patent discusses various post-encapsulation trim and form processes including trimming and cutting away the leads. CX-1, col. 7, 11. 3-7.

FF E 227. The '027 patent also discusses the testing of plastic encapsulated devices. CX-1, col. 6, 11. 27-31.

FF E 228. The '027 patent discusses the furnishing of plastic encapsulated devices to customer specifications. CX-1, col. 2, 11. 48-51; col. 7, 11. 3-7; col. 8, 11. 13-21.

FF E 229. INTENTIONALLY OMITTED

FF E 230. INTENTIONALLY OMITTED

FF E 231. Most of the projects listed in CX-4 relate to plastic encapsulated packages which involve bond wires, a two-sided mold, a product planar in form, with leads on two sides of the package. Adams Tr. 1130.

FF E 232. Cavity Packages projects listed on CX-4 include: 20 pin 160 width Cavity Molds, 68 pin PLCC Cavity Packages, and Process and Package Development. CX-4 at 3, 13, 19, 25.

FF E 233. The Cavity Packages listed on CX-4 are those related to plastic cavity packages and therefore concern plastic encapsulation. Adams Tr. 1210.

FF E 234. TI deleted three (3) projects from its list relating to cavity package development. Five (5) other research projects relating to cavity packages and plastic encapsulation totalling [C] were included on TI's list of R&D projects relating to the '027 patent. TI's Supplemental Response to Commission Investigative Staff's Second Set of Interrogatories, April 15, 1991, RX 475, CX-425, CX-426.

FF E 235. [C] Adams Tr. 1204, 1206, RX 469 at col. 6, lines 25-45, SPX 7 at p. 295, RX-336 Exhibit 19, RPX 54 at p. 169-170.

FF E 236. [C] CX-4 at 12, 15, 17, 18, 20.

FF E 237. Tape Automated Bonding Projects encompass the requirements of the '027 patent. They utilize encapsulation, lead frames, wire and tab bonding, and are planar in nature. Adams Tr. 1204.

FF E 238. TI included six [C] research projects on [C]

development totalling [C] in its list of projects relating to the '027 patent. RX-475, CX-425, CX-426.

FF E 239. Flip chip technology involves inverting the chip so that the active portion faces downward and then placing the chip on an insulative substrate for support. The insulative substrate has conductive pathways etched into it which make electrical contact with the active portions of the chip. Adams Tr. 1198-1199, RX 337 at p. 297, RX 469 at col. 6, lines 6-24.

FF E 240. No whisker wires are used to connect the active portions of a die to the leads in a flip chip. RX 337 at p. 125-127, RPX 54 at p. 144.

FF E 241. The Advanced Packaging projects listed on CX-4 is a project relating to flip chips. CX-4 at 6.

FF E 242. TI included research expenditures of [C] relating to development of flip chips on its list of expenditures relating to the '027 patent. Adams, Tr. 1201, CX-425.

FF E 243. TI's experiments with flip chips meet the requirements of the '027 patent in that it fits the five outlined categories. Adams Tr. 1201.

FF E 244. TI included 14 projects totalling [C] relating to research and development for specific products (e.g. 4MB DRAM VLSI). CX 425, CX 426.

FF E 245. Other projects that are related to Plastic Leaded Chip Carriers listed on CX-4 include: 44 pin, 32 pin, 28 pin, 38 pin and 4 megabit PLCCS. CX-4 at 2, 3, 9.

FF E 246. Package design of Plastic Leaded Chip Carriers includes all aspects of the assembly process, lead frame design, molding equipment, die attach and wire bonding. CX-4 at 9.

FF E 247. Many research projects included in CX-4 were projects that

concerned the encapsulation of various large size chips. These projects included: 1 Megabit DRAM VLSI, 1 Megabit DRAM Development, 4 Megabit DRAM Package/Process Development, 16 Megabit Packaging, Large Bar Automation, Packaging and Package Development, Advanced Packaging and Low Cost Heat Dissipation. CX-4 at 1-2, 8, 13, 15, 18, -26, 29, 31.

FF E 248. J-Leaded SOIC projects listed on CX-4 included: J-Leaded SOIC Narrow Body Package and Thin Package High Density Memory. CX-4 at 2, 16.

FF E 249. J-Leaded projects concern J-leaded plastic packages, which fit the requirements of the '027 patent. Adams Tr. 1135.

FF E 250. Other products that were the subject of TI's plastic encapsulation research and development and which are listed on CX-4 include the 28 pin DIP, 54 pin Quad package, Multi Chip Arrangements, and Products for Matrix Lead Frame. CX-4 at 7, 14, 21, 31.

FF E 251. These projects concern lead frame design, die attach, wire bonding, assembly, and molding. CX-4 at 7, 14, 21, 31.

FF E 252. The Test Equipment projects listed on CX-4 include the following types of equipment: SOIC Wide Body, Accelerated Stress Test, Large Bar Reliability, Test Structure Fab, Dip Factory Assembly Test, MOS Assembly Cost Reduction, Trim/Form, Gemini Test Handler, Other Test Handlers, Test Structure, CMOS Reliability, Parallel Test, Megabit/VLSI Process Reliability, Factory Cost Center Level 3 Systems, and Commercial Electronics. CX-4 at 5, 8, 10-11, 16, 19, 22-, 27-29, 33.

FF E 253. Testing equipment projects are related to plastic encapsulation. Adams Tr. 1222.

FF E 254. TI included nine [C] in its list totalling [C] that were listed as monies spent on the assembly process lab, which was aimed

at improving molding technology. Mr. Adams testified that it was impossible to allocate this money to a particular project, but the monies were easily identifiable as devoted to plastic-related projects. Schroen Tr. 206, Adams Tr. 1130, 1237, CX 425, CX 426.

FF E 255. Many of TI's research and development projects relate to equipment that is used in the manufacture of ceramic packages as well as plastic encapsulated ones. Adams Tr. 1140, 1222, 1231.

FF E 256. TI utilizes the FAM in Sherman in conjunction with its research and development projects. New equipment is primarily tried out at the FAM. Schroen Tr. 50, 52; Wilson Tr. 761.

FF E 257. TI's overall research and development budget in 1990 was over
[C] RX 401.

FF F 1. [C] [C]
] TI and [C] entered into a cross-license agreement ("the [C] license agreement") with an effective date of [C] RX 286.

FF F 2. The [C] license agreement states that it is to be construed, interpreted, applied and governed in all respects in accordance with the laws of the [C] RX 286.

FF F 3. Section 13 of the [C] license agreements provides:

[C]
]
[C]
]
]

Each of said items (a) through (i) is defined in the [C] license agreement. RX 286.

FF F 4. The [C] license agreement covers patents that issued during a [C] effective date, and includes semiconductors and plastic encapsulated integrated circuits. The '027 patent, which issued in 1977, is covered by the [C] license agreement. RX 286; Donaldson Tr. 913.

FF F 5. Article VII, Section 3 of the [C] license agreement provides:

[C]

]

[C

] RX 286.

FF F 6. On January 14, 1971, [C] executed a patent license agreement ("the [C] agreement"). Section 11 of the [C] agreement provides:

[C

]

[C

]

[

C

]

[

C

]

RX 423.

FF F 7. On August 8, 1990, [C] became a wholly-owned subsidiary of Analog. On that date, Analog acquired all of [C] stock. On November 3, 1990, Analog and [C] formally merged, with articles of merger having been filed with the Massachusetts Secretary of State on October 31, 1990. Analog acquired all of [C] assets and is a third party that has acquired [

C] of []. Order No. 21 at 2-6; Hinchey, Tr. 1284.

FF F 8. Joseph Hinchey, who testified at the hearing for Analog, is a senior vice president of Analog, and is chief financial officer for the corporation. Hinchey, Tr. 1262-1263.

FF F 9. [C] total worldwide sales of all of its products were over [C] [C] in the twelve months preceding its merger with Analog. Hinchey, Tr. 1286-1289, 1292; RX 465.

FF F 10. At the time that it merged with Analog, [C] entire product line was covered by the [C] license agreement. Hinchey, Tr. 1289, 1293; RX 286.

FF F 11. [C] sales of plastic encapsulated integrated circuits in the United States were about [C] during the year preceding [C] merger with Analog. Hinchey, Tr. 1290, 1292-1294.

FF F 12. Analog's total worldwide sales for its fiscal year 1990, which ended at the end of October of 1990, were about [C] [C]]. RX 278; Hinchey, Tr. 1264-1265, 1272.

FF F 13. Analog's sales of plastic encapsulated integrated circuits for its fiscal year, which ended at the end of October of 1990, were about [C] [C]. Hinchey, Tr. 1264, 1272-1274, 1290; RX 281A.

FF F 14. Analog's annual sales were about [C] [C] sales at the time that Analog acquired [C]. See Hinchey, Tr. 1297-1298.

FF F 15. Analog has two of its own encapsulation facilities offshore, whereas [C] did not have any offshore encapsulation facilities at the time it was acquired by Analog. Hinchey, Tr. 1298.

FF F 16. At the time that [C] was acquired by Analog, Analog had already been sued for patent infringement in a U.S. District court. Hinchey, Tr. 1296.

FF F 17. The combined sales of Analog's and [C] plastic encapsulated integrated circuits for 1990 were about [C]. Hinchey, Tr. 1290-1291.

FF F 18. Analog, even after acquiring [C], projects [C] [C] Analog bases this projection [C] [C] [C] [C] [C] Hinchey, Tr. 1291.

FF G 1. Analog established its subsidiary in Limerick, Ireland ("ADBV") in 1976. Hinchey, Tr. 1278, 1280; RX 256; SX 1 at 3.

FF G 2. ADBV makes plastic encapsulated products from the manufacture of wafers through testing. Hinchey, Tr. 1276; RX 256.

FF G 3. Analog has continuously sold products in the United States from ADBV since ADBV began its operations in plastic encapsulation of products. ADBV acquired the capability of encapsulating integrated circuits no later than 1978. Hinchey, Tr. 1280; SX 1 at 11.

FF G 4. Analog built its facility in the Philippines ("ADPI") in 1982. Hinchey, Tr. 1280-1281; RX 256; SX 1 at 3.

FF G 5. Plastic encapsulation of products takes place at ADPI, but most of the wafer manufacturing, testing and other finishing operations for the products encapsulated in the Philippines are carried out in the United States at Analog's facility in Massachusetts. Hinchey, Tr. 1276. ADPI currently plastic encapsulates most of Analog's domestically manufactured devices. SX 1 at 12. Few if any of the products from ADPI are sold without first being shipped to the United States. Hinchey, Tr. 1276-1277.

FF G 6. By 1988, Analog had invested more than [C] in ADBV and more than [C] in ADPI. Hinchey, Tr. 1279-1281; RX 279; RX 280.

FF G 7. Analog's total sales for its fiscal year 1988 were about [C] [C] [C]. Analog's total sales for its fiscal year 1989 were about [C] [C] [C]. Analog's total sales for its fiscal year 1990 were about [C] [C] [C]. RX 278; Hinchey, Tr. 1264-1265, 1272.

CONCLUSIONS OF LAW

1. The U.S. International Trade Commission has jurisdiction over the subject matter of this investigation. 19 U.S.C. § 1337.
2. Respondents' manufacturing processes do not literally infringe claims 1, 12 or 17 of the '027 patent. Opn. at 7 - 42
3. Respondents' manufacturing processes literally infringe claim 14 of the '027 patent. Opn. at 7 - 42
4. Respondents' manufacturing processes infringe claim 12 of the '027 patent under the doctrine of equivalents. Opn. at 7 - 42
5. The '027 patent is not invalid for obviousness. Opn. at 43 - 71
6. The '027 patent is not anticipated by the Helda-Lincoln invention. Opn. at 71
7. The '027 patent is not invalid for failure to set forth the best mode of practicing the invention. Opn. at 72 - 73
8. The '027 patent is not invalid for obviousness-type double patenting. Opn. at 73 - 82
9. The '027 patent is not unenforceable. Opn. at 82
10. Respondents have imported plastic encapsulated integrated circuits into the United States. Opn. at 82
11. A domestic industry exists with respect to the '027 patent. Opn. at 82 - 94
12. Analog's acquisition of [C] does not justify dismissal of charges under Section 337. Opn. at 94 - 105
13. The "grandfather clause" of the Process Patents Amendment Act does not provide Analog a defense to Section 337. Opn. at 106 - 110
14. There is a violation of section 337 of the Tariff Act of 1930, as

amended, in the importation of certain plastic encapsulated integrated circuits by reason of infringement of U.S. Letters Patent No. 4,043,027.

Conclusions of Law 2-13.

INITIAL DETERMINATION AND ORDER

Based on the foregoing opinion, findings of fact, conclusions of law, the evidence, and the record as a whole, and having considered all pleadings and arguments as well as proposed findings of fact and conclusions of law, it is the Administrative Law Judge's INITIAL DETERMINATION (ID) that a violation of § 337 exists in the importation of certain plastic encapsulated integrated circuits by reason of infringement of claims 12 and 14 of U.S. Letters Patent No. 4,043,027.

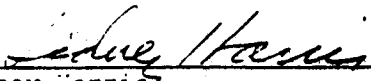
The Administrative Law Judge hereby CERTIFIES to the Commission this Initial Determination, together with the record of the hearing in this investigation consisting of the following:

1. The transcript of the hearing, with appropriate corrections as may hereafter be ordered by the Administrative Law Judge; and further
2. The exhibits accepted into evidence in this investigation as listed in the attached exhibit lists.

In accordance with Commission Interim Rule 210.44(b), all material found to be confidential by the Administrative Law Judge under Rule 210.6 is to be given in camera treatment.

The Secretary is instructed to serve a public version of this ID upon all parties of record and the confidential version upon counsel who are signatories to the protective order issued by the Administrative Law Judge in this investigation, and the Commission Investigative Attorney. To expedite service of the public version, counsel are hereby ordered to serve on the Administrative Law Judge by no later than October 28, 1991, a copy of this ID with those sections considered by the party to be confidential bracketed in red.

This ID shall become the determination of the Commission 45 days after its date of service unless the Commission within those 45 days shall have ordered review of this ID, or certain issues herein pursuant to Commission Interim Rule 210.54(b) or 210.55.



Sidney Harris
Administrative Law Judge

Issued: October 15, 1991

